

TPS7H5006-SEP Neutron Displacement Damage (NDD) Characterization



ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H5006-SEP PWM controller. The TPS7H5006-SEP showed a strong degree of hardness to neutron irradiation up to fluence level 1×10^{13} n/cm².

The neutron irradiation test is a destructive test. Test procedure follows MIL-STD-883 method 1017 as guidance. The purpose of this test is to determine the device susceptibility to non-ionizing energy loss (NIEL) degradation. Objectives of the test are, to detect and measure the degradation of critical device parameters as a function of neutron fluence and to determine if these parameters are within specified limits after exposure to a specified level of neutron fluence.

Table of Contents

1 Device Information	2
1.1 Product Description.....	2
1.2 Device Details.....	2
2 Total Dose Test Setup	3
2.1 Test Overview.....	3
2.2 Test Facility.....	3
2.3 Test Setup Details.....	3
3 Test Results	4
3.1 NDD Characterization Summary.....	4
3.2 Data Sheet Electrical Parameters and Associated Tests.....	5
4 Applicable and Reference Documents	9
4.1 Applicable Documents.....	9
4.2 Reference Documents.....	9
A Appendix: NDD Report Data	10

List of Figures

Figure 1-1. TPS7H5006-SEP Device.....	2
---------------------------------------	---

List of Tables

Table 1-1. Device and Exposure Details.....	2
Table 2-1. Neutron Irradiation Conditions.....	3
Table 3-1. TPS7H5006-SEP Electrical Parameters Table.....	5

Trademarks

All trademarks are the property of their respective owners.

1 Device Information

1.1 Product Description

The TPS7H5006-SEP is a radiation-tolerant, current mode, a single output PWM controller that supports buck applications and single ended isolated topologies optimized for DC-DC converters in space applications. The high switching frequency capability of the TPS7H5006-SEP, small footprint, and low-current consumption makes the device ideal for fully exploiting the area reduction and high-efficiency benefits of DC-DC converters. The TPS7H5006-SEP features integrated synchronous rectification output optimized for GaN power semiconductor based applications, the controller has configurable dead time and configurable leading edge blank time.

The TPS7H5006-SEP controller can be configured for maximum duty cycle of 75% or 100%. As such, the DCL pin can be left floating or connected to VLDO. The TPS7H5006-SEP is packaged in a very small 24-pin TSSOP (thin-shrink small outline package) package.

1.2 Device Details

Device and Exposure Details lists the device information and test conditions used in the NDD characterization.

Table 1-1. Device and Exposure Details

NDD Exposure Details	
TI Device	TPS7H5006-SEP
TI Part Name	TPS7H5006MPWTSEP
Device Function	PWM controller
Package	24-pin TSSOP
Technology	LBC7
Lot Number / Lot Trace Code	1805055 / 1AC5PSK
Sample Quantity	9 + 1 control unit
Exposure Facility	Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor (UMLRR)
Neutron Fluence (1-MeV equivalent) Level	1×10^{12} , 5×10^{12} , 1×10^{13} n/cm ²
Irradiation Temperature	25°C

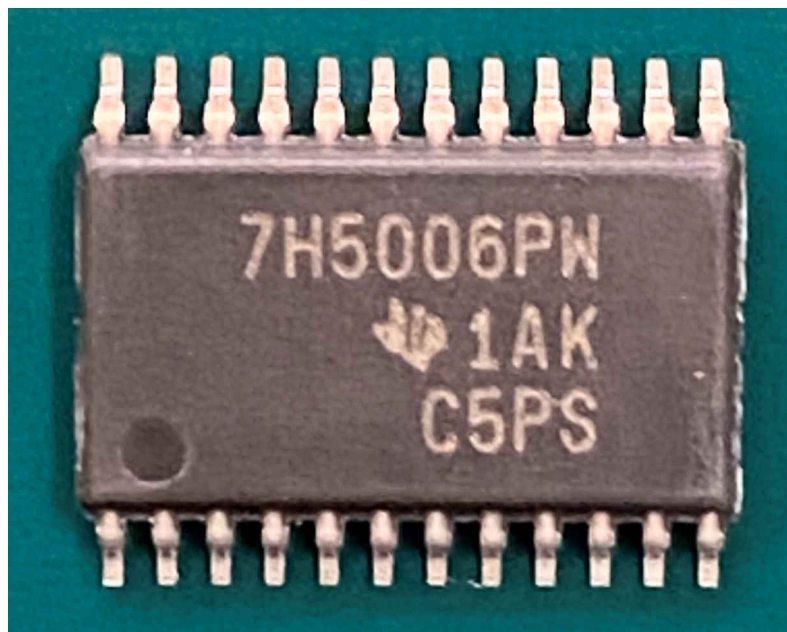


Figure 1-1. TPS7H5006-SEP Device

2 Total Dose Test Setup

2.1 Test Overview

General test procedures adhere to MIL-STD-883, Method 1017 as a guide for neutron irradiation. The TPS7H5006-SEP was electrically tested using the production automated test equipment (ATE) program at an ambient room temperature of 25°C before and after neutron irradiation.

2.2 Test Facility

The utilized test facility is the Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor. The neutron fluence for this irradiation was measured utilizing ASTM E-265 “Measuring Reaction Rates and Fast Neutron Fluence by Radioactivation of Sulfur-32” and correlated to the measured reactor power level. All irradiation conditions required under ASTM 722 were met, this includes: neutron fluence, distribution and uncertainty. The Average Integrated Neutron Fluence, 1-MeV(Si) equivalent, reflects these factors.

Detailed information of the radiation facility is available at the following link:

https://www.uml.edu/docs/FNI%20Brochure_tcm18-90375.pdf

2.3 Test Setup Details

Devices were irradiated at three fluence levels in unbiased conditions: 1.0×10^{12} n/cm², 5.0×10^{12} n/cm² and 1.0×10^{13} n/cm².

Table 2-1. Neutron Irradiation Conditions

GROUP	SAMPLE QTY	NEUTRON FLUENCE (n/cm ²)	BIAS
A	3	1.0×10^{12}	Unbias
B	3	5.0×10^{12}	Unbias
C	3	1.0×10^{13}	Unbias
Control Unit	1	N/A	N/A

3 Test Results

3.1 NDD Characterization Summary

The results show that all devices were fully functional and within specification limits. A sample size of nine units was exposed for neutron irradiation and an additional unirradiated control unit was used as correlation.

Overall, the TPS7H5006-SEP showed a strong degree of hardness to Neutron irradiation up to fluence level 1×10^{13} n/cm². The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each fluence level. The parameters that showed a greater degree of change between pre- and post- irradiation were still within the Electrical Performance Characteristics specified in the Data Sheet Electrical Parameters table. See [Table 3-1](#) for the Data Sheet Electrical Parameters and Associated Tests.

Electrical testing is done for pre- and post- neutron irradiation by ATE. ATE electrical test is done at an ambient room temperature of 25°C. Parameters not listed in the [Table 3-1](#) are omitted either because there is no parametric data or because verification was done through bench testing.

See [Appendix A](#) for NDD report up to 1.0×10^{13} n/cm².

3.2 Data Sheet Electrical Parameters and Associated Tests

Table 3-1. TPS7H5006-SEP Electrical Parameters Table

PARAMETER	TEST CONDITION	TPS7H5006-SEP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
SUPPLY VOLTAGES AND CURRENTS						
IDD Operating supply current	f _{SW} = 500 kHz, No load for OUTA, OUTB, SRA, and SRB		6.25	8	mA	5.24 __IDD_ACT_500K_NOLOAD_4V, 5.25 __IDD_ACT_500K_NOLOAD_5V, 5.26 __IDD_ACT_500K_NOLOAD_12V, 5.27 __IDD_ACT_500K_NOLOAD_14V
	f _{SW} = 1 MHz, No load for OUTA, OUTB, SRA, and SRB		6.75	9.5	mA	5.28 __IDD_ACT_1M_NOLOAD_4V, 5.29 __IDD_ACT_1M_NOLOAD_5V, 5.30 __IDD_ACT_1M_NOLOAD_12V, 5.31 __IDD_ACT_1M_NOLOAD_14V
	f _{SW} = 2 MHz, No load for OUTA, OUTB, SRA, and SRB		8.5	13.5	mA	5.36 __IDD_ACT_2M_NOLOAD_4V, 5.37 __IDD_ACT_2M_NOLOAD_5V, 5.38 __IDD_ACT_2M_NOLOAD_12V, 5.39 __IDD_ACT_2M_NOLOAD_14V
	f _{SW} = 500 kHz, C _{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		7.5	9.5	mA	5.48 __IDD_ACT_500K_4V, 5.49 __IDD_ACT_500K_5V, 5.50 __IDD_ACT_500K_12V, 5.51 __IDD_ACT_500K_14V
	f _{SW} = 1 MHz, C _{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		9	12	mA	5.52 __IDD_ACT_1M_4V, 5.53 __IDD_ACT_1M_5V, 5.54 __IDD_ACT_1M_12V, 5.55 __IDD_ACT_1M_14V
	f _{SW} = 2 MHz, C _{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		14	19.5	mA	5.60 __IDD_ACT_2M_4V, 5.61 __IDD_ACT_2M_5V, 5.62 __IDD_ACT_2M_12V, 5.63 __IDD_ACT_2M_14V
I _{DD(dis)} Standby current	EN = 0 V			3	mA	5.1 __IDD_DIS_4V, 5.2 __IDD_DIS_5V, 5.3 __IDD_DIS_12V, 5.4 __IDD_DIS_14V
VLDO Internal linear regulator output voltage	5 V ≤ VIN ≤ 14 V, f _{sw} ≤ 1 MHz	4.75	5	5.2	V	5.65 __V_LDO_100K_5V, 5.66 __V_LDO_100K_12V, 5.67 __V_LDO_100K_14V, 5.69 __V_LDO_200K_5V, 5.70 __V_LDO_200K_12V, 5.71 __V_LDO_200K_14V, 5.73 __V_LDO_500K_5V, 5.74 __V_LDO_500K_12V, 5.75 __V_LDO_500K_14V, 5.77 __V_LDO_1M_5V, 5.78 __V_LDO_1M_12V, 5.79 __V_LDO_1M_14V
	5 V ≤ VIN ≤ 14 V, f _{sw} = 2 MHz	4.65	5	5.2	V	5.85 __V_LDO_2M_5V, 5.86 __V_LDO_2M_12V, 5.87 __V_LDO_2M_14V
ENABLE AND UNDERVOLTAGE LOCKOUT						
V _{ENR} EN threshold rising		0.57	0.6	0.65	V	6.5 __V_EN_RISE_4V, 6.8 __V_EN_RISE_5V, 6.11 __V_EN_RISE_12V, 6.14 __V_EN_RISE_14V
V _{ENF} EN threshold falling		0.47	0.5	0.55	V	6.6 __V_EN_FALL_4V, 6.9 __V_EN_FALL_5V, 6.12 __V_EN_FALL_12V, 6.15 __V_EN_FALL_14V
V _{ENH} EN hysteresis voltage		85	95	105	mV	6.7 __V_EN_HYS_4V, 6.10 __V_EN_HYS_5V, 6.13 __V_EN_HYS_12V, 6.16 __V_EN_HYS_14V
I _{EN} EN pin input leakage current	VIN = 14 V, EN = 5 V		5	50	nA	6.1 __I_EN_LEAK_4V, 6.2 __I_EN_LEAK_5V, 6.3 __I_EN_LEAK_12V, 6.4 __I_EN_LEAK_14V
VLDO _{UVLOR} VLDO UVLO rising		3.44	3.55	3.66	V	6.34 __UVLO_VLDO_RISE_1MHz, 6.37 __UVLO_VLDO_RISE_100kHz, 6.40 __UVLO_VLDO_RISE_200kHz, 6.43 __UVLO_VLDO_RISE_500kHz, 6.46 __UVLO_VLDO_RISE_2MHz
VLDO _{UVLOF} VLDO UVLO falling		3.29	3.4	3.51	V	6.35 __UVLO_VLDO_FALL_1MHz, 6.38 __UVLO_VLDO_FALL_100kHz, 6.41 __UVLO_VLDO_FALL_200kHz, 6.44 __UVLO_VLDO_FALL_500kHz, 6.47 __UVLO_VLDO_FALL_2MHz
VLDO _{UVLOH} VLDO UVLO hysteresis		115	135	160	mV	6.36 __UVLO_VLDO_HYS_1MHz, 6.39 __UVLO_VLDO_HYS_100kHz, 6.42 __UVLO_VLDO_HYS_200kHz, 6.45 __UVLO_VLDO_HYS_500kHz, 6.48 __UVLO_VLDO_HYS_2MHz
SOFT START						
I _{SS} Soft-start current	SS = 0.3 V	1.98	2.7	3.32	μA	7.1 __I_SS_4V, 7.3 __I_SS_5V, 7.5 __I_SS_12V, 7.7 __I_SS_14V
ERROR AMPLIFIER						
E _{A_{gm}} Transconductance	-2 μA < I _{COMP} < 2 μA, V _(COMP) = 1 V	1150	1800	2500	μA/V	8.9 __EA_GM_4V, 8.10 __EA_GM_5V, 8.11 __EA_GM_12V, 8.12 __EA_GM_14V

Table 3-1. TPS7H5006-SEP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5006-SEP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
EA _{ISRC} Error amplifier source current	V _(COMP) = 1 V, 100-mV input overdrive	100		190	μA	8.13 __EA_I_SOURCE_4V, 8.14 __EA_I_SOURCE_5V, 8.15 __EA_I_SOURCE_12V, 8.16 __EA_I_SOURCE_14V
EA _{ISNK} Error amplifier sink current	V _(COMP) = 1 V, 100-mV input overdrive	100		190	μA	8.17 __EA_I_SINK_4V, 8.18 __EA_I_SINK_5V, 8.19 __EA_I_SINK_12V, 8.20 __EA_I_SINK_14V
EA _{OS} Error amplifier offset voltage		-2		2	mV	8.5 __EA_OS_4V, 8.6 __EA_OS_5V, 8.7 __EA_OS_12V, 8.8 __EA_OS_14V
OSCILLATOR						
SYNC _{RT} SYNC out low-to-high rise time (10%/90%)	C _{LOAD} = 25 pF		6	15	ns	9.1 __T_SYNC_RISE_100kHz_4V, 9.5 __T_SYNC_RISE_200kHz_4V, 9.9 __T_SYNC_RISE_500kHz_4V, 9.13 __T_SYNC_RISE_1MHz_4V, 9.17 __T_SYNC_RISE_1p5MHz_4V, 9.21 __T_SYNC_RISE_2MHz_4V, 9.25 __T_SYNC_RISE_100kHz_5V, 9.29 __T_SYNC_RISE_200kHz_5V, 9.33 __T_SYNC_RISE_500kHz_5V, 9.37 __T_SYNC_RISE_1MHz_5V, 9.41 __T_SYNC_RISE_1p5MHz_5V, 9.45 __T_SYNC_RISE_2MHz_5V, 9.49 __T_SYNC_RISE_100kHz_12V, 9.53 __T_SYNC_RISE_200kHz_12V, 9.57 __T_SYNC_RISE_500kHz_12V, 9.61 __T_SYNC_RISE_1MHz_12V, 9.65 __T_SYNC_RISE_1p5MHz_12V, 9.69 __T_SYNC_RISE_2MHz_12V, 9.73 __T_SYNC_RISE_100kHz_14V, 9.77 __T_SYNC_RISE_200kHz_14V, 9.81 __T_SYNC_RISE_500kHz_14V, 9.85 __T_SYNC_RISE_1MHz_14V, 9.89 __T_SYNC_RISE_1p5MHz_14V, 9.93 __T_SYNC_RISE_2MHz_14V
SYNC _{FT} SYNC out high-to-low fall time (10%/90%)	C _{LOAD} = 25 pF		6	17	ns	9.2 __T_SYNC_FALL_100kHz_4V, 9.14 __T_SYNC_FALL_1MHz_4V, 9.22 __T_SYNC_FALL_2MHz_4V, 9.26 __T_SYNC_FALL_100kHz_5V, 9.38 __T_SYNC_FALL_1MHz_5V, 9.46 __T_SYNC_FALL_2MHz_5V, 9.74 __T_SYNC_FALL_100kHz_14V, 9.86 __T_SYNC_FALL_1MHz_14V, 9.94 __T_SYNC_FALL_2MHz_14V
SYNC _{OL} SYNC out low level	I _{OL} = 10 mA			500	mV	9.186 __SYNC_VOL_4V, 9.187 __SYNC_VOL_5V, 9.188 __SYNC_VOL_12V, 9.189 __SYNC_VOL_14V
EXT _{DT} Externally set frequency detection time	RT = Open, f = 200 kHz			20	μs	9.185 __T_SYNC_DETECT
FSW _{EXT} Externally set frequency	RT = 1.07 MΩ	95	105	115	kHz	9.4 __FSW_EXT_RT_100kHz_4V, 9.28 __FSW_EXT_RT_100kHz_5V, 9.52 __FSW_EXT_RT_100kHz_12V, 9.76 __FSW_EXT_RT_100kHz_14V
	RT = 511 kΩ	190	210	230	kHz	9.8 __FSW_EXT_RT_200kHz_4V, 9.32 __FSW_EXT_RT_200kHz_5V, 9.56 __FSW_EXT_RT_200kHz_12V, 9.80 __FSW_EXT_RT_200kHz_14V
	RT = 90.9 kΩ	900	1000	1100	kHz	9.16 __FSW_EXT_RT_1MHz_4V, 9.40 __FSW_EXT_RT_1MHz_5V, 9.64 __FSW_EXT_RT_1MHz_12V, 9.88 __FSW_EXT_RT_1MHz_14V
	RT = 34.8 kΩ	1700	2000	2300	kHz	9.24 __FSW_EXT_RT_2MHz_4V, 9.48 __FSW_EXT_RT_2MHz_5V, 9.72 __FSW_EXT_RT_2MHz_12V, 9.96 __FSW_EXT_RT_2MHz_14V
VOLTAGE REFERENCE						
VREF Internal voltage reference initial tolerance	Measured at COMP, 25°C	0.609	0.613	0.615	V	8.1 __VREF_4V, 8.2 __VREF_5V, 8.3 __VREF_12V, 8.4 __VREF_14V

Table 3-1. TPS7H5006-SEP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5006-SEP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
REFCAP REFCAP voltage	REFCAP = 470 nF	1.213	1.225	1.237	V	5.88 __V_REFCAP_100K_4V, 5.89 __V_REFCAP_100K_5V, 5.90 __V_REFCAP_100K_12V, 5.91 __V_REFCAP_100K_14V, 5.92 __V_REFCAP_200K_4V, 5.93 __V_REFCAP_200K_5V, 5.94 __V_REFCAP_200K_12V, 5.95 __V_REFCAP_200K_14V, 5.96 __V_REFCAP_500K_4V, 5.97 __V_REFCAP_500K_5V, 5.98 __V_REFCAP_500K_12V, 5.99 __V_REFCAP_500K_14V, 5.100 __V_REFCAP_1M_4V, 5.101 __V_REFCAP_1M_5V, 5.102 __V_REFCAP_1M_12V, 5.103 __V_REFCAP_1M_14V, 5.104 __V_REFCAP_1P5M_4V, 5.105 __V_REFCAP_1P5M_5V, 5.106 __V_REFCAP_1P5M_12V, 5.107 __V_REFCAP_1P5M_14V, 5.108 __V_REFCAP_2M_4V, 5.109 __V_REFCAP_2M_5V, 5.110 __V_REFCAP_2M_12V, 5.111 __V_REFCAP_2M_14V
CURRENT SENSE, CURRENT LIMIT, AND HICCUP						
CCSR	COMP to CS_ILIM ratio	2.00	2.06	2.12		10.49 __CCSR_Ratio
V _{CS_ILIM} Current limit (over-current) threshold			1.05	1.09	V	10.1 __V_CS_ILIM_OC_Rise_4V, 10.3 __V_CS_ILIM_OC_Rise_5V, 10.5 __V_CS_ILIM_OC_Rise_12V, 10.7 __V_CS_ILIM_OC_Rise_14V
FAULT						
V _{FLTR} FLT threshold rising		0.57	0.6	0.65	V	12.1 __V_FAULT_RISE_4V, 12.4 __V_FAULT_RISE_5V, 12.7 __V_FAULT_RISE_12V, 12.10 __V_FAULT_RISE_14V
V _{FLTF} FLT threshold falling		0.47	0.5	0.55	V	12.2 __V_FAULT_FALL_4V, 12.5 __V_FAULT_FALL_5V, 12.8 __V_FAULT_FALL_12V, 12.11 __V_FAULT_FALL_14V
V _{FLTH} FLT hysteresis voltage		90	100	110	mV	12.3 __V_FAULT_HYS_4V, 12.6 __V_FAULT_HYS_5V, 12.9 __V_FAULT_HYS_12V, 12.12 __V_FAULT_HYS_14V
T _{FLT} FLT minimum pulse width	V _{FLT} = 1 V	0.4		1.4	μs	12.14 __T_FAULT_MIN
t _{DFLT} FLT delay duration	f _{sw} = 100 kHz	140	152	169	μs	12.15 __T_FAULT_DELAY_100kHz
	f _{sw} = 200 kHz	66	78	86	μs	12.17 __T_FAULT_DELAY_200kHz
	f _{sw} = 1 MHz	14	17	21	μs	12.21 __T_FAULT_DELAY_1MHz
	f _{sw} = 2 MHz	7	11	14	μs	12.23 __T_FAULT_DELAY_2MHz
PRIMARY AND SYNCHRONOUS RECTIFIER OUTPUTS						
Rise/fall time	R _{LOAD} = 50 kΩ, C _{LOAD} = 100 pF, 10% to 90%		10	17	ns	13.1 __OUTA_RISE_1MHz_4V, 13.9 __OUTA_RISE_1MHz_5V, 13.17 __OUTA_RISE_1MHz_12V, 13.25 __OUTA_RISE_1MHz_14V, 13.3 __OUTA_FALL_1MHz_4V, 13.11 __OUTA_FALL_1MHz_5V, 13.19 __OUTA_FALL_1MHz_12V, 13.27 __OUTA_FALL_1MHz_14V
t _{MIN} Minimum on-time LEB = 10 kΩ	LEB = 10 kΩ, 5 V ≤ VIN ≤ 14 V			85	ns	13.145 __OUT_T_ON_MIN

Table 3-1. TPS7H5006-SEP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5006-SEP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
TD _{PS} Primary off to secondary on dead time	PS = floating, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	5	8	11	ns	13.37 __PSA_DT_0ns_1M_5V, 13.41 __PSA_DT_0ns_1M_12V, 13.45 __PSA_DT_0ns_1M_14V
	PS = 49.9 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	43	50	55	ns	13.53 __PSA_DT_50ns_1M_5V, 13.57 __PSA_DT_50ns_1M_12V, 13.61 __PSA_DT_50ns_1M_14V
	PS = 107 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	85	100	110	ns	13.69 __PSA_DT_100ns_1M_5V, 13.73 __PSA_DT_100ns_1M_12V, 13.77 __PSA_DT_100ns_1M_14V
TD _{SP} Secondary off to primary on dead time	SP = floating, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	5	8	11	ns	13.39 __SPA_DT_0ns_1M_5V, 13.43 __SPA_DT_0ns_1M_12V, 13.47 __SPA_DT_0ns_1M_14V
	SP = 49.9 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	43	50	55	ns	13.55 __SPA_DT_50ns_1M_5V, 13.59 __SPA_DT_50ns_1M_12V, 13.63 __SPA_DT_50ns_1M_14V
	SP = 100 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	85	100	110	ns	13.71 __SPA_DT_100ns_1M_5V, 13.75 __SPA_DT_100ns_1M_12V, 13.79 __SPA_DT_100ns_1M_14V
DUTY CYCLE						
D _{MAX} Maximum duty cycle	DCL = floating	70	75	80	%	13.163 __MAX_DC_DCL_OPEN
	DCL =VLDO			100	%	13.166 __MAX_DC_DCL_VLDO

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, [TPS7H5006-SEP Radiation-Hardness-Assured Si and GaN Dual Output Controller data sheet](#)
- Texas Instruments, [TPS7H500x-SEP Evaluation Module \(EVM\)](#)
- Texas Instruments, [TPS7H500x-SEP Single-Event Effects \(SEE\) Radiation Report](#)

4.2 Reference Documents

Texas Instruments neutron irradiation test follow the guideline from MIL-STD-883 TM 1017. The document is available in Defense Logistic Agency's website.

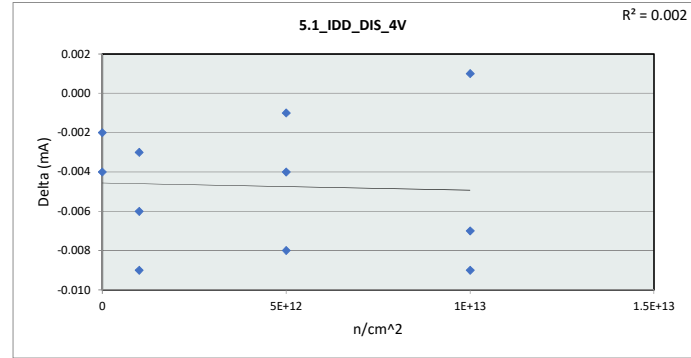
A Appendix: NDD Report Data

This appendix contains the NDD report data.

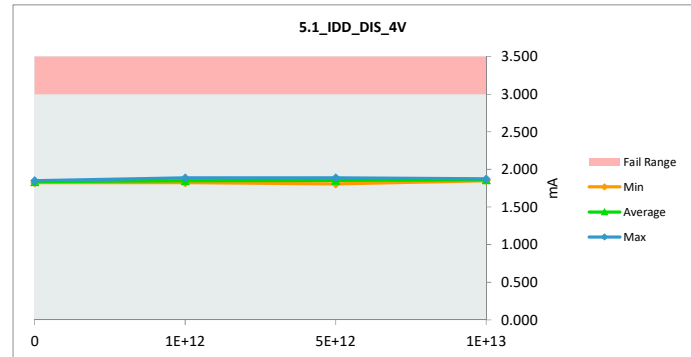
NDD Characterization Report
TPS7H5006-SEP

NDD Characterization Report TPS7H5006-SEP

5.1_IDD_DIS_4V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.6	3	
Min Limit		1		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.827	1.825	-0.002
0	49	1.855	1.851	-0.004
1E+12	11	1.888	1.885	-0.003
1E+12	12	1.855	1.846	-0.009
1E+12	13	1.830	1.824	-0.006
5E+12	14	1.812	1.808	-0.004
5E+12	15	1.867	1.866	-0.001
5E+12	16	1.896	1.888	-0.008
1E+13	17	1.883	1.874	-0.009
1E+13	18	1.865	1.866	0.001
1E+13	19	1.859	1.852	-0.007
Max		1.896	1.888	0.001
Average		1.858	1.853	-0.005
Min		1.812	1.808	-0.009
Std Dev		0.026	0.026	0.003

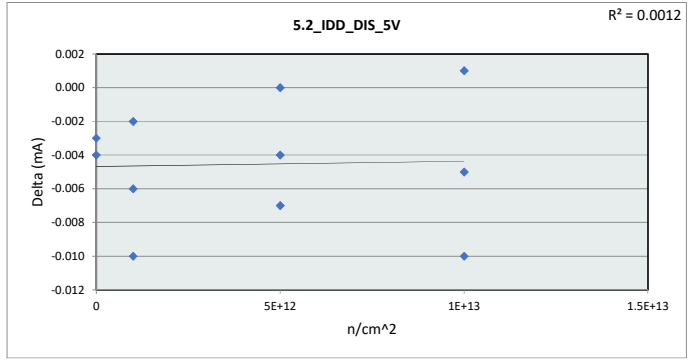


5.1_IDD_DIS_4V				
Test Site				
Tester				
Test Number				
Max Limit	3		mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	1.825	1.824	1.808	1.852
Average	1.838	1.852	1.854	1.864
Max	1.851	1.885	1.888	1.874
UL	3.000	3.000	3.000	3.000

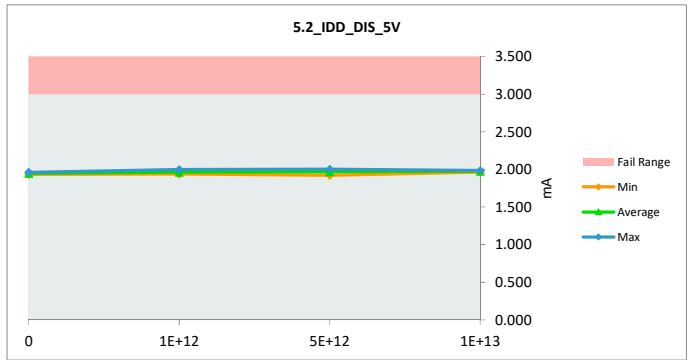


NDD Characterization Report TPS7H5006-SEP

5.2_IDD_DIS_5V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.8	3	
Min Limit		1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.937	1.934	-0.003
0	49	1.966	1.962	-0.004
1E+12	11	2.000	1.998	-0.002
1E+12	12	1.967	1.957	-0.010
1E+12	13	1.943	1.937	-0.006
5E+12	14	1.925	1.921	-0.004
5E+12	15	1.980	1.980	0.000
5E+12	16	2.009	2.002	-0.007
1E+13	17	1.995	1.985	-0.010
1E+13	18	1.977	1.978	0.001
1E+13	19	1.971	1.966	-0.005
Max		2.009	2.002	0.001
Average		1.970	1.965	-0.005
Min		1.925	1.921	-0.010
Std Dev		0.027	0.026	0.004

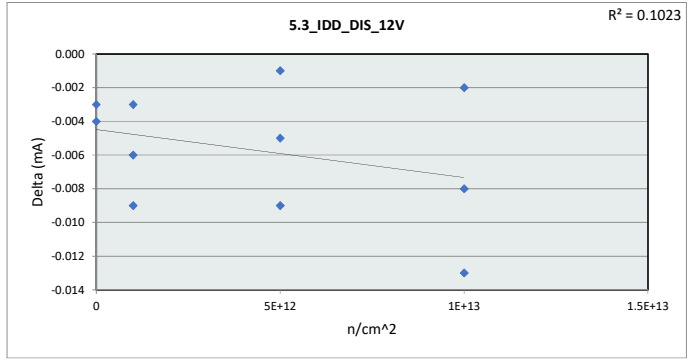


5.2_IDD_DIS_5V				
Test Site				
Tester				
Test Number				
Max Limit	3		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.934	1.937	1.921	1.966
Average	1.948	1.964	1.968	1.976
Max	1.962	1.998	2.002	1.985
UL	3.000	3.000	3.000	3.000

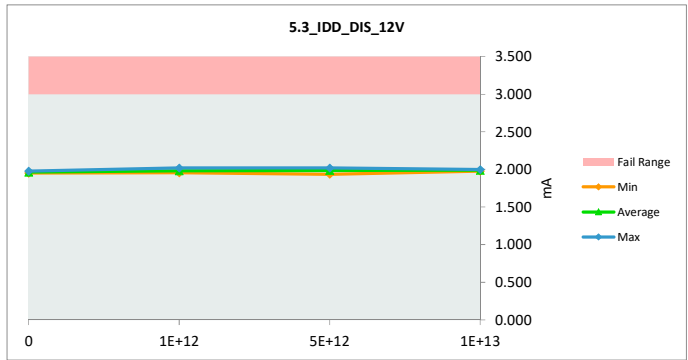


NDD Characterization Report TPS7H5006-SEP

5.3_IDD_DIS_12V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.8	3	
Min Limit		1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.956	1.952	-0.004
0	49	1.980	1.977	-0.003
1E+12	11	2.023	2.020	-0.003
1E+12	12	1.984	1.975	-0.009
1E+12	13	1.960	1.954	-0.006
5E+12	14	1.942	1.937	-0.005
5E+12	15	1.999	1.998	-0.001
5E+12	16	2.028	2.019	-0.009
1E+13	17	2.012	1.999	-0.013
1E+13	18	1.992	1.990	-0.002
1E+13	19	1.987	1.979	-0.008
Max		2.028	2.020	-0.001
Average		1.988	1.982	-0.006
Min		1.942	1.937	-0.013
Std Dev		0.027	0.027	0.004

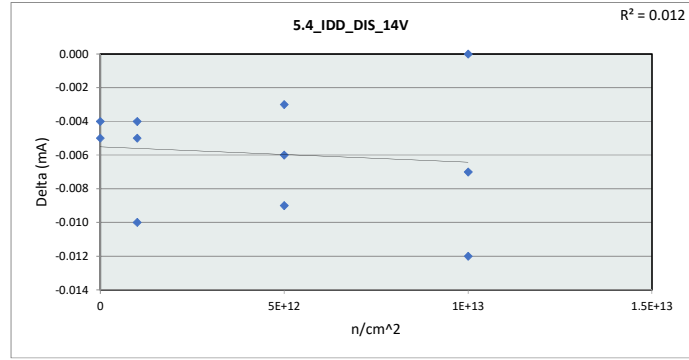


5.3_IDD_DIS_12V				
Test Site				
Tester				
Test Number				
Max Limit	3		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.952	1.954	1.937	1.979
Average	1.965	1.983	1.985	1.989
Max	1.977	2.020	2.019	1.999
UL	3.000	3.000	3.000	3.000

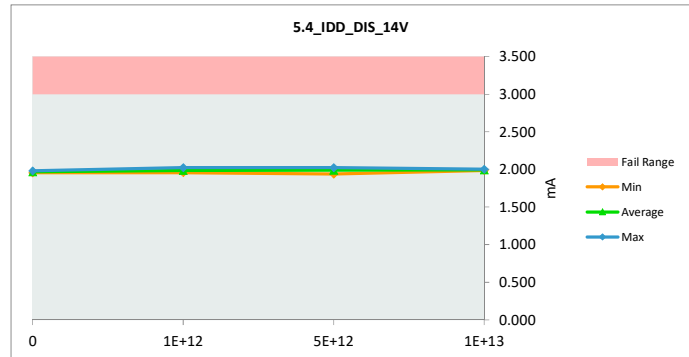


NDD Characterization Report TPS7H5006-SEP

5.4_IDD_DIS_14V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.8	3	
Min Limit		1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.960	1.956	-0.004
0	49	1.985	1.980	-0.005
1E+12	11	2.028	2.024	-0.004
1E+12	12	1.989	1.979	-0.010
1E+12	13	1.963	1.958	-0.005
5E+12	14	1.947	1.941	-0.006
5E+12	15	2.004	2.001	-0.003
5E+12	16	2.033	2.024	-0.009
1E+13	17	2.016	2.004	-0.012
1E+13	18	1.995	1.995	0.000
1E+13	19	1.992	1.985	-0.007
Max		2.033	2.024	0.000
Average		1.992	1.986	-0.006
Min		1.947	1.941	-0.012
Std Dev		0.028	0.027	0.003

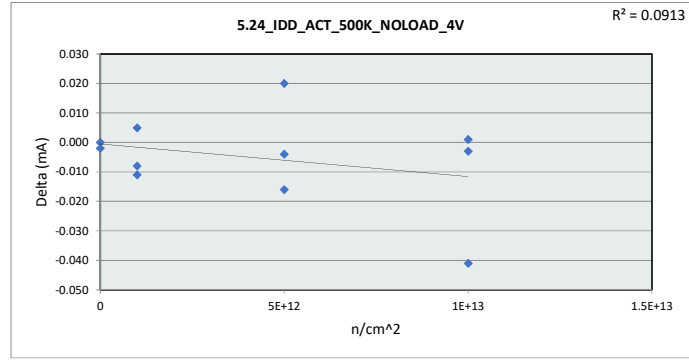


5.4_IDD_DIS_14V				
Test Site				
Tester				
Test Number				
Max Limit	3		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.956	1.958	1.941	1.985
Average	1.968	1.987	1.989	1.995
Max	1.980	2.024	2.024	2.004
UL	3.000	3.000	3.000	3.000

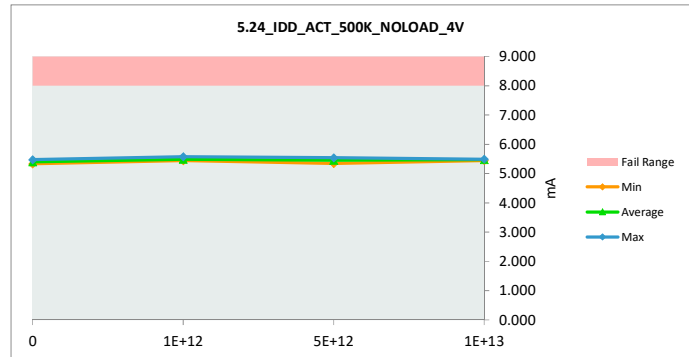


NDD Characterization Report TPS7H5006-SEP

5.24_IDD_ACT_500K_NOLOAD_4V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		7.8	8	
Min Limit		2		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.334	5.332	-0.002
0	49	5.475	5.475	0.000
1E+12	11	5.574	5.579	0.005
1E+12	12	5.453	5.442	-0.011
1E+12	13	5.466	5.458	-0.008
5E+12	14	5.352	5.348	-0.004
5E+12	15	5.518	5.538	0.020
5E+12	16	5.496	5.480	-0.016
1E+13	17	5.452	5.449	-0.003
1E+13	18	5.483	5.484	0.001
1E+13	19	5.533	5.492	-0.041
Max		5.574	5.579	0.020
Average		5.467	5.462	-0.005
Min		5.334	5.332	-0.041
Std Dev		0.071	0.072	0.015

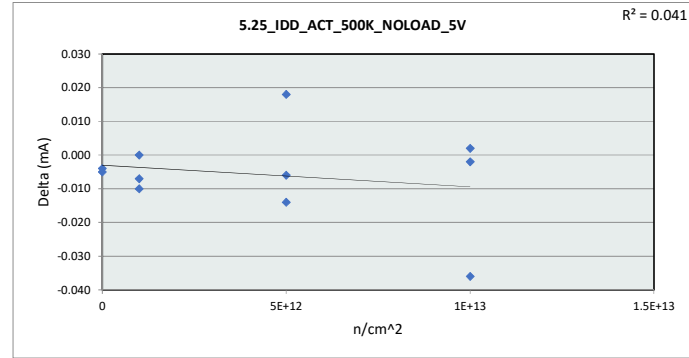


5.24_IDD_ACT_500K_NOLOAD				
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	5.332	5.442	5.348	5.449
Average	5.404	5.493	5.455	5.475
Max	5.475	5.579	5.538	5.492
UL	8.000	8.000	8.000	8.000

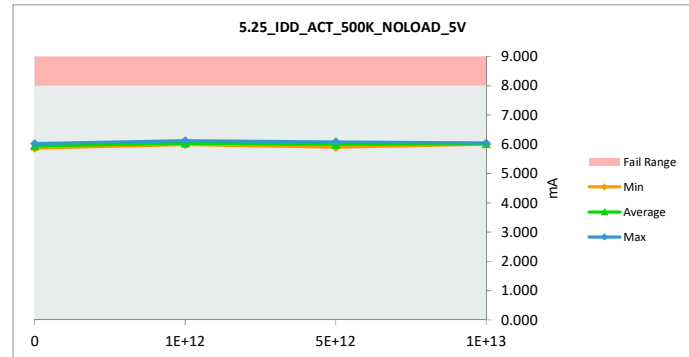


NDD Characterization Report TPS7H5006-SEP

5.25_IDD_ACT_500K_NOLOAD_5V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		7.8	8	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.879	5.875	-0.004
0	49	6.029	6.024	-0.005
1E+12	11	6.124	6.124	0.000
1E+12	12	6.002	5.992	-0.010
1E+12	13	6.016	6.009	-0.007
5E+12	14	5.904	5.898	-0.006
5E+12	15	6.069	6.087	0.018
5E+12	16	6.050	6.036	-0.014
1E+13	17	6.001	5.999	-0.002
1E+13	18	6.032	6.034	0.002
1E+13	19	6.082	6.046	-0.036
Max		6.124	6.124	0.018
Average		6.017	6.011	-0.006
Min		5.879	5.875	-0.036
Std Dev		0.072	0.073	0.013

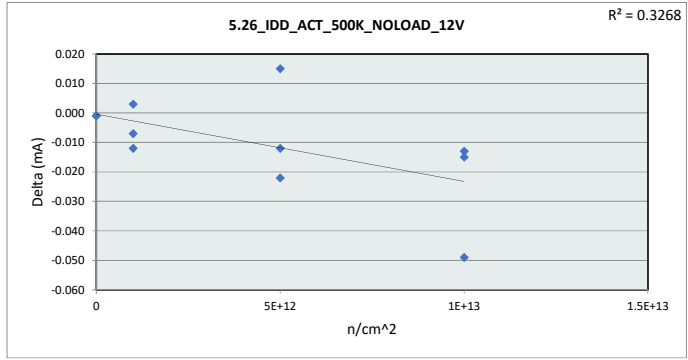


5.25_IDD_ACT_500K_NOLOAD				
Test Site				
Tester				
Test Number				
Max Limit	8		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.875	5.992	5.898	5.999
Average	5.950	6.042	6.007	6.026
Max	6.024	6.124	6.087	6.046
UL	8.000	8.000	8.000	8.000

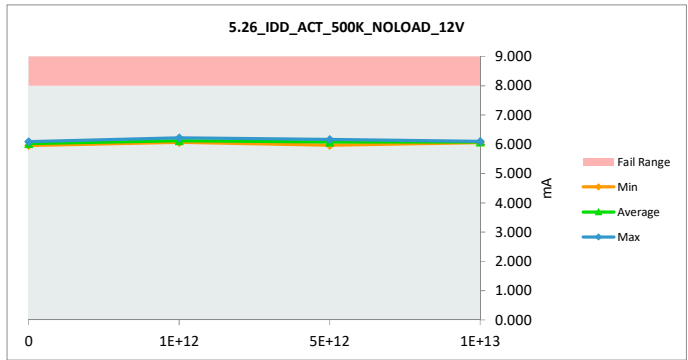


NDD Characterization Report TPS7H5006-SEP

5.26_IDD_ACT_500K_NOLOAD_12V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		7.8	8	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.965	5.964	-0.001
0	49	6.089	6.088	-0.001
1E+12	11	6.219	6.222	0.003
1E+12	12	6.079	6.067	-0.012
1E+12	13	6.086	6.079	-0.007
5E+12	14	5.978	5.966	-0.012
5E+12	15	6.146	6.161	0.015
5E+12	16	6.134	6.112	-0.022
1E+13	17	6.072	6.057	-0.015
1E+13	18	6.098	6.085	-0.013
1E+13	19	6.153	6.104	-0.049
Max		6.219	6.222	0.015
Average		6.093	6.082	-0.010
Min		5.965	5.964	-0.049
Std Dev		0.074	0.075	0.016

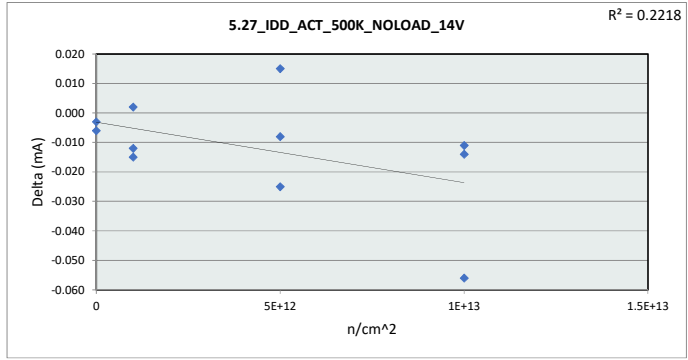


5.26_IDD_ACT_500K_NOLOAD				
Test Site				
Tester				
Test Number				
Max Limit	8		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.964	6.067	5.966	6.057
Average	6.026	6.123	6.080	6.082
Max	6.088	6.222	6.161	6.104
UL	8.000	8.000	8.000	8.000

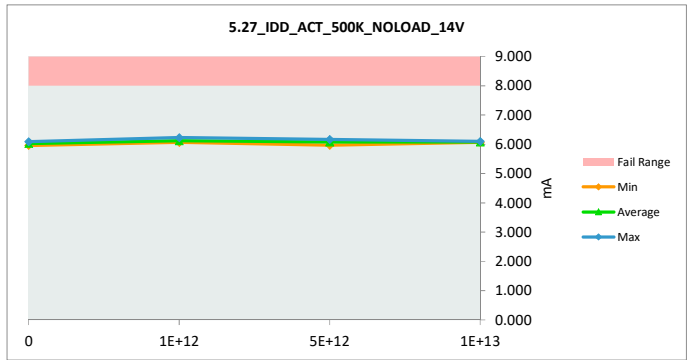


NDD Characterization Report TPS7H5006-SEP

5.27_IDD_ACT_500K_NOLOAD_14V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		7.8	8	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.970	5.964	-0.006
0	49	6.096	6.093	-0.003
1E+12	11	6.227	6.229	0.002
1E+12	12	6.084	6.069	-0.015
1E+12	13	6.092	6.080	-0.012
5E+12	14	5.978	5.970	-0.008
5E+12	15	6.151	6.166	0.015
5E+12	16	6.141	6.116	-0.025
1E+13	17	6.076	6.062	-0.014
1E+13	18	6.102	6.091	-0.011
1E+13	19	6.161	6.105	-0.056
Max		6.227	6.229	0.015
Average		6.098	6.086	-0.012
Min		5.970	5.964	-0.056
Std Dev		0.075	0.076	0.018

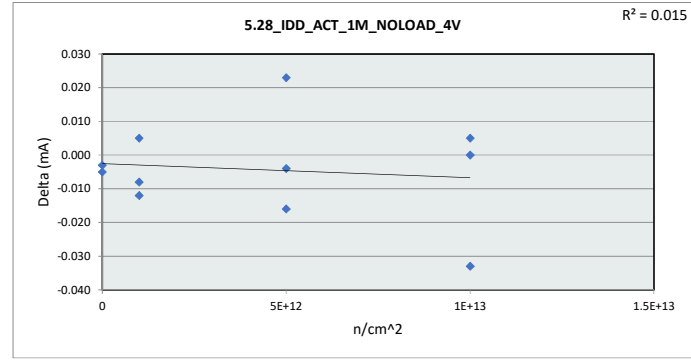


5.27_IDD_ACT_500K_NOLOAD				
Test Site				
Tester				
Test Number				
Max Limit	8		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.964	6.069	5.970	6.062
Average	6.029	6.126	6.084	6.086
Max	6.093	6.229	6.166	6.105
UL	8.000	8.000	8.000	8.000

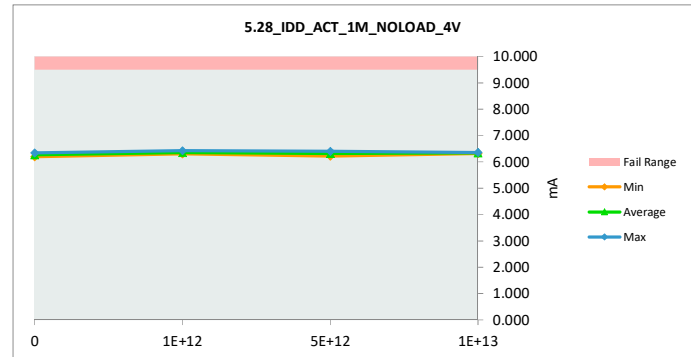


NDD Characterization Report TPS7H5006-SEP

5.28_IDD_ACT_1M_NOLOAD_4V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.198	6.195	-0.003
0	49	6.351	6.346	-0.005
1E+12	11	6.423	6.428	0.005
1E+12	12	6.320	6.308	-0.012
1E+12	13	6.333	6.325	-0.008
5E+12	14	6.221	6.217	-0.004
5E+12	15	6.377	6.400	0.023
5E+12	16	6.368	6.352	-0.016
1E+13	17	6.319	6.319	0.000
1E+13	18	6.347	6.352	0.005
1E+13	19	6.393	6.360	-0.033
Max		6.423	6.428	0.023
Average		6.332	6.327	-0.004
Min		6.198	6.195	-0.033
Std Dev		0.068	0.069	0.014

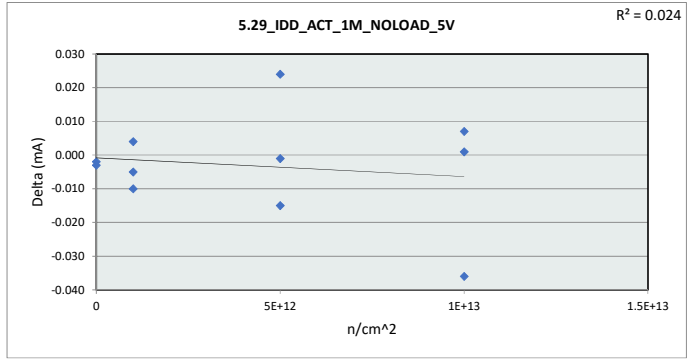


5.28_IDD_ACT_1M_NOLOAD_4V				
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.195	6.308	6.217	6.319
Average	6.271	6.354	6.323	6.344
Max	6.346	6.428	6.400	6.360
UL	9.500	9.500	9.500	9.500

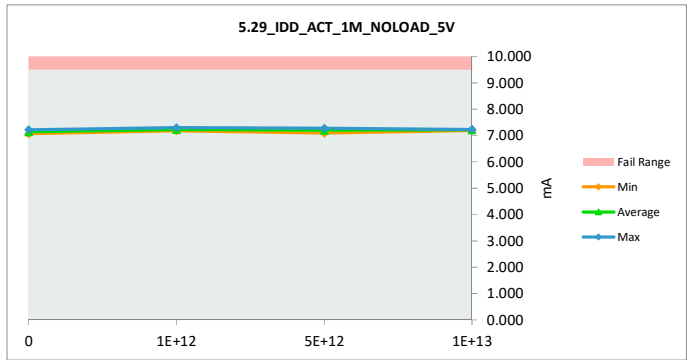


NDD Characterization Report TPS7H5006-SEP

5.29_IDD_ACT_1M_NOLOAD_5V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.071	7.069	-0.002
0	49	7.226	7.223	-0.003
1E+12	11	7.296	7.300	0.004
1E+12	12	7.190	7.180	-0.010
1E+12	13	7.206	7.201	-0.005
5E+12	14	7.096	7.095	-0.001
5E+12	15	7.250	7.274	0.024
5E+12	16	7.251	7.236	-0.015
1E+13	17	7.196	7.197	0.001
1E+13	18	7.225	7.232	0.007
1E+13	19	7.273	7.237	-0.036
Max		7.296	7.300	0.024
Average		7.207	7.204	-0.003
Min		7.071	7.069	-0.036
Std Dev		0.069	0.069	0.015

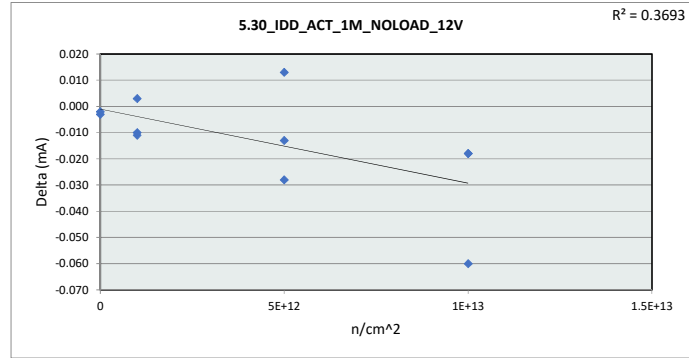


5.29_IDD_ACT_1M_NOLOAD_5V				
Test Site				
Tester				
Test Number				
Max Limit	9.5		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.069	7.180	7.095	7.197
Average	7.146	7.227	7.202	7.222
Max	7.223	7.300	7.274	7.237
UL	9.500	9.500	9.500	9.500

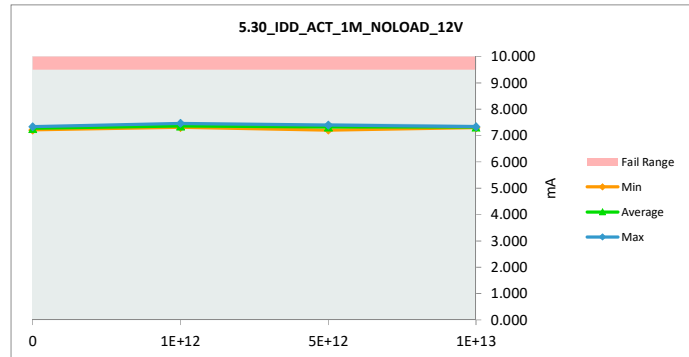


NDD Characterization Report TPS7H5006-SEP

5.30_IDD_ACT_1M_NOLOAD_12V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.214	7.212	-0.002
0	49	7.337	7.334	-0.003
1E+12	11	7.461	7.464	0.003
1E+12	12	7.319	7.309	-0.010
1E+12	13	7.327	7.316	-0.011
5E+12	14	7.224	7.211	-0.013
5E+12	15	7.387	7.400	0.013
5E+12	16	7.394	7.366	-0.028
1E+13	17	7.316	7.298	-0.018
1E+13	18	7.337	7.319	-0.018
1E+13	19	7.396	7.336	-0.060
Max		7.461	7.464	0.013
Average		7.337	7.324	-0.013
Min		7.214	7.211	-0.060
Std Dev		0.073	0.073	0.019

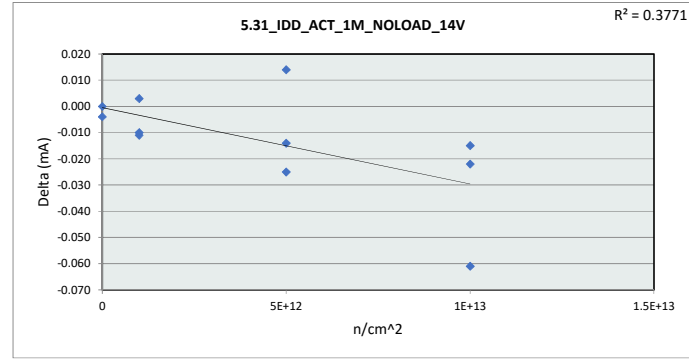


5.30_IDD_ACT_1M_NOLOAD_12V				
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.212	7.309	7.211	7.298
Average	7.273	7.363	7.326	7.318
Max	7.334	7.464	7.400	7.336
UL	9.500	9.500	9.500	9.500

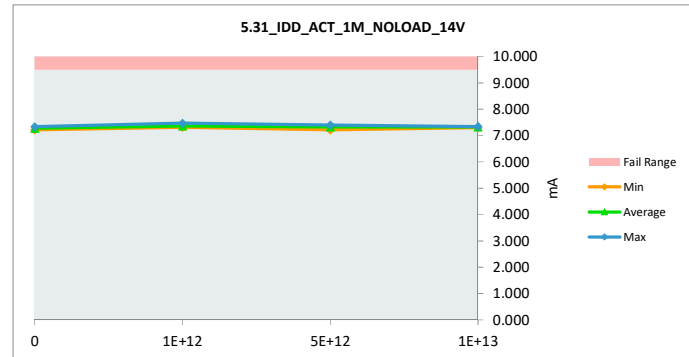


NDD Characterization Report TPS7H5006-SEP

5.31_IDD_ACT_1M_NOLOAD_14V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.220	7.216	-0.004
0	49	7.337	7.337	0.000
1E+12	11	7.466	7.469	0.003
1E+12	12	7.324	7.313	-0.011
1E+12	13	7.332	7.322	-0.010
5E+12	14	7.228	7.214	-0.014
5E+12	15	7.391	7.405	0.014
5E+12	16	7.397	7.372	-0.025
1E+13	17	7.323	7.301	-0.022
1E+13	18	7.339	7.324	-0.015
1E+13	19	7.403	7.342	-0.061
Max		7.466	7.469	0.014
Average		7.342	7.329	-0.013
Min		7.220	7.214	-0.061
Std Dev		0.073	0.074	0.019

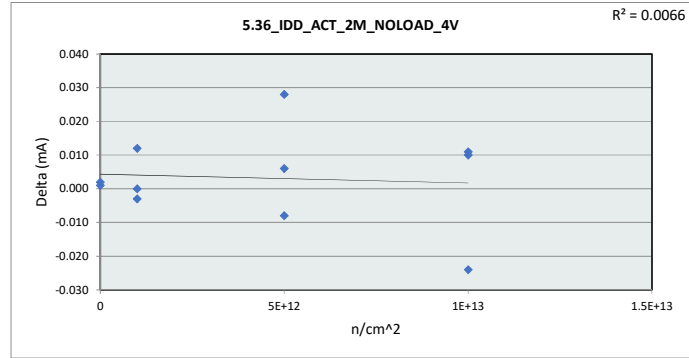


5.31_IDD_ACT_1M_NOLOAD_14V				
Test Site				
Tester				
Test Number				
Max Limit	9.5		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.216	7.313	7.214	7.301
Average	7.277	7.368	7.330	7.322
Max	7.337	7.469	7.405	7.342
UL	9.500	9.500	9.500	9.500

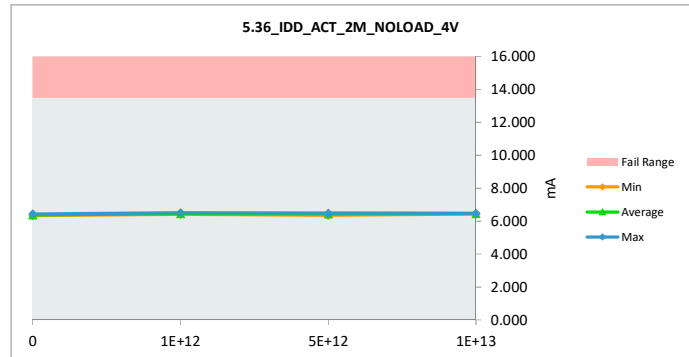


NDD Characterization Report TPS7H5006-SEP

5.36_IDD_ACT_2M_NOLOAD_4V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.5	13.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.330	6.331	0.001
0	49	6.440	6.442	0.002
1E+12	11	6.495	6.507	0.012
1E+12	12	6.407	6.404	-0.003
1E+12	13	6.442	6.442	0.000
5E+12	14	6.353	6.359	0.006
5E+12	15	6.460	6.488	0.028
5E+12	16	6.479	6.471	-0.008
1E+13	17	6.422	6.433	0.011
1E+13	18	6.465	6.475	0.010
1E+13	19	6.484	6.460	-0.024
Max		6.495	6.507	0.028
Average		6.434	6.437	0.003
Min		6.330	6.331	-0.024
Std Dev		0.053	0.054	0.013

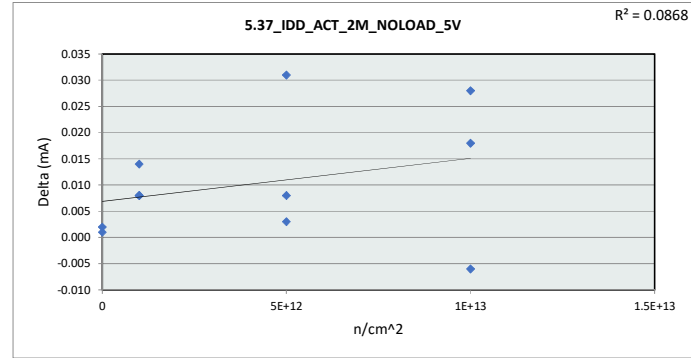


5.36_IDD_ACT_2M_NOLOAD_4V				
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.331	6.404	6.359	6.433
Average	6.387	6.451	6.439	6.456
Max	6.442	6.507	6.488	6.475
UL	13.500	13.500	13.500	13.500

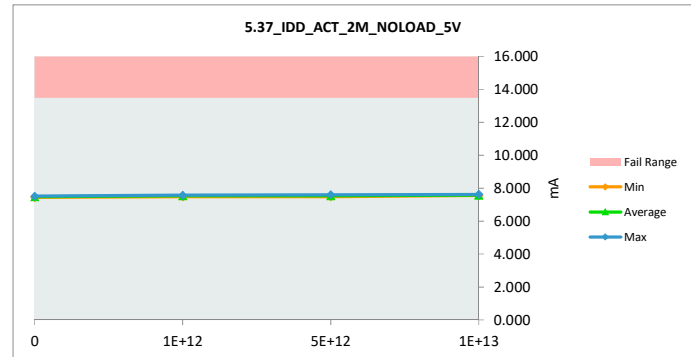


NDD Characterization Report TPS7H5006-SEP

5.37_IDD_ACT_2M_NOLOAD_5V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		12	13.5	
Min Limit		5		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.443	7.444	0.001
0	49	7.518	7.520	0.002
1E+12	11	7.552	7.566	0.014
1E+12	12	7.475	7.483	0.008
1E+12	13	7.560	7.568	0.008
5E+12	14	7.476	7.484	0.008
5E+12	15	7.527	7.558	0.031
5E+12	16	7.600	7.603	0.003
1E+13	17	7.535	7.563	0.028
1E+13	18	7.608	7.626	0.018
1E+13	19	7.575	7.569	-0.006
Max		7.608	7.626	0.031
Average		7.534	7.544	0.010
Min		7.443	7.444	-0.006
Std Dev		0.053	0.055	0.011

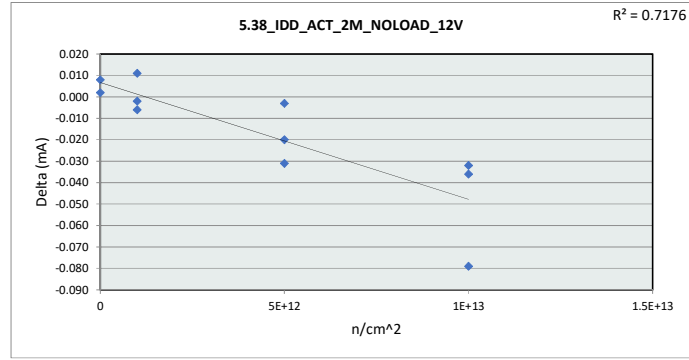


5.37_IDD_ACT_2M_NOLOAD_5V				
Test Site				
Tester				
Test Number				
Max Limit	13.5		mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	7.444	7.483	7.484	7.563
Average	7.482	7.539	7.548	7.586
Max	7.520	7.568	7.603	7.626
UL	13.500	13.500	13.500	13.500

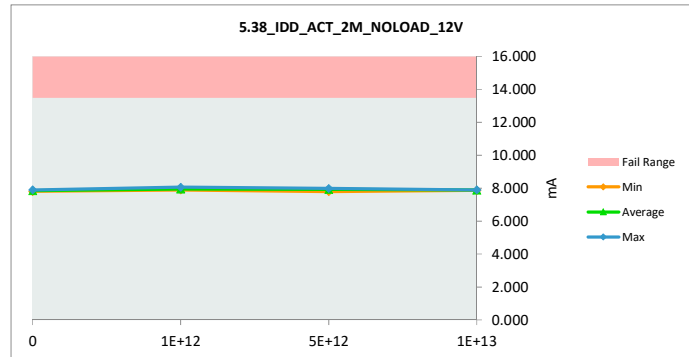


NDD Characterization Report TPS7H5006-SEP

5.38_IDD_ACT_2M_NOLOAD_12V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		12	13.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.809	7.811	0.002
0	49	7.888	7.896	0.008
1E+12	11	8.052	8.063	0.011
1E+12	12	7.901	7.899	-0.002
1E+12	13	7.918	7.912	-0.006
5E+12	14	7.811	7.791	-0.020
5E+12	15	7.979	7.976	-0.003
5E+12	16	8.028	7.997	-0.031
1E+13	17	7.916	7.880	-0.036
1E+13	18	7.916	7.884	-0.032
1E+13	19	7.975	7.896	-0.079
Max		8.052	8.063	0.011
Average		7.927	7.910	-0.017
Min		7.809	7.791	-0.079
Std Dev		0.078	0.078	0.026

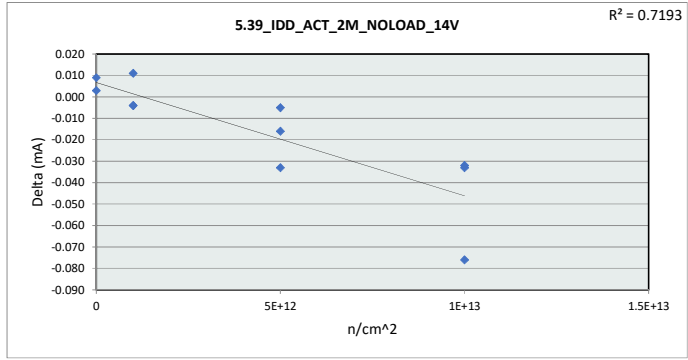


5.38_IDD_ACT_2M_NOLOAD_12V				
Test Site				
Tester				
Test Number				
Max Limit		13.5	mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.811	7.899	7.791	7.880
Average	7.854	7.958	7.921	7.887
Max	7.896	8.063	7.997	7.896
UL	13.500	13.500	13.500	13.500

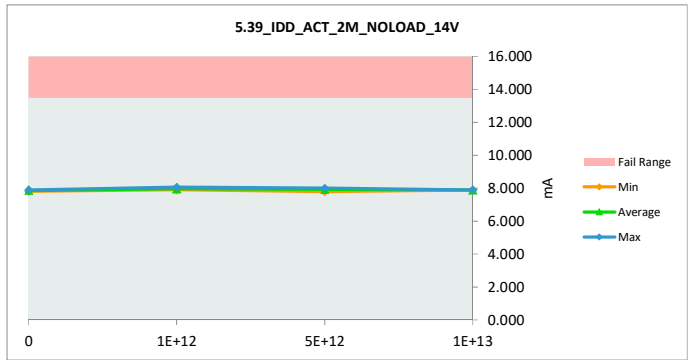


NDD Characterization Report TPS7H5006-SEP

5.39_IDD_ACT_2M_NOLOAD_14V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		12	13.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.813	7.816	0.003
0	49	7.893	7.902	0.009
1E+12	11	8.056	8.067	0.011
1E+12	12	7.907	7.903	-0.004
1E+12	13	7.920	7.916	-0.004
5E+12	14	7.812	7.796	-0.016
5E+12	15	7.984	7.979	-0.005
5E+12	16	8.035	8.002	-0.033
1E+13	17	7.919	7.886	-0.033
1E+13	18	7.920	7.888	-0.032
1E+13	19	7.978	7.902	-0.076
Max		8.056	8.067	0.011
Average		7.931	7.914	-0.016
Min		7.812	7.796	-0.016
Std Dev		0.079	0.078	0.026

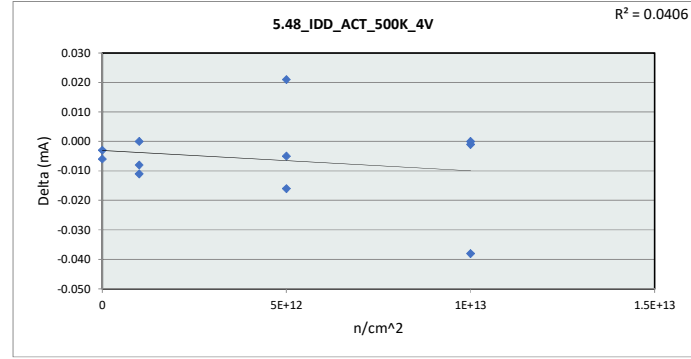


5.39_IDD_ACT_2M_NOLOAD_14V				
Test Site				
Tester				
Test Number				
Max Limit		13.5	mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.816	7.903	7.796	7.886
Average	7.859	7.962	7.926	7.892
Max	7.902	8.067	8.002	7.902
UL	13.500	13.500	13.500	13.500

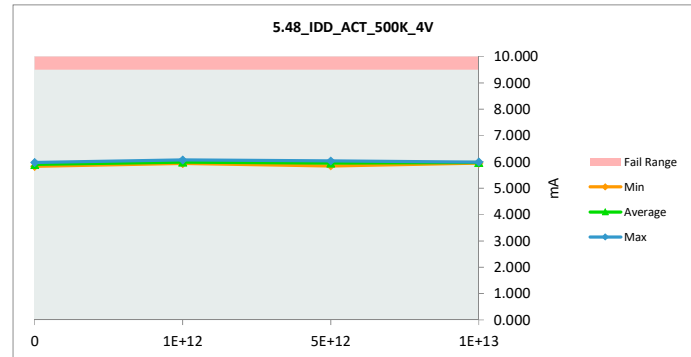


NDD Characterization Report TPS7H5006-SEP

5.48_IDD_ACT_500K_4V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.837	5.831	-0.006
0	49	5.980	5.977	-0.003
1E+12	11	6.076	6.076	0.000
1E+12	12	5.956	5.945	-0.011
1E+12	13	5.969	5.961	-0.008
5E+12	14	5.856	5.851	-0.005
5E+12	15	6.019	6.040	0.021
5E+12	16	5.999	5.983	-0.016
1E+13	17	5.954	5.953	-0.001
1E+13	18	5.983	5.983	0.000
1E+13	19	6.034	5.996	-0.038
Max		6.076	6.076	0.021
Average		5.969	5.963	-0.006
Min		5.837	5.831	-0.038
Std Dev		0.071	0.072	0.014

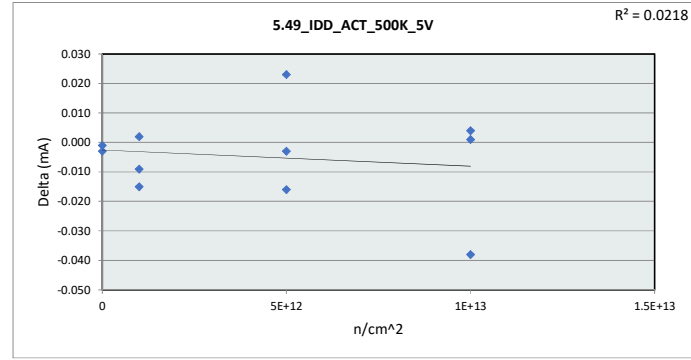


5.48_IDD_ACT_500K_4V				
Test Site				
Tester				
Test Number				
Max Limit	9.5		mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	5.831	5.945	5.851	5.953
Average	5.904	5.994	5.958	5.977
Max	5.977	6.076	6.040	5.996
UL	9.500	9.500	9.500	9.500

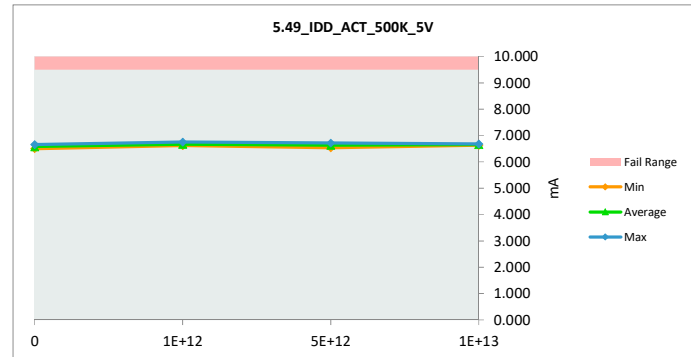


NDD Characterization Report TPS7H5006-SEP

5.49_IDD_ACT_500K_5V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.509	6.506	-0.003
0	49	6.657	6.656	-0.001
1E+12	11	6.753	6.755	0.002
1E+12	12	6.636	6.621	-0.015
1E+12	13	6.650	6.641	-0.009
5E+12	14	6.535	6.532	-0.003
5E+12	15	6.696	6.719	0.023
5E+12	16	6.683	6.667	-0.016
1E+13	17	6.632	6.633	0.001
1E+13	18	6.663	6.667	0.004
1E+13	19	6.719	6.681	-0.038
Max		6.753	6.755	0.023
Average		6.648	6.643	-0.005
Min		6.509	6.506	-0.038
Std Dev		0.072	0.073	0.015

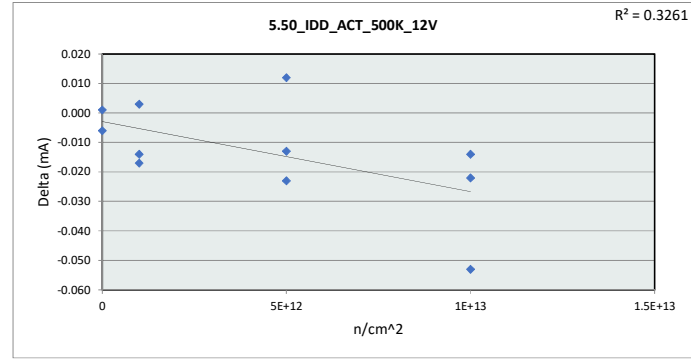


5.49_IDD_ACT_500K_5V				
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.506	6.621	6.532	6.633
Average	6.581	6.672	6.639	6.660
Max	6.656	6.755	6.719	6.681
UL	9.500	9.500	9.500	9.500

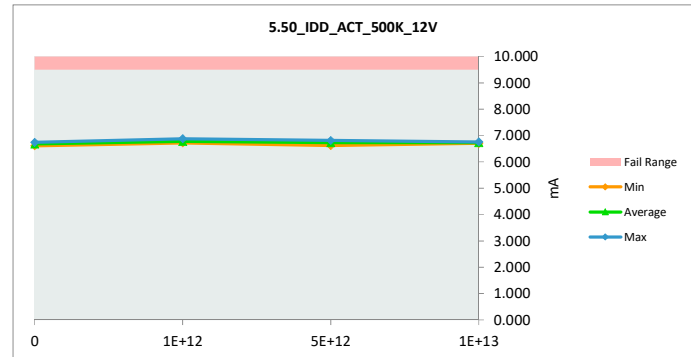


NDD Characterization Report TPS7H5006-SEP

5.50_IDD_ACT_500K_12V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.621	6.615	-0.006
0	49	6.741	6.742	0.001
1E+12	11	6.879	6.882	0.003
1E+12	12	6.738	6.721	-0.017
1E+12	13	6.744	6.730	-0.014
5E+12	14	6.631	6.618	-0.013
5E+12	15	6.804	6.816	0.012
5E+12	16	6.792	6.769	-0.023
1E+13	17	6.729	6.707	-0.022
1E+13	18	6.748	6.734	-0.014
1E+13	19	6.812	6.759	-0.053
Max		6.879	6.882	0.012
Average		6.749	6.736	-0.013
Min		6.621	6.615	-0.053
Std Dev		0.075	0.077	0.017

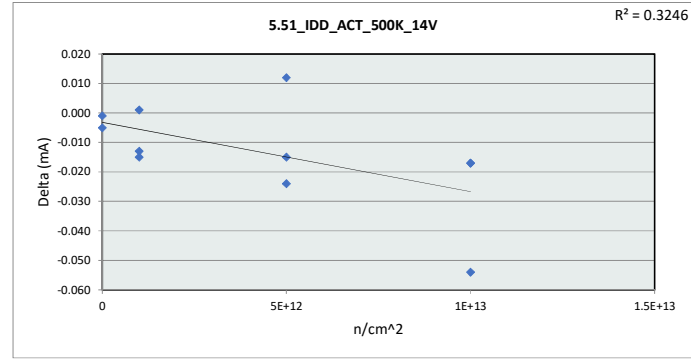


5.50_IDD_ACT_500K_12V				
Test Site				
Tester				
Test Number				
Max Limit	9.5		mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	6.615	6.721	6.618	6.707
Average	6.679	6.778	6.734	6.733
Max	6.742	6.882	6.816	6.759
UL	9.500	9.500	9.500	9.500

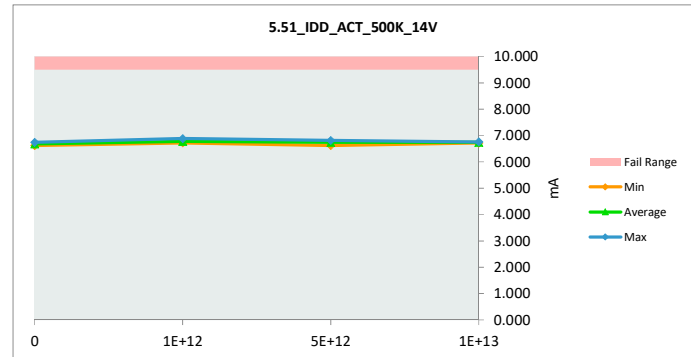


NDD Characterization Report TPS7H5006-SEP

5.51_IDD_ACT_500K_14V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.626	6.621	-0.005
0	49	6.747	6.746	-0.001
1E+12	11	6.885	6.886	0.001
1E+12	12	6.740	6.725	-0.015
1E+12	13	6.749	6.736	-0.013
5E+12	14	6.637	6.622	-0.015
5E+12	15	6.808	6.820	0.012
5E+12	16	6.798	6.774	-0.024
1E+13	17	6.732	6.715	-0.017
1E+13	18	6.754	6.737	-0.017
1E+13	19	6.816	6.762	-0.054
Max		6.885	6.886	0.012
Average		6.754	6.740	-0.013
Min		6.626	6.621	-0.054
Std Dev		0.075	0.076	0.017

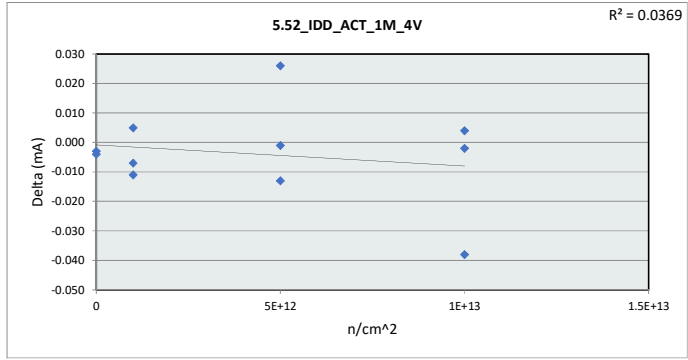


5.51_IDD_ACT_500K_14V				
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.621	6.725	6.622	6.715
Average	6.684	6.782	6.739	6.738
Max	6.746	6.886	6.820	6.762
UL	9.500	9.500	9.500	9.500

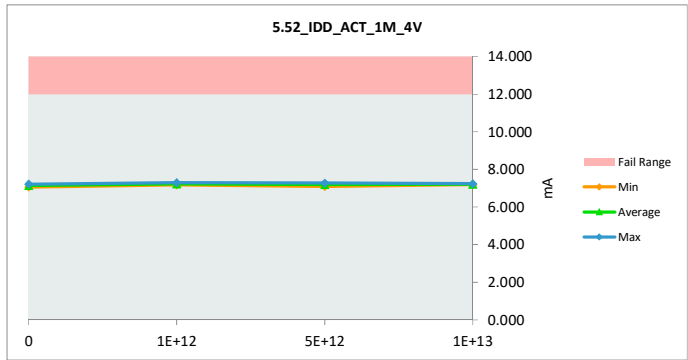


NDD Characterization Report TPS7H5006-SEP

5.52_IDD_ACT_1M_4V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.071	7.067	-0.004
0	49	7.223	7.220	-0.003
1E+12	11	7.295	7.300	0.005
1E+12	12	7.192	7.181	-0.011
1E+12	13	7.207	7.200	-0.007
5E+12	14	7.094	7.093	-0.001
5E+12	15	7.250	7.276	0.026
5E+12	16	7.240	7.227	-0.013
1E+13	17	7.195	7.193	-0.002
1E+13	18	7.221	7.225	0.004
1E+13	19	7.272	7.234	-0.038
Max		7.295	7.300	0.026
Average		7.205	7.201	-0.004
Min		7.071	7.067	-0.038
Std Dev		0.069	0.069	0.015

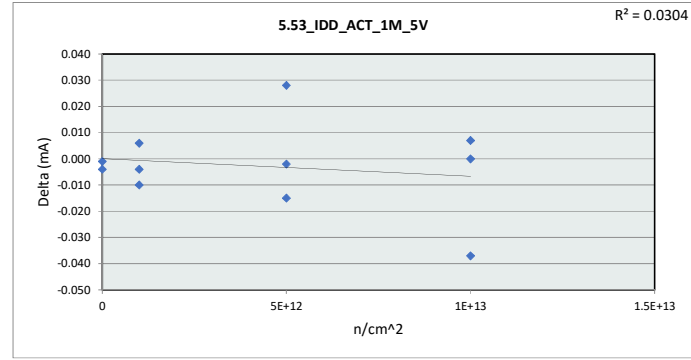


5.52_IDD_ACT_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	7.067	7.181	7.093	7.193
Average	7.144	7.227	7.199	7.217
Max	7.220	7.300	7.276	7.234
UL	12.000	12.000	12.000	12.000

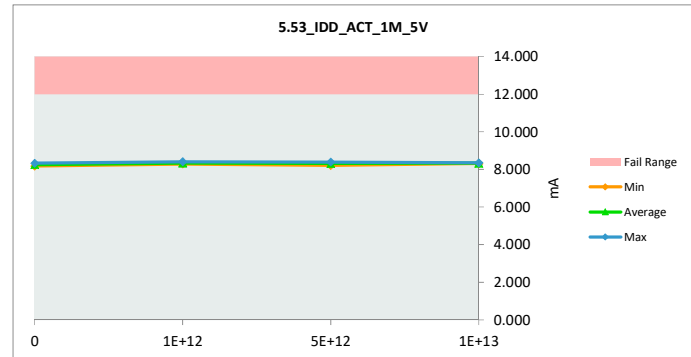


NDD Characterization Report TPS7H5006-SEP

5.53_IDD_ACT_1M_5V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.177	8.176	-0.001
0	49	8.338	8.334	-0.004
1E+12	11	8.405	8.411	0.006
1E+12	12	8.302	8.292	-0.010
1E+12	13	8.317	8.313	-0.004
5E+12	14	8.206	8.204	-0.002
5E+12	15	8.360	8.388	0.028
5E+12	16	8.361	8.346	-0.015
1E+13	17	8.311	8.311	0.000
1E+13	18	8.335	8.342	0.007
1E+13	19	8.390	8.353	-0.037
Max		8.405	8.411	0.028
Average		8.318	8.315	-0.003
Min		8.177	8.176	-0.037
Std Dev		0.071	0.071	0.016

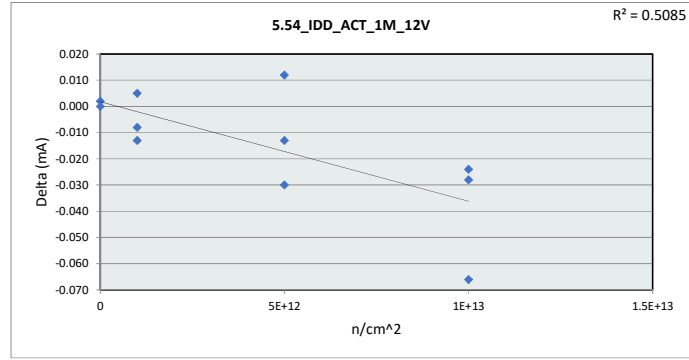


5.53_IDD_ACT_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	8.176	8.292	8.204	8.311
Average	8.255	8.339	8.313	8.335
Max	8.334	8.411	8.388	8.353
UL	12.000	12.000	12.000	12.000

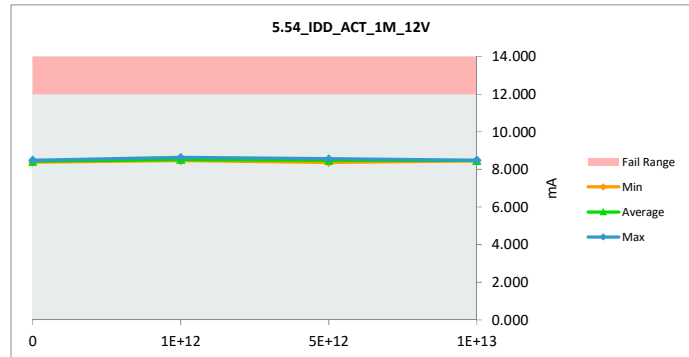


NDD Characterization Report TPS7H5006-SEP

5.54_IDD_ACT_1M_12V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.377	8.377	0.000
0	49	8.492	8.494	0.002
1E+12	11	8.633	8.638	0.005
1E+12	12	8.485	8.472	-0.013
1E+12	13	8.488	8.480	-0.008
5E+12	14	8.383	8.370	-0.013
5E+12	15	8.553	8.565	0.012
5E+12	16	8.561	8.531	-0.030
1E+13	17	8.482	8.454	-0.028
1E+13	18	8.494	8.470	-0.024
1E+13	19	8.564	8.498	-0.066
Max		8.633	8.638	0.012
Average		8.501	8.486	-0.015
Min		8.377	8.370	-0.066
Std Dev		0.076	0.076	0.022

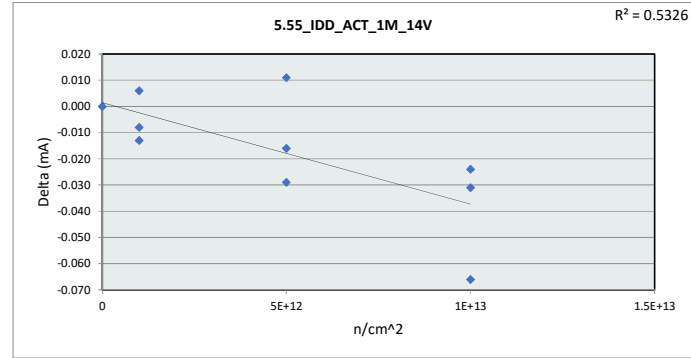


5.54_IDD_ACT_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	12		mA	
Min Limit			mA	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.377	8.472	8.370	8.454
Average	8.436	8.530	8.489	8.474
Max	8.494	8.638	8.565	8.498
UL	12.000	12.000	12.000	12.000

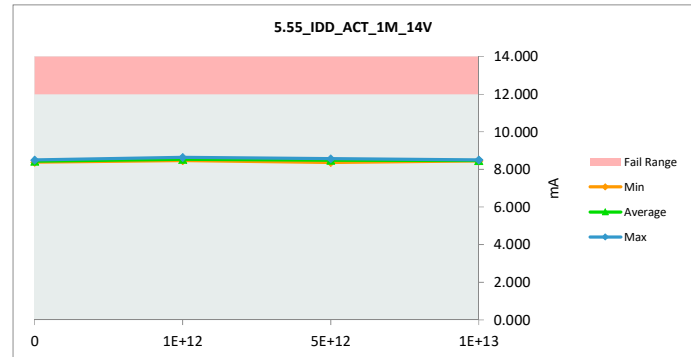


NDD Characterization Report TPS7H5006-SEP

5.55_IDD_ACT_1M_14V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.380	8.380	0.000
0	49	8.498	8.498	0.000
1E+12	11	8.635	8.641	0.006
1E+12	12	8.490	8.477	-0.013
1E+12	13	8.493	8.485	-0.008
5E+12	14	8.387	8.371	-0.016
5E+12	15	8.559	8.570	0.011
5E+12	16	8.565	8.536	-0.029
1E+13	17	8.488	8.457	-0.031
1E+13	18	8.499	8.475	-0.024
1E+13	19	8.568	8.502	-0.066
Max		8.635	8.641	0.011
Average		8.506	8.490	-0.015
Min		8.380	8.371	-0.066
Std Dev		0.076	0.077	0.022

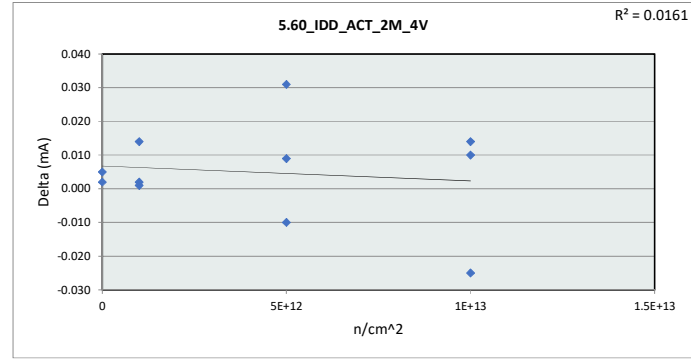


5.55_IDD_ACT_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.380	8.477	8.371	8.457
Average	8.439	8.534	8.492	8.478
Max	8.498	8.641	8.570	8.502
UL	12.000	12.000	12.000	12.000

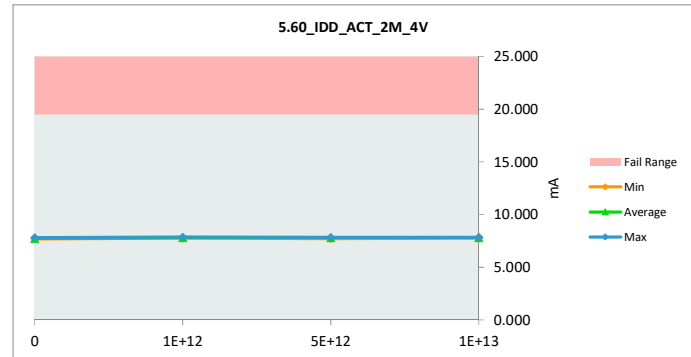


NDD Characterization Report TPS7H5006-SEP

5.60_IDD_ACT_2M_4V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		13	19.5	
Min Limit		5		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.684	7.689	0.005
0	49	7.795	7.797	0.002
1E+12	11	7.846	7.860	0.014
1E+12	12	7.763	7.764	0.001
1E+12	13	7.803	7.805	0.002
5E+12	14	7.712	7.721	0.009
5E+12	15	7.817	7.848	0.031
5E+12	16	7.834	7.824	-0.010
1E+13	17	7.776	7.786	0.010
1E+13	18	7.822	7.836	0.014
1E+13	19	7.845	7.820	-0.025
Max		7.846	7.860	0.031
Average		7.791	7.795	0.005
Min		7.684	7.689	-0.025
Std Dev		0.053	0.053	0.014

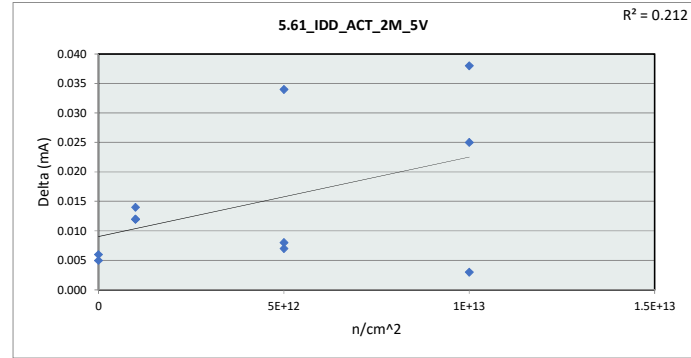


5.60_IDD_ACT_2M_4V				
Test Site				
Tester				
Test Number				
Max Limit		19.5	mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	7.689	7.764	7.721	7.786
Average	7.743	7.810	7.798	7.814
Max	7.797	7.860	7.848	7.836
UL	19.500	19.500	19.500	19.500

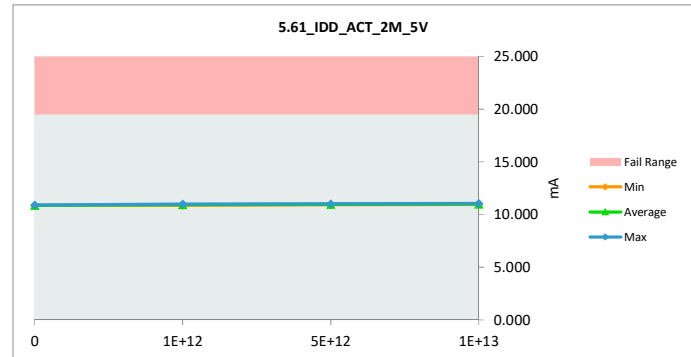


NDD Characterization Report TPS7H5006-SEP

5.61_IDD_ACT_2M_5V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		18	19.5	
Min Limit		10		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	10.860	10.866	0.006
0	49	10.906	10.911	0.005
1E+12	11	10.946	10.958	0.012
1E+12	12	10.868	10.880	0.012
1E+12	13	10.976	10.990	0.014
5E+12	14	10.906	10.914	0.008
5E+12	15	10.922	10.956	0.034
5E+12	16	11.001	11.008	0.007
1E+13	17	10.933	10.971	0.038
1E+13	18	11.021	11.046	0.025
1E+13	19	10.983	10.986	0.003
Max		11.021	11.046	0.038
Average		10.938	10.953	0.015
Min		10.860	10.866	0.003
Std Dev		0.053	0.055	0.012

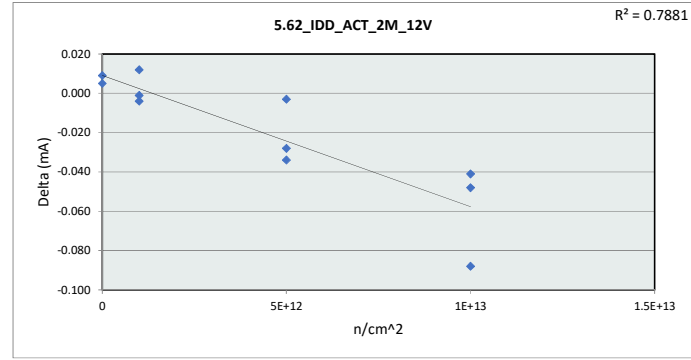


5.61_IDD_ACT_2M_5V				
Test Site				
Tester				
Test Number				
Max Limit	19.5		mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	10.866	10.880	10.914	10.971
Average	10.889	10.943	10.959	11.001
Max	10.911	10.990	11.008	11.046
UL	19.500	19.500	19.500	19.500

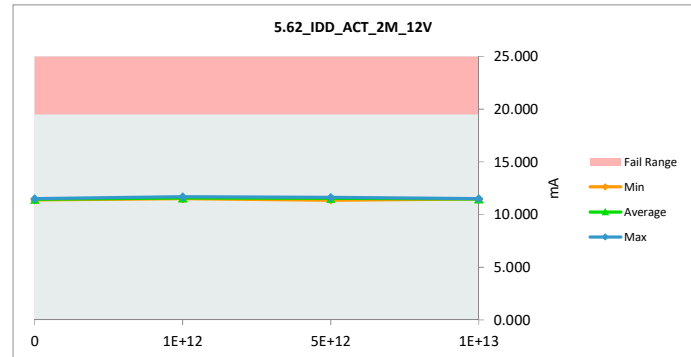


NDD Characterization Report TPS7H5006-SEP

5.62_IDD_ACT_2M_12V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		18	19.5	
Min Limit		10		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	11.390	11.395	0.005
0	49	11.492	11.501	0.009
1E+12	11	11.678	11.690	0.012
1E+12	12	11.514	11.513	-0.001
1E+12	13	11.537	11.533	-0.004
5E+12	14	11.404	11.376	-0.028
5E+12	15	11.605	11.602	-0.003
5E+12	16	11.660	11.626	-0.034
1E+13	17	11.536	11.488	-0.048
1E+13	18	11.515	11.474	-0.041
1E+13	19	11.594	11.506	-0.088
Max		11.678	11.690	0.012
Average		11.539	11.519	-0.020
Min		11.390	11.376	-0.088
Std Dev		0.092	0.093	0.031

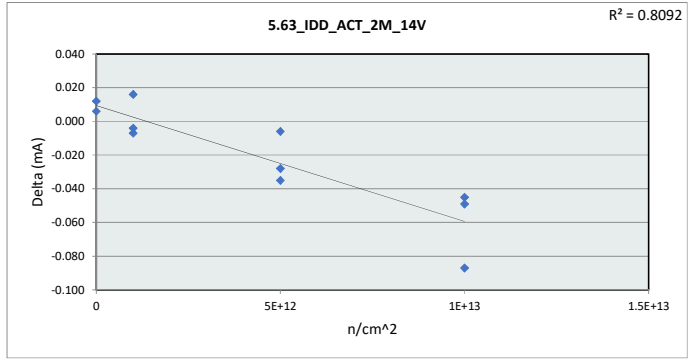


5.62_IDD_ACT_2M_12V				
Test Site				
Tester				
Test Number				
Max Limit		19.5	mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	11.395	11.513	11.376	11.474
Average	11.448	11.579	11.535	11.489
Max	11.501	11.690	11.626	11.506
UL	19.500	19.500	19.500	19.500

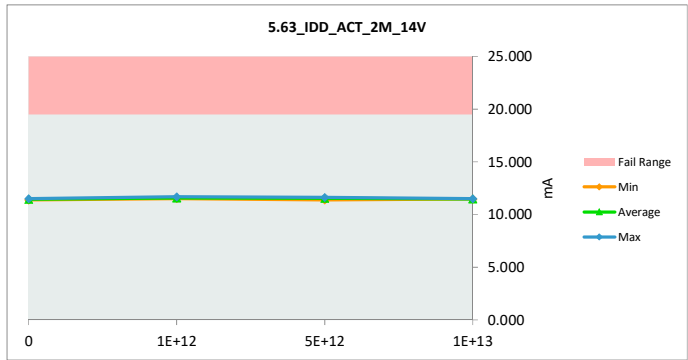


NDD Characterization Report TPS7H5006-SEP

5.63_IDD_ACT_2M_14V				
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		18	19.5	
Min Limit		10		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	11.395	11.401	0.006
0	49	11.494	11.506	0.012
1E+12	11	11.678	11.694	0.016
1E+12	12	11.521	11.517	-0.004
1E+12	13	11.543	11.536	-0.007
5E+12	14	11.410	11.382	-0.028
5E+12	15	11.610	11.604	-0.006
5E+12	16	11.664	11.629	-0.035
1E+13	17	11.541	11.492	-0.049
1E+13	18	11.522	11.477	-0.045
1E+13	19	11.598	11.511	-0.087
Max		11.678	11.694	0.016
Average		11.543	11.523	-0.021
Min		11.395	11.382	-0.087
Std Dev		0.091	0.092	0.031

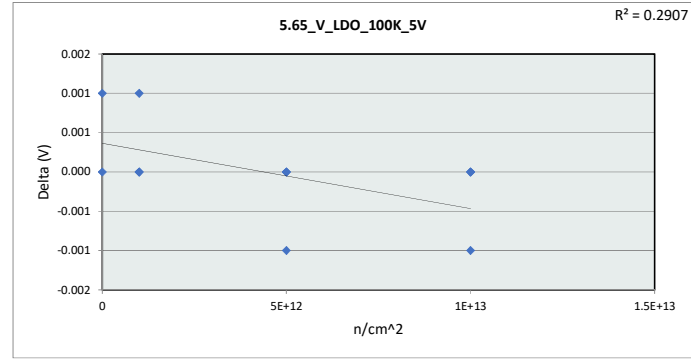


5.63_IDD_ACT_2M_14V				
Test Site				
Tester				
Test Number				
Max Limit		19.5	mA	
Min Limit			mA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	11.401	11.517	11.382	11.477
Average	11.454	11.582	11.538	11.493
Max	11.506	11.694	11.629	11.511
UL	19.500	19.500	19.500	19.500

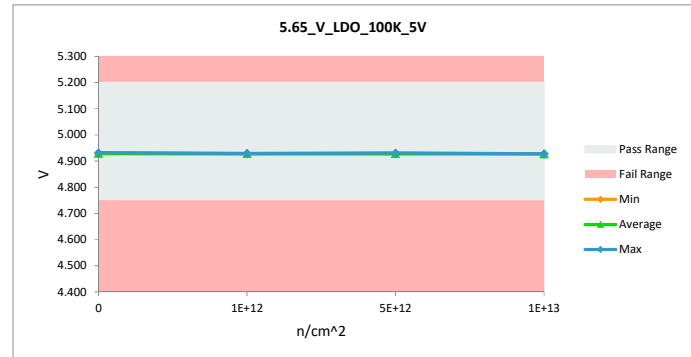


NDD Characterization Report TPS7H5006-SEP

5.65_V_LDO_100K_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.1	5.2	
Min Limit		4.85	4.75	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.931	4.932	0.001
0	49	4.928	4.928	0.000
1E+12	11	4.927	4.927	0.000
1E+12	12	4.929	4.929	0.000
1E+12	13	4.928	4.929	0.001
5E+12	14	4.931	4.931	0.000
5E+12	15	4.928	4.928	0.000
5E+12	16	4.928	4.927	-0.001
1E+13	17	4.929	4.928	-0.001
1E+13	18	4.928	4.928	0.000
1E+13	19	4.928	4.928	0.000
Max		4.931	4.932	0.001
Average		4.929	4.929	0.000
Min		4.927	4.927	-0.001
Std Dev		0.001	0.002	0.001

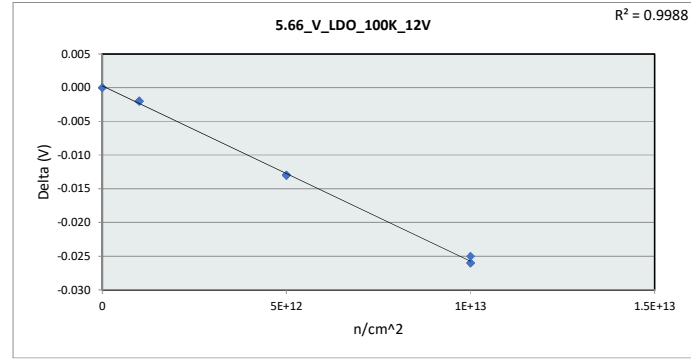


5.65_V_LDO_100K_5V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.928	4.927	4.927	4.928
Average	4.930	4.928	4.929	4.928
Max	4.932	4.929	4.931	4.928
UL	5.200	5.200	5.200	5.200

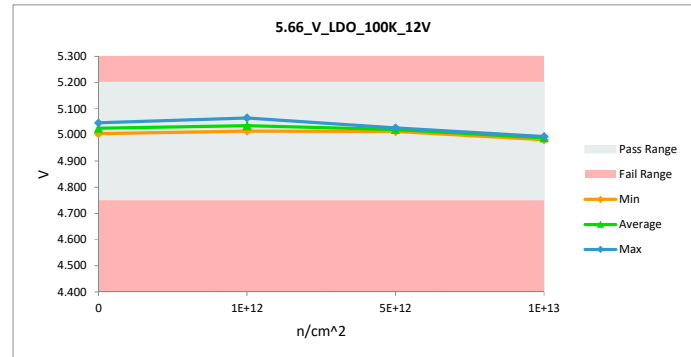


NDD Characterization Report TPS7H5006-SEP

5.66_V_LDO_100K_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	5.15	5.2	5.2	5.2
Min Limit	4.85	4.75	4.75	4.75
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.067	5.065	-0.002
1E+12	12	5.029	5.027	-0.002
1E+12	13	5.017	5.015	-0.002
5E+12	14	5.026	5.013	-0.013
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.992	-0.026
1E+13	18	5.007	4.981	-0.026
1E+13	19	5.019	4.994	-0.025
Max		5.067	5.065	0.000
Average		5.028	5.017	-0.011
Min		5.005	4.981	-0.026
Std Dev		0.018	0.024	0.011

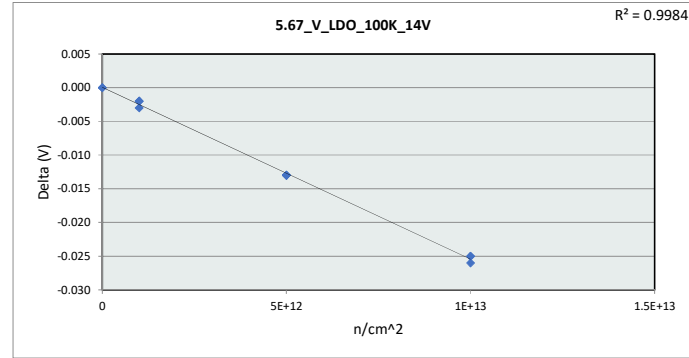


5.66_V_LDO_100K_12V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V	V	V
Min Limit	4.75	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.015	5.013	4.981
Average	5.026	5.036	5.020	4.989
Max	5.046	5.065	5.027	4.994
UL	5.200	5.200	5.200	5.200

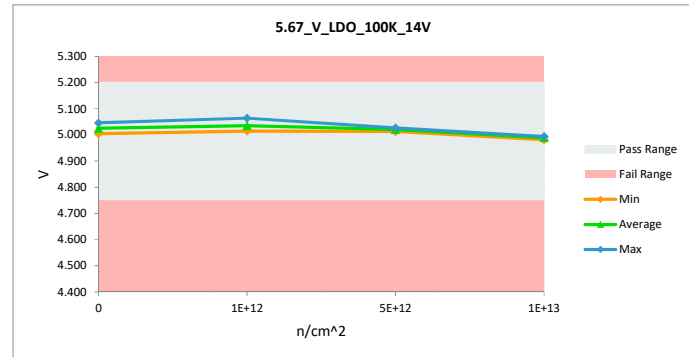


NDD Characterization Report TPS7H5006-SEP

5.67_V_LDO_100K_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	5.15		5.2	
Min Limit	4.85		4.75	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.067	5.064	-0.003
1E+12	12	5.029	5.027	-0.002
1E+12	13	5.017	5.015	-0.002
5E+12	14	5.026	5.013	-0.013
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.993	-0.025
1E+13	18	5.007	4.981	-0.026
1E+13	19	5.019	4.994	-0.025
Max		5.067	5.064	0.000
Average		5.028	5.017	-0.011
Min		5.005	4.981	-0.026
Std Dev		0.018	0.024	0.010

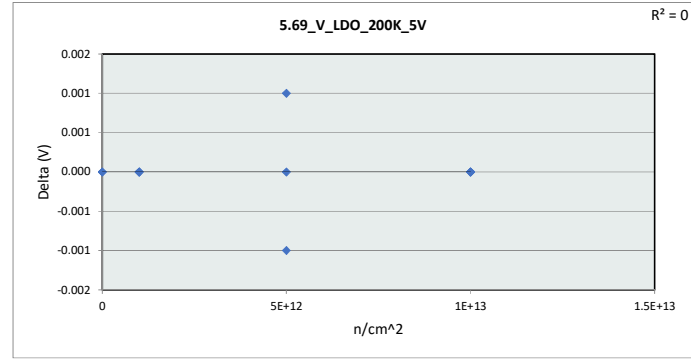


5.67_V_LDO_100K_14V				
Test Site				
Tester				
Test Number				
Max Limit	5.2		V	
Min Limit	4.75		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.015	5.013	4.981
Average	5.026	5.035	5.020	4.989
Max	5.046	5.064	5.027	4.994
UL	5.200	5.200	5.200	5.200

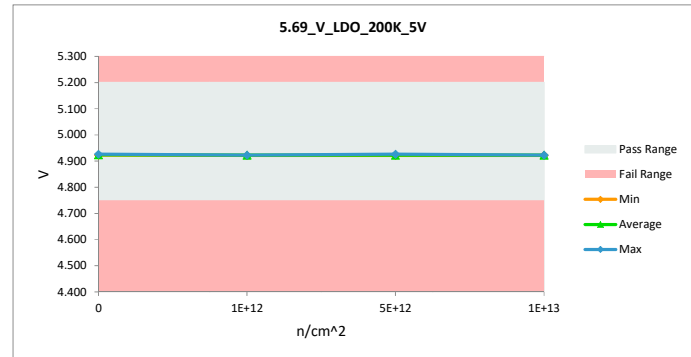


NDD Characterization Report TPS7H5006-SEP

5.69_V_LDO_200K_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.1	5.2	
Min Limit		4.84	4.75	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.926	4.926	0.000
0	49	4.923	4.923	0.000
1E+12	11	4.921	4.921	0.000
1E+12	12	4.923	4.923	0.000
1E+12	13	4.923	4.923	0.000
5E+12	14	4.925	4.926	0.001
5E+12	15	4.922	4.922	0.000
5E+12	16	4.922	4.921	-0.001
1E+13	17	4.923	4.923	0.000
1E+13	18	4.922	4.922	0.000
1E+13	19	4.922	4.922	0.000
Max		4.926	4.926	0.001
Average		4.923	4.923	0.000
Min		4.921	4.921	-0.001
Std Dev		0.001	0.002	0.000

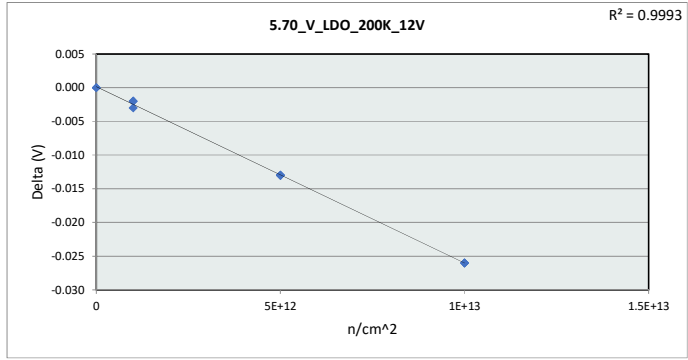


5.69_V_LDO_200K_5V				
Test Site				
Tester				
Test Number				
Max Limit		5.2	V	
Min Limit		4.75	V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.923	4.921	4.921	4.922
Average	4.925	4.922	4.923	4.922
Max	4.926	4.923	4.926	4.923
UL	5.200	5.200	5.200	5.200

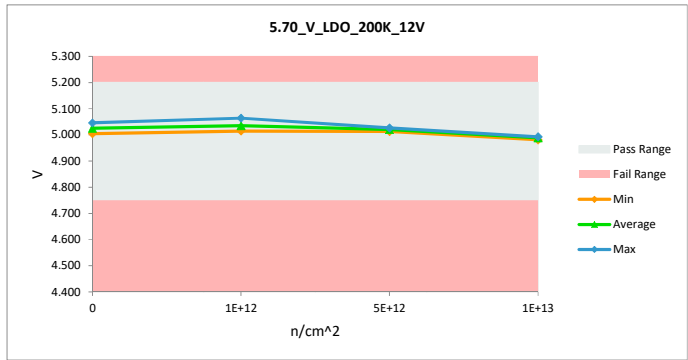


NDD Characterization Report TPS7H5006-SEP

5.70_V_LDO_200K_12V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	5.15		5.2	
Min Limit	4.84		4.75	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.067	5.064	-0.003
1E+12	12	5.029	5.027	-0.002
1E+12	13	5.017	5.015	-0.002
5E+12	14	5.026	5.013	-0.013
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.992	-0.026
1E+13	18	5.007	4.981	-0.026
1E+13	19	5.019	4.993	-0.026
Max		5.067	5.064	0.000
Average		5.028	5.017	-0.011
Min		5.005	4.981	-0.026
Std Dev		0.018	0.024	0.011

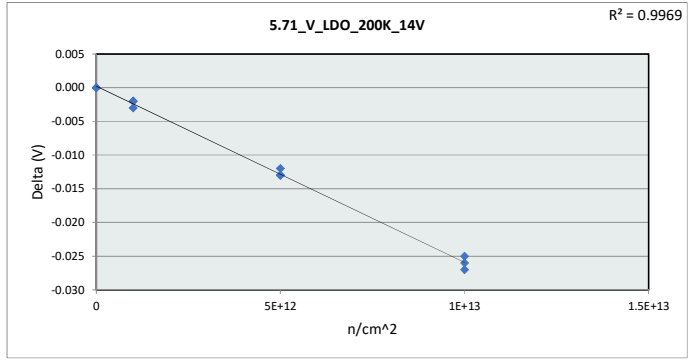


5.70_V_LDO_200K_12V				
Test Site				
Tester				
Test Number				
Max Limit	5.2		V	
Min Limit	4.75		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.015	5.013	4.981
Average	5.026	5.035	5.020	4.989
Max	5.046	5.064	5.027	4.993
UL	5.200	5.200	5.200	5.200

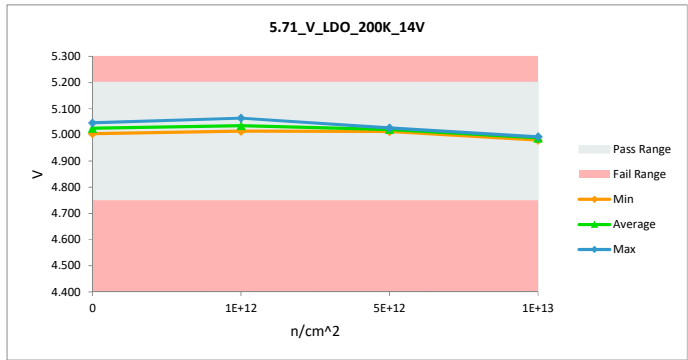


NDD Characterization Report TPS7H5006-SEP

5.71_V_LDO_200K_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	5.15		5.2	
Min Limit	4.84		4.75	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.066	5.064	-0.002
1E+12	12	5.029	5.026	-0.003
1E+12	13	5.016	5.014	-0.002
5E+12	14	5.025	5.013	-0.012
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.992	-0.026
1E+13	18	5.007	4.980	-0.027
1E+13	19	5.018	4.993	-0.025
Max		5.066	5.064	0.000
Average		5.028	5.016	-0.011
Min		5.005	4.980	-0.027
Std Dev		0.018	0.024	0.011

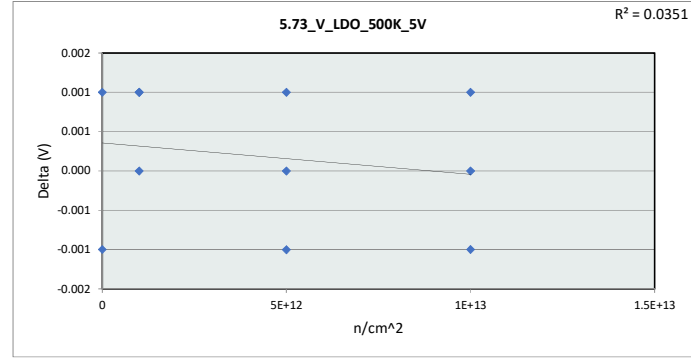


5.71_V_LDO_200K_14V				
Test Site				
Tester				
Test Number				
Max Limit	5.2		V	
Min Limit	4.75		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.014	5.013	4.980
Average	5.026	5.035	5.020	4.988
Max	5.046	5.064	5.027	4.993
UL	5.200	5.200	5.200	5.200

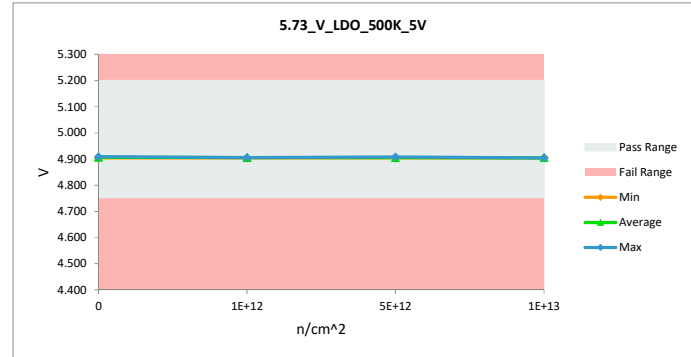


NDD Characterization Report TPS7H5006-SEP

5.73_V_LDO_500K_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.1	5.2	
Min Limit		4.81	4.75	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.908	4.909	0.001
0	49	4.906	4.905	-0.001
1E+12	11	4.904	4.905	0.001
1E+12	12	4.906	4.906	0.000
1E+12	13	4.905	4.906	0.001
5E+12	14	4.907	4.908	0.001
5E+12	15	4.905	4.905	0.000
5E+12	16	4.905	4.904	-0.001
1E+13	17	4.906	4.905	-0.001
1E+13	18	4.905	4.905	0.000
1E+13	19	4.904	4.905	0.001
Max		4.908	4.909	0.001
Average		4.906	4.906	0.000
Min		4.904	4.904	-0.001
Std Dev		0.001	0.001	0.001

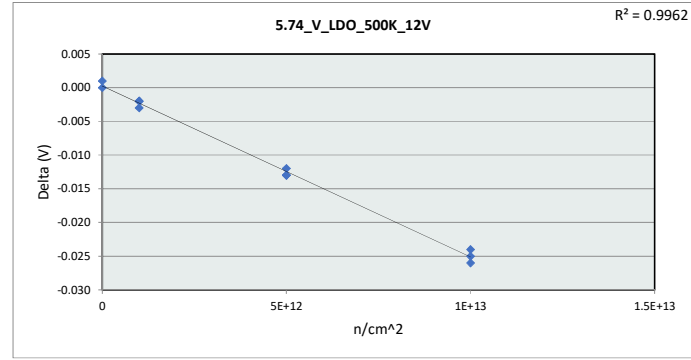


5.73_V_LDO_500K_5V				
Test Site				
Tester				
Test Number				
Max Limit		5.2	V	
Min Limit		4.75	V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.905	4.905	4.904	4.905
Average	4.907	4.906	4.906	4.905
Max	4.909	4.906	4.908	4.905
UL	5.200	5.200	5.200	5.200

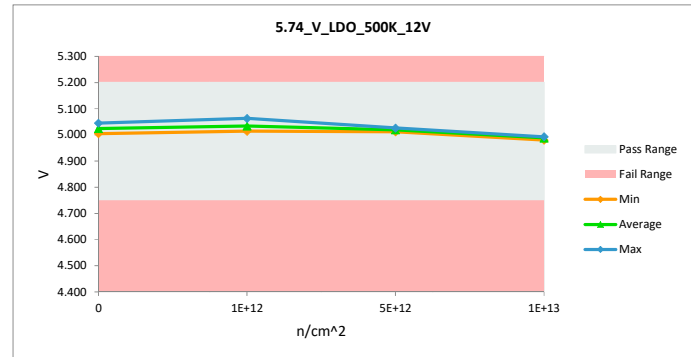


NDD Characterization Report TPS7H5006-SEP

5.74_V_LDO_500K_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	5.15	5.2	5.2	5.2
Min Limit	4.81	4.75	4.75	4.75
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.045	5.045	0.000
0	49	5.004	5.005	0.001
1E+12	11	5.065	5.063	-0.002
1E+12	12	5.028	5.025	-0.003
1E+12	13	5.016	5.014	-0.002
5E+12	14	5.024	5.012	-0.012
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.039	5.026	-0.013
1E+13	17	5.017	4.992	-0.025
1E+13	18	5.006	4.980	-0.026
1E+13	19	5.017	4.993	-0.024
Max		5.065	5.063	0.001
Average		5.027	5.016	-0.011
Min		5.004	4.980	-0.026
Std Dev		0.018	0.024	0.010

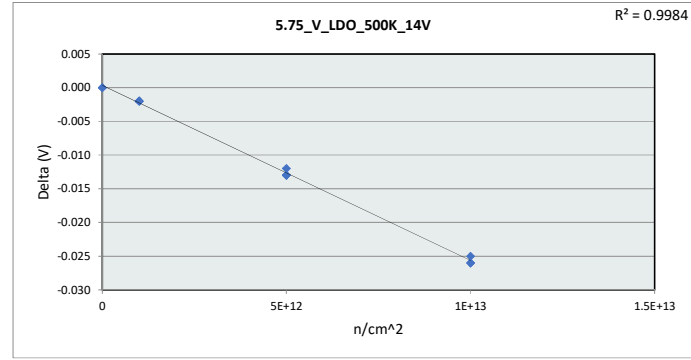


5.74_V_LDO_500K_12V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V	V	V
Min Limit	4.75	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.014	5.012	4.980
Average	5.025	5.034	5.020	4.988
Max	5.045	5.063	5.026	4.993
UL	5.200	5.200	5.200	5.200

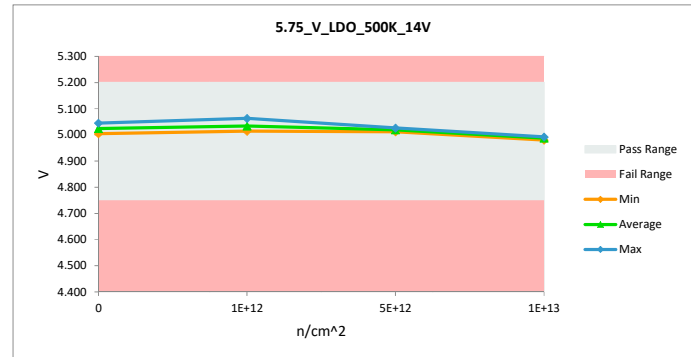


NDD Characterization Report TPS7H5006-SEP

5.75_V_LDO_500K_14V				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	5.15	5.2		
Min Limit	4.81	4.75		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.045	5.045	0.000
0	49	5.004	5.004	0.000
1E+12	11	5.065	5.063	-0.002
1E+12	12	5.028	5.026	-0.002
1E+12	13	5.016	5.014	-0.002
5E+12	14	5.024	5.012	-0.012
5E+12	15	5.033	5.020	-0.013
5E+12	16	5.039	5.026	-0.013
1E+13	17	5.017	4.991	-0.026
1E+13	18	5.006	4.980	-0.026
1E+13	19	5.017	4.992	-0.025
Max		5.065	5.063	0.000
Average		5.027	5.016	-0.011
Min		5.004	4.980	-0.026
Std Dev		0.018	0.024	0.011

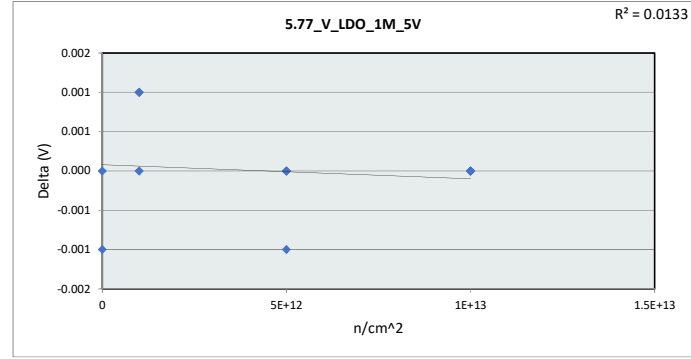


5.75_V_LDO_500K_14V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.004	5.014	5.012	4.980
Average	5.025	5.034	5.019	4.988
Max	5.045	5.063	5.026	4.992
UL	5.200	5.200	5.200	5.200

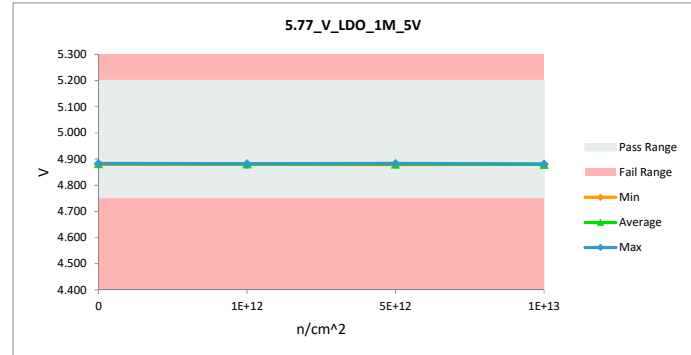


NDD Characterization Report TPS7H5006-SEP

5.77_V_LDO_1M_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.1	5.2	
Min Limit		4.75	4.75	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.884	4.884	0.000
0	49	4.881	4.880	-0.001
1E+12	11	4.880	4.880	0.000
1E+12	12	4.881	4.882	0.001
1E+12	13	4.881	4.882	0.001
5E+12	14	4.883	4.883	0.000
5E+12	15	4.880	4.880	0.000
5E+12	16	4.880	4.879	-0.001
1E+13	17	4.881	4.881	0.000
1E+13	18	4.880	4.880	0.000
1E+13	19	4.880	4.880	0.000
Max		4.884	4.884	0.001
Average		4.881	4.881	0.000
Min		4.880	4.879	-0.001
Std Dev		0.001	0.002	0.001

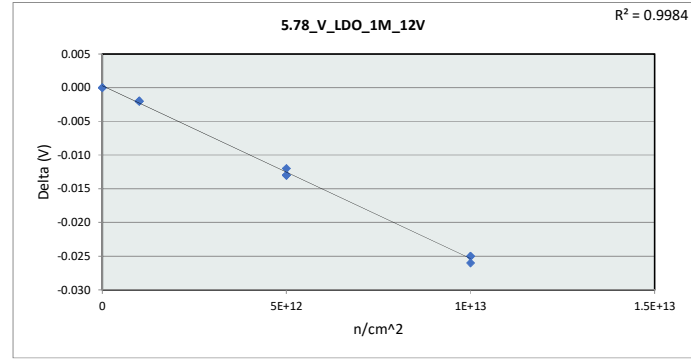


5.77_V_LDO_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.880	4.880	4.879	4.880
Average	4.882	4.881	4.881	4.880
Max	4.884	4.882	4.883	4.881
UL	5.200	5.200	5.200	5.200

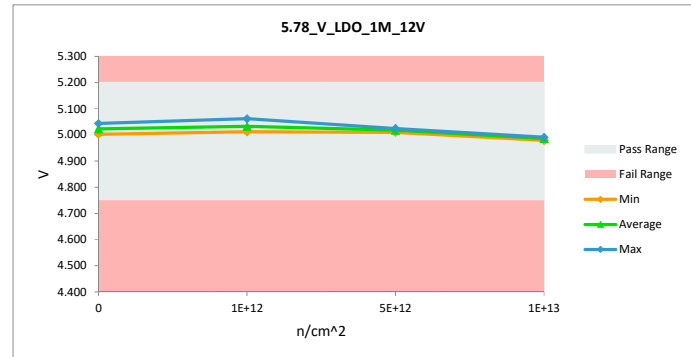


NDD Characterization Report TPS7H5006-SEP

5.78_V_LDO_1M_12V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	5.15		5.2	
Min Limit	4.85		4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.044	5.044	0.000
0	49	5.003	5.003	0.000
1E+12	11	5.064	5.062	-0.002
1E+12	12	5.026	5.024	-0.002
1E+12	13	5.014	5.012	-0.002
5E+12	14	5.023	5.010	-0.013
5E+12	15	5.032	5.019	-0.013
5E+12	16	5.037	5.025	-0.012
1E+13	17	5.015	4.990	-0.025
1E+13	18	5.005	4.979	-0.026
1E+13	19	5.016	4.991	-0.025
Max		5.064	5.062	0.000
Average		5.025	5.014	-0.011
Min		5.003	4.979	-0.026
Std Dev		0.018	0.024	0.011

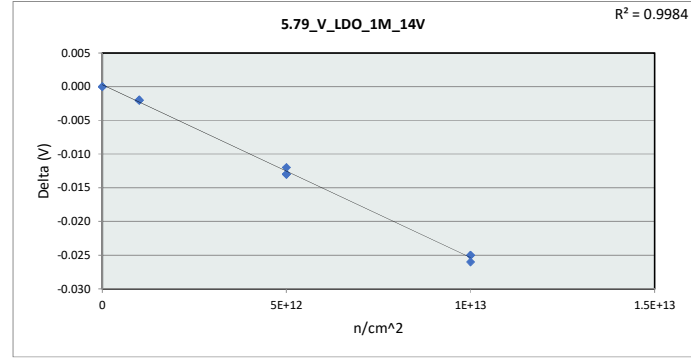


5.78_V_LDO_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	5.2		V	
Min Limit	4.75		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.003	5.012	5.010	4.979
Average	5.024	5.033	5.018	4.987
Max	5.044	5.062	5.025	4.991
UL	5.200	5.200	5.200	5.200

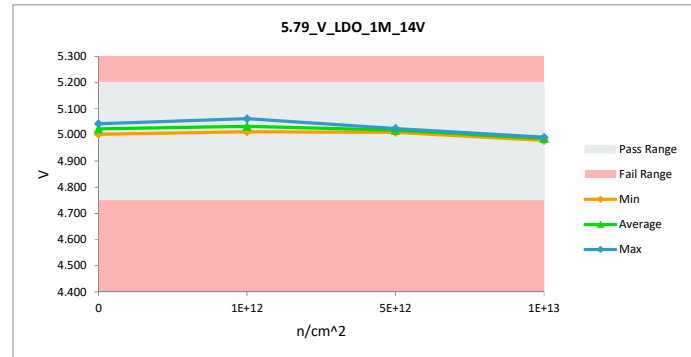


NDD Characterization Report TPS7H5006-SEP

5.79_V_LDO_1M_14V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	5.15	5.2	5.2	5.2
Min Limit	4.85	4.75	4.75	4.75
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.043	5.043	0.000
0	49	5.003	5.003	0.000
1E+12	11	5.064	5.062	-0.002
1E+12	12	5.026	5.024	-0.002
1E+12	13	5.014	5.012	-0.002
5E+12	14	5.023	5.010	-0.013
5E+12	15	5.032	5.019	-0.013
5E+12	16	5.037	5.025	-0.012
1E+13	17	5.015	4.990	-0.025
1E+13	18	5.005	4.979	-0.026
1E+13	19	5.016	4.991	-0.025
Max		5.064	5.062	0.000
Average		5.025	5.014	-0.011
Min		5.003	4.979	-0.026
Std Dev		0.018	0.024	0.011

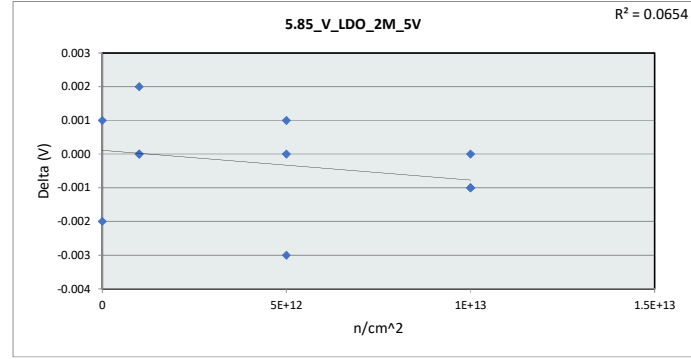


5.79_V_LDO_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.003	5.012	5.010	4.979
Average	5.023	5.033	5.018	4.987
Max	5.043	5.062	5.025	4.991
UL	5.200	5.200	5.200	5.200

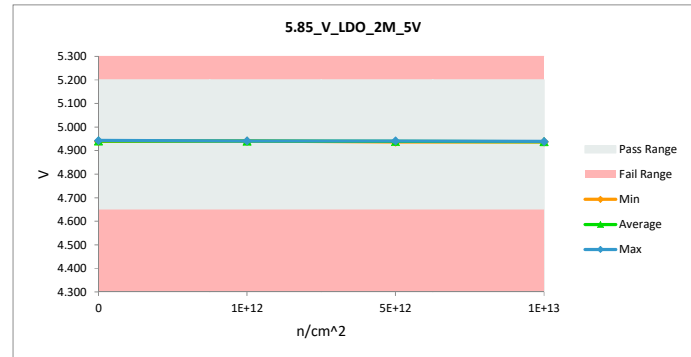


NDD Characterization Report TPS7H5006-SEP

5.85_V_LDO_2M_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.1	5.2	
Min Limit		4.8	4.65	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.942	4.943	0.001
0	49	4.941	4.939	-0.002
1E+12	11	4.940	4.940	0.000
1E+12	12	4.941	4.941	0.000
1E+12	13	4.938	4.940	0.002
5E+12	14	4.940	4.941	0.001
5E+12	15	4.940	4.940	0.000
5E+12	16	4.939	4.936	-0.003
1E+13	17	4.940	4.939	-0.001
1E+13	18	4.938	4.937	-0.001
1E+13	19	4.938	4.938	0.000
Max		4.942	4.943	0.002
Average		4.940	4.939	0.000
Min		4.938	4.936	-0.003
Std Dev		0.001	0.002	0.001

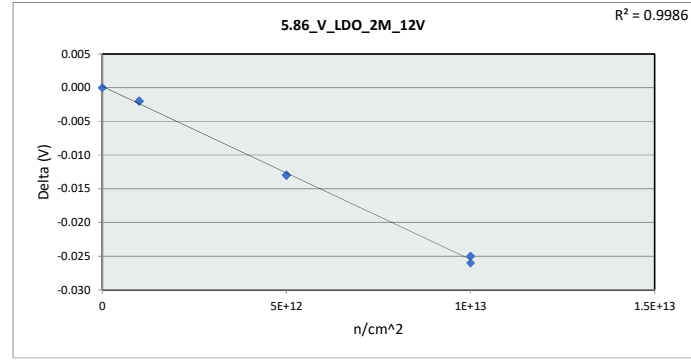


5.85_V_LDO_2M_5V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	4.939	4.940	4.936	4.937
Average	4.941	4.940	4.939	4.938
Max	4.943	4.941	4.941	4.939
UL	5.200	5.200	5.200	5.200

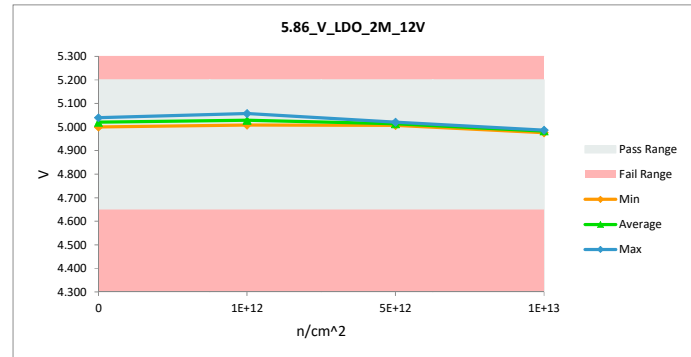


NDD Characterization Report TPS7H5006-SEP

5.86_V_LDO_2M_12V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.15	5.2	
Min Limit		4.8	4.65	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.040	5.040	0.000
0	49	5.000	5.000	0.000
1E+12	11	5.060	5.058	-0.002
1E+12	12	5.022	5.020	-0.002
1E+12	13	5.011	5.009	-0.002
5E+12	14	5.020	5.007	-0.013
5E+12	15	5.029	5.016	-0.013
5E+12	16	5.034	5.021	-0.013
1E+13	17	5.012	4.987	-0.025
1E+13	18	5.002	4.976	-0.026
1E+13	19	5.012	4.987	-0.025
Max		5.060	5.058	0.000
Average		5.022	5.011	-0.011
Min		5.000	4.976	-0.026
Std Dev		0.018	0.024	0.011

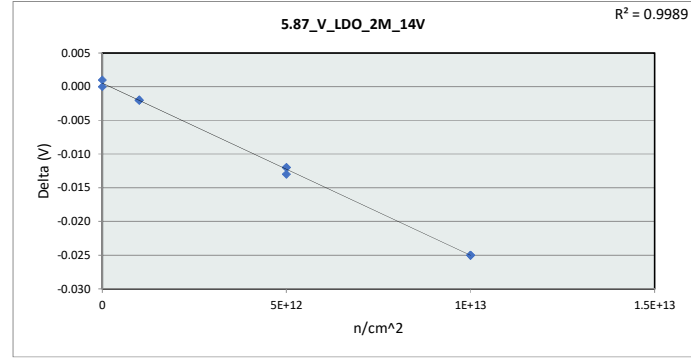


5.86_V_LDO_2M_12V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.000	5.009	5.007	4.976
Average	5.020	5.029	5.015	4.983
Max	5.040	5.058	5.021	4.987
UL	5.200	5.200	5.200	5.200

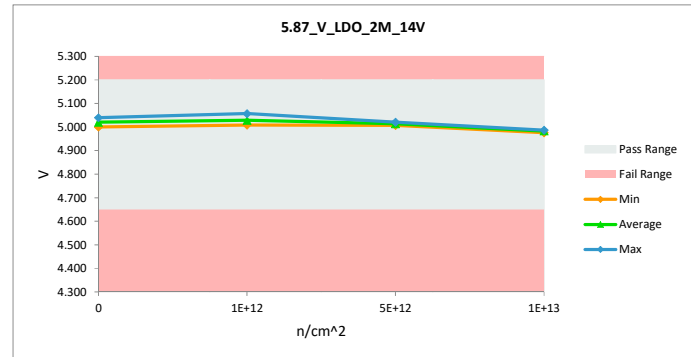


NDD Characterization Report TPS7H5006-SEP

5.87_V_LDO_2M_14V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.15	5.2	
Min Limit		4.8	4.65	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.040	5.040	0.000
0	49	4.999	5.000	0.001
1E+12	11	5.059	5.057	-0.002
1E+12	12	5.022	5.020	-0.002
1E+12	13	5.011	5.009	-0.002
5E+12	14	5.019	5.007	-0.012
5E+12	15	5.028	5.016	-0.012
5E+12	16	5.034	5.021	-0.013
1E+13	17	5.012	4.987	-0.025
1E+13	18	5.001	4.976	-0.025
1E+13	19	5.012	4.987	-0.025
Max		5.059	5.057	0.001
Average		5.022	5.011	-0.011
Min		4.999	4.976	-0.025
Std Dev		0.018	0.024	0.010

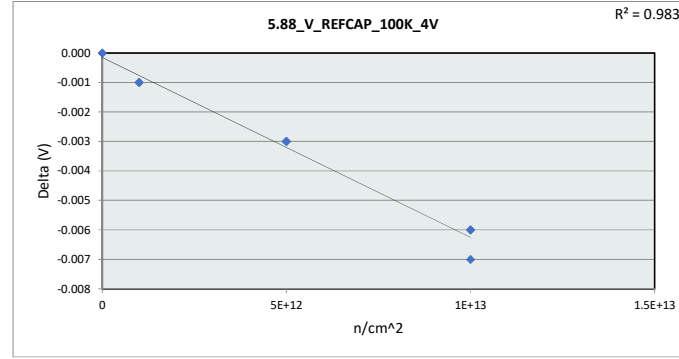


5.87_V_LDO_2M_14V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.000	5.009	5.007	4.976
Average	5.020	5.029	5.015	4.983
Max	5.040	5.057	5.021	4.987
UL	5.200	5.200	5.200	5.200

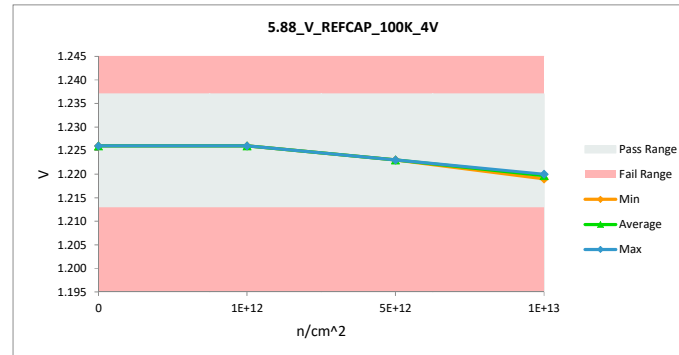


NDD Characterization Report TPS7H5006-SEP

5.88_V_REFCAP_100K_4V				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.237	1.237		
Min Limit	1.213	1.213		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.226	-0.001
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.219	-0.007
1E+13	18	1.226	1.220	-0.006
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.226	0.000
Average		1.226	1.223	-0.003
Min		1.226	1.219	-0.007
Std Dev		0.000	0.003	0.003

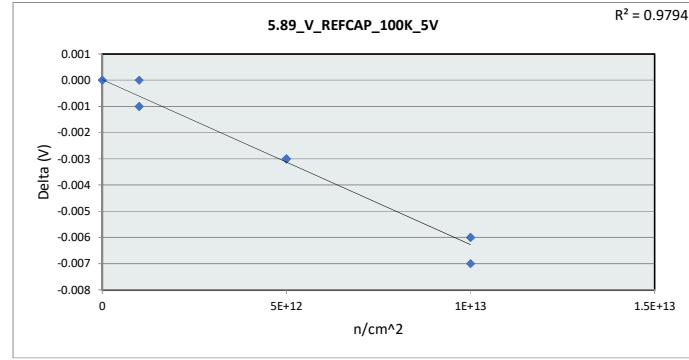


5.88_V_REFCAP_100K_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.219
Average	1.226	1.226	1.223	1.220
Max	1.226	1.226	1.223	1.220
UL	1.237	1.237	1.237	1.237

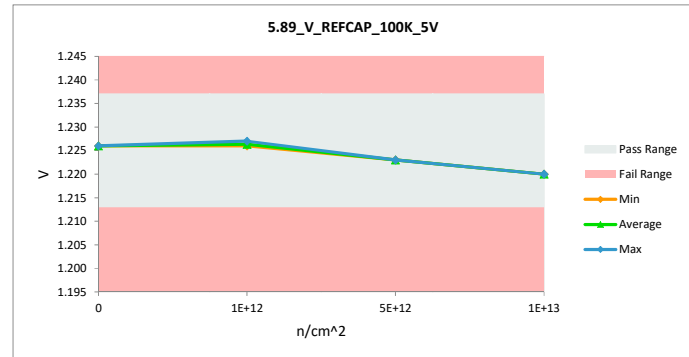


NDD Characterization Report TPS7H5006-SEP

5.89_V_REFCAP_100K_5V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

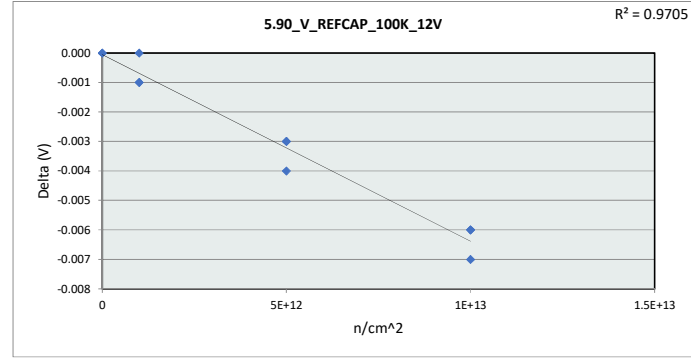


5.89_V_REFCAP_100K_5V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

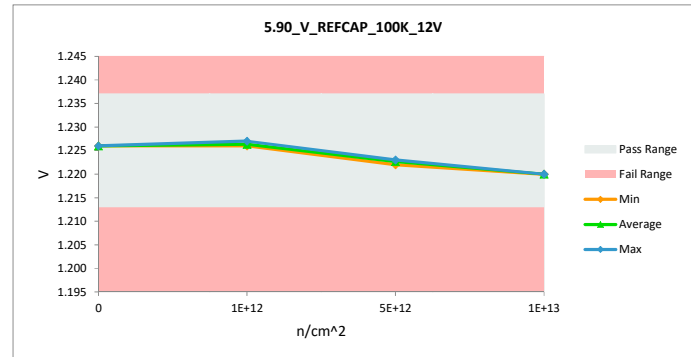


NDD Characterization Report TPS7H5006-SEP

5.90_V_REFCAP_100K_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.222	-0.004
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

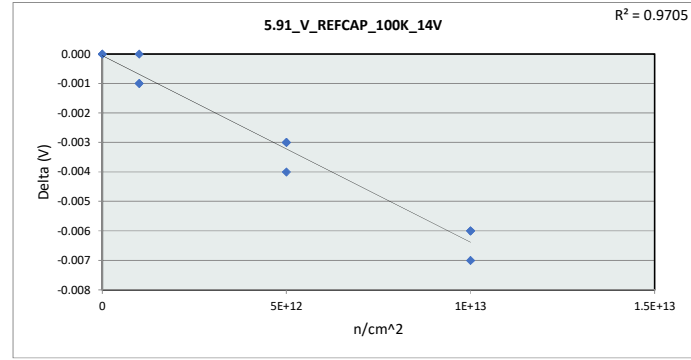


5.90_V_REFCAP_100K_12V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.222	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

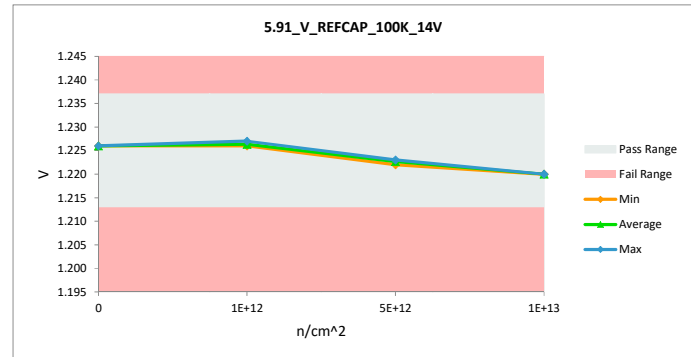


NDD Characterization Report TPS7H5006-SEP

5.91_V_REFCAP_100K_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	1.237		1.237	
Min Limit	1.213		1.213	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.222	-0.004
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

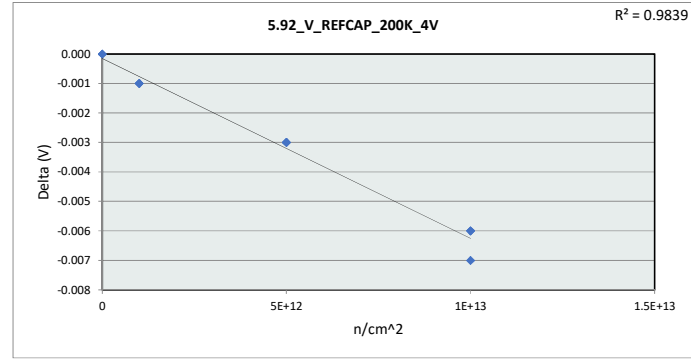


5.91_V_REFCAP_100K_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237		V	
Min Limit	1.213		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.222	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

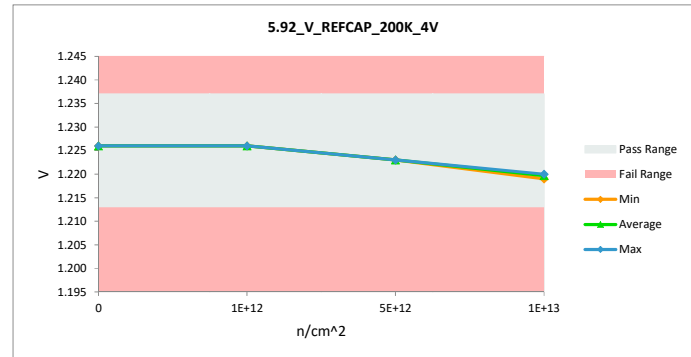


NDD Characterization Report TPS7H5006-SEP

5.92_V_REFCAP_200K_4V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	1.237		1.237	
Min Limit	1.213		1.213	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.226	-0.001
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.219	-0.007
1E+13	18	1.226	1.220	-0.006
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.226	0.000
Average		1.226	1.223	-0.003
Min		1.226	1.219	-0.007
Std Dev		0.000	0.003	0.003

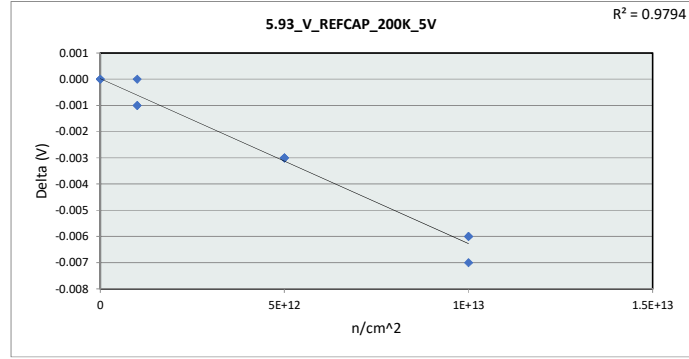


5.92_V_REFCAP_200K_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237		V	
Min Limit	1.213		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.219
Average	1.226	1.226	1.223	1.220
Max	1.226	1.226	1.223	1.220
UL	1.237	1.237	1.237	1.237

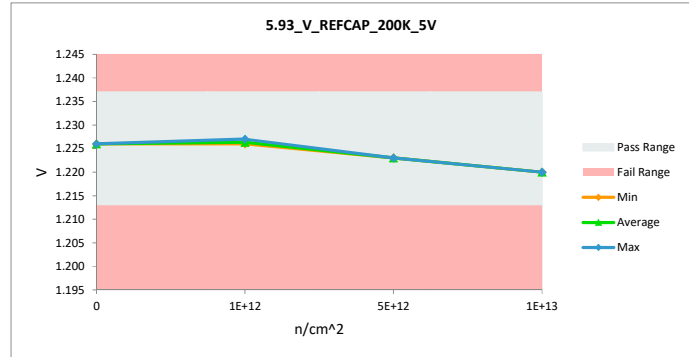


NDD Characterization Report TPS7H5006-SEP

5.93_V_REFCAP_200K_5V				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.237	1.237		
Min Limit	1.213	1.213		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

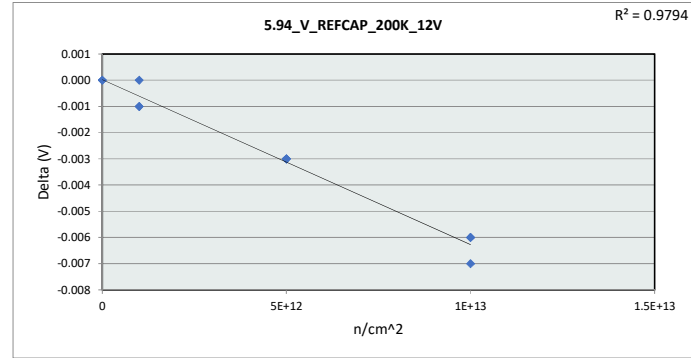


5.93_V_REFCAP_200K_5V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

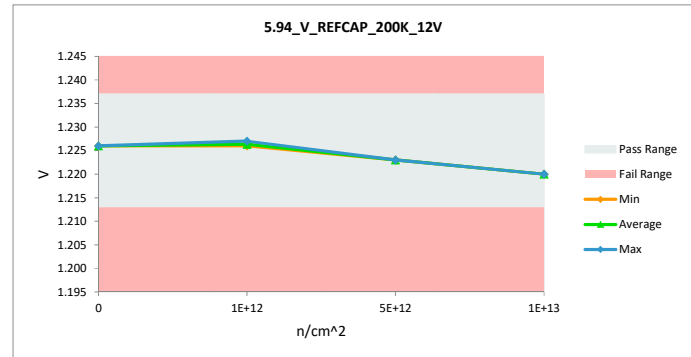


NDD Characterization Report TPS7H5006-SEP

5.94_V_REFCAP_200K_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

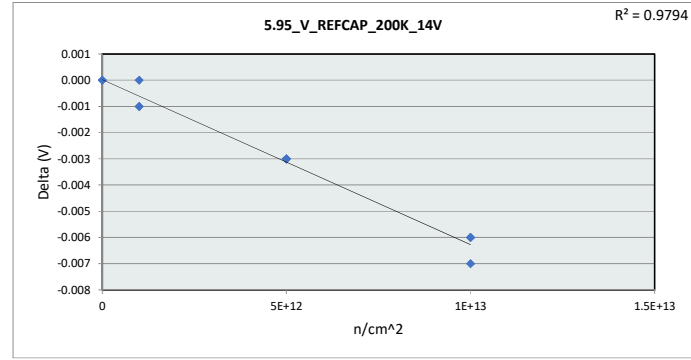


5.94_V_REFCAP_200K_12V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

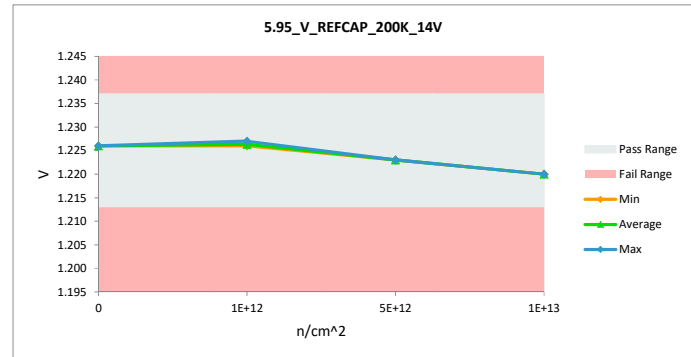


NDD Characterization Report TPS7H5006-SEP

5.95_V_REFCAP_200K_14V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

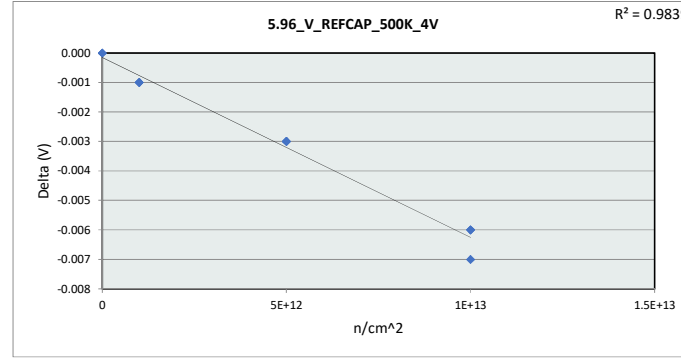


5.95_V_REFCAP_200K_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

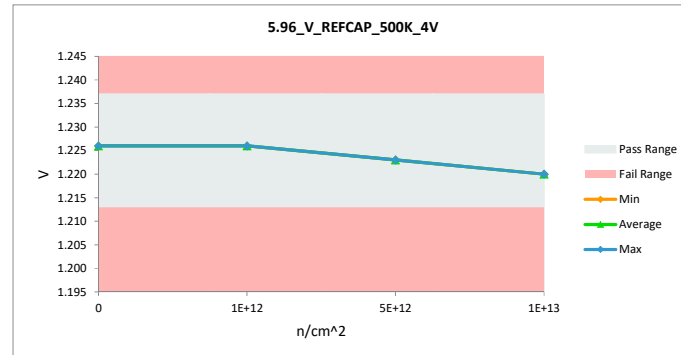


NDD Characterization Report TPS7H5006-SEP

5.96_V_REFCAP_500K_4V				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.237	1.237		
Min Limit	1.213	1.213		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.226	-0.001
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.226	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

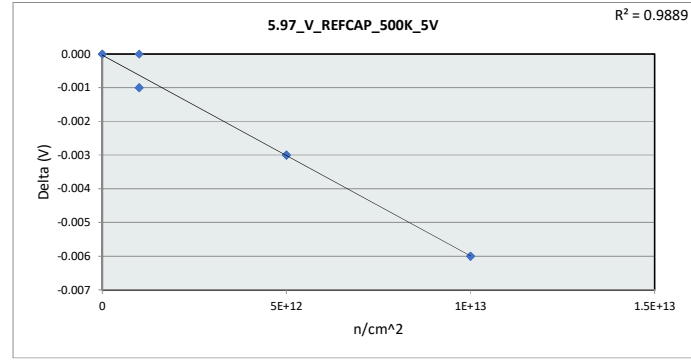


5.96_V_REFCAP_500K_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.226	1.223	1.220
UL	1.237	1.237	1.237	1.237

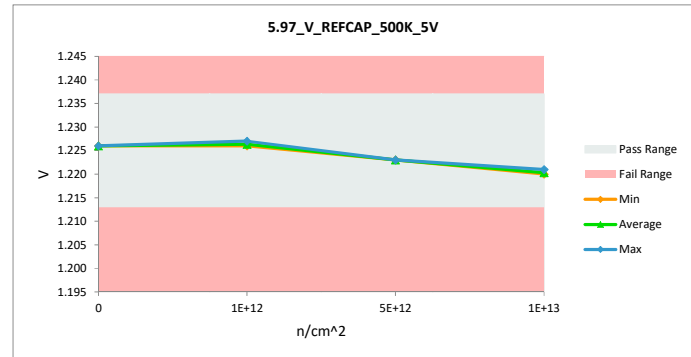


NDD Characterization Report TPS7H5006-SEP

5.97_V_REFCAP_500K_5V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.002

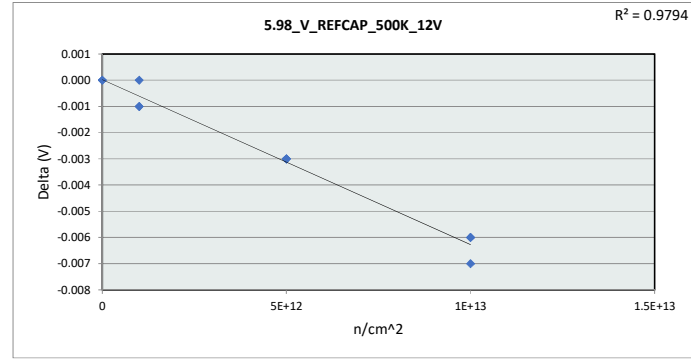


5.97_V_REFCAP_500K_5V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.221
UL	1.237	1.237	1.237	1.237

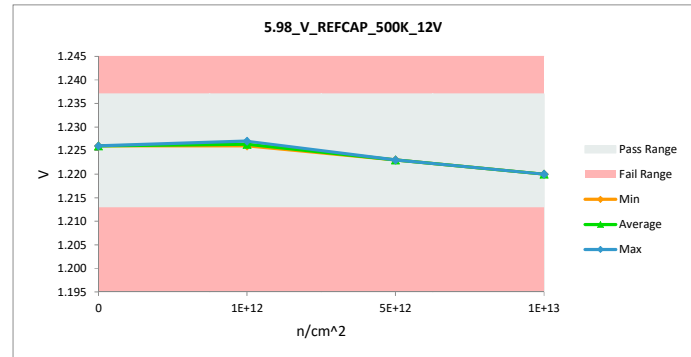


NDD Characterization Report TPS7H5006-SEP

5.98_V_REFCAP_500K_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

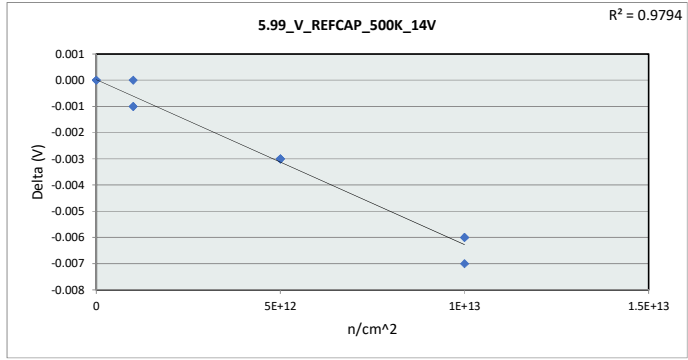


5.98_V_REFCAP_500K_12V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

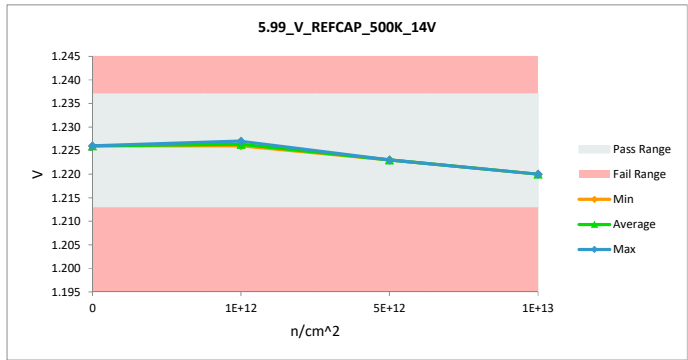


NDD Characterization Report TPS7H5006-SEP

5.99_V_REFCAP_500K_14V				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.237	1.237		
Min Limit	1.213	1.213		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.007
Std Dev		0.001	0.003	0.003

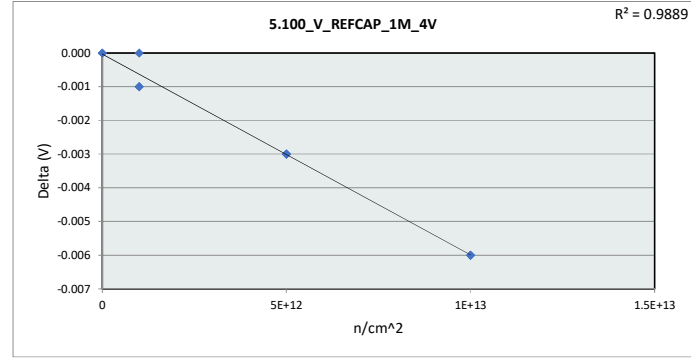


5.99_V_REFCAP_500K_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

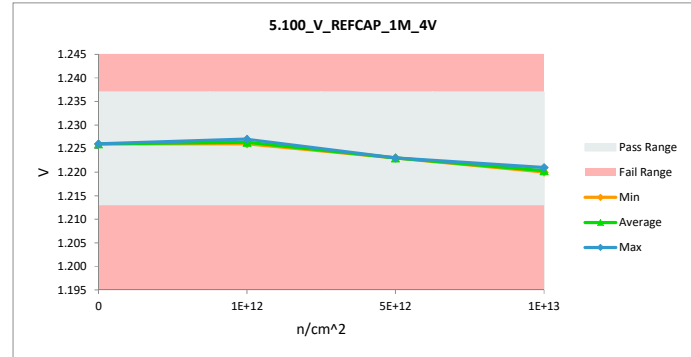


NDD Characterization Report TPS7H5006-SEP

5.100_V_REFCAP_1M_4V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.000
Average		1.226	1.224	-0.003
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.002

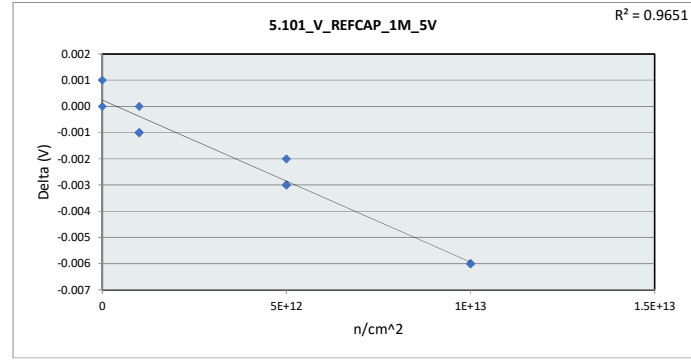


5.100_V_REFCAP_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.221
UL	1.237	1.237	1.237	1.237

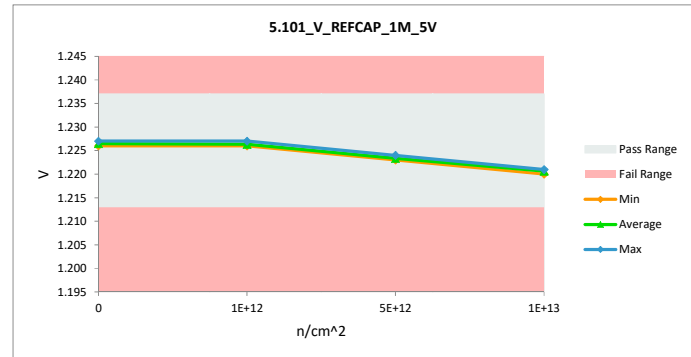


NDD Characterization Report TPS7H5006-SEP

5.101_V_REFCAP_1M_5V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.226	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

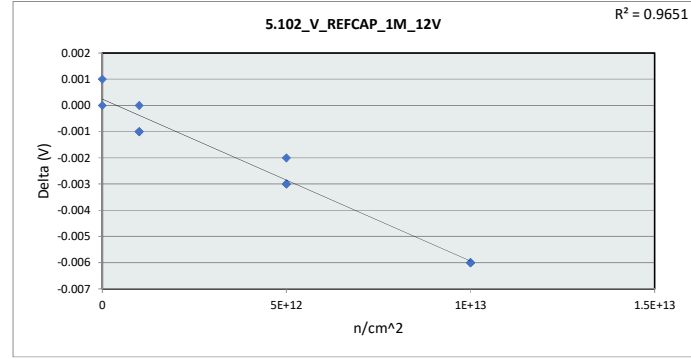


5.101_V_REFCAP_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

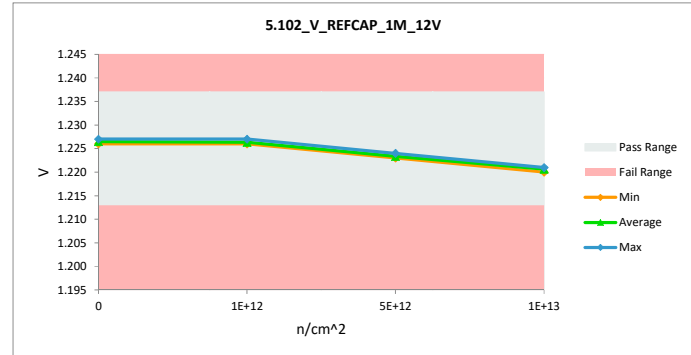


NDD Characterization Report TPS7H5006-SEP

5.102_V_REFCAP_1M_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.226	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

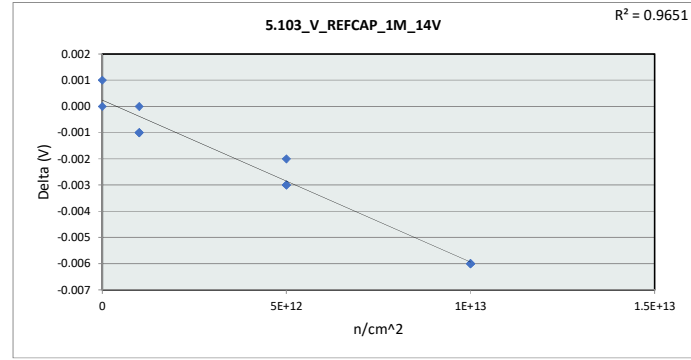


5.102_V_REFCAP_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

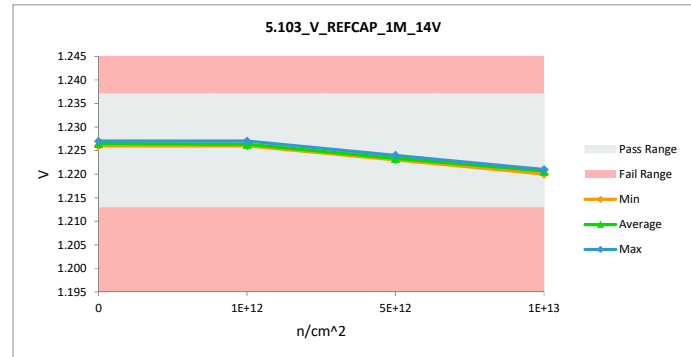


NDD Characterization Report TPS7H5006-SEP

5.103_V_REFCAP_1M_14V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.226	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

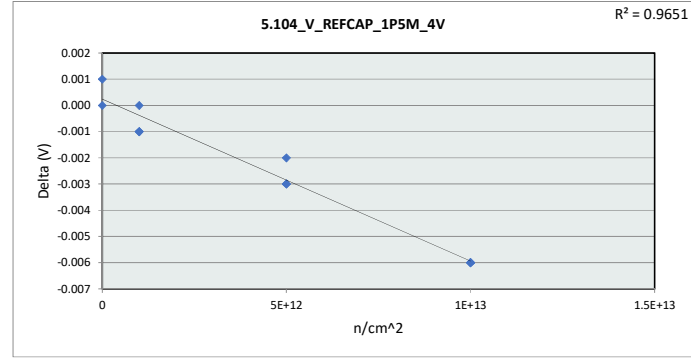


5.103_V_REFCAP_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

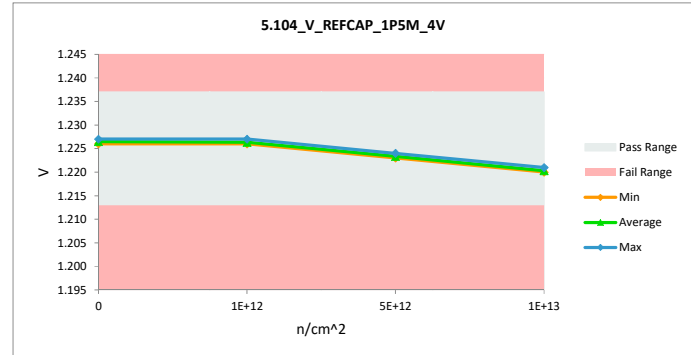


NDD Characterization Report TPS7H5006-SEP

5.104_V_REFCAP_1P5M_4V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.226	1.220	-0.006
Max		1.227	1.227	0.001
Average		1.226	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

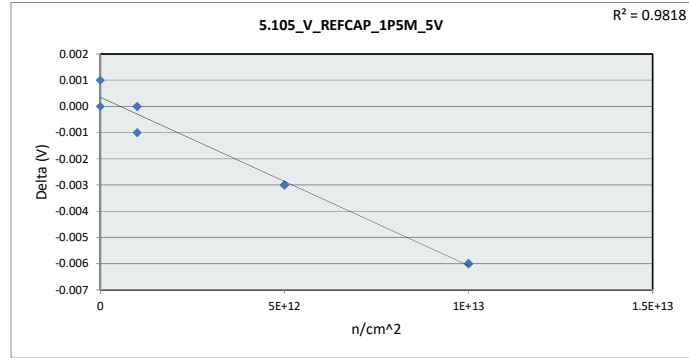


5.104_V_REFCAP_1P5M_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.220
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

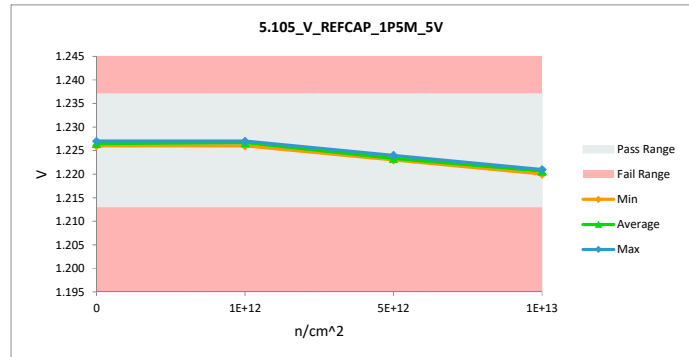


NDD Characterization Report TPS7H5006-SEP

5.105_V_REFCAP_1P5M_5V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	1.237		1.237	
Min Limit	1.213		1.213	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.227	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

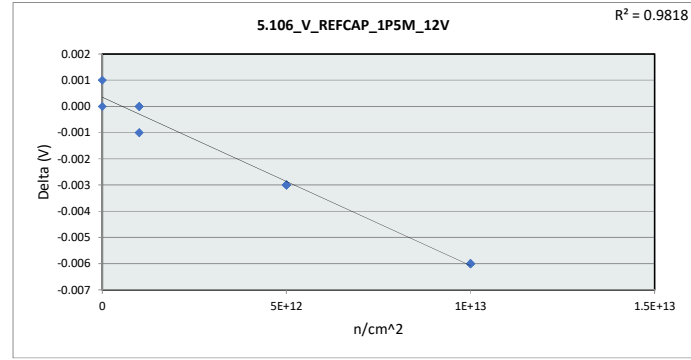


5.105_V_REFCAP_1P5M_5V				
Test Site				
Tester				
Test Number				
Max Limit	1.237		V	
Min Limit	1.213		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

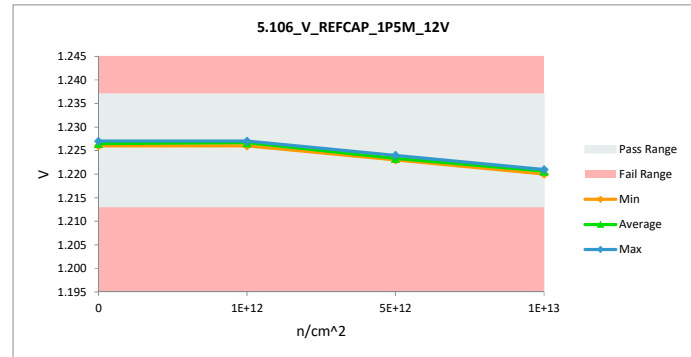


NDD Characterization Report TPS7H5006-SEP

5.106_V_REFCAP_1P5M_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.227	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

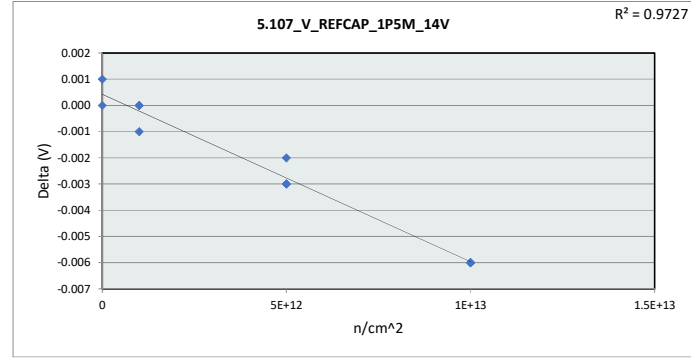


5.106_V_REFCAP_1P5M_12V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

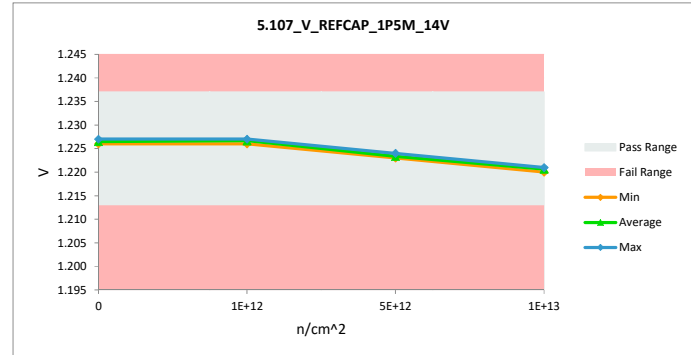


NDD Characterization Report TPS7H5006-SEP

5.107_V_REFCAP_1P5M_14V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.226	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

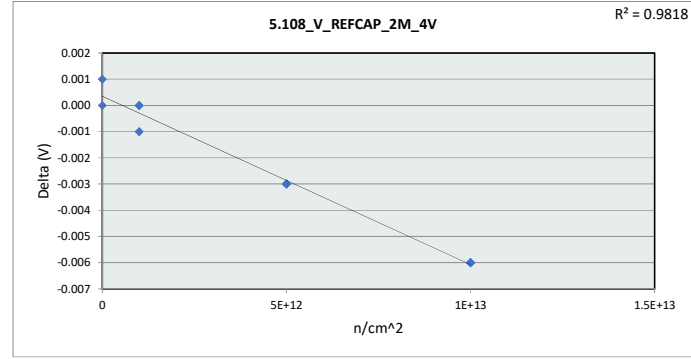


5.107_V_REFCAP_1P5M_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

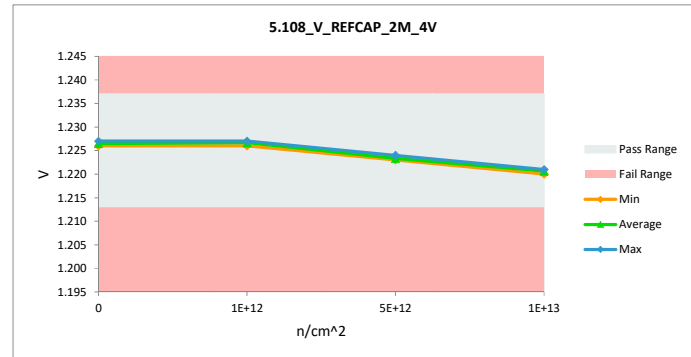


NDD Characterization Report TPS7H5006-SEP

5.108_V_REFCAP_2M_4V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	1.237		1.237	
Min Limit	1.213		1.213	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.227	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

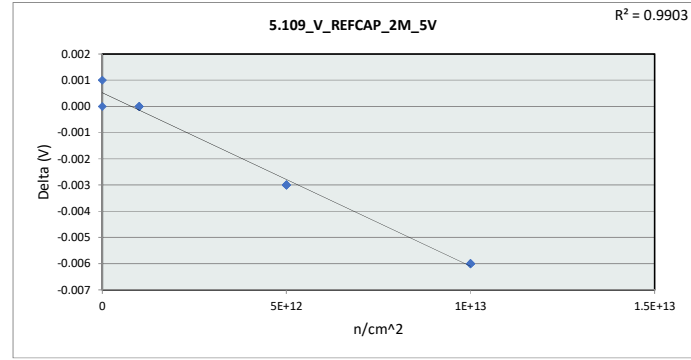


5.108_V_REFCAP_2M_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237		V	
Min Limit	1.213		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

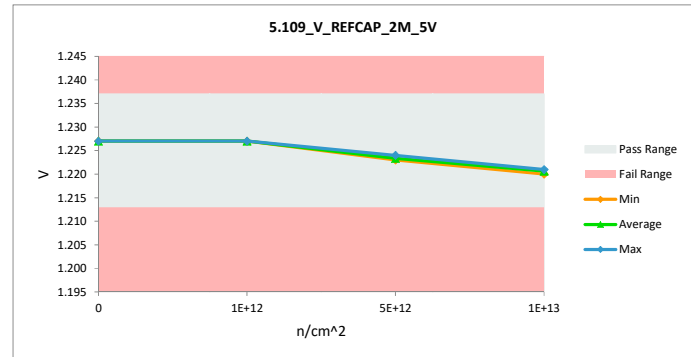


NDD Characterization Report TPS7H5006-SEP

5.109_V_REFCAP_2M_5V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.227	0.001
0	49	1.227	1.227	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.227	0.000
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.227	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

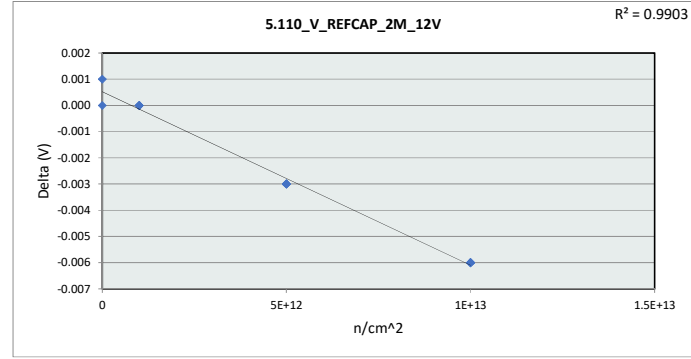


5.109_V_REFCAP_2M_5V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

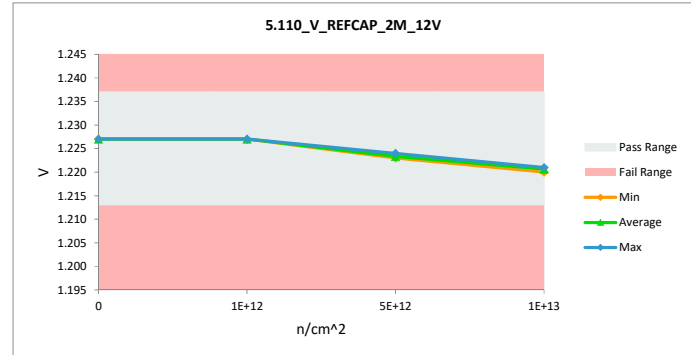


NDD Characterization Report TPS7H5006-SEP

5.110_V_REFCAP_2M_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.227	0.001
0	49	1.227	1.227	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.227	0.000
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.227	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

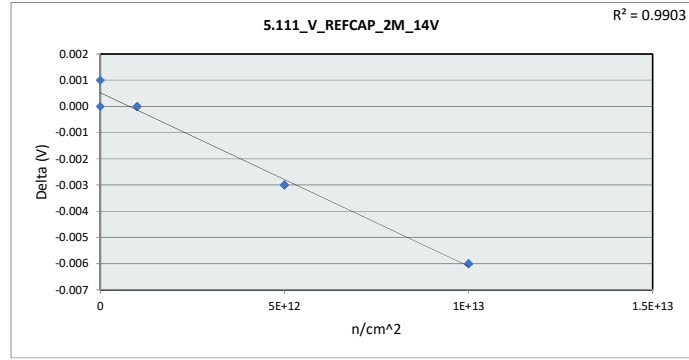


5.110_V_REFCAP_2M_12V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

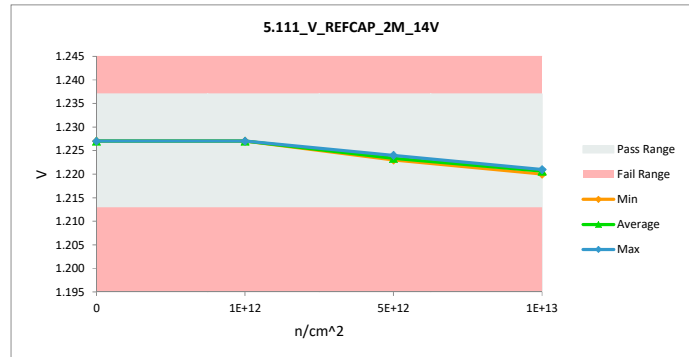


NDD Characterization Report TPS7H5006-SEP

5.111_V_REFCAP_2M_14V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	1.237	1.237	1.237	1.237
Min Limit	1.213	1.213	1.213	1.213
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.227	0.001
0	49	1.227	1.227	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.227	0.000
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
Max		1.227	1.227	0.001
Average		1.227	1.224	-0.002
Min		1.226	1.220	-0.006
Std Dev		0.001	0.003	0.003

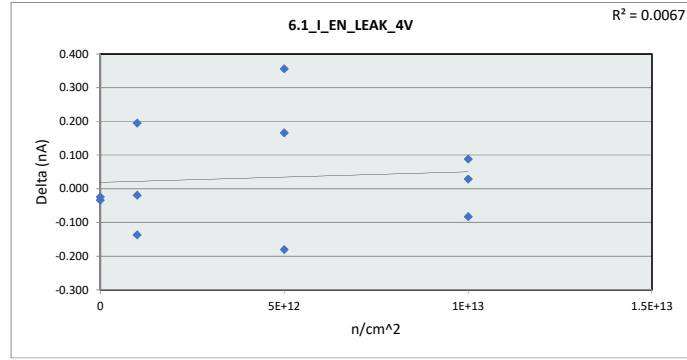


5.111_V_REFCAP_2M_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V	V	V
Min Limit	1.213	V	V	V
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

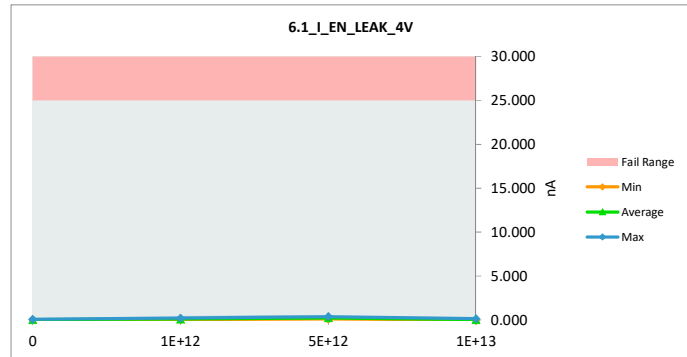


NDD Characterization Report TPS7H5006-SEP

6.1_I_EN_LEAK_4V				
Test Site				
Tester				
Test Number				
Unit		nA		nA
Max Limit		5		25
Min Limit		-0.1		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.095	0.071	-0.024
0	49	0.056	0.022	-0.034
1E+12	11	0.012	0.207	0.195
1E+12	12	0.051	0.032	-0.019
1E+12	13	0.203	0.066	-0.137
5E+12	14	0.290	0.110	-0.180
5E+12	15	0.027	0.383	0.356
5E+12	16	0.051	0.217	0.166
1E+13	17	0.085	0.002	-0.083
1E+13	18	0.012	0.041	0.029
1E+13	19	0.041	0.129	0.088
Max		0.290	0.383	0.356
Average		0.084	0.116	0.032
Min		0.012	0.002	-0.180
Std Dev		0.087	0.114	0.158

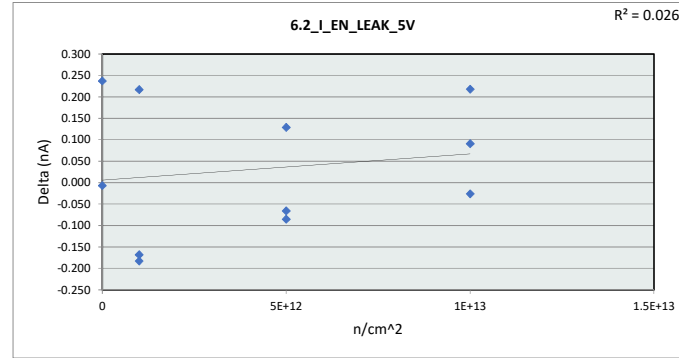


6.1_I_EN_LEAK_4V				
Test Site				
Tester				
Test Number				
Max Limit	25		nA	
Min Limit			nA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	0.022	0.032	0.110	0.002
Average	0.047	0.102	0.237	0.057
Max	0.071	0.207	0.383	0.129
UL	25.000	25.000	25.000	25.000

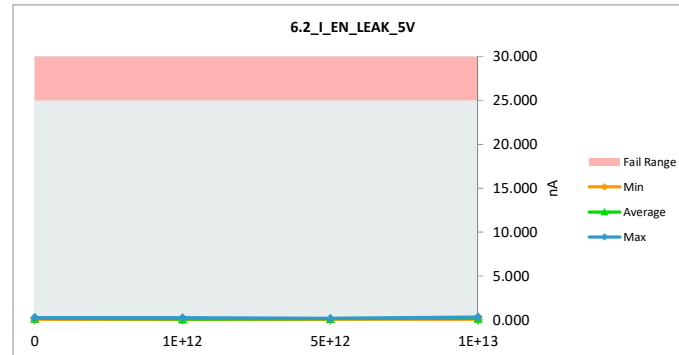


NDD Characterization Report TPS7H5006-SEP

6.2_I_EN_LEAK_5V				
Test Site				
Tester				
Test Number				
Unit	nA		nA	
Max Limit	5		25	
Min Limit	-0.1			
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.029	0.266	0.237
0	49	0.088	0.081	-0.007
1E+12	11	0.029	0.246	0.217
1E+12	12	0.185	0.017	-0.168
1E+12	13	0.244	0.061	-0.183
5E+12	14	0.195	0.129	-0.066
5E+12	15	0.166	0.081	-0.085
5E+12	16	0.039	0.168	0.129
1E+13	17	0.107	0.081	-0.026
1E+13	18	0.107	0.325	0.218
1E+13	19	0.068	0.159	0.091
Max		0.244	0.325	0.237
Average		0.114	0.147	0.032
Min		0.029	0.017	-0.183
Std Dev		0.074	0.097	0.154

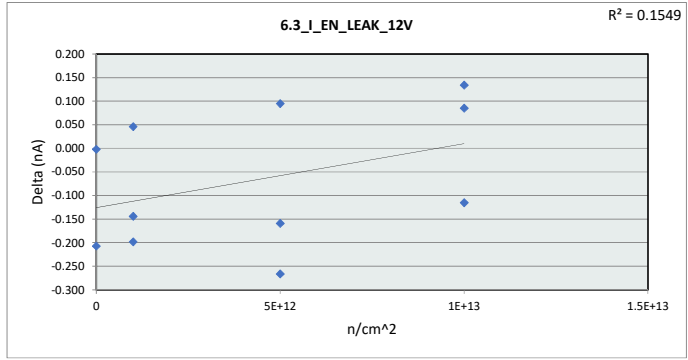


6.2_I_EN_LEAK_5V				
Test Site				
Tester				
Test Number				
Max Limit	25		nA	
Min Limit			nA	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	0.081	0.017	0.081	0.081
Average	0.174	0.108	0.126	0.188
Max	0.266	0.246	0.168	0.325
UL	25.000	25.000	25.000	25.000

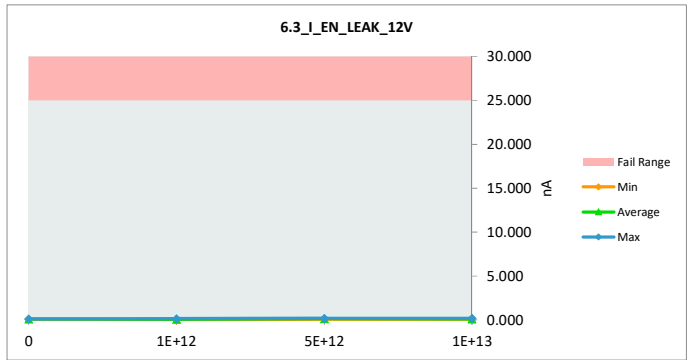


NDD Characterization Report TPS7H5006-SEP

6.3_I_EN_LEAK_12V				
Test Site				
Tester				
Test Number				
Unit	nA	nA		
Max Limit	5	25		
Min Limit	-0.1			
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.273	0.066	-0.207
0	49	0.107	0.105	-0.002
1E+12	11	0.088	0.134	0.046
1E+12	12	0.283	0.085	-0.198
1E+12	13	0.156	0.012	-0.144
5E+12	14	0.342	0.183	-0.159
5E+12	15	0.078	0.173	0.095
5E+12	16	0.342	0.076	-0.266
1E+13	17	0.176	0.061	-0.115
1E+13	18	0.000	0.085	0.085
1E+13	19	0.049	0.183	0.134
Max		0.342	0.183	0.134
Average		0.172	0.106	-0.066
Min		0.000	0.012	-0.266
Std Dev		0.121	0.056	0.141

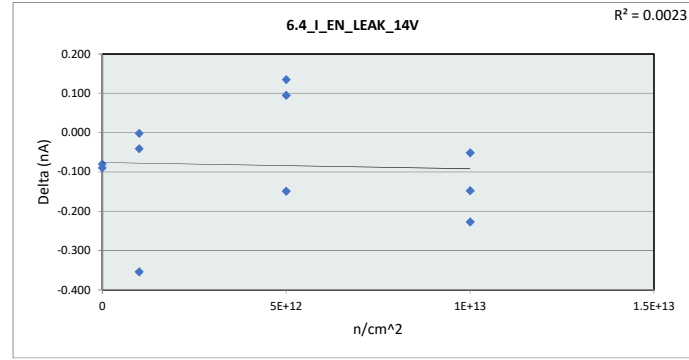


6.3_I_EN_LEAK_12V				
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.066	0.012	0.076	0.061
Average	0.086	0.077	0.144	0.110
Max	0.105	0.134	0.183	0.183
UL	25.000	25.000	25.000	25.000

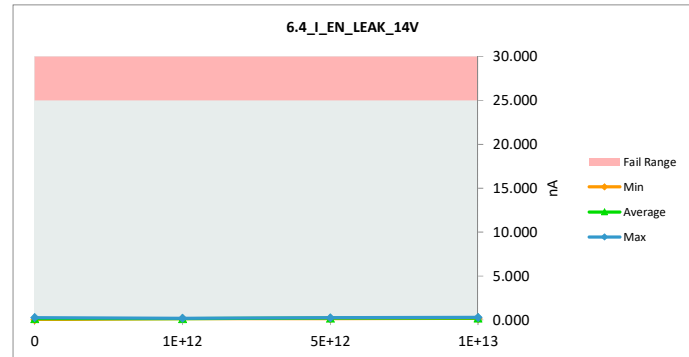


NDD Characterization Report TPS7H5006-SEP

6.4_I_EN_LEAK_14V				
Test Site				
Tester				
Test Number				
Unit		nA	nA	
Max Limit		5	25	
Min Limit		-0.1		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.127	0.037	-0.090
0	49	0.351	0.271	-0.080
1E+12	11	0.488	0.134	-0.354
1E+12	12	0.156	0.154	-0.002
1E+12	13	0.234	0.193	-0.041
5E+12	14	0.107	0.242	0.135
5E+12	15	0.283	0.134	-0.149
5E+12	16	0.137	0.232	0.095
1E+13	17	0.429	0.281	-0.148
1E+13	18	0.410	0.183	-0.227
1E+13	19	0.254	0.203	-0.051
Max		0.488	0.281	0.135
Average		0.271	0.188	-0.083
Min		0.107	0.037	-0.354
Std Dev		0.134	0.071	0.138

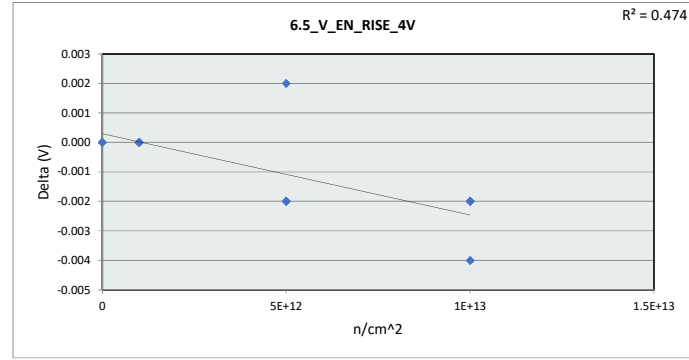


6.4_I_EN_LEAK_14V				
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	0.037	0.134	0.134	0.183
Average	0.154	0.160	0.203	0.222
Max	0.271	0.193	0.242	0.281
UL	25.000	25.000	25.000	25.000

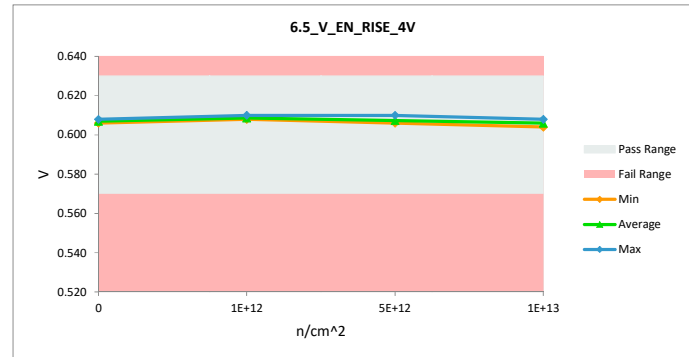


NDD Characterization Report TPS7H5006-SEP

6.5_V_EN_RISE_4V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.63		0.63	
Min Limit	0.58		0.57	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.608	0.608	0.000
1E+12	12	0.610	0.610	0.000
1E+12	13	0.608	0.608	0.000
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.610	0.002
5E+12	16	0.608	0.606	-0.002
1E+13	17	0.608	0.604	-0.004
1E+13	18	0.608	0.606	-0.002
1E+13	19	0.610	0.608	-0.002
Max		0.610	0.610	0.002
Average		0.608	0.607	-0.001
Min		0.606	0.604	-0.004
Std Dev		0.001	0.002	0.002

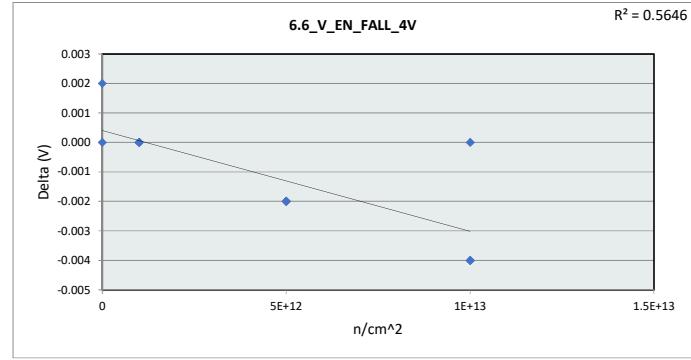


6.5_V_EN_RISE_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.63		V	
Min Limit	0.57		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.608	0.606	0.604
Average	0.607	0.609	0.607	0.606
Max	0.608	0.610	0.610	0.608
UL	0.630	0.630	0.630	0.630

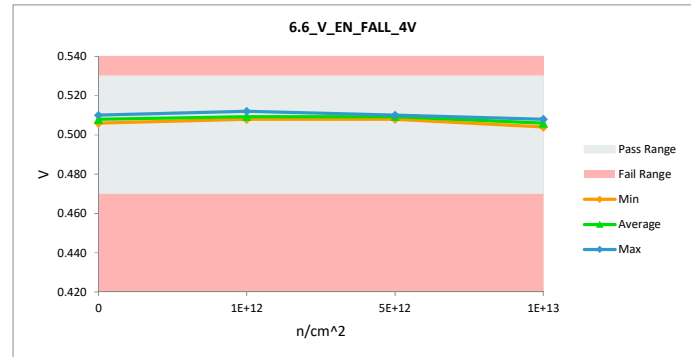


NDD Characterization Report TPS7H5006-SEP

6.6_V_EN_FALL_4V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.508	0.510	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.508	0.508	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.504	-0.004
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.508	0.508	0.000
Max		0.512	0.512	0.002
Average		0.509	0.508	-0.001
Min		0.506	0.504	-0.004
Std Dev		0.002	0.002	0.002

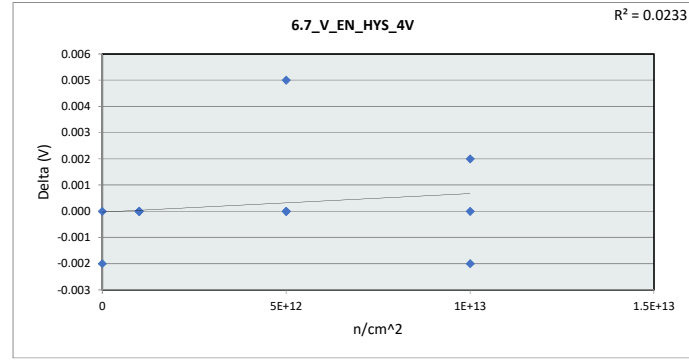


6.6_V_EN_FALL_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.504
Average	0.508	0.509	0.509	0.506
Max	0.510	0.512	0.510	0.508
UL	0.530	0.530	0.530	0.530

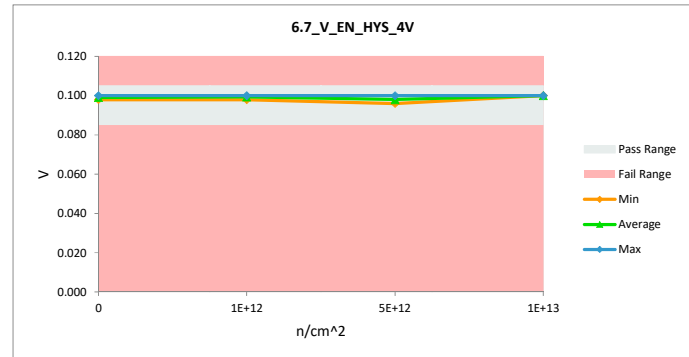


NDD Characterization Report TPS7H5006-SEP

6.7_V_EN_HYS_4V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	0.105	0.105	0.105	0.105
Min Limit	0.085	0.085	0.085	0.085
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.100	0.098	-0.002
1E+12	11	0.100	0.100	0.000
1E+12	12	0.098	0.098	0.000
1E+12	13	0.100	0.100	0.000
5E+12	14	0.098	0.098	0.000
5E+12	15	0.095	0.100	0.005
5E+12	16	0.096	0.096	0.000
1E+13	17	0.100	0.100	0.000
1E+13	18	0.098	0.100	0.002
1E+13	19	0.102	0.100	-0.002
Max		0.102	0.100	0.005
Average		0.099	0.099	0.000
Min		0.095	0.096	-0.002
Std Dev		0.002	0.001	0.002

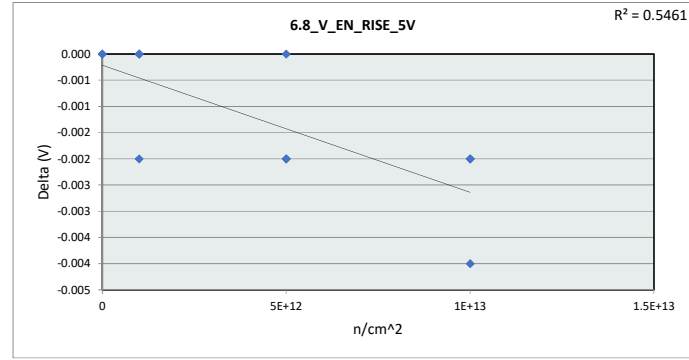


6.7_V_EN_HYS_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.098	0.098	0.096	0.100
Average	0.099	0.099	0.098	0.100
Max	0.100	0.100	0.100	0.100
UL	0.105	0.105	0.105	0.105

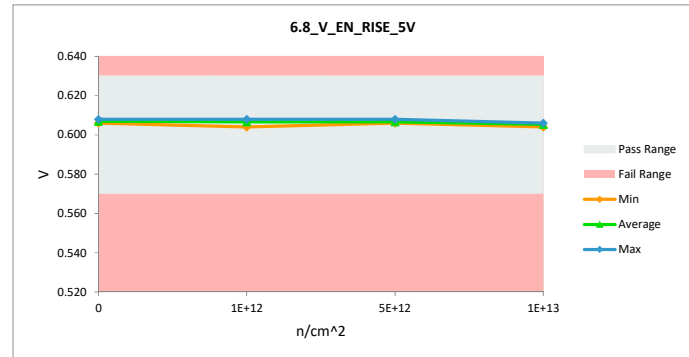


NDD Characterization Report TPS7H5006-SEP

6.8_V_EN_RISE_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.58	0.57	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.604	0.604	0.000
1E+12	12	0.608	0.608	0.000
1E+12	13	0.610	0.608	-0.002
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.606	-0.002
5E+12	16	0.608	0.608	0.000
1E+13	17	0.608	0.606	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.606	0.604	-0.002
Max		0.610	0.608	0.000
Average		0.608	0.606	-0.001
Min		0.604	0.604	-0.004
Std Dev		0.002	0.002	0.001

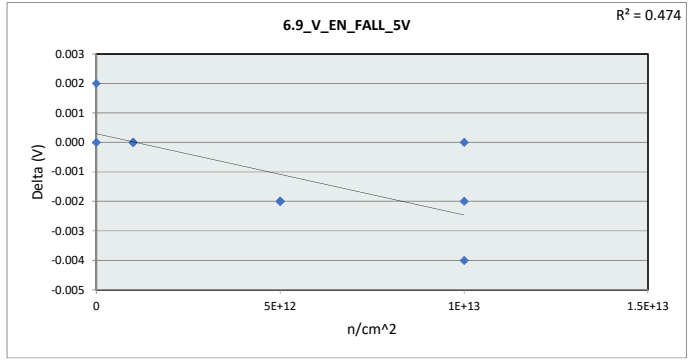


6.8_V_EN_RISE_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.604	0.606	0.604
Average	0.607	0.607	0.607	0.605
Max	0.608	0.608	0.608	0.606
UL	0.630	0.630	0.630	0.630

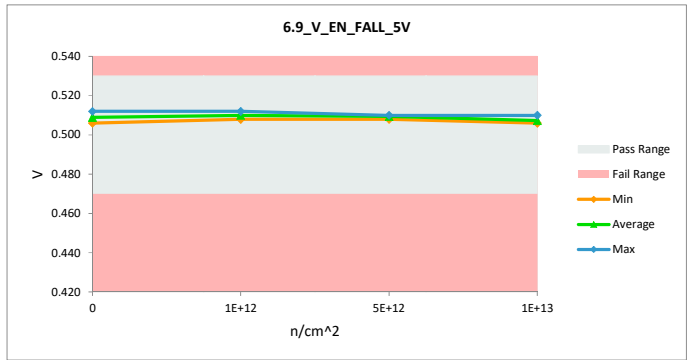


NDD Characterization Report TPS7H5006-SEP

6.9_V_EN_FALL_5V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.53		0.53	
Min Limit	0.48		0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.510	0.512	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.510	0.510	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.506	-0.002
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.510	0.510	0.000
Max		0.512	0.512	0.002
Average		0.510	0.509	-0.001
Min		0.506	0.506	-0.004
Std Dev		0.002	0.002	0.002

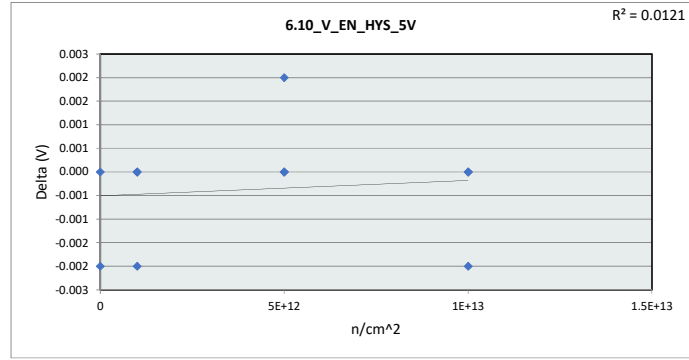


6.9_V_EN_FALL_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.53		V	
Min Limit	0.47		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.506
Average	0.509	0.510	0.509	0.507
Max	0.512	0.512	0.510	0.510
UL	0.530	0.530	0.530	0.530

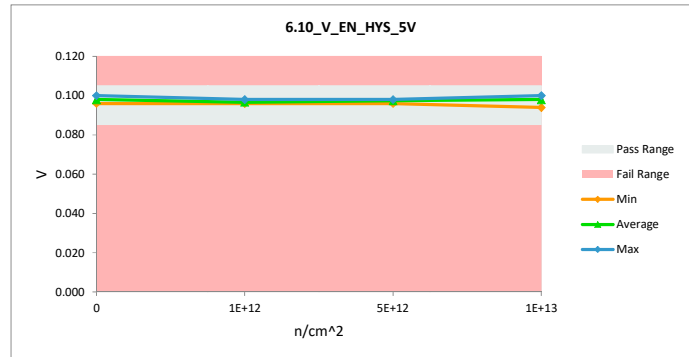


NDD Characterization Report TPS7H5006-SEP

6.10_V_EN_HYS_5V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.105		0.105	
Min Limit	0.085		0.085	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.098	0.096	-0.002
1E+12	11	0.096	0.096	0.000
1E+12	12	0.096	0.096	0.000
1E+12	13	0.100	0.098	-0.002
5E+12	14	0.098	0.098	0.000
5E+12	15	0.096	0.096	0.000
5E+12	16	0.096	0.098	0.002
1E+13	17	0.100	0.100	0.000
1E+13	18	0.100	0.100	0.000
1E+13	19	0.096	0.094	-0.002
Max		0.100	0.100	0.002
Average		0.098	0.097	0.000
Min		0.096	0.094	-0.002
Std Dev		0.002	0.002	0.001

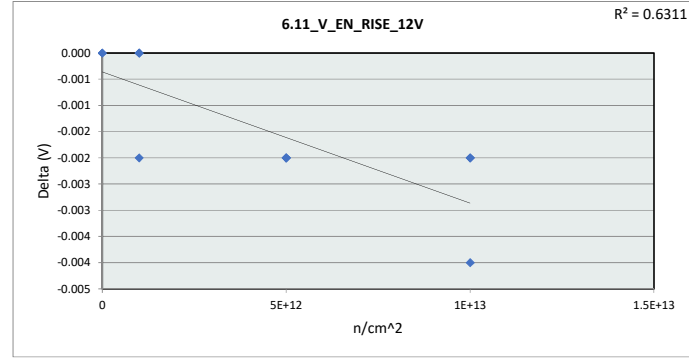


6.10_V_EN_HYS_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.105		V	
Min Limit	0.085		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.096	0.096	0.096	0.094
Average	0.098	0.097	0.097	0.098
Max	0.100	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

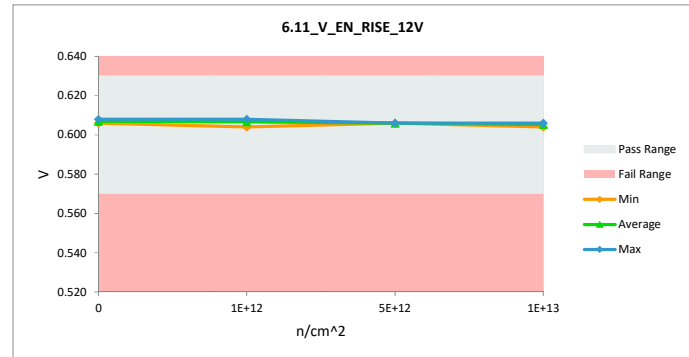


NDD Characterization Report TPS7H5006-SEP

6.11_V_EN_RISE_12V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	0.63	0.63	0.63	0.63
Min Limit	0.58	0.57	0.57	0.57
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.604	0.604	0.000
1E+12	12	0.608	0.608	0.000
1E+12	13	0.610	0.608	-0.002
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.606	-0.002
5E+12	16	0.608	0.606	-0.002
1E+13	17	0.608	0.606	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.606	0.604	-0.002
Max		0.610	0.608	0.000
Average		0.608	0.606	-0.001
Min		0.604	0.604	-0.004
Std Dev		0.002	0.001	0.001

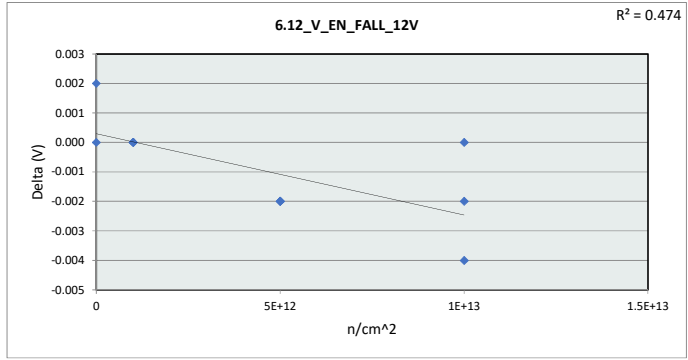


6.11_V_EN_RISE_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.604	0.606	0.604
Average	0.607	0.607	0.606	0.605
Max	0.608	0.608	0.606	0.606
UL	0.630	0.630	0.630	0.630

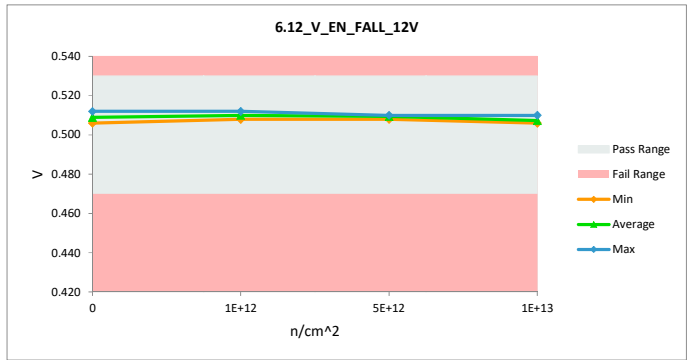


NDD Characterization Report TPS7H5006-SEP

6.12_V_EN_FALL_12V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.53		0.53	
Min Limit	0.48		0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.510	0.512	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.510	0.510	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.506	-0.002
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.510	0.510	0.000
Max		0.512	0.512	0.002
Average		0.510	0.509	-0.001
Min		0.506	0.506	-0.004
Std Dev		0.002	0.002	0.002

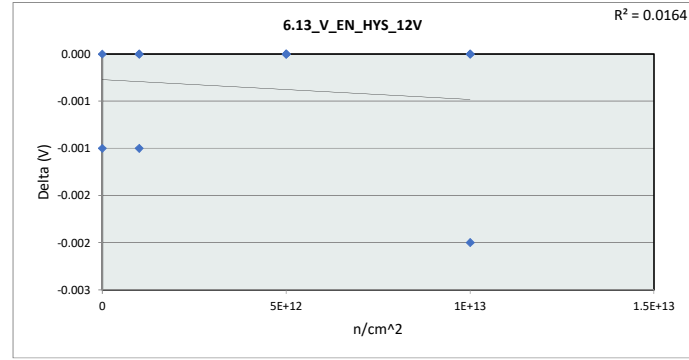


6.12_V_EN_FALL_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.53		V	
Min Limit	0.47		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.506
Average	0.509	0.510	0.509	0.507
Max	0.512	0.512	0.510	0.510
UL	0.530	0.530	0.530	0.530

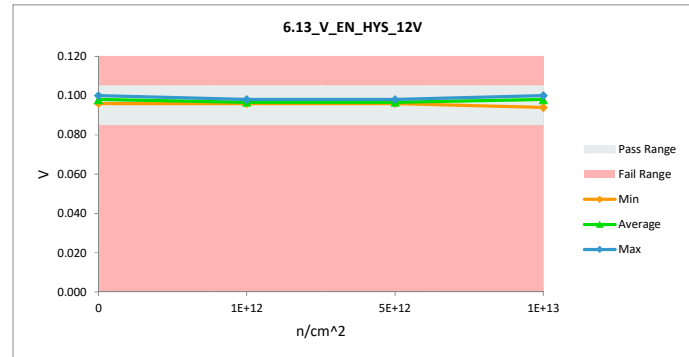


NDD Characterization Report TPS7H5006-SEP

6.13_V_EN_HYS_12V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.105		0.105	
Min Limit	0.085		0.085	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.097	0.096	-0.001
1E+12	11	0.096	0.096	0.000
1E+12	12	0.096	0.096	0.000
1E+12	13	0.099	0.098	-0.001
5E+12	14	0.098	0.098	0.000
5E+12	15	0.096	0.096	0.000
5E+12	16	0.096	0.096	0.000
1E+13	17	0.100	0.100	0.000
1E+13	18	0.100	0.100	0.000
1E+13	19	0.096	0.094	-0.002
Max		0.100	0.100	0.000
Average		0.098	0.097	0.000
Min		0.096	0.094	-0.002
Std Dev		0.002	0.002	0.001

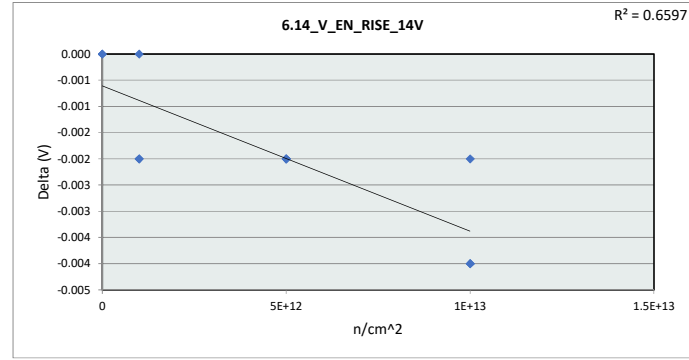


6.13_V_EN_HYS_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.105		V	
Min Limit	0.085		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.096	0.096	0.096	0.094
Average	0.098	0.097	0.097	0.098
Max	0.100	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

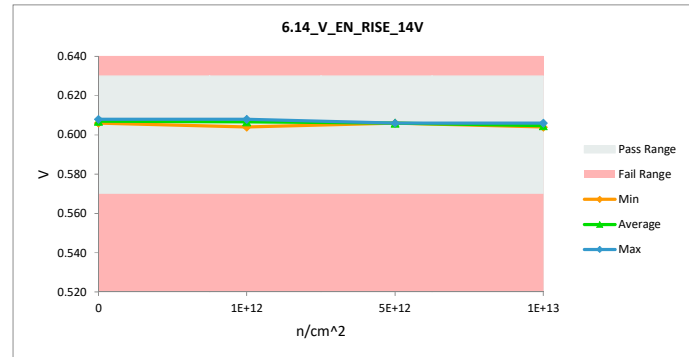


NDD Characterization Report TPS7H5006-SEP

6.14_V_EN_RISE_14V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	0.63	0.63	0.63	0.63
Min Limit	0.58	0.57	0.57	0.57
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.606	0.604	-0.002
1E+12	12	0.608	0.608	0.000
1E+12	13	0.610	0.608	-0.002
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.606	-0.002
5E+12	16	0.608	0.606	-0.002
1E+13	17	0.608	0.604	-0.004
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.606	0.604	-0.002
Max		0.610	0.608	0.000
Average		0.608	0.606	-0.002
Min		0.606	0.604	-0.004
Std Dev		0.001	0.002	0.001

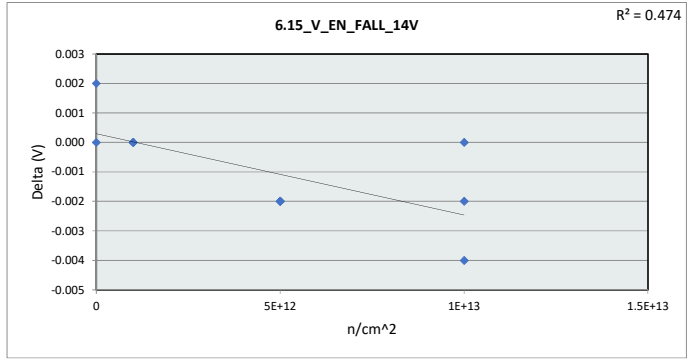


6.14_V_EN_RISE_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.604	0.606	0.604
Average	0.607	0.607	0.606	0.605
Max	0.608	0.608	0.606	0.606
UL	0.630	0.630	0.630	0.630

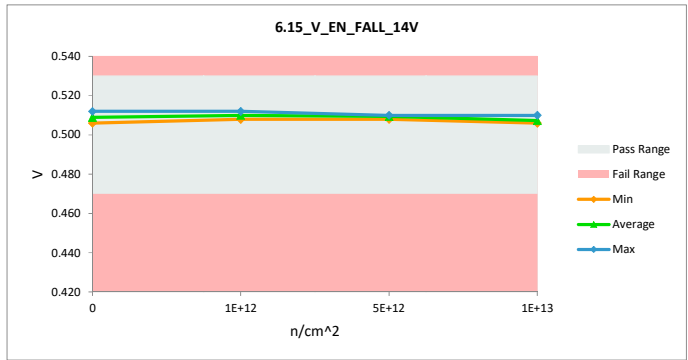


NDD Characterization Report TPS7H5006-SEP

6.15_V_EN_FALL_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.53		0.53	
Min Limit	0.48		0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.510	0.512	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.510	0.510	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.506	-0.002
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.510	0.510	0.000
Max		0.512	0.512	0.002
Average		0.510	0.509	-0.001
Min		0.506	0.506	-0.004
Std Dev		0.002	0.002	0.002

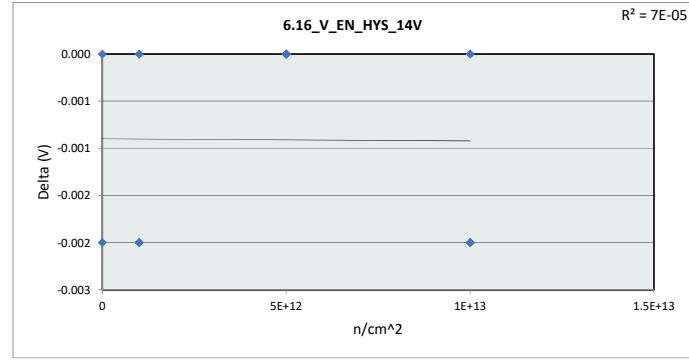


6.15_V_EN_FALL_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.53		V	
Min Limit	0.47		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.506
Average	0.509	0.510	0.509	0.507
Max	0.512	0.512	0.510	0.510
UL	0.530	0.530	0.530	0.530

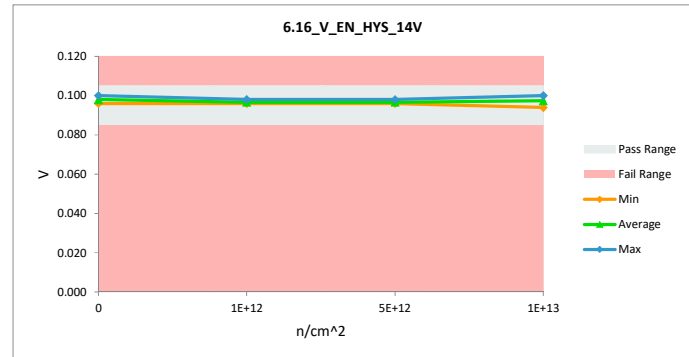


NDD Characterization Report TPS7H5006-SEP

6.16_V_EN_HYS_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.105		0.105	
Min Limit	0.085		0.085	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.098	0.096	-0.002
1E+12	11	0.098	0.096	-0.002
1E+12	12	0.096	0.096	0.000
1E+12	13	0.100	0.098	-0.002
5E+12	14	0.098	0.098	0.000
5E+12	15	0.096	0.096	0.000
5E+12	16	0.096	0.096	0.000
1E+13	17	0.100	0.098	-0.002
1E+13	18	0.100	0.100	0.000
1E+13	19	0.096	0.094	-0.002
Max		0.100	0.100	0.000
Average		0.098	0.097	-0.001
Min		0.096	0.094	-0.002
Std Dev		0.002	0.002	0.001

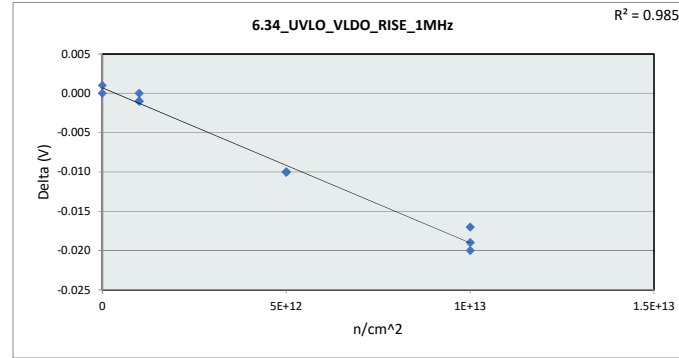


6.16_V_EN_HYS_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.105		V	
Min Limit	0.085		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.096	0.096	0.096	0.094
Average	0.098	0.097	0.097	0.097
Max	0.100	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

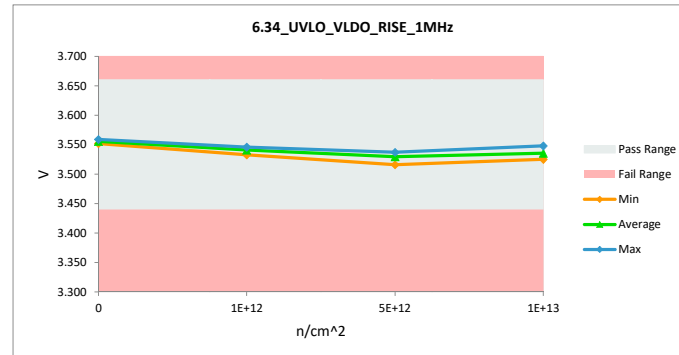


NDD Characterization Report TPS7H5006-SEP

6.34_UVLO_VLDO_RISE_1MHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.66		3.66	
Min Limit	3.44		3.44	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.558	3.559	0.001
0	49	3.552	3.552	0.000
1E+12	11	3.533	3.533	0.000
1E+12	12	3.544	3.543	-0.001
1E+12	13	3.547	3.546	-0.001
5E+12	14	3.546	3.536	-0.010
5E+12	15	3.547	3.537	-0.010
5E+12	16	3.526	3.516	-0.010
1E+13	17	3.568	3.548	-0.020
1E+13	18	3.544	3.525	-0.019
1E+13	19	3.551	3.534	-0.017
Max		3.568	3.559	0.001
Average		3.547	3.539	-0.008
Min		3.526	3.516	-0.020
Std Dev		0.011	0.012	0.008

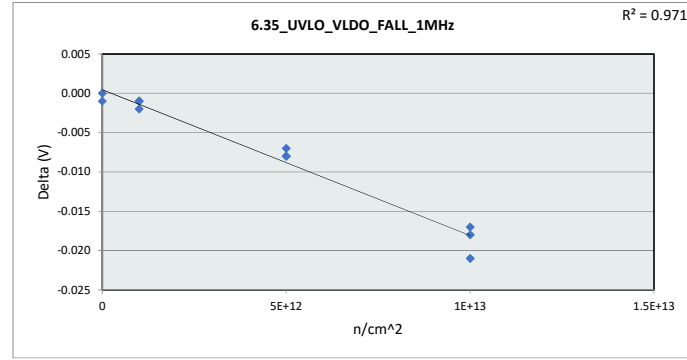


6.34_UVLO_VLDO_RISE_1MHz				
Test Site				
Tester				
Test Number				
Max Limit	3.66		V	
Min Limit	3.44		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.552	3.533	3.516	3.525
Average	3.556	3.541	3.530	3.536
Max	3.559	3.546	3.537	3.548
UL	3.660	3.660	3.660	3.660

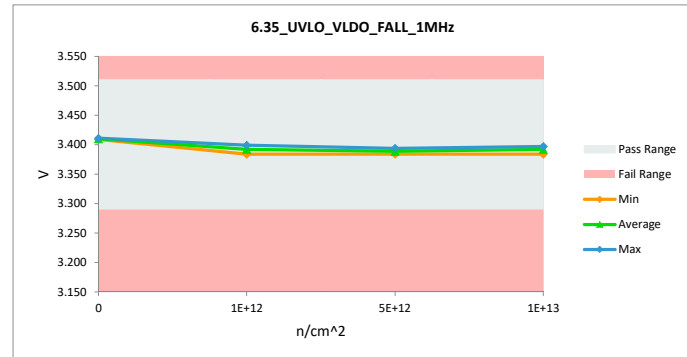


NDD Characterization Report TPS7H5006-SEP

6.35_UVLO_VLDO_FALL_1MHz				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.51	3.51	
Min Limit		3.29	3.29	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.410	3.409	-0.001
0	49	3.411	3.411	0.000
1E+12	11	3.385	3.384	-0.001
1E+12	12	3.395	3.393	-0.002
1E+12	13	3.400	3.399	-0.001
5E+12	14	3.395	3.388	-0.007
5E+12	15	3.402	3.394	-0.008
5E+12	16	3.392	3.384	-0.008
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.401	3.384	-0.017
Max		3.418	3.411	0.000
Average		3.402	3.394	-0.008
Min		3.385	3.384	-0.021
Std Dev		0.010	0.009	0.008

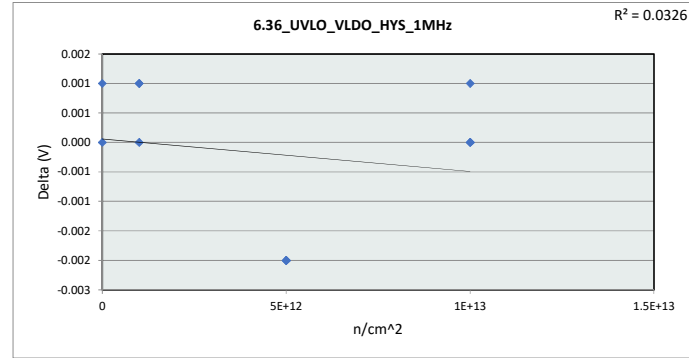


6.35_UVLO_VLDO_FALL_1MHz				
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.384	3.384	3.384
Average	3.410	3.392	3.389	3.392
Max	3.411	3.399	3.394	3.397
UL	3.510	3.510	3.510	3.510

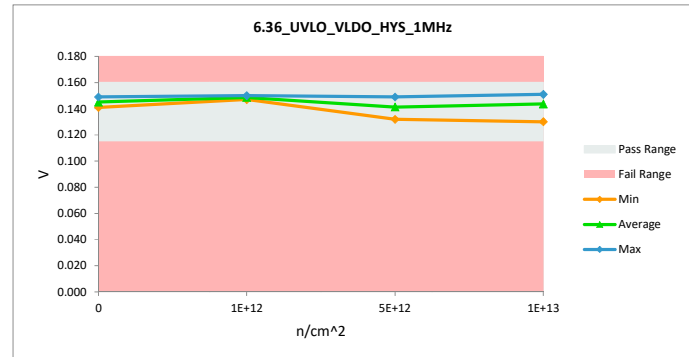


NDD Characterization Report TPS7H5006-SEP

6.36_UVLO_VLDO_HYS_1MHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.158		0.16	
Min Limit	0.115		0.115	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.148	0.149	0.001
0	49	0.141	0.141	0.000
1E+12	11	0.148	0.149	0.001
1E+12	12	0.149	0.150	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.151	0.149	-0.002
5E+12	15	0.145	0.143	-0.002
5E+12	16	0.134	0.132	-0.002
1E+13	17	0.150	0.151	0.001
1E+13	18	0.130	0.130	0.000
1E+13	19	0.150	0.150	0.000
Max		0.151	0.151	0.001
Average		0.145	0.145	0.000
Min		0.130	0.130	-0.002
Std Dev		0.007	0.007	0.001

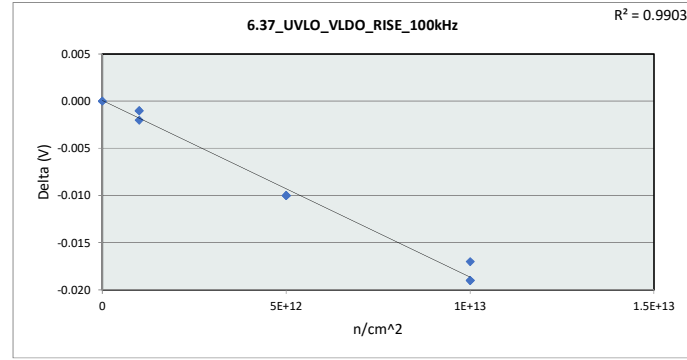


6.36_UVLO_VLDO_HYS_1MHz				
Test Site				
Tester				
Test Number				
Max Limit	0.16		V	
Min Limit	0.115		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.132	0.130
Average	0.145	0.149	0.141	0.144
Max	0.149	0.150	0.149	0.151
UL	0.160	0.160	0.160	0.160

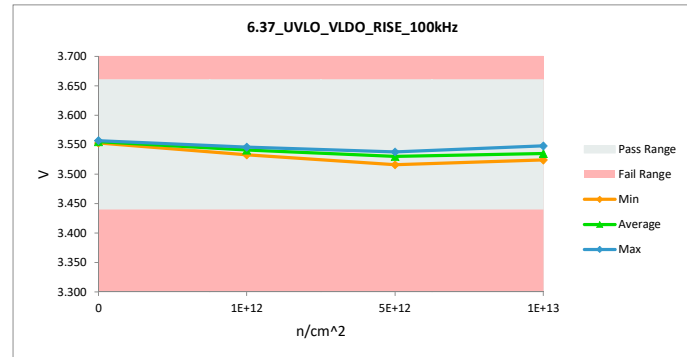


NDD Characterization Report TPS7H5006-SEP

6.37_UVLO_VLDO_RISE_100kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.66		3.66	
Min Limit	3.44		3.44	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.557	3.557	0.000
0	49	3.553	3.553	0.000
1E+12	11	3.534	3.533	-0.001
1E+12	12	3.544	3.543	-0.001
1E+12	13	3.548	3.546	-0.002
5E+12	14	3.546	3.536	-0.010
5E+12	15	3.548	3.538	-0.010
5E+12	16	3.526	3.516	-0.010
1E+13	17	3.567	3.548	-0.019
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.534	-0.017
Max		3.567	3.557	0.000
Average		3.547	3.539	-0.008
Min		3.526	3.516	-0.019
Std Dev		0.011	0.012	0.008

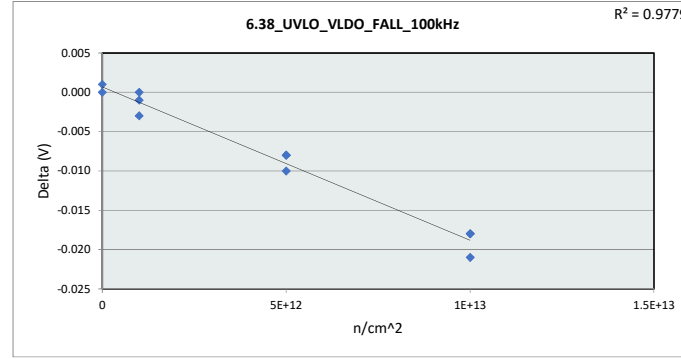


6.37_UVLO_VLDO_RISE_100kHz				
Test Site				
Tester				
Test Number				
Max Limit	3.66		V	
Min Limit	3.44		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.516	3.524
Average	3.555	3.541	3.530	3.535
Max	3.557	3.546	3.538	3.548
UL	3.660	3.660	3.660	3.660

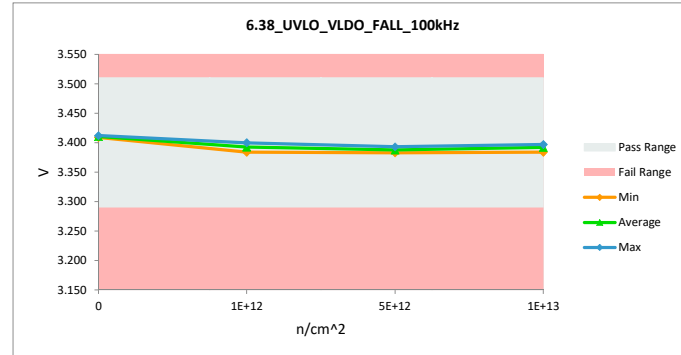


NDD Characterization Report TPS7H5006-SEP

6.38_UVLO_VLDO_FALL_100kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.51		3.51	
Min Limit	3.29		3.29	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.412	0.001
1E+12	11	3.387	3.384	-0.003
1E+12	12	3.394	3.394	0.000
1E+12	13	3.401	3.400	-0.001
5E+12	14	3.395	3.387	-0.008
5E+12	15	3.401	3.393	-0.008
5E+12	16	3.393	3.383	-0.010
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.402	3.384	-0.018
Max		3.418	3.412	0.001
Average		3.402	3.394	-0.008
Min		3.387	3.383	-0.021
Std Dev		0.010	0.010	0.008

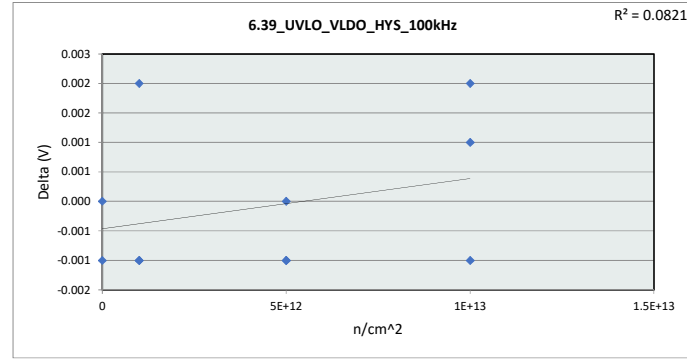


6.38_UVLO_VLDO_FALL_100kHz				
Test Site				
Tester				
Test Number				
Max Limit	3.51		V	
Min Limit	3.29		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.384	3.383	3.384
Average	3.411	3.393	3.388	3.392
Max	3.412	3.400	3.393	3.397
UL	3.510	3.510	3.510	3.510

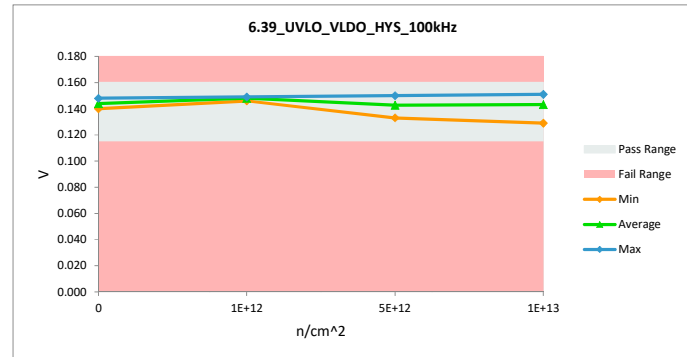


NDD Characterization Report TPS7H5006-SEP

6.39_UVLO_VLDO_HYS_100kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.158		0.16	
Min Limit	0.115		0.115	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.148	0.148	0.000
0	49	0.141	0.140	-0.001
1E+12	11	0.147	0.149	0.002
1E+12	12	0.150	0.149	-0.001
1E+12	13	0.147	0.146	-0.001
5E+12	14	0.151	0.150	-0.001
5E+12	15	0.146	0.145	-0.001
5E+12	16	0.133	0.133	0.000
1E+13	17	0.149	0.151	0.002
1E+13	18	0.130	0.129	-0.001
1E+13	19	0.149	0.150	0.001
Max		0.151	0.151	0.002
Average		0.145	0.145	0.000
Min		0.130	0.129	-0.001
Std Dev		0.007	0.007	0.001

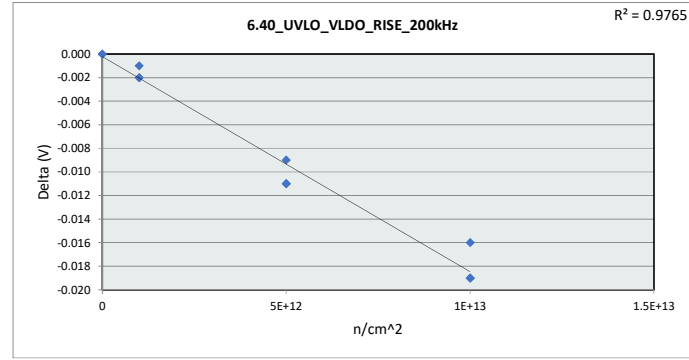


6.39_UVLO_VLDO_HYS_100kHz				
Test Site				
Tester				
Test Number				
Max Limit	0.16		V	
Min Limit	0.115		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.140	0.146	0.133	0.129
Average	0.144	0.148	0.143	0.143
Max	0.148	0.149	0.150	0.151
UL	0.160	0.160	0.160	0.160

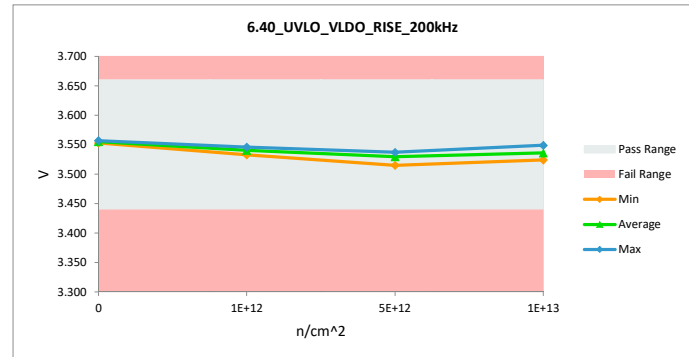


NDD Characterization Report TPS7H5006-SEP

6.40_UVLO_VLDO_RISE_200kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.66		3.66	
Min Limit	3.44		3.44	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.557	3.557	0.000
0	49	3.553	3.553	0.000
1E+12	11	3.534	3.533	-0.001
1E+12	12	3.544	3.542	-0.002
1E+12	13	3.548	3.546	-0.002
5E+12	14	3.546	3.537	-0.009
5E+12	15	3.548	3.537	-0.011
5E+12	16	3.526	3.515	-0.011
1E+13	17	3.568	3.549	-0.019
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.535	-0.016
Max		3.568	3.557	0.000
Average		3.547	3.539	-0.008
Min		3.526	3.515	-0.019
Std Dev		0.011	0.012	0.008

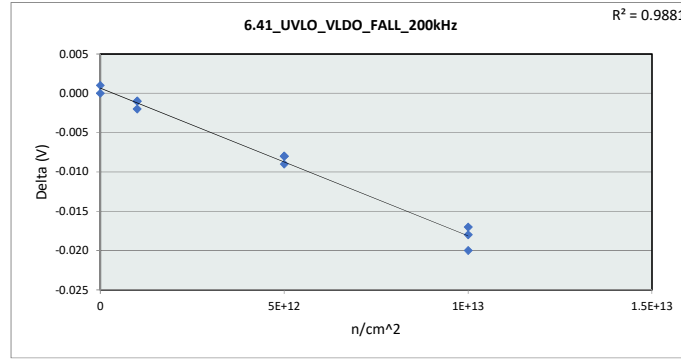


6.40_UVLO_VLDO_RISE_200kHz				
Test Site				
Tester				
Test Number				
Max Limit	3.66		V	
Min Limit	3.44		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.515	3.524
Average	3.555	3.540	3.530	3.536
Max	3.557	3.546	3.537	3.549
UL	3.660	3.660	3.660	3.660

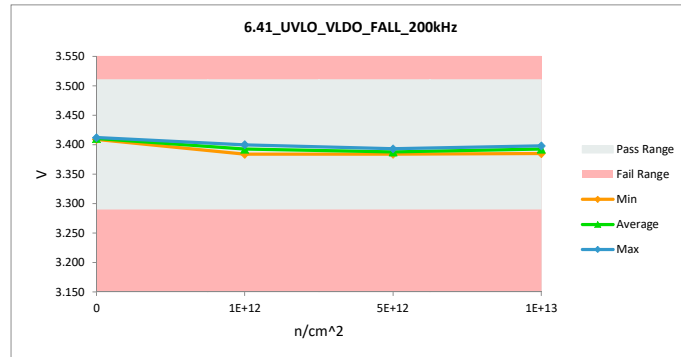


NDD Characterization Report TPS7H5006-SEP

6.41_UVLO_VLDO_FALL_200kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.51		3.51	
Min Limit	3.29		3.29	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.412	0.001
1E+12	11	3.385	3.384	-0.001
1E+12	12	3.395	3.393	-0.002
1E+12	13	3.401	3.400	-0.001
5E+12	14	3.395	3.387	-0.008
5E+12	15	3.402	3.393	-0.009
5E+12	16	3.392	3.384	-0.008
1E+13	17	3.418	3.398	-0.020
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.402	3.385	-0.017
Max		3.418	3.412	0.001
Average		3.402	3.395	-0.008
Min		3.385	3.384	-0.020
Std Dev		0.010	0.010	0.008

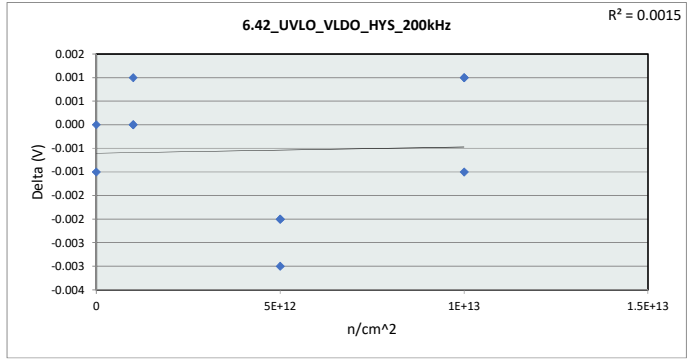


6.41_UVLO_VLDO_FALL_200kHz				
Test Site				
Tester				
Test Number				
Max Limit	3.51		V	
Min Limit	3.29		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.384	3.384	3.385
Average	3.411	3.392	3.388	3.393
Max	3.412	3.400	3.393	3.398
UL	3.510	3.510	3.510	3.510

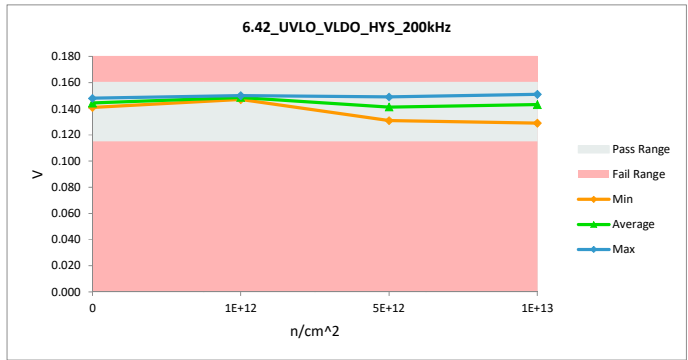


NDD Characterization Report TPS7H5006-SEP

6.42_UVLO_VLDO_HYS_200kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.158		0.16	
Min Limit	0.115		0.115	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.148	0.148	0.000
0	49	0.142	0.141	-0.001
1E+12	11	0.149	0.149	0.000
1E+12	12	0.149	0.150	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.151	0.149	-0.002
5E+12	15	0.146	0.144	-0.002
5E+12	16	0.134	0.131	-0.003
1E+13	17	0.150	0.151	0.001
1E+13	18	0.130	0.129	-0.001
1E+13	19	0.149	0.150	0.001
Max		0.151	0.151	0.001
Average		0.145	0.144	-0.001
Min		0.130	0.129	-0.003
Std Dev		0.007	0.008	0.001

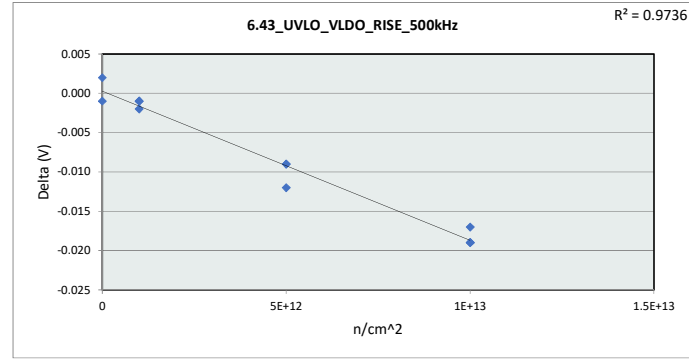


6.42_UVLO_VLDO_HYS_200kHz				
Test Site				
Tester				
Test Number				
Max Limit	0.16		V	
Min Limit	0.115		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.131	0.129
Average	0.145	0.149	0.141	0.143
Max	0.148	0.150	0.149	0.151
UL	0.160	0.160	0.160	0.160

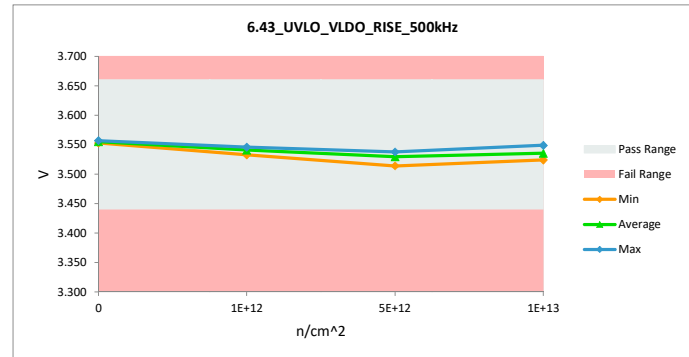


NDD Characterization Report TPS7H5006-SEP

6.43_UVLO_VLDO_RISE_500kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.66		3.66	
Min Limit	3.44		3.44	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.558	3.557	-0.001
0	49	3.551	3.553	0.002
1E+12	11	3.534	3.533	-0.001
1E+12	12	3.545	3.543	-0.002
1E+12	13	3.547	3.546	-0.001
5E+12	14	3.546	3.537	-0.009
5E+12	15	3.547	3.538	-0.009
5E+12	16	3.526	3.514	-0.012
1E+13	17	3.568	3.549	-0.019
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.534	-0.017
Max		3.568	3.557	0.002
Average		3.547	3.539	-0.008
Min		3.526	3.514	-0.019
Std Dev		0.011	0.013	0.008

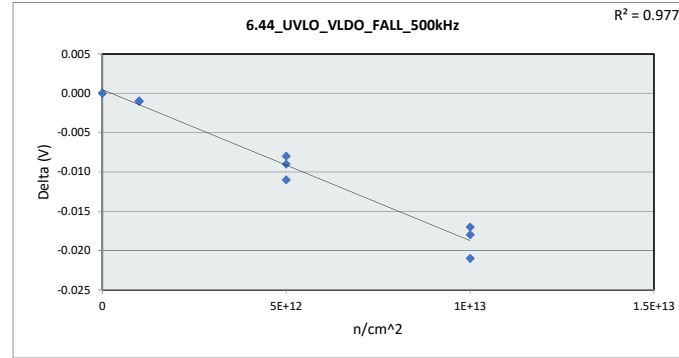


6.43_UVLO_VLDO_RISE_500kHz				
Test Site				
Tester				
Test Number				
Max Limit	3.66		V	
Min Limit	3.44		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.514	3.524
Average	3.555	3.541	3.530	3.536
Max	3.557	3.546	3.538	3.549
UL	3.660	3.660	3.660	3.660

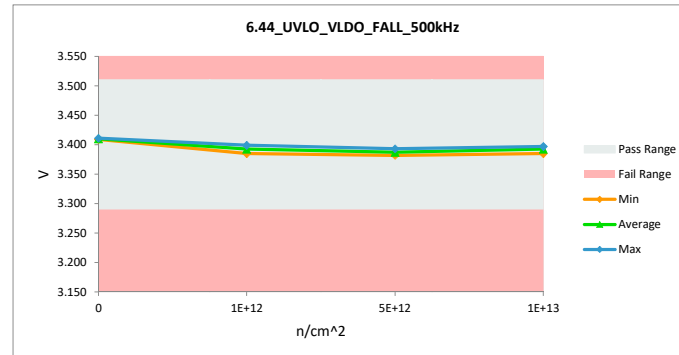


NDD Characterization Report TPS7H5006-SEP

6.44_UVLO_VLDO_FALL_500kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.51		3.51	
Min Limit	3.29		3.29	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.411	0.000
1E+12	11	3.386	3.385	-0.001
1E+12	12	3.394	3.393	-0.001
1E+12	13	3.400	3.399	-0.001
5E+12	14	3.395	3.387	-0.008
5E+12	15	3.402	3.393	-0.009
5E+12	16	3.393	3.382	-0.011
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.402	3.385	-0.017
Max		3.418	3.411	0.000
Average		3.402	3.394	-0.008
Min		3.386	3.382	-0.021
Std Dev		0.010	0.010	0.008

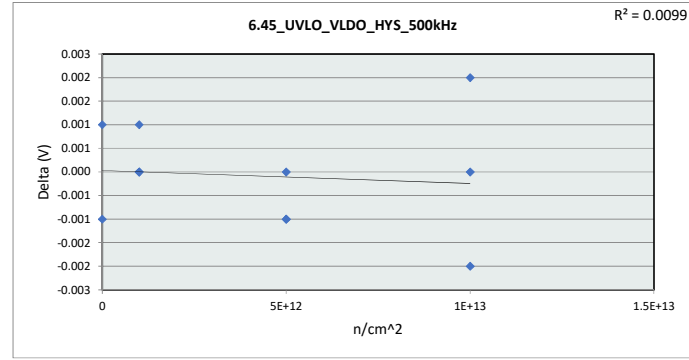


6.44_UVLO_VLDO_FALL_500kHz				
Test Site				
Tester				
Test Number				
Max Limit	3.51		V	
Min Limit	3.29		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.385	3.382	3.385
Average	3.410	3.392	3.387	3.392
Max	3.411	3.399	3.393	3.397
UL	3.510	3.510	3.510	3.510

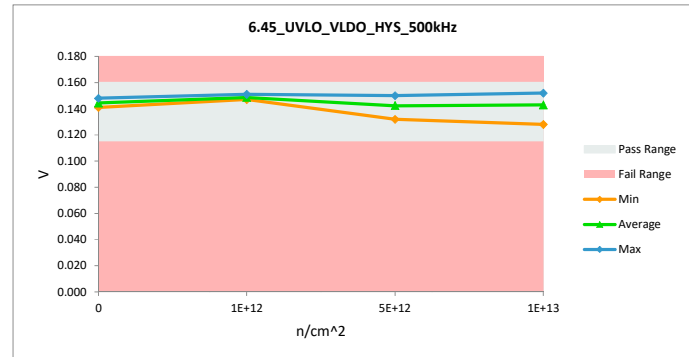


NDD Characterization Report TPS7H5006-SEP

6.45_UVLO_VLDO_HYS_500kHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.158		0.16	
Min Limit	0.115		0.115	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.149	0.148	-0.001
0	49	0.140	0.141	0.001
1E+12	11	0.148	0.148	0.000
1E+12	12	0.150	0.151	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.151	0.150	-0.001
5E+12	15	0.145	0.145	0.000
5E+12	16	0.133	0.132	-0.001
1E+13	17	0.150	0.152	0.002
1E+13	18	0.130	0.128	-0.002
1E+13	19	0.149	0.149	0.000
Max		0.151	0.152	0.002
Average		0.145	0.145	0.000
Min		0.130	0.128	-0.002
Std Dev		0.007	0.008	0.001

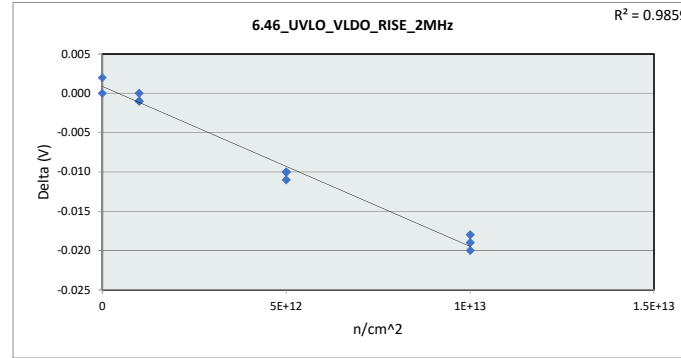


6.45_UVLO_VLDO_HYS_500kHz				
Test Site				
Tester				
Test Number				
Max Limit	0.16		V	
Min Limit	0.115		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.132	0.128
Average	0.145	0.149	0.142	0.143
Max	0.148	0.151	0.150	0.152
UL	0.160	0.160	0.160	0.160

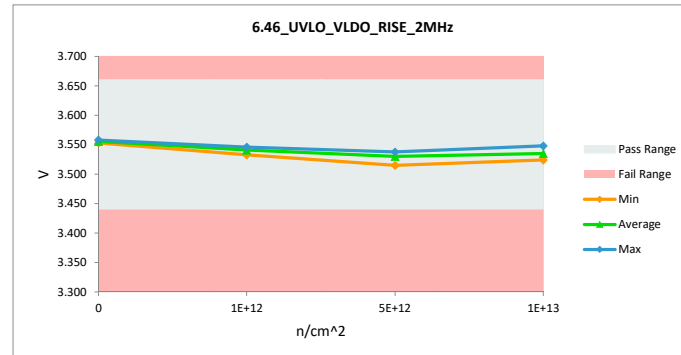


NDD Characterization Report TPS7H5006-SEP

6.46_UVLO_VLDO_RISE_2MHz				
Test Site				
Tester				
Test Number				
Unit		V		V
Max Limit		3.66		3.66
Min Limit		3.44		3.44
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.558	3.558	0.000
0	49	3.551	3.553	0.002
1E+12	11	3.533	3.533	0.000
1E+12	12	3.544	3.543	-0.001
1E+12	13	3.547	3.546	-0.001
5E+12	14	3.547	3.537	-0.010
5E+12	15	3.548	3.538	-0.010
5E+12	16	3.526	3.515	-0.011
1E+13	17	3.568	3.548	-0.020
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.533	-0.018
Max		3.568	3.558	0.002
Average		3.547	3.539	-0.008
Min		3.526	3.515	-0.020
Std Dev		0.011	0.013	0.008

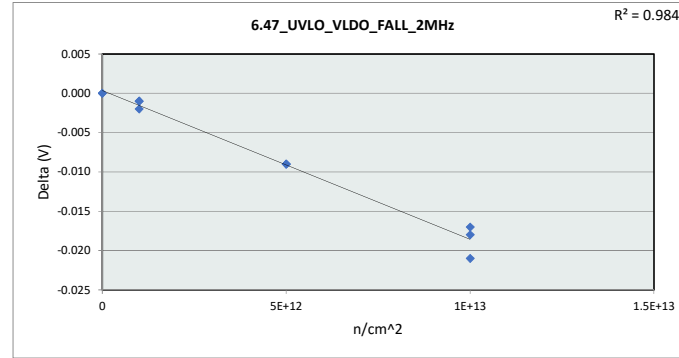


6.46_UVLO_VLDO_RISE_2MHz				
Test Site				
Tester				
Test Number				
Max Limit	3.66		V	
Min Limit	3.44		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.515	3.524
Average	3.556	3.541	3.530	3.535
Max	3.558	3.546	3.538	3.548
UL	3.660	3.660	3.660	3.660

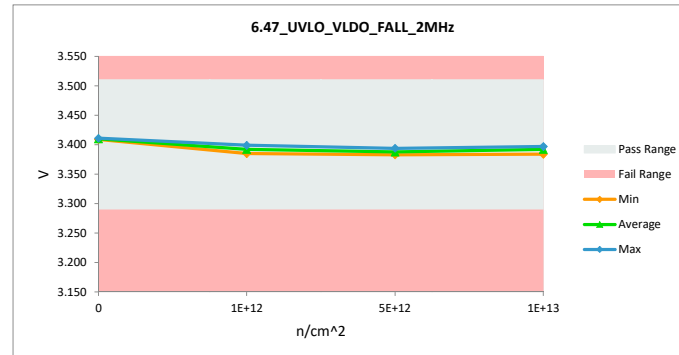


NDD Characterization Report TPS7H5006-SEP

6.47_UVLO_VLDO_FALL_2MHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	3.51		3.51	
Min Limit	3.29		3.29	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.411	0.000
1E+12	11	3.386	3.385	-0.001
1E+12	12	3.394	3.392	-0.002
1E+12	13	3.400	3.399	-0.001
5E+12	14	3.395	3.386	-0.009
5E+12	15	3.403	3.394	-0.009
5E+12	16	3.392	3.383	-0.009
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.401	3.384	-0.017
Max		3.418	3.411	0.000
Average		3.402	3.394	-0.008
Min		3.386	3.383	-0.021
Std Dev		0.010	0.010	0.008

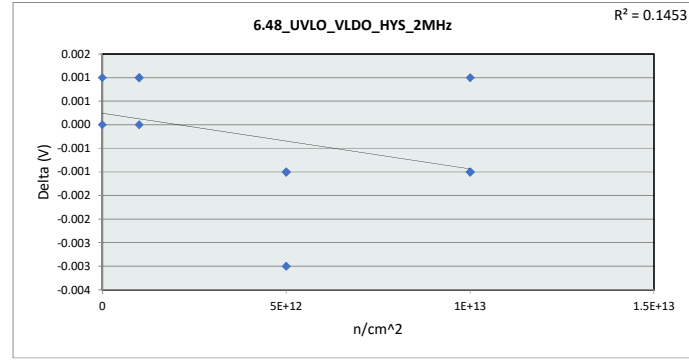


6.47_UVLO_VLDO_FALL_2MHz				
Test Site				
Tester				
Test Number				
Max Limit	3.51		V	
Min Limit	3.29		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.385	3.383	3.384
Average	3.410	3.392	3.388	3.392
Max	3.411	3.399	3.394	3.397
UL	3.510	3.510	3.510	3.510

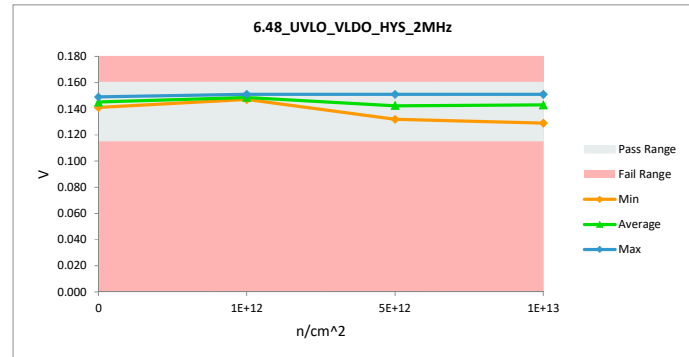


NDD Characterization Report TPS7H5006-SEP

6.48_UVLO_VLDO_HYS_2MHz				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.158		0.16	
Min Limit	0.115		0.115	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.149	0.149	0.000
0	49	0.140	0.141	0.001
1E+12	11	0.147	0.148	0.001
1E+12	12	0.150	0.151	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.152	0.151	-0.001
5E+12	15	0.145	0.144	-0.001
5E+12	16	0.135	0.132	-0.003
1E+13	17	0.150	0.151	0.001
1E+13	18	0.130	0.129	-0.001
1E+13	19	0.150	0.149	-0.001
Max		0.152	0.151	0.001
Average		0.145	0.145	0.000
Min		0.130	0.129	-0.003
Std Dev		0.007	0.008	0.001

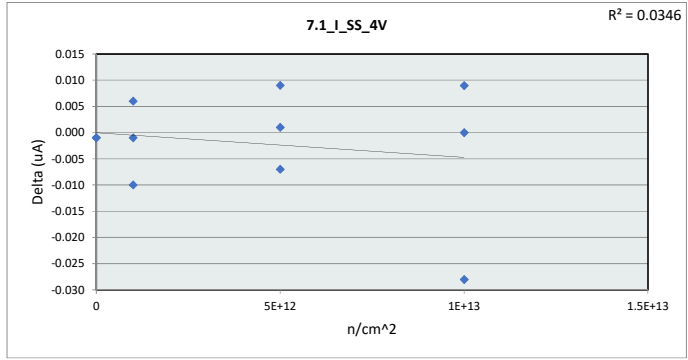


6.48_UVLO_VLDO_HYS_2MHz				
Test Site				
Tester				
Test Number				
Max Limit	0.16		V	
Min Limit	0.115		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.132	0.129
Average	0.145	0.149	0.142	0.143
Max	0.149	0.151	0.151	0.151
UL	0.160	0.160	0.160	0.160

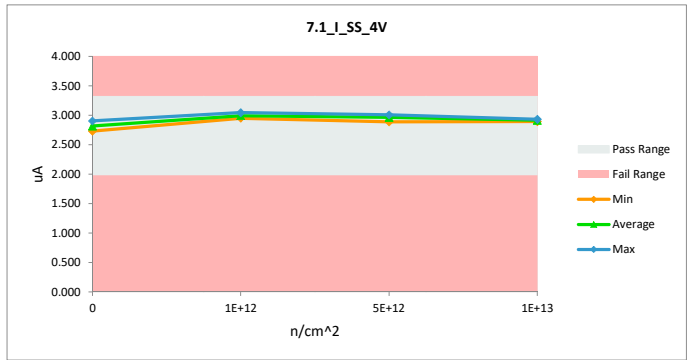


NDD Characterization Report TPS7H5006-SEP

7.1_I_SS_4V				
Test Site				
Tester				
Test Number				
Unit		uA		uA
Max Limit		3.2		3.32
Min Limit		2.2		1.98
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.732	2.731	-0.001
0	49	2.905	2.904	-0.001
1E+12	11	3.039	3.045	0.006
1E+12	12	2.996	2.986	-0.010
1E+12	13	2.952	2.951	-0.001
5E+12	14	2.885	2.886	0.001
5E+12	15	2.988	2.997	0.009
5E+12	16	3.016	3.009	-0.007
1E+13	17	2.894	2.894	0.000
1E+13	18	2.913	2.922	0.009
1E+13	19	2.960	2.932	-0.028
Max		3.039	3.045	0.009
Average		2.935	2.932	-0.002
Min		2.732	2.731	-0.028
Std Dev		0.085	0.084	0.010

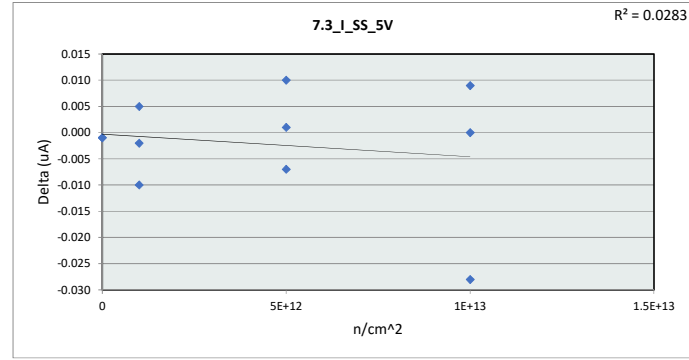


7.1_I_SS_4V				
Test Site				
Tester				
Test Number				
Max Limit	3.32			uA
Min Limit	1.98			uA
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.731	2.951	2.886	2.894
Average	2.818	2.994	2.964	2.916
Max	2.904	3.045	3.009	2.932
UL	3.320	3.320	3.320	3.320

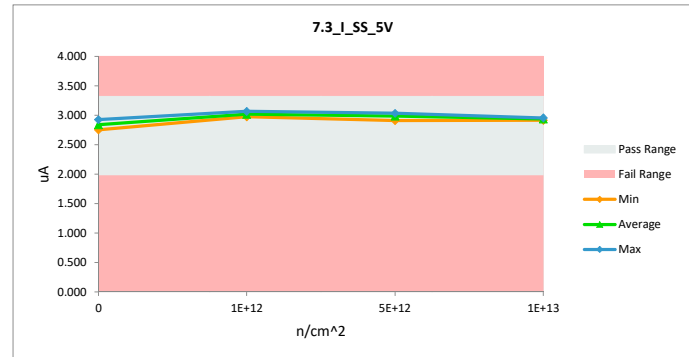


NDD Characterization Report TPS7H5006-SEP

7.3_I_SS_5V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		3.2	3.32	
Min Limit		2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.754	2.753	-0.001
0	49	2.928	2.927	-0.001
1E+12	11	3.063	3.068	0.005
1E+12	12	3.019	3.009	-0.010
1E+12	13	2.976	2.974	-0.002
5E+12	14	2.908	2.909	0.001
5E+12	15	3.011	3.021	0.010
5E+12	16	3.040	3.033	-0.007
1E+13	17	2.917	2.917	0.000
1E+13	18	2.936	2.945	0.009
1E+13	19	2.984	2.956	-0.028
Max		3.063	3.068	0.010
Average		2.958	2.956	-0.002
Min		2.754	2.753	-0.028
Std Dev		0.085	0.085	0.010

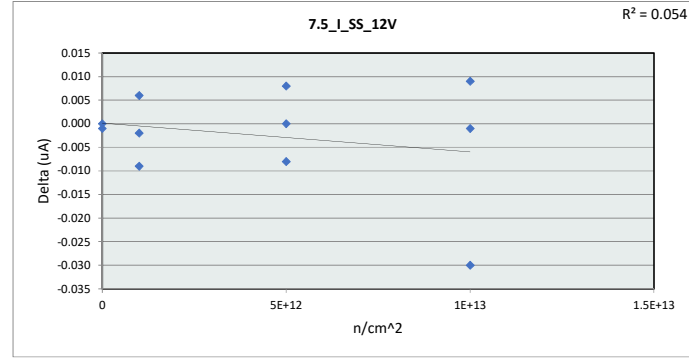


7.3_I_SS_5V				
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.753	2.974	2.909	2.917
Average	2.840	3.017	2.988	2.939
Max	2.927	3.068	3.033	2.956
UL	3.320	3.320	3.320	3.320

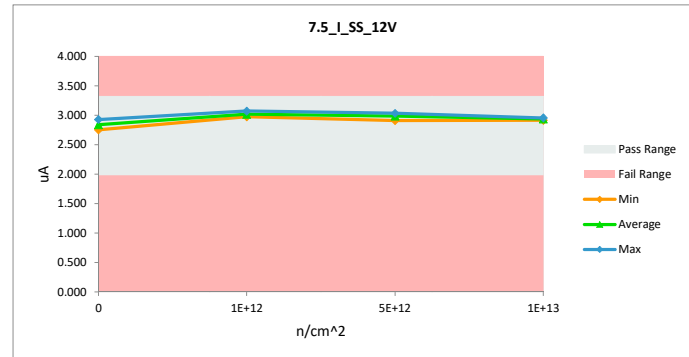


NDD Characterization Report TPS7H5006-SEP

7.5_I_SS_12V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		3.2	3.32	
Min Limit		2.2	1.98	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.755	2.755	0.000
0	49	2.929	2.928	-0.001
1E+12	11	3.065	3.071	0.006
1E+12	12	3.020	3.011	-0.009
1E+12	13	2.977	2.975	-0.002
5E+12	14	2.910	2.910	0.000
5E+12	15	3.014	3.022	0.008
5E+12	16	3.042	3.034	-0.008
1E+13	17	2.918	2.917	-0.001
1E+13	18	2.936	2.945	0.009
1E+13	19	2.987	2.957	-0.030
Max		3.065	3.071	0.009
Average		2.959	2.957	-0.003
Min		2.755	2.755	-0.030
Std Dev		0.086	0.085	0.011

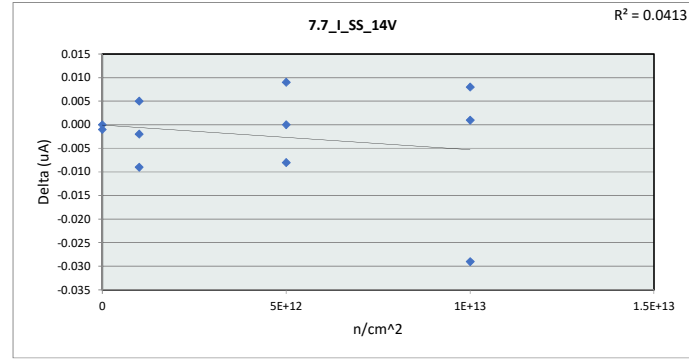


7.5_I_SS_12V				
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.755	2.975	2.910	2.917
Average	2.842	3.019	2.989	2.940
Max	2.928	3.071	3.034	2.957
UL	3.320	3.320	3.320	3.320

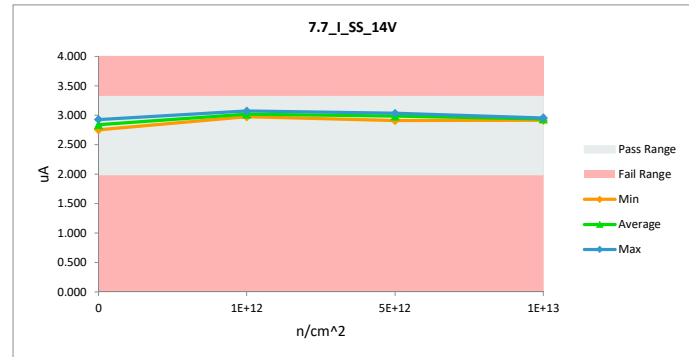


NDD Characterization Report TPS7H5006-SEP

7.7_I_SS_14V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		3.2	3.32	
Min Limit		2.2	1.98	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.755	2.755	0.000
0	49	2.929	2.928	-0.001
1E+12	11	3.066	3.071	0.005
1E+12	12	3.020	3.011	-0.009
1E+12	13	2.978	2.976	-0.002
5E+12	14	2.910	2.910	0.000
5E+12	15	3.013	3.022	0.009
5E+12	16	3.041	3.033	-0.008
1E+13	17	2.917	2.918	0.001
1E+13	18	2.937	2.945	0.008
1E+13	19	2.986	2.957	-0.029
Max		3.066	3.071	0.009
Average		2.959	2.957	-0.002
Min		2.755	2.755	-0.029
Std Dev		0.085	0.085	0.010

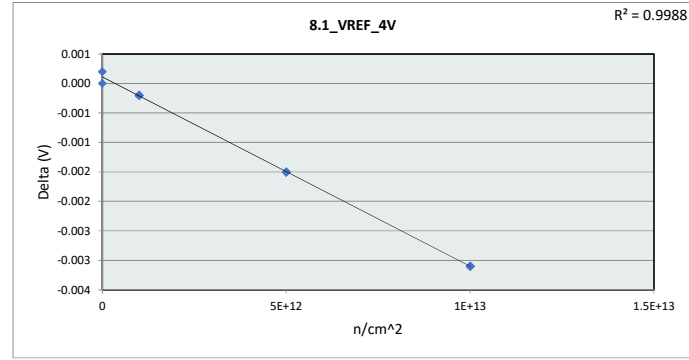


7.7_I_SS_14V				
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.755	2.976	2.910	2.918
Average	2.842	3.019	2.988	2.940
Max	2.928	3.071	3.033	2.957
UL	3.320	3.320	3.320	3.320

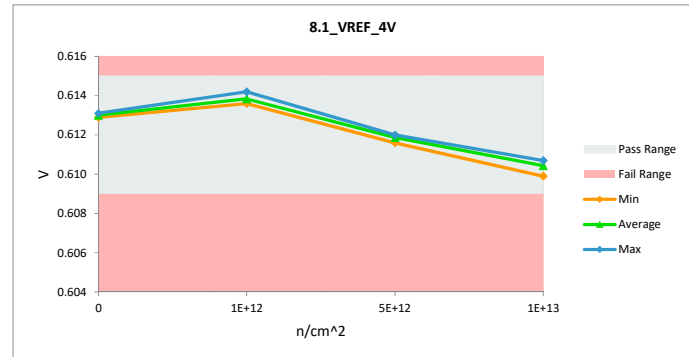


NDD Characterization Report TPS7H5006-SEP

8.1_VREF_4V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.615		0.615	
Min Limit	0.611		0.609	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.002
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
Max		0.614	0.614	0.000
Average		0.614	0.612	-0.001
Min		0.613	0.610	-0.003
Std Dev		0.000	0.001	0.001

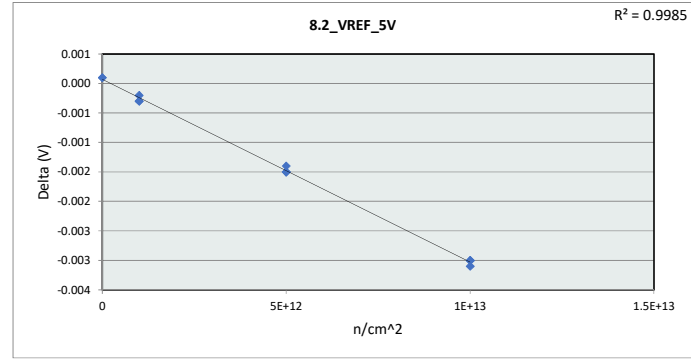


8.1_VREF_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.615		V	
Min Limit	0.609		V	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

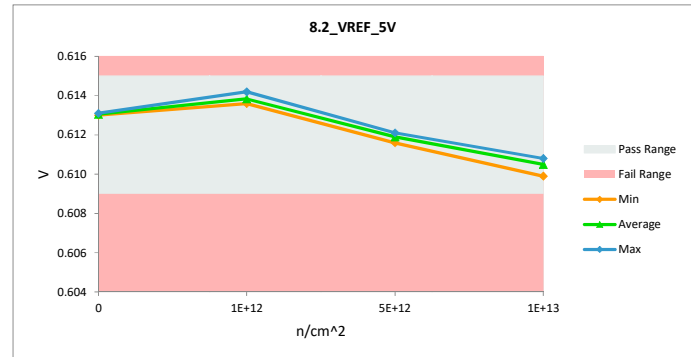


NDD Characterization Report TPS7H5006-SEP

8.2_VREF_5V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.615		0.615	
Min Limit	0.611		0.609	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.001
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
Max		0.614	0.614	0.000
Average		0.614	0.612	-0.001
Min		0.613	0.610	-0.003
Std Dev		0.001	0.001	0.001

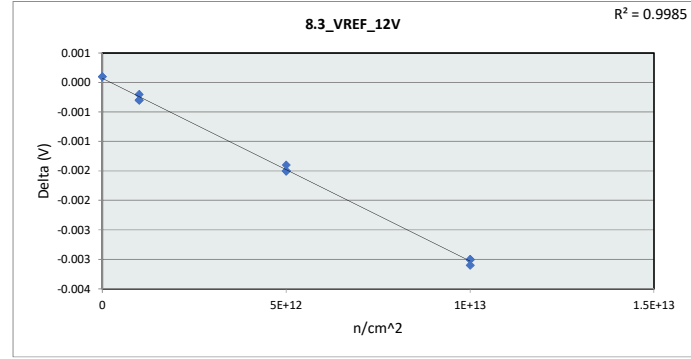


8.2_VREF_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.615		V	
Min Limit	0.609		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.611
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

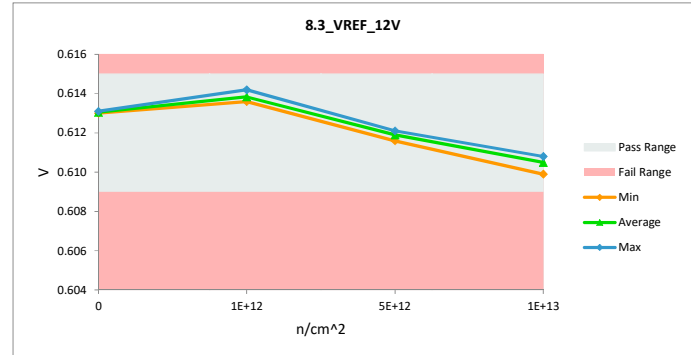


NDD Characterization Report TPS7H5006-SEP

8.3_VREF_12V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.615		0.615	
Min Limit	0.611		0.609	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.001
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
Max		0.614	0.614	0.000
Average		0.614	0.612	-0.001
Min		0.613	0.610	-0.003
Std Dev		0.001	0.001	0.001

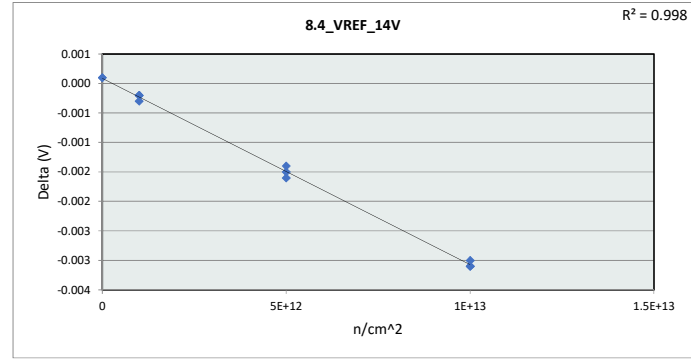


8.3_VREF_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.615		V	
Min Limit	0.609		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.611
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

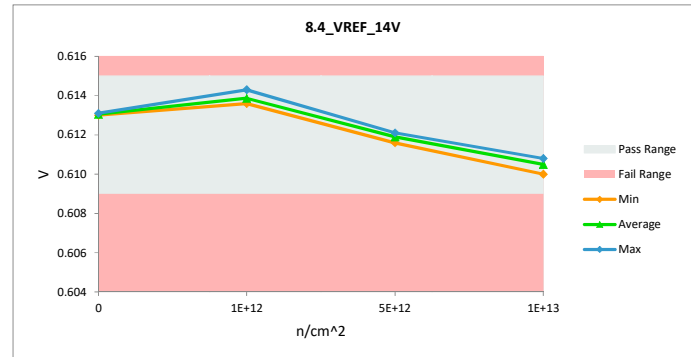


NDD Characterization Report TPS7H5006-SEP

8.4_VREF_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.615		0.615	
Min Limit	0.611		0.609	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.001
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
Max		0.614	0.614	0.000
Average		0.614	0.612	-0.001
Min		0.613	0.610	-0.003
Std Dev		0.000	0.001	0.001

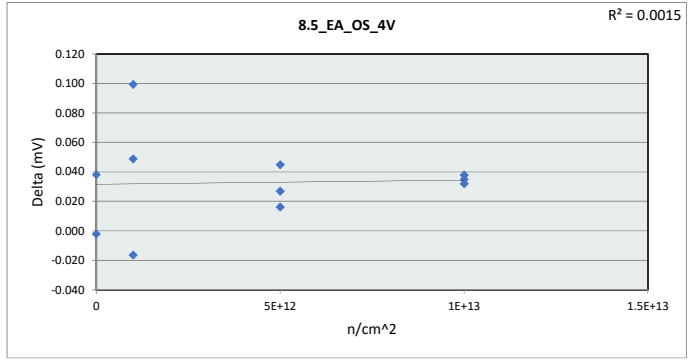


8.4_VREF_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.615		V	
Min Limit	0.609		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.611
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

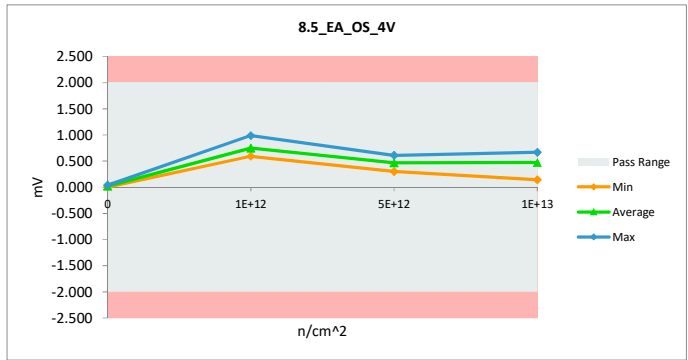


NDD Characterization Report TPS7H5006-SEP

8.5_EA_OS_4V				
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		1.9	2	
Min Limit		-1.8	-2	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.043	0.041	-0.002
0	49	-0.032	0.006	0.038
1E+12	11	1.008	0.991	-0.016
1E+12	12	0.619	0.668	0.049
1E+12	13	0.495	0.594	0.099
5E+12	14	0.287	0.304	0.016
5E+12	15	0.441	0.486	0.045
5E+12	16	0.584	0.611	0.027
1E+13	17	0.112	0.147	0.035
1E+13	18	0.557	0.595	0.038
1E+13	19	0.640	0.672	0.032
Max		1.008	0.991	0.099
Average		0.432	0.465	0.033
Min		-0.032	0.006	-0.016
Std Dev		0.307	0.306	0.030

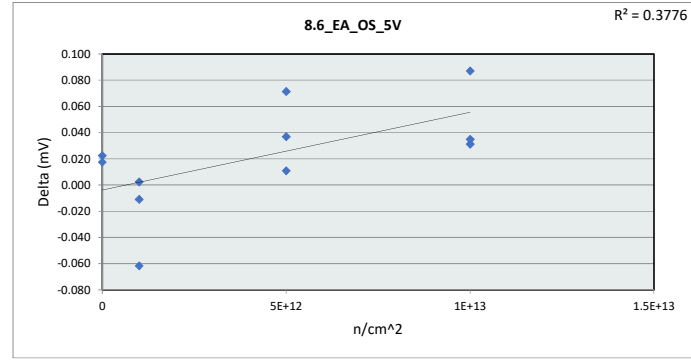


8.5_EA_OS_4V				
Test Site				
Tester				
Test Number				
Max Limit	2		mV	
Min Limit	-2		mV	
n/cm ²	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.006	0.594	0.304	0.147
Average	0.023	0.751	0.467	0.471
Max	0.041	0.991	0.611	0.672
UL	2.000	2.000	2.000	2.000

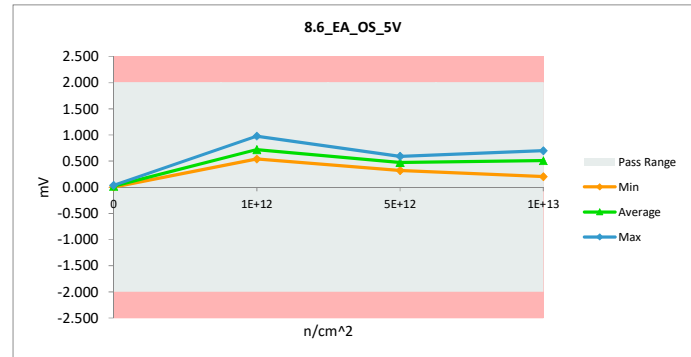


NDD Characterization Report TPS7H5006-SEP

8.6_EA_OS_5V				
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		1.9	2	
Min Limit		-1.8	-2	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.015	0.037	0.022
0	49	-0.013	0.005	0.018
1E+12	11	1.040	0.978	-0.062
1E+12	12	0.658	0.647	-0.011
1E+12	13	0.540	0.542	0.002
5E+12	14	0.309	0.320	0.011
5E+12	15	0.445	0.517	0.071
5E+12	16	0.555	0.592	0.037
1E+13	17	0.117	0.204	0.087
1E+13	18	0.585	0.620	0.035
1E+13	19	0.668	0.699	0.031
Max		1.040	0.978	0.087
Average		0.447	0.469	0.022
Min		-0.013	0.005	-0.062
Std Dev		0.318	0.297	0.040

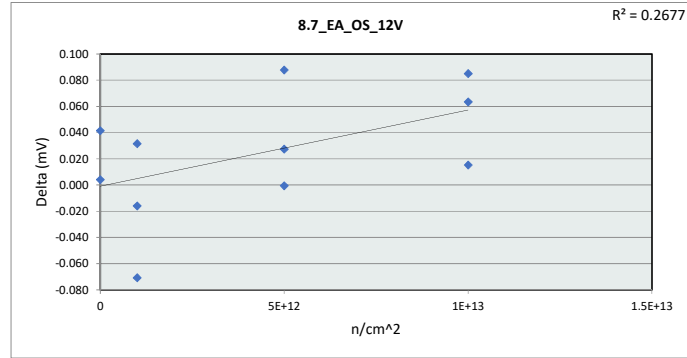


8.6_EA_OS_5V				
Test Site				
Tester				
Test Number				
Max Limit	2		mV	
Min Limit	-2		mV	
n/cm ²	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.005	0.542	0.320	0.204
Average	0.021	0.722	0.476	0.508
Max	0.037	0.978	0.592	0.699
UL	2.000	2.000	2.000	2.000

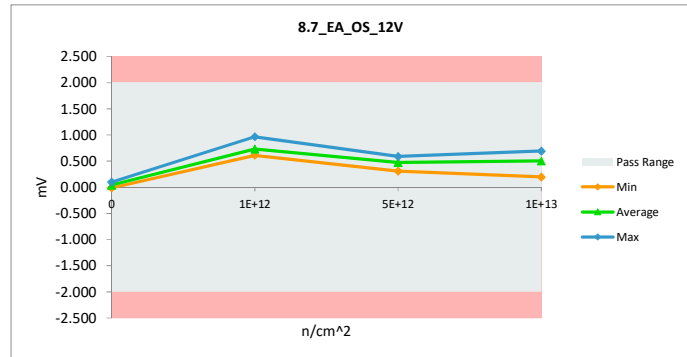


NDD Characterization Report TPS7H5006-SEP

8.7_EA_OS_12V				
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		1.9	2	
Min Limit		-1.8	-2	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.058	0.100	0.041
0	49	-0.015	-0.011	0.004
1E+12	11	1.037	0.966	-0.071
1E+12	12	0.641	0.625	-0.016
1E+12	13	0.579	0.610	0.032
5E+12	14	0.309	0.309	0.000
5E+12	15	0.439	0.527	0.088
5E+12	16	0.562	0.589	0.027
1E+13	17	0.133	0.197	0.064
1E+13	18	0.536	0.622	0.085
1E+13	19	0.678	0.693	0.015
Max		1.037	0.966	0.088
Average		0.451	0.475	0.024
Min		-0.015	-0.011	-0.071
Std Dev		0.310	0.291	0.046

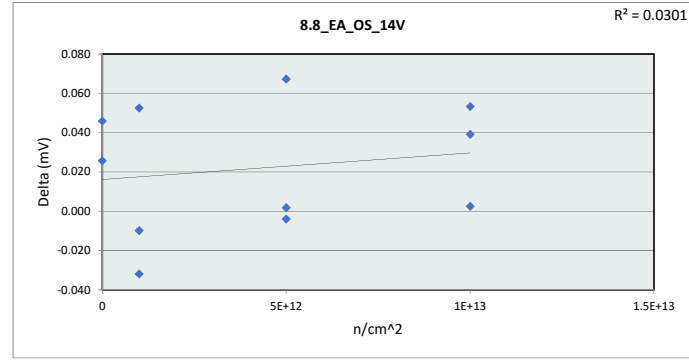


8.7_EA_OS_12V				
Test Site				
Tester				
Test Number				
Max Limit	2		mV	
Min Limit	-2		mV	
n/cm ²	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	-0.011	0.610	0.309	0.197
Average	0.044	0.734	0.475	0.504
Max	0.100	0.966	0.589	0.693
UL	2.000	2.000	2.000	2.000

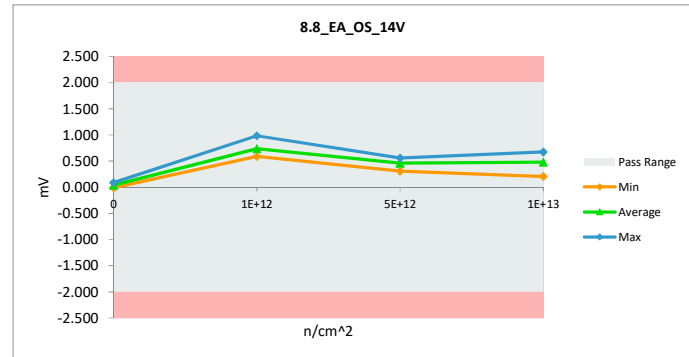


NDD Characterization Report TPS7H5006-SEP

8.8_EA_OS_14V				
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		1.9	2	
Min Limit		-1.8	-2	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.043	0.089	0.046
0	49	-0.034	-0.008	0.026
1E+12	11	1.018	0.986	-0.032
1E+12	12	0.644	0.634	-0.010
1E+12	13	0.539	0.591	0.052
5E+12	14	0.315	0.311	-0.004
5E+12	15	0.449	0.516	0.067
5E+12	16	0.558	0.560	0.002
1E+13	17	0.154	0.208	0.053
1E+13	18	0.556	0.559	0.002
1E+13	19	0.640	0.679	0.039
Max		1.018	0.986	0.067
Average		0.444	0.466	0.022
Min		-0.034	-0.008	-0.032
Std Dev		0.305	0.289	0.032

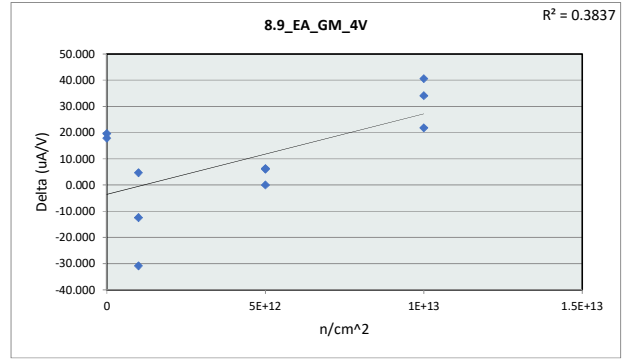


8.8_EA_OS_14V				
Test Site				
Tester				
Test Number				
Max Limit	2		mV	
Min Limit	-2		mV	
n/cm ²	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	-0.008	0.591	0.311	0.208
Average	0.040	0.737	0.463	0.482
Max	0.089	0.986	0.560	0.679
UL	2.000	2.000	2.000	2.000

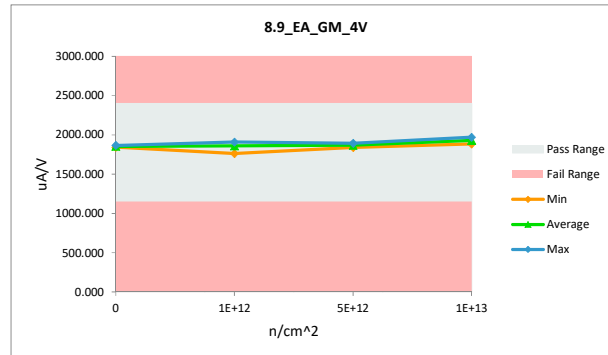


NDD Characterization Report TPS7H5006-SEP

8.9_EA_GM_4V				
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2350	2400	
Min Limit		1200	1150	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1823.640	1841.556	17.916
0	49	1846.511	1866.188	19.677
1E+12	11	1918.690	1906.253	-12.437
1E+12	12	1940.449	1909.638	-30.811
1E+12	13	1756.409	1761.129	4.720
5E+12	14	1835.009	1841.313	6.304
5E+12	15	1887.944	1894.008	6.064
5E+12	16	1864.042	1864.032	-0.010
1E+13	17	1850.850	1884.932	34.082
1E+13	18	1929.458	1970.035	40.577
1E+13	19	1913.482	1935.300	21.818
Max		1940.449	1970.035	40.577
Average		1869.680	1879.489	9.809
Min		1756.409	1761.129	-30.811
Std Dev		55.055	55.227	20.339

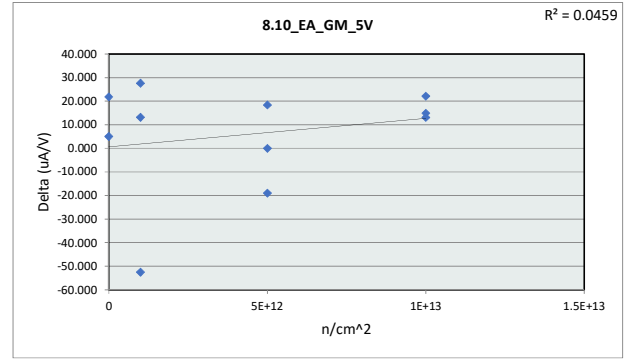


8.9_EA_GM_4V				
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1841.556	1761.129	1841.313	1884.932
Average	1853.872	1859.007	1866.451	1930.089
Max	1866.188	1909.638	1894.008	1970.035
UL	2400.000	2400.000	2400.000	2400.000

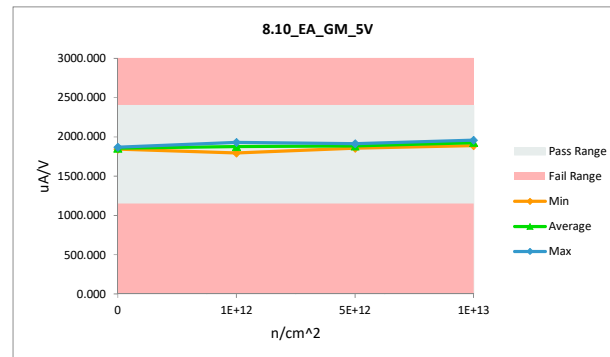


NDD Characterization Report TPS7H5006-SEP

8.10_EA_GM_5V				
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2350	2400	
Min Limit		1200	1150	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1823.640	1845.465	21.825
0	49	1864.042	1869.057	5.015
1E+12	11	1918.076	1931.257	13.181
1E+12	12	1952.610	1900.121	-52.489
1E+12	13	1768.881	1796.459	27.578
5E+12	14	1875.912	1856.986	-18.926
5E+12	15	1894.019	1912.457	18.438
5E+12	16	1881.909	1881.898	-0.011
1E+13	17	1873.262	1888.125	14.863
1E+13	18	1936.451	1958.571	22.120
1E+13	19	1922.163	1935.245	13.082
	Max	1952.610	1958.571	27.578
	Average	1882.815	1888.695	5.880
	Min	1768.881	1796.459	-52.489
	Std Dev	52.574	46.228	23.217

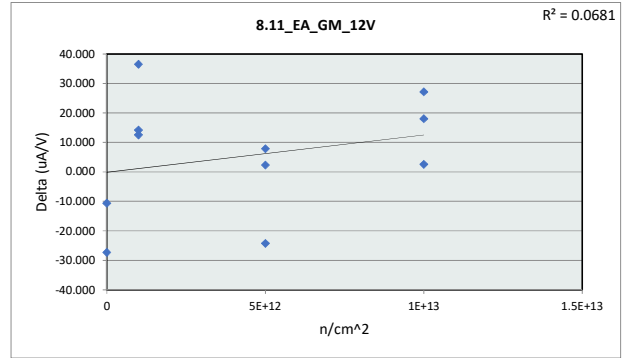


8.10_EA_GM_5V				
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1845.465	1796.459	1856.986	1888.125
Average	1857.261	1875.946	1883.780	1927.314
Max	1869.057	1931.257	1912.457	1958.571
UL	2400.000	2400.000	2400.000	2400.000

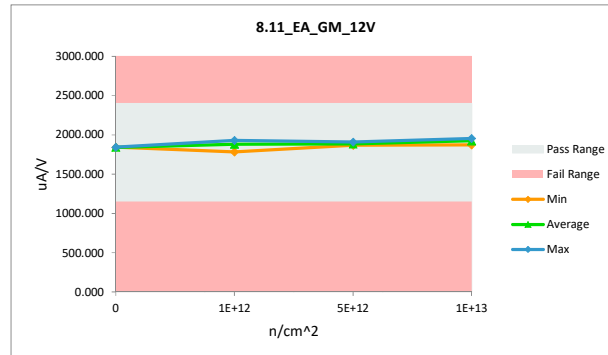


NDD Characterization Report TPS7H5006-SEP

8.11_EA_GM_12V				
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2350	2400	
Min Limit		1200	1150	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1852.321	1841.727	-10.594
0	49	1869.963	1842.658	-27.305
1E+12	11	1894.756	1931.257	36.501
1E+12	12	1918.690	1931.268	12.578
1E+12	13	1768.881	1783.103	14.222
5E+12	14	1864.042	1866.406	2.364
5E+12	15	1901.489	1909.344	7.855
5E+12	16	1900.121	1875.901	-24.220
1E+13	17	1869.963	1872.583	2.620
1E+13	18	1927.308	1954.475	27.167
1E+13	19	1927.264	1945.297	18.033
Max		1927.308	1954.475	36.501
Average		1881.345	1886.729	5.384
Min		1768.881	1783.103	-27.305
Std Dev		45.391	52.852	19.889

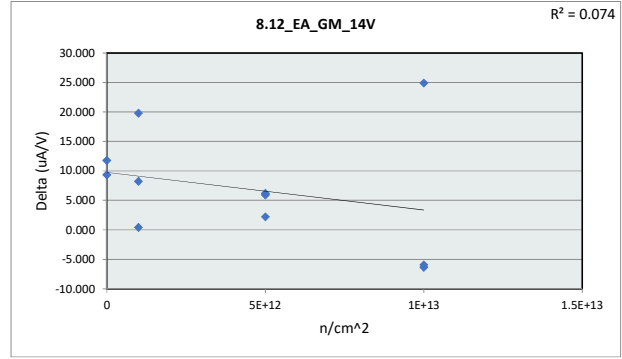


8.11_EA_GM_12V				
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1841.727	1783.103	1866.406	1872.583
Average	1842.193	1881.876	1883.884	1924.118
Max	1842.658	1931.268	1909.344	1954.475
UL	2400.000	2400.000	2400.000	2400.000

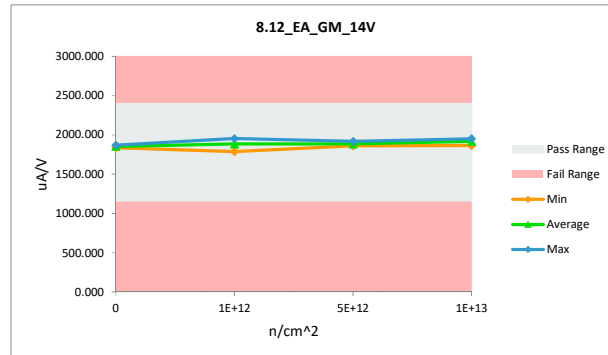


NDD Characterization Report TPS7H5006-SEP

8.12_EA_GM_14V				
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2350	2400	
Min Limit		1200	1150	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1829.307	1838.659	9.352
0	49	1858.168	1869.942	11.774
1E+12	11	1904.219	1912.457	8.238
1E+12	12	1931.958	1951.747	19.789
1E+12	13	1784.962	1785.380	0.418
5E+12	14	1858.158	1860.363	2.205
5E+12	15	1912.457	1918.679	6.222
5E+12	16	1869.963	1875.901	5.938
1E+13	17	1871.444	1865.524	-5.920
1E+13	18	1927.474	1952.383	24.909
1E+13	19	1938.420	1932.058	-6.362
Max		1938.420	1952.383	24.909
Average		1880.594	1887.554	6.960
Min		1784.962	1785.380	-6.362
Std Dev		47.678	51.375	9.631

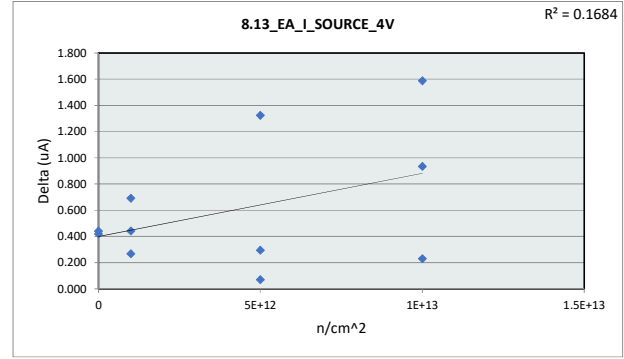


8.12_EA_GM_14V				
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1838.659	1785.380	1860.363	1865.524
Average	1854.301	1883.195	1884.981	1916.655
Max	1869.942	1951.747	1918.679	1952.383
UL	2400.000	2400.000	2400.000	2400.000

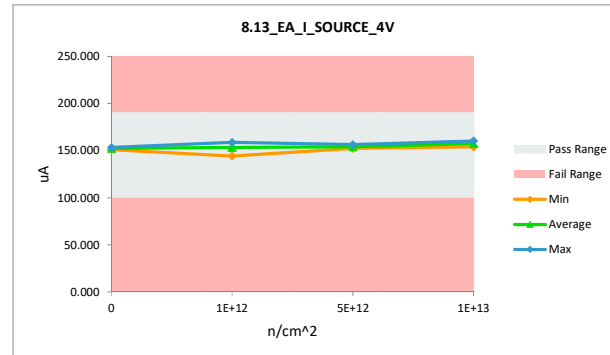


NDD Characterization Report TPS7H5006-SEP

8.13_EA_I_SOURCE_4V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	150.678	151.097	0.419
0	49	152.990	153.431	0.441
1E+12	11	156.353	157.045	0.692
1E+12	12	158.421	158.690	0.269
1E+12	13	143.839	144.280	0.441
5E+12	14	151.997	152.291	0.294
5E+12	15	154.994	156.319	1.325
5E+12	16	153.963	154.033	0.070
1E+13	17	153.077	154.012	0.935
1E+13	18	158.702	160.291	1.589
1E+13	19	157.823	158.053	0.230
Max		158.702	160.291	1.589
Average		153.894	154.504	0.610
Min		143.839	144.280	0.070
Std Dev		4.276	4.427	0.482

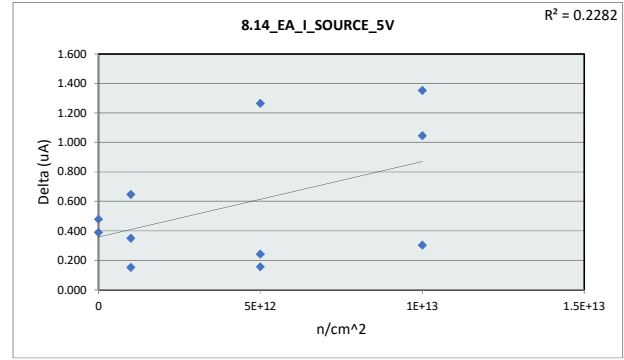


8.13_EA_I_SOURCE_4V				
Test Site				
Tester				
Test Number				
Max Limit	190		uA	
Min Limit	100		uA	
n/cm ²	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.097	144.280	152.291	154.012
Average	152.264	153.338	154.214	157.452
Max	153.431	158.690	156.319	160.291
UL	190.000	190.000	190.000	190.000

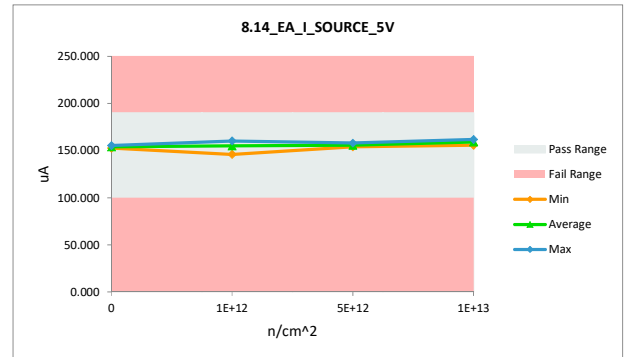


NDD Characterization Report TPS7H5006-SEP

8.14_EA_I_SOURCE_5V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	152.278	152.668	0.390
0	49	154.821	155.300	0.479
1E+12	11	158.058	158.705	0.647
1E+12	12	160.198	160.351	0.153
1E+12	13	145.589	145.939	0.350
5E+12	14	153.654	153.897	0.243
5E+12	15	156.709	157.974	1.265
5E+12	16	155.641	155.798	0.157
1E+13	17	154.767	155.813	1.046
1E+13	18	160.625	161.978	1.353
1E+13	19	159.570	159.874	0.304
Max		160.625	161.978	1.353
Average		155.628	156.209	0.581
Min		145.589	145.939	0.153
Std Dev		4.310	4.447	0.440

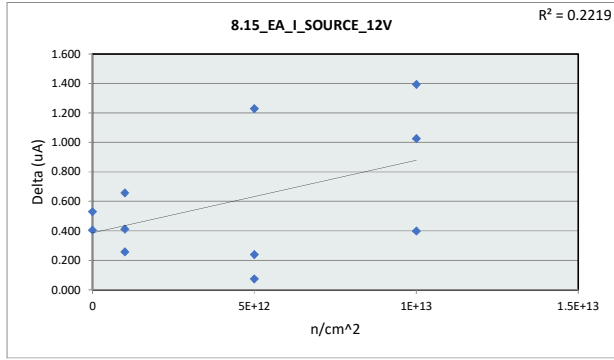


8.14_EA_I_SOURCE_5V				
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm ²	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	152.668	145.939	153.897	155.813
Average	153.984	154.998	155.890	159.222
Max	155.300	160.351	157.974	161.978
UL	190.000	190.000	190.000	190.000

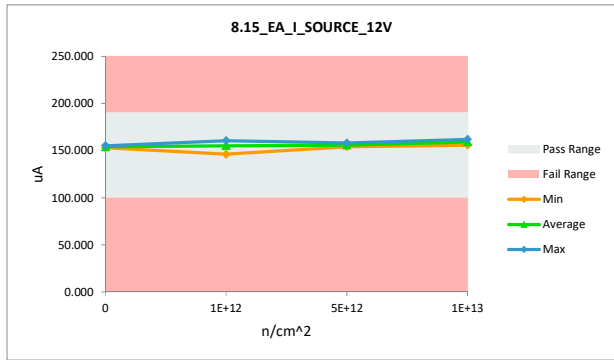


NDD Characterization Report TPS7H5006-SEP

8.15_EA_I_SOURCE_12V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	152.353	152.882	0.529
0	49	154.730	155.134	0.404
1E+12	11	158.179	158.836	0.657
1E+12	12	160.153	160.410	0.257
1E+12	13	145.676	146.086	0.410
5E+12	14	153.695	153.933	0.238
5E+12	15	156.742	157.970	1.228
5E+12	16	155.673	155.746	0.073
1E+13	17	154.790	155.815	1.025
1E+13	18	160.563	161.956	1.393
1E+13	19	159.471	159.869	0.398
Max		160.563	161.956	1.393
Average		155.639	156.240	0.601
Min		145.676	146.086	0.073
Std Dev		4.270	4.408	0.431

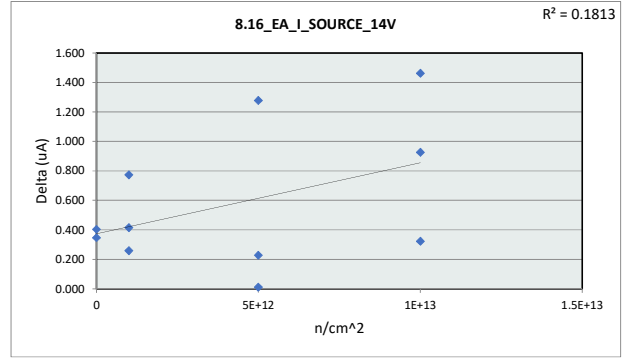


8.15_EA_I_SOURCE_12V				
Test Site				
Tester				
Test Number				
Max Limit	190		uA	
Min Limit	100		uA	
n/cm ²	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	152.882	146.086	153.933	155.815
Average	154.008	155.111	155.883	159.213
Max	155.134	160.410	157.970	161.956
UL	190.000	190.000	190.000	190.000

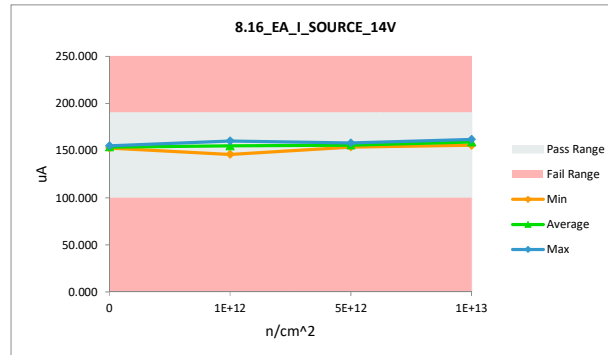


NDD Characterization Report TPS7H5006-SEP

8.16_EA_I_SOURCE_14V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	152.287	152.690	0.403
0	49	154.703	155.048	0.345
1E+12	11	158.066	158.838	0.772
1E+12	12	160.039	160.297	0.258
1E+12	13	145.579	145.993	0.414
5E+12	14	153.622	153.849	0.227
5E+12	15	156.656	157.933	1.277
5E+12	16	155.539	155.550	0.011
1E+13	17	154.744	155.669	0.925
1E+13	18	160.402	161.863	1.461
1E+13	19	159.393	159.715	0.322
Max		160.402	161.863	1.461
Average		155.548	156.131	0.583
Min		145.579	145.993	0.011
Std Dev		4.256	4.418	0.464

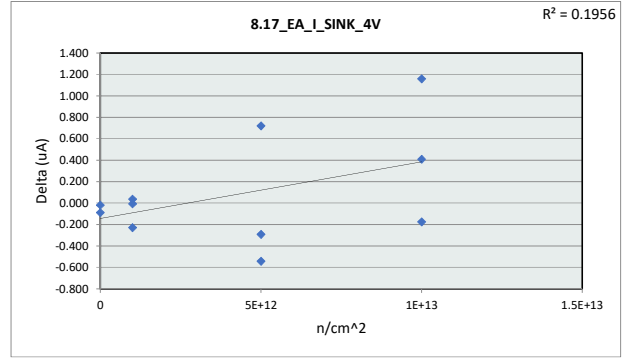


8.16_EA_I_SOURCE_14V				
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm ²	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	152.690	145.993	153.849	155.669
Average	153.869	155.043	155.777	159.082
Max	155.048	160.297	157.933	161.863
UL	190.000	190.000	190.000	190.000

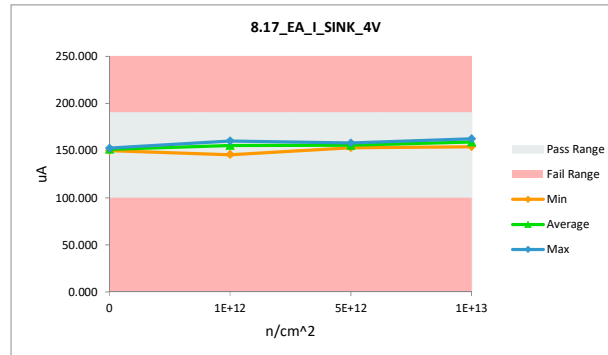


NDD Characterization Report TPS7H5006-SEP

8.17_EA_I_SINK_4V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	150.057	149.967	-0.090
0	49	152.578	152.557	-0.021
1E+12	11	160.076	160.111	0.035
1E+12	12	160.508	160.277	-0.231
1E+12	13	145.723	145.714	-0.009
5E+12	14	153.247	152.954	-0.293
5E+12	15	157.343	158.062	0.719
5E+12	16	156.063	155.519	-0.544
1E+13	17	153.672	154.079	0.407
1E+13	18	161.437	162.594	1.157
1E+13	19	160.762	160.586	-0.176
Max		161.437	162.594	1.157
Average		155.588	155.675	0.087
Min		145.723	145.714	-0.544
Std Dev		5.047	5.197	0.491

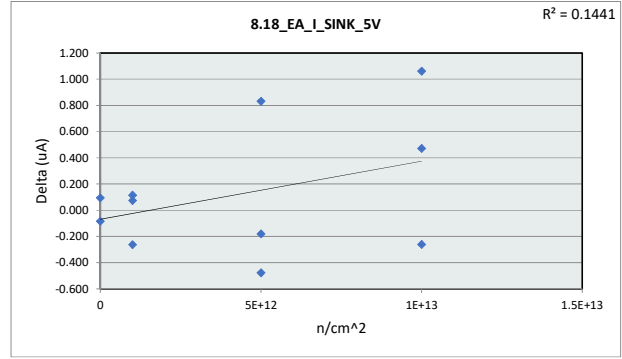


8.17_EA_I_SINK_4V				
Test Site				
Tester				
Test Number				
Max Limit	190		uA	
Min Limit	100		uA	
n/cm ²	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	149.967	145.714	152.954	154.079
Average	151.262	155.367	155.512	159.086
Max	152.557	160.277	158.062	162.594
UL	190.000	190.000	190.000	190.000

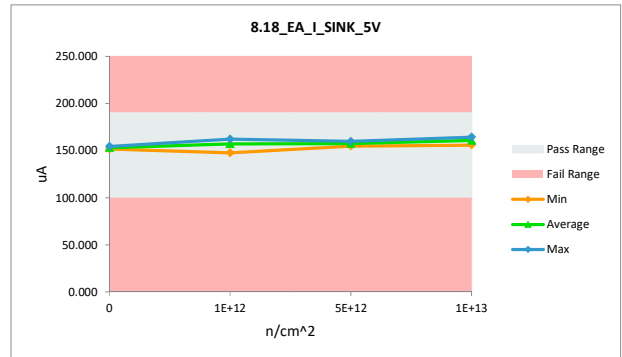


NDD Characterization Report TPS7H5006-SEP

8.18_EA_I_SINK_5V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	151.743	151.658	-0.085
0	49	154.421	154.514	0.093
1E+12	11	161.878	161.992	0.114
1E+12	12	162.402	162.138	-0.264
1E+12	13	147.551	147.624	0.073
5E+12	14	154.952	154.770	-0.182
5E+12	15	159.082	159.913	0.831
5E+12	16	157.921	157.443	-0.478
1E+13	17	155.422	155.892	0.470
1E+13	18	163.339	164.399	1.060
1E+13	19	162.627	162.364	-0.263
Max		163.339	164.399	1.060
Average		157.394	157.519	0.124
Min		147.551	147.624	-0.478
Std Dev		5.085	5.190	0.480

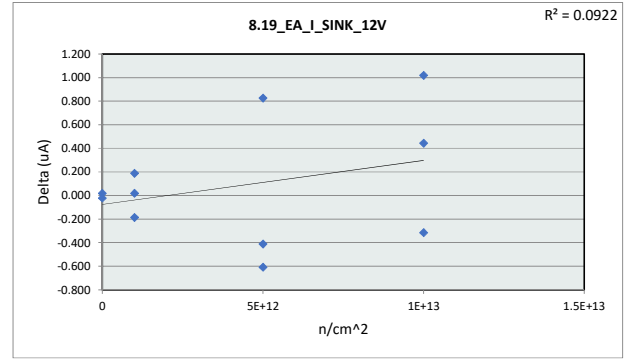


8.18_EA_I_SINK_5V				
Test Site				
Tester				
Test Number				
Max Limit	190		uA	
Min Limit	100		uA	
n/cm ²	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.658	147.624	154.770	155.892
Average	153.086	157.251	157.375	160.885
Max	154.514	162.138	159.913	164.399
UL	190.000	190.000	190.000	190.000

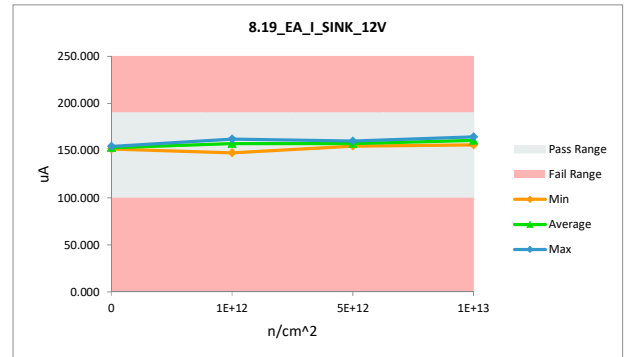


NDD Characterization Report TPS7H5006-SEP

8.19_EA_I_SINK_12V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	151.742	151.719	-0.023
0	49	154.449	154.467	0.018
1E+12	11	162.065	162.252	0.187
1E+12	12	162.394	162.207	-0.187
1E+12	13	147.642	147.660	0.018
5E+12	14	155.085	154.672	-0.413
5E+12	15	159.144	159.969	0.825
5E+12	16	158.073	157.463	-0.610
1E+13	17	155.482	155.925	0.443
1E+13	18	163.457	164.474	1.017
1E+13	19	162.693	162.377	-0.316
	Max	163.457	164.474	1.017
	Average	157.475	157.562	0.087
	Min	147.642	147.660	-0.610
	Std Dev	5.097	5.226	0.504

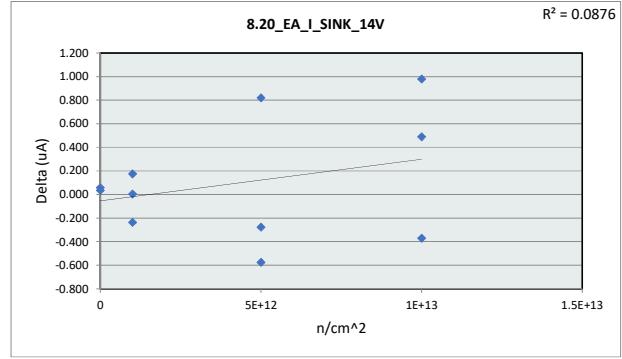


8.19_EA_I_SINK_12V				
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm ²	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.719	147.660	154.672	155.925
Average	153.093	157.373	157.368	160.925
Max	154.467	162.252	159.969	164.474
UL	190.000	190.000	190.000	190.000

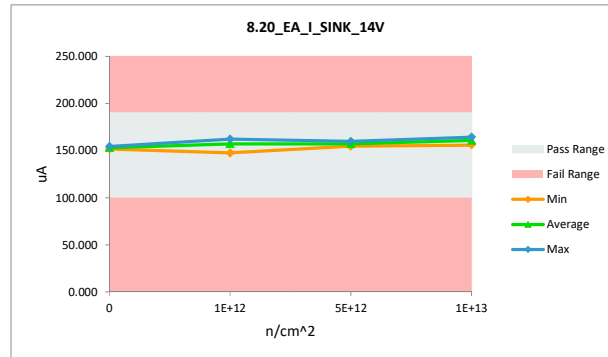


NDD Characterization Report TPS7H5006-SEP

8.20_EA_I_SINK_14V				
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		185	190	
Min Limit		105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	151.674	151.708	0.034
0	49	154.378	154.435	0.057
1E+12	11	161.895	162.069	0.174
1E+12	12	162.303	162.065	-0.238
1E+12	13	147.525	147.528	0.003
5E+12	14	154.829	154.550	-0.279
5E+12	15	158.971	159.790	0.819
5E+12	16	157.938	157.361	-0.577
1E+13	17	155.418	155.906	0.488
1E+13	18	163.370	164.348	0.978
1E+13	19	162.623	162.251	-0.372
	Max	163.370	164.348	0.978
	Average	157.357	157.456	0.099
	Min	147.525	147.528	-0.577
	Std Dev	5.098	5.197	0.490

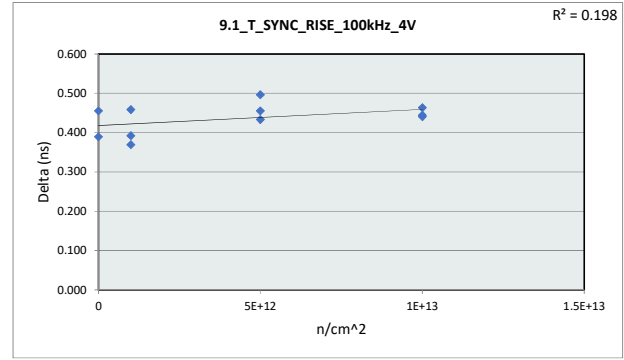


8.20_EA_I_SINK_14V				
Test Site				
Tester				
Test Number				
Max Limit	190		uA	
Min Limit	100		uA	
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.708	147.528	154.550	155.906
Average	153.072	157.221	157.234	160.835
Max	154.435	162.069	159.790	164.348
UL	190.000	190.000	190.000	190.000

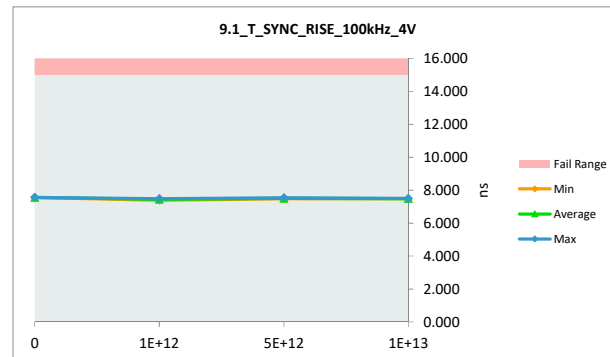


NDD Characterization Report TPS7H5006-SEP

9.1_T_SYNC_RISE_100kHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14.5		15
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.117	7.572	0.455
0	49	7.166	7.555	0.389
1E+12	11	7.055	7.447	0.392
1E+12	12	7.013	7.382	0.369
1E+12	13	7.036	7.494	0.458
5E+12	14	7.062	7.495	0.433
5E+12	15	7.019	7.474	0.455
5E+12	16	7.047	7.543	0.496
1E+13	17	7.044	7.507	0.463
1E+13	18	7.059	7.499	0.440
1E+13	19	7.040	7.484	0.444
Max		7.166	7.572	0.496
Average		7.060	7.496	0.436
Min		7.013	7.382	0.369
Std Dev		0.045	0.053	0.038

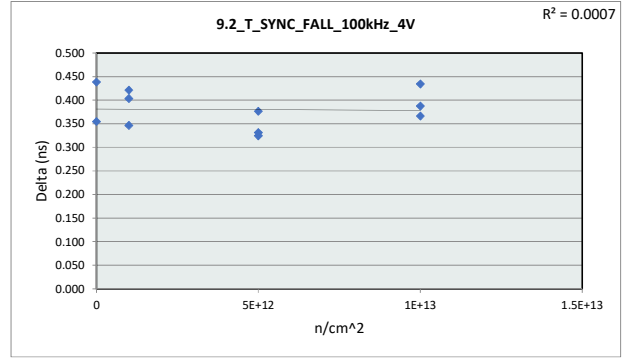


9.1_T_SYNC_RISE_100kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	7.555	7.382	7.474	7.484
Average	7.564	7.441	7.504	7.497
Max	7.572	7.494	7.543	7.507
UL	15.000	15.000	15.000	15.000

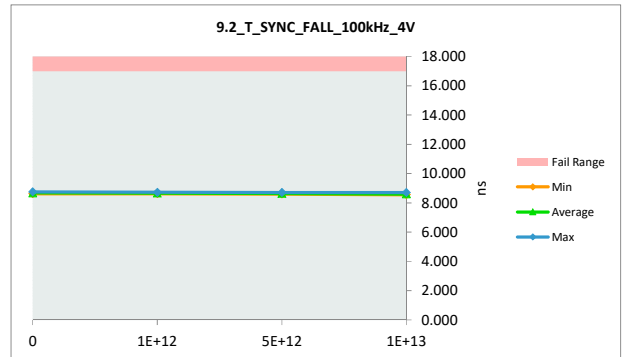


NDD Characterization Report TPS7H5006-SEP

9.2_T_SYNC_FALL_100kHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14.5		17
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.267	8.621	0.354
0	49	8.302	8.740	0.438
1E+12	11	8.200	8.621	0.421
1E+12	12	8.289	8.635	0.346
1E+12	13	8.317	8.720	0.403
5E+12	14	8.291	8.622	0.331
5E+12	15	8.331	8.707	0.376
5E+12	16	8.279	8.603	0.324
1E+13	17	8.119	8.553	0.434
1E+13	18	8.322	8.709	0.387
1E+13	19	8.188	8.554	0.366
Max		8.331	8.740	0.438
Average		8.264	8.644	0.380
Min		8.119	8.553	0.324
Std Dev		0.067	0.065	0.040

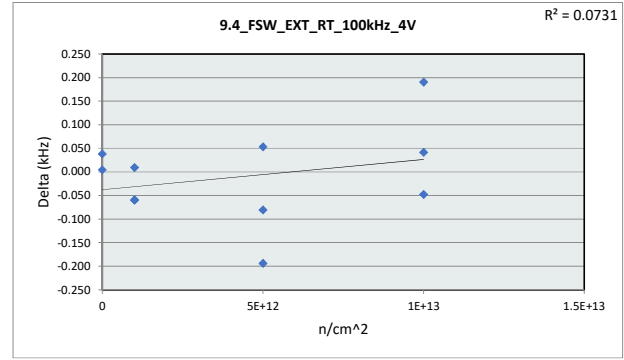


9.2_T_SYNC_FALL_100kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	8.621	8.621	8.603	8.553
Average	8.681	8.659	8.644	8.605
Max	8.740	8.720	8.707	8.709
UL	17.000	17.000	17.000	17.000

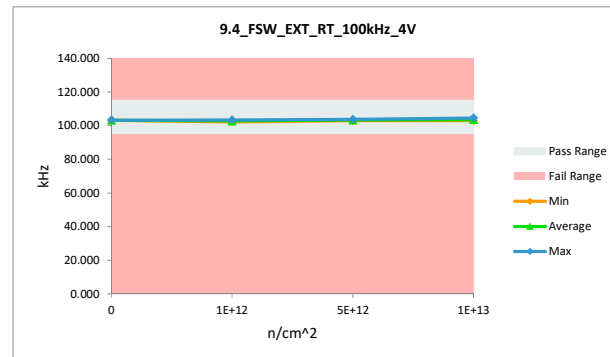


NDD Characterization Report TPS7H5006-SEP

9.4_FSW_EXT_RT_100kHz_4V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.279	103.283	0.004
0	49	103.068	103.106	0.038
1E+12	11	102.574	102.583	0.009
1E+12	12	102.348	102.288	-0.060
1E+12	13	103.353	103.293	-0.060
5E+12	14	103.185	102.991	-0.194
5E+12	15	103.060	103.113	0.053
5E+12	16	103.854	103.773	-0.081
1E+13	17	102.838	103.028	0.190
1E+13	18	103.105	103.146	0.041
1E+13	19	104.658	104.610	-0.048
Max		104.658	104.610	0.190
Average		103.211	103.201	-0.010
Min		102.348	102.288	-0.194
Std Dev		0.623	0.603	0.097

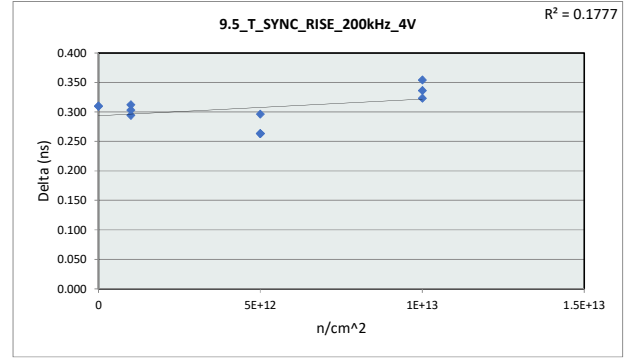


9.4_FSW_EXT_RT_100kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.106	102.288	102.991	103.028
Average	103.195	102.721	103.292	103.595
Max	103.283	103.293	103.773	104.610
UL	115.000	115.000	115.000	115.000

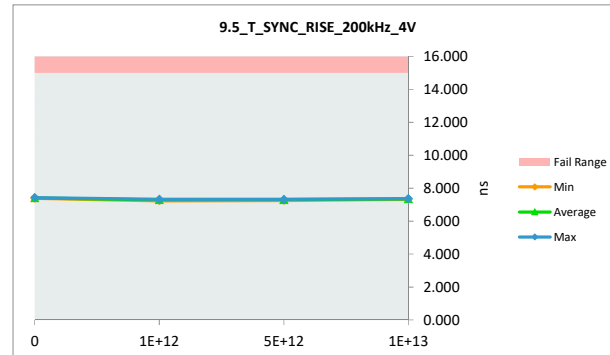


NDD Characterization Report TPS7H5006-SEP

9.5_T_SYNC_RISE_200kHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14.5		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.079	7.388	0.309
0	49	7.125	7.435	0.310
1E+12	11	7.015	7.309	0.294
1E+12	12	6.921	7.233	0.312
1E+12	13	7.025	7.328	0.303
5E+12	14	7.056	7.319	0.263
5E+12	15	6.965	7.261	0.296
5E+12	16	7.059	7.322	0.263
1E+13	17	6.990	7.326	0.336
1E+13	18	7.018	7.341	0.323
1E+13	19	7.016	7.370	0.354
Max		7.125	7.435	0.354
Average		7.024	7.330	0.306
Min		6.921	7.233	0.263
Std Dev		0.056	0.056	0.027

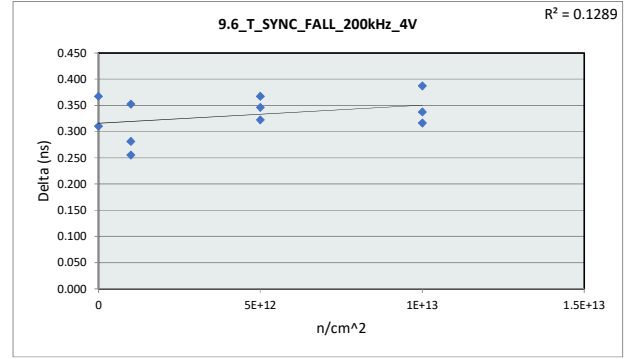


9.5_T_SYNC_RISE_200kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.388	7.233	7.261	7.326
Average	7.412	7.290	7.301	7.346
Max	7.435	7.328	7.322	7.370
UL	15.000	15.000	15.000	15.000

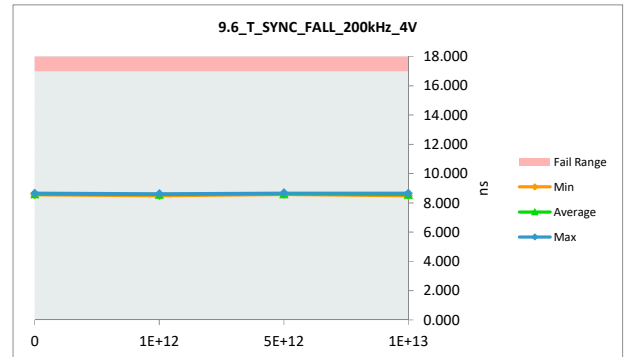


NDD Characterization Report TPS7H5006-SEP

9.6_T_SYNC_FALL_200kHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.234	8.544	0.310
0	49	8.288	8.655	0.367
1E+12	11	8.244	8.596	0.352
1E+12	12	8.244	8.499	0.255
1E+12	13	8.328	8.609	0.281
5E+12	14	8.255	8.577	0.322
5E+12	15	8.305	8.672	0.367
5E+12	16	8.251	8.597	0.346
1E+13	17	8.163	8.479	0.316
1E+13	18	8.319	8.656	0.337
1E+13	19	8.175	8.562	0.387
Max		8.328	8.672	0.387
Average		8.255	8.586	0.331
Min		8.163	8.479	0.255
Std Dev		0.053	0.063	0.039

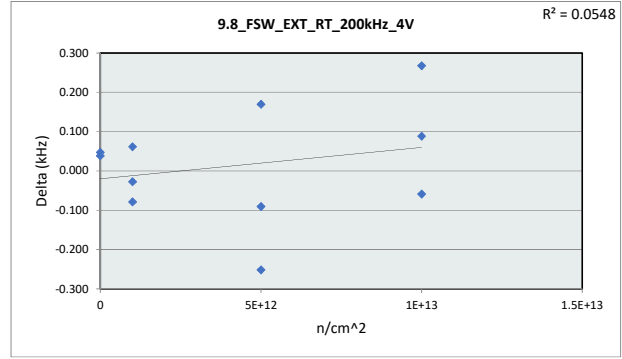


9.6_T_SYNC_FALL_200kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	8.544	8.499	8.577	8.479
Average	8.600	8.568	8.615	8.566
Max	8.655	8.609	8.672	8.656
UL	17.000	17.000	17.000	17.000

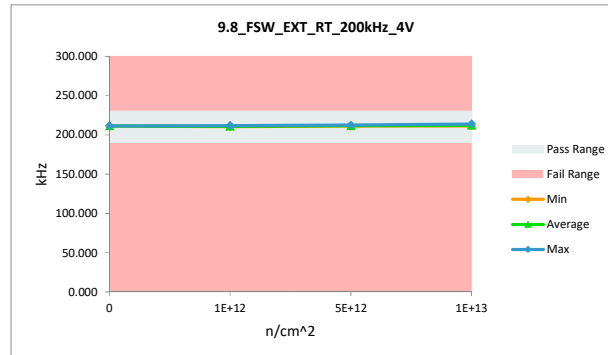


NDD Characterization Report TPS7H5006-SEP

9.8_FSW_EXT_RT_200kHz_4V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	211.430	211.477	0.047
0	49	211.292	211.330	0.038
1E+12	11	210.469	210.530	0.061
1E+12	12	210.491	210.463	-0.028
1E+12	13	211.763	211.684	-0.079
5E+12	14	211.622	211.370	-0.252
5E+12	15	211.251	211.420	0.169
5E+12	16	212.520	212.429	-0.091
1E+13	17	211.269	211.536	0.267
1E+13	18	211.444	211.532	0.088
1E+13	19	213.855	213.796	-0.059
	Max	213.855	213.796	0.267
	Average	211.582	211.597	0.015
	Min	210.469	210.463	-0.252
	Std Dev	0.940	0.902	0.140

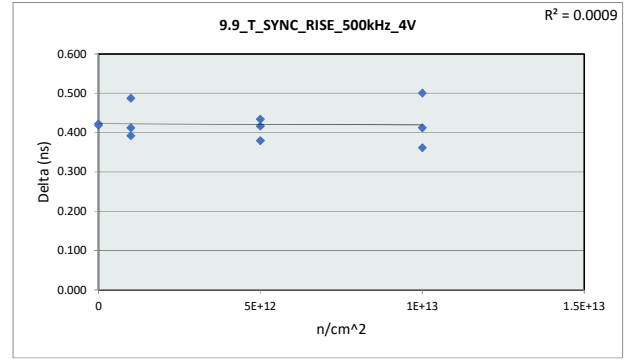


9.8_FSW_EXT_RT_200kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	211.330	210.463	211.370	211.532
Average	211.404	210.892	211.740	212.288
Max	211.477	211.684	212.429	213.796
UL	230.000	230.000	230.000	230.000

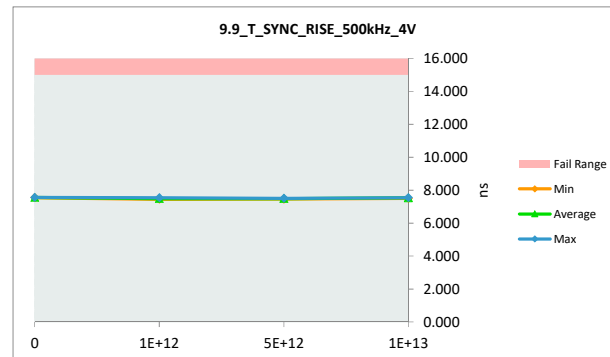


NDD Characterization Report TPS7H5006-SEP

9.9_T_SYNC_RISE_500kHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14.5		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.147	7.565	0.418
0	49	7.128	7.550	0.422
1E+12	11	7.091	7.483	0.392
1E+12	12	7.040	7.452	0.412
1E+12	13	7.046	7.533	0.487
5E+12	14	7.078	7.512	0.434
5E+12	15	7.044	7.460	0.416
5E+12	16	7.109	7.488	0.379
1E+13	17	7.144	7.505	0.361
1E+13	18	7.053	7.553	0.500
1E+13	19	7.134	7.546	0.412
Max		7.147	7.565	0.500
Average		7.092	7.513	0.421
Min		7.040	7.452	0.361
Std Dev		0.042	0.039	0.041

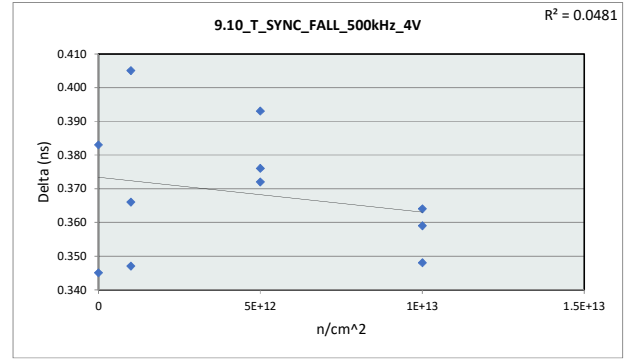


9.9_T_SYNC_RISE_500kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	15		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.550	7.452	7.460	7.505
Average	7.558	7.489	7.487	7.535
Max	7.565	7.533	7.512	7.553
UL	15.000	15.000	15.000	15.000

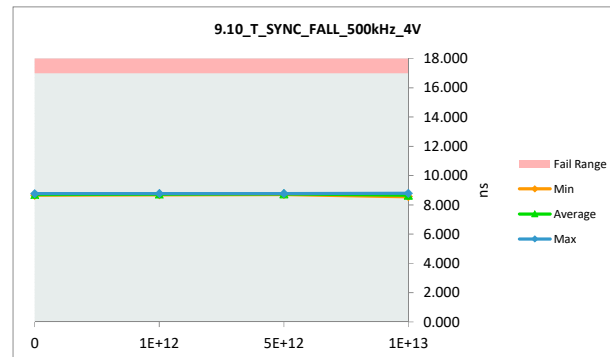


NDD Characterization Report TPS7H5006-SEP

9.10_T_SYNC_FALL_500kHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.305	8.650	0.345
0	49	8.377	8.760	0.383
1E+12	11	8.272	8.677	0.405
1E+12	12	8.377	8.724	0.347
1E+12	13	8.408	8.774	0.366
5E+12	14	8.359	8.752	0.393
5E+12	15	8.391	8.763	0.372
5E+12	16	8.324	8.700	0.376
1E+13	17	8.209	8.557	0.348
1E+13	18	8.424	8.783	0.359
1E+13	19	8.268	8.632	0.364
Max		8.424	8.783	0.405
Average		8.338	8.707	0.369
Min		8.209	8.557	0.345
Std Dev		0.068	0.071	0.019

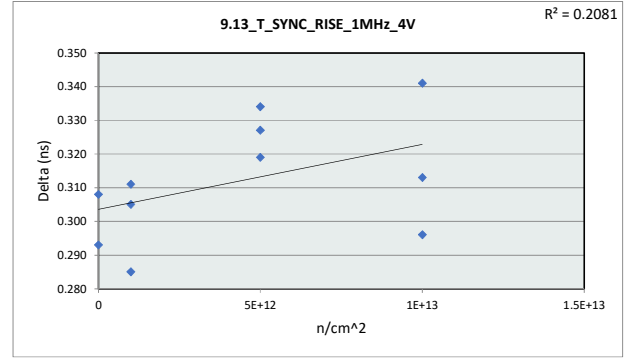


9.10_T_SYNC_FALL_500kHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	8.650	8.677	8.700	8.557
Average	8.705	8.725	8.738	8.657
Max	8.760	8.774	8.763	8.783
UL	17.000	17.000	17.000	17.000

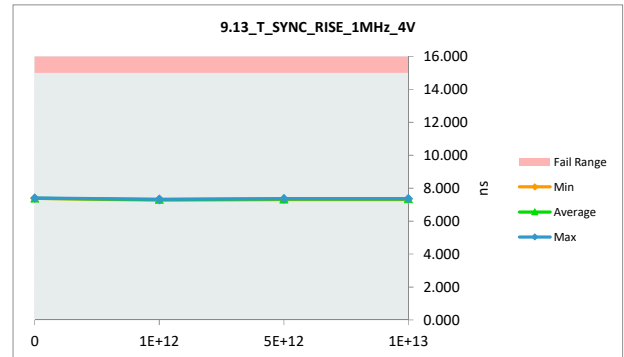


NDD Characterization Report TPS7H5006-SEP

9.13_T_SYNC_RISE_1MHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14.5	15	
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.090	7.383	0.293
0	49	7.090	7.398	0.308
1E+12	11	7.042	7.327	0.285
1E+12	12	6.975	7.280	0.305
1E+12	13	7.028	7.339	0.311
5E+12	14	7.035	7.354	0.319
5E+12	15	6.965	7.299	0.334
5E+12	16	7.037	7.364	0.327
1E+13	17	7.063	7.376	0.313
1E+13	18	7.018	7.314	0.296
1E+13	19	7.038	7.379	0.341
Max		7.090	7.398	0.341
Average		7.035	7.347	0.312
Min		6.965	7.280	0.285
Std Dev		0.040	0.038	0.017

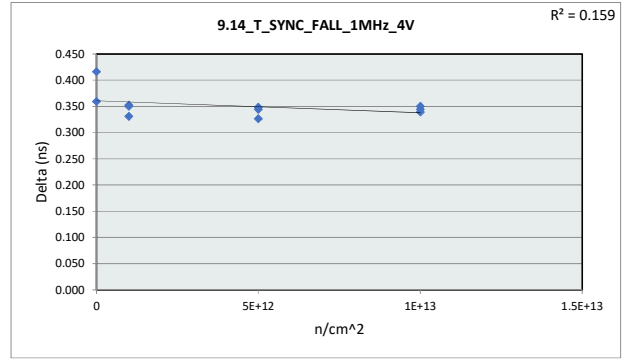


9.13_T_SYNC_RISE_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	7.383	7.280	7.299	7.314
Average	7.391	7.315	7.339	7.356
Max	7.398	7.339	7.364	7.379
UL	15.000	15.000	15.000	15.000

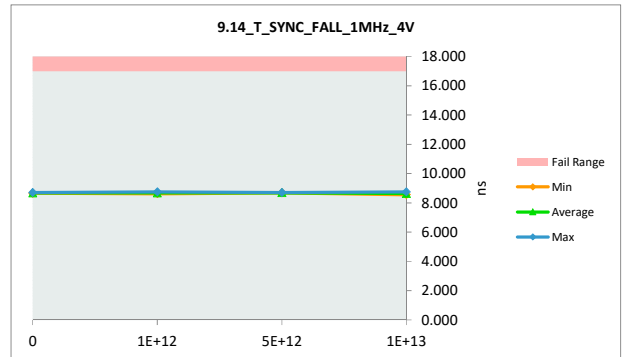


NDD Characterization Report TPS7H5006-SEP

9.14_T_SYNC_FALL_1MHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.233	8.649	0.416
0	49	8.341	8.700	0.359
1E+12	11	8.278	8.628	0.350
1E+12	12	8.319	8.671	0.352
1E+12	13	8.410	8.741	0.331
5E+12	14	8.339	8.687	0.348
5E+12	15	8.381	8.707	0.326
5E+12	16	8.335	8.679	0.344
1E+13	17	8.212	8.556	0.344
1E+13	18	8.401	8.740	0.339
1E+13	19	8.246	8.596	0.350
Max		8.410	8.741	0.416
Average		8.318	8.669	0.351
Min		8.212	8.556	0.326
Std Dev		0.068	0.058	0.024

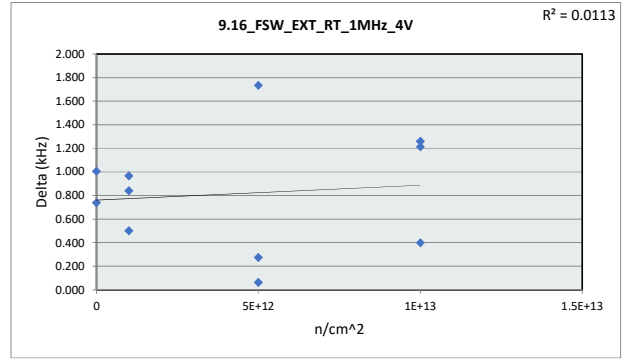


9.14_T_SYNC_FALL_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.649	8.628	8.679	8.556
Average	8.675	8.680	8.691	8.631
Max	8.700	8.741	8.707	8.740
UL	17.000	17.000	17.000	17.000

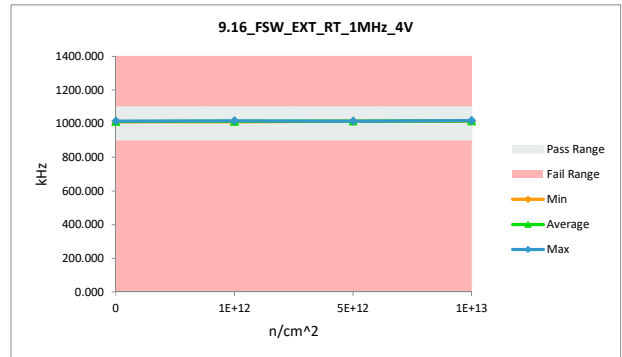


NDD Characterization Report TPS7H5006-SEP

9.16_FSW_EXT_RT_1MHz_4V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1010.364	1011.101	0.737
0	49	1014.509	1015.513	1.004
1E+12	11	1010.436	1011.274	0.838
1E+12	12	1013.306	1014.271	0.965
1E+12	13	1015.233	1015.733	0.500
5E+12	14	1013.513	1013.575	0.062
5E+12	15	1013.653	1015.385	1.732
5E+12	16	1015.091	1015.365	0.274
1E+13	17	1014.036	1015.248	1.212
1E+13	18	1014.634	1015.893	1.259
1E+13	19	1018.260	1018.657	0.397
Max		1018.260	1018.657	1.732
Average		1013.912	1014.729	0.816
Min		1010.364	1011.101	0.062
Std Dev		2.195	2.148	0.489

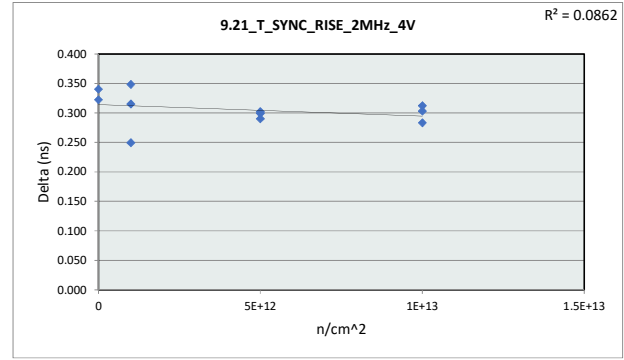


9.16_FSW_EXT_RT_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1011.101	1011.274	1013.575	1015.248
Average	1013.307	1013.759	1014.775	1016.599
Max	1015.513	1015.733	1015.385	1018.657
UL	1100.000	1100.000	1100.000	1100.000

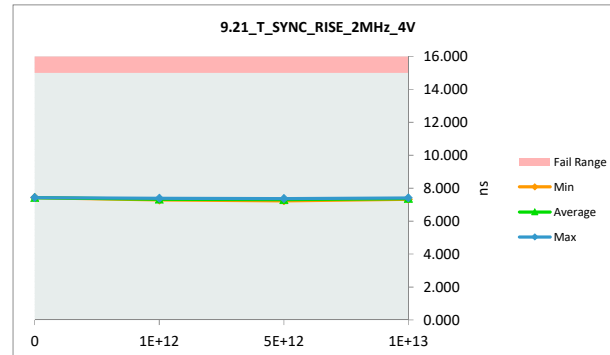


NDD Characterization Report TPS7H5006-SEP

9.21_T_SYNC_RISE_2MHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		15		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.091	7.431	0.340
0	49	7.102	7.424	0.322
1E+12	11	7.069	7.384	0.315
1E+12	12	6.959	7.307	0.348
1E+12	13	7.031	7.280	0.249
5E+12	14	7.058	7.360	0.302
5E+12	15	6.947	7.237	0.290
5E+12	16	7.032	7.331	0.299
1E+13	17	7.096	7.408	0.312
1E+13	18	7.048	7.331	0.283
1E+13	19	7.095	7.398	0.303
Max		7.102	7.431	0.348
Average		7.048	7.354	0.306
Min		6.947	7.237	0.249
Std Dev		0.053	0.062	0.027

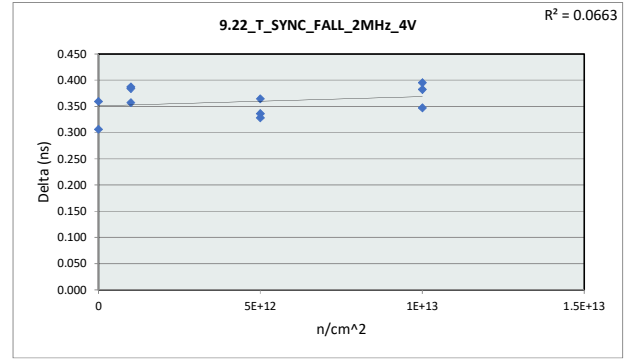


9.21_T_SYNC_RISE_2MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.424	7.280	7.237	7.331
Average	7.428	7.324	7.309	7.379
Max	7.431	7.384	7.360	7.408
UL	15.000	15.000	15.000	15.000

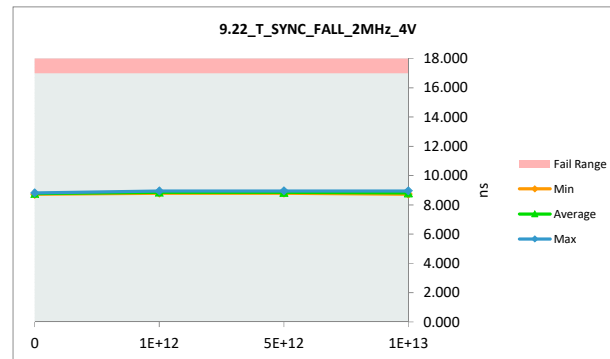


NDD Characterization Report TPS7H5006-SEP

9.22_T_SYNC_FALL_2MHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.363	8.722	0.359
0	49	8.501	8.807	0.306
1E+12	11	8.439	8.796	0.357
1E+12	12	8.484	8.871	0.387
1E+12	13	8.551	8.935	0.384
5E+12	14	8.461	8.797	0.336
5E+12	15	8.585	8.949	0.364
5E+12	16	8.468	8.796	0.328
1E+13	17	8.369	8.751	0.382
1E+13	18	8.553	8.948	0.395
1E+13	19	8.382	8.729	0.347
Max		8.585	8.949	0.395
Average		8.469	8.827	0.359
Min		8.363	8.722	0.306
Std Dev		0.076	0.085	0.028

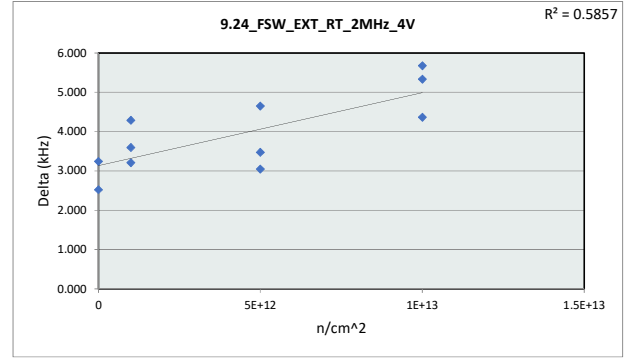


9.22_T_SYNC_FALL_2MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.722	8.796	8.796	8.729
Average	8.765	8.867	8.847	8.809
Max	8.807	8.935	8.949	8.948
UL	17.000	17.000	17.000	17.000

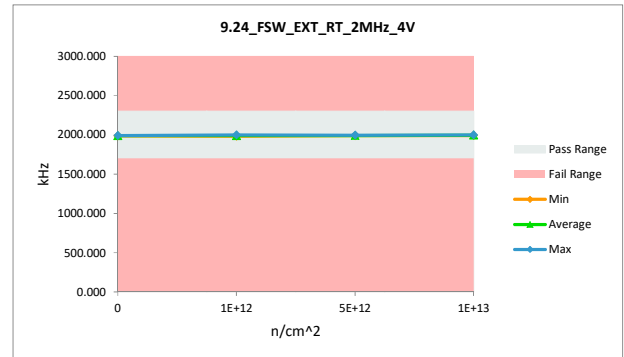


NDD Characterization Report TPS7H5006-SEP

9.24_FSW_EXT_RT_2MHz_4V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1988.291	1990.807	2.516
0	49	1984.655	1987.895	3.240
1E+12	11	1978.903	1982.107	3.204
1E+12	12	1985.352	1989.635	4.283
1E+12	13	1995.899	1999.490	3.591
5E+12	14	1992.487	1995.531	3.044
5E+12	15	1985.544	1990.191	4.647
5E+12	16	1989.406	1992.874	3.468
1E+13	17	1986.200	1991.869	5.669
1E+13	18	1994.020	1999.351	5.331
1E+13	19	1990.826	1995.187	4.361
	Max	1995.899	1999.490	5.669
	Average	1988.326	1992.267	3.941
	Min	1978.903	1982.107	2.516
	Std Dev	4.877	5.077	0.996

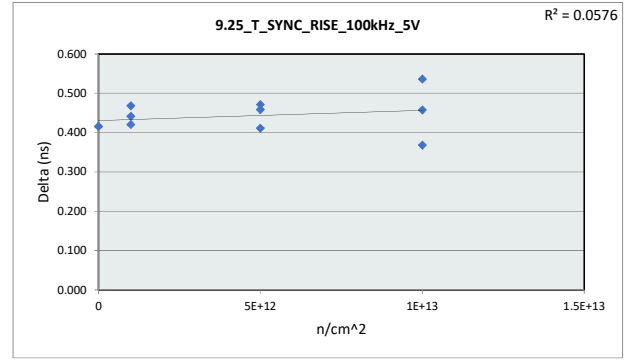


9.24_FSW_EXT_RT_2MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1987.895	1982.107	1990.191	1991.869
Average	1989.351	1990.411	1992.865	1995.469
Max	1990.807	1999.490	1995.531	1999.351
UL	2300.000	2300.000	2300.000	2300.000

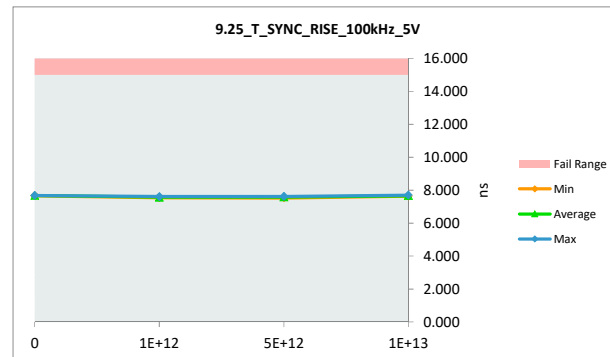


NDD Characterization Report TPS7H5006-SEP

9.25_T_SYNC_RISE_100kHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.253	7.668	0.415
0	49	7.266	7.681	0.415
1E+12	11	7.145	7.613	0.468
1E+12	12	7.111	7.552	0.441
1E+12	13	7.144	7.564	0.420
5E+12	14	7.163	7.621	0.458
5E+12	15	7.122	7.533	0.411
5E+12	16	7.145	7.616	0.471
1E+13	17	7.163	7.699	0.536
1E+13	18	7.185	7.642	0.457
1E+13	19	7.277	7.645	0.368
Max		7.277	7.699	0.536
Average		7.179	7.621	0.442
Min		7.111	7.533	0.368
Std Dev		0.059	0.054	0.044

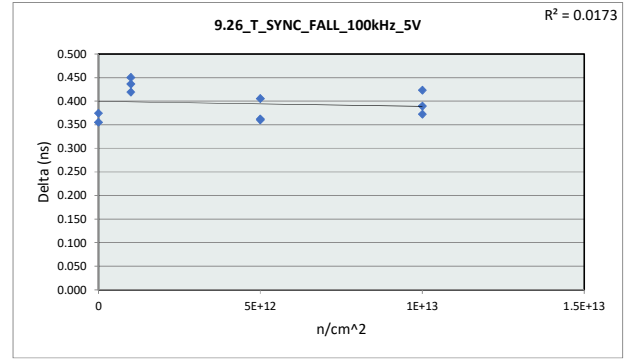


9.25_T_SYNC_RISE_100kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.668	7.552	7.533	7.642
Average	7.675	7.576	7.590	7.662
Max	7.681	7.613	7.621	7.699
UL	15.000	15.000	15.000	15.000

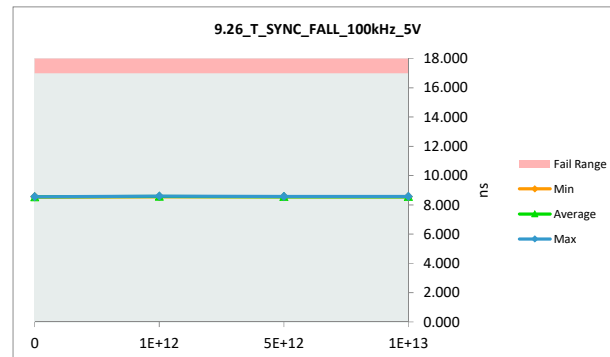


NDD Characterization Report TPS7H5006-SEP

9.26_T_SYNC_FALL_100kHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.185	8.540	0.355
0	49	8.183	8.557	0.374
1E+12	11	8.126	8.562	0.436
1E+12	12	8.177	8.596	0.419
1E+12	13	8.137	8.587	0.450
5E+12	14	8.188	8.548	0.360
5E+12	15	8.204	8.566	0.362
5E+12	16	8.162	8.567	0.405
1E+13	17	8.155	8.578	0.423
1E+13	18	8.171	8.560	0.389
1E+13	19	8.175	8.547	0.372
Max		8.204	8.596	0.450
Average		8.169	8.564	0.395
Min		8.126	8.540	0.355
Std Dev		0.023	0.017	0.033

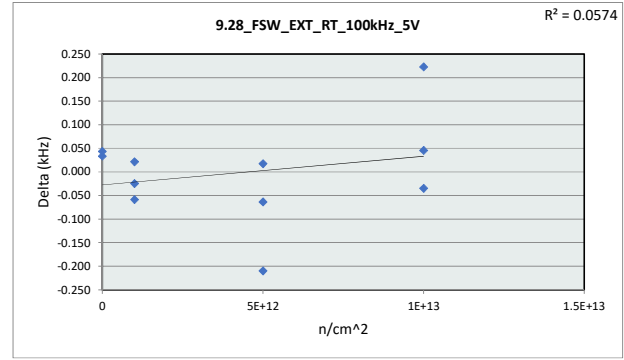


9.26_T_SYNC_FALL_100kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	8.540	8.562	8.548	8.547
Average	8.549	8.582	8.560	8.562
Max	8.557	8.596	8.567	8.578
UL	17.000	17.000	17.000	17.000

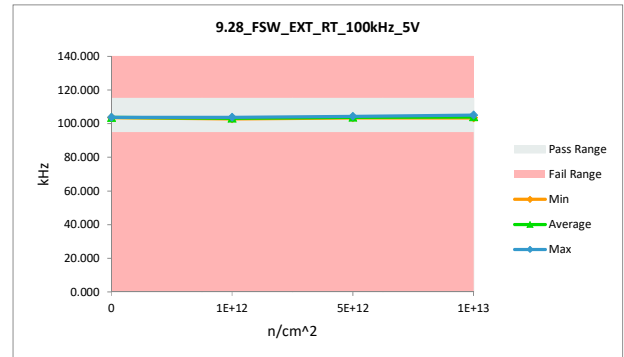


NDD Characterization Report TPS7H5006-SEP

9.28_FSW_EXT_RT_100kHz_5V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.778	103.811	0.033
0	49	103.521	103.564	0.043
1E+12	11	103.048	103.069	0.021
1E+12	12	102.846	102.821	-0.025
1E+12	13	103.830	103.771	-0.059
5E+12	14	103.665	103.455	-0.210
5E+12	15	103.540	103.557	0.017
5E+12	16	104.376	104.312	-0.064
1E+13	17	103.259	103.481	0.222
1E+13	18	103.544	103.589	0.045
1E+13	19	105.093	105.058	-0.035
Max		105.093	105.058	0.222
Average		103.682	103.681	-0.001
Min		102.846	102.821	-0.210
Std Dev		0.620	0.597	0.104

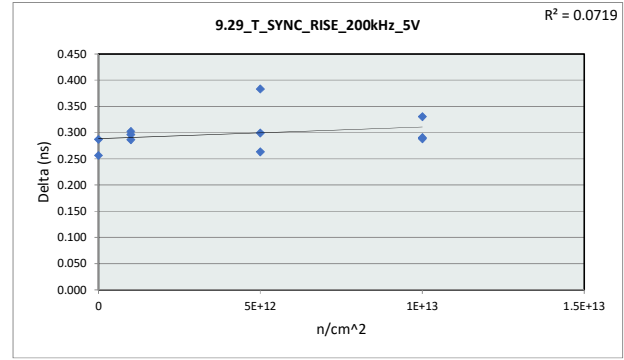


9.28_FSW_EXT_RT_100kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.564	102.821	103.455	103.481
Average	103.688	103.220	103.775	104.043
Max	103.811	103.771	104.312	105.058
UL	115.000	115.000	115.000	115.000

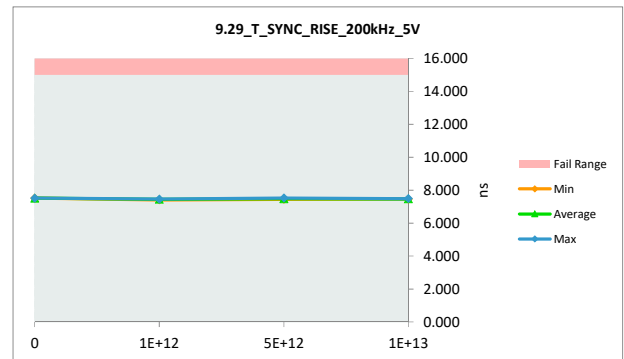


NDD Characterization Report TPS7H5006-SEP

9.29_T_SYNC_RISE_200kHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.264	7.520	0.256
0	49	7.232	7.519	0.287
1E+12	11	7.155	7.451	0.296
1E+12	12	7.109	7.411	0.302
1E+12	13	7.172	7.458	0.286
5E+12	14	7.158	7.457	0.299
5E+12	15	7.145	7.528	0.383
5E+12	16	7.181	7.444	0.263
1E+13	17	7.183	7.473	0.290
1E+13	18	7.163	7.451	0.288
1E+13	19	7.165	7.495	0.330
Max		7.264	7.528	0.383
Average		7.175	7.473	0.298
Min		7.109	7.411	0.256
Std Dev		0.042	0.037	0.034

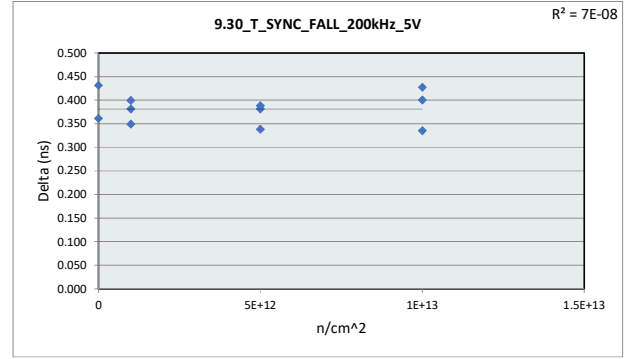


9.29_T_SYNC_RISE_200kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.519	7.411	7.444	7.451
Average	7.520	7.440	7.476	7.473
Max	7.520	7.458	7.528	7.495
UL	15.000	15.000	15.000	15.000

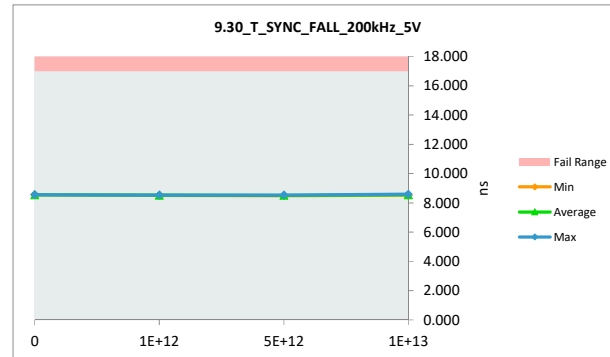


NDD Characterization Report TPS7H5006-SEP

9.30_T_SYNC_FALL_200kHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.123	8.554	0.431
0	49	8.190	8.551	0.361
1E+12	11	8.184	8.533	0.349
1E+12	12	8.121	8.502	0.381
1E+12	13	8.117	8.516	0.399
5E+12	14	8.149	8.537	0.388
5E+12	15	8.155	8.493	0.338
5E+12	16	8.122	8.503	0.381
1E+13	17	8.135	8.535	0.400
1E+13	18	8.160	8.587	0.427
1E+13	19	8.190	8.525	0.335
Max		8.190	8.587	0.431
Average		8.150	8.531	0.381
Min		8.117	8.493	0.335
Std Dev		0.029	0.027	0.033

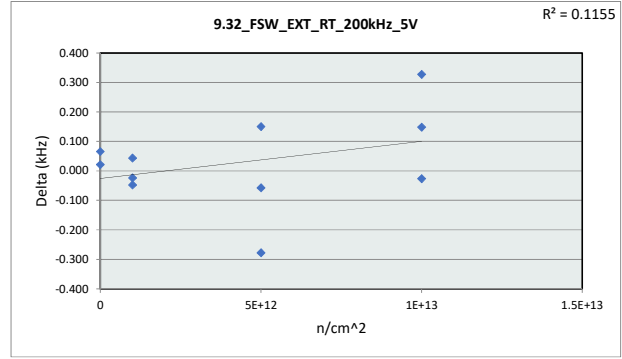


9.30_T_SYNC_FALL_200kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.551	8.502	8.493	8.525
Average	8.553	8.517	8.511	8.549
Max	8.554	8.533	8.537	8.587
UL	17.000	17.000	17.000	17.000

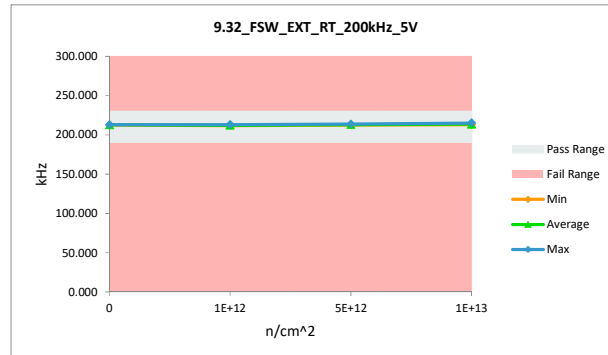


NDD Characterization Report TPS7H5006-SEP

9.32_FSW_EXT_RT_200kHz_5V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	212.889	212.910	0.021
0	49	212.633	212.698	0.065
1E+12	11	211.870	211.913	0.043
1E+12	12	211.954	211.930	-0.024
1E+12	13	213.135	213.087	-0.048
5E+12	14	212.972	212.694	-0.278
5E+12	15	212.617	212.767	0.150
5E+12	16	214.018	213.960	-0.058
1E+13	17	212.598	212.925	0.327
1E+13	18	212.723	212.871	0.148
1E+13	19	215.224	215.197	-0.027
Max		215.224	215.197	0.327
Average		212.967	212.996	0.029
Min		211.870	211.913	-0.278
Std Dev		0.943	0.914	0.153

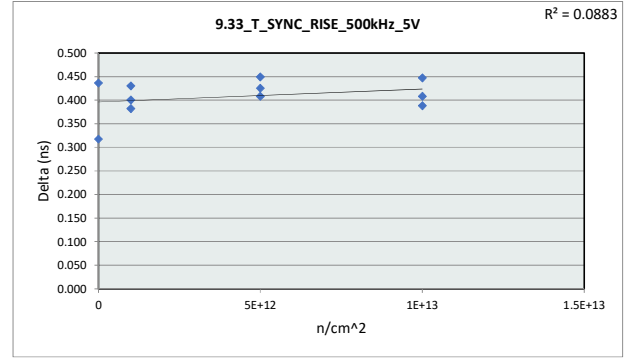


9.32_FSW_EXT_RT_200kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit		230	kHz	
Min Limit		190	kHz	
n/cm ²	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	212.698	211.913	212.694	212.871
Average	212.804	212.310	213.140	213.664
Max	212.910	213.087	213.960	215.197
UL	230.000	230.000	230.000	230.000

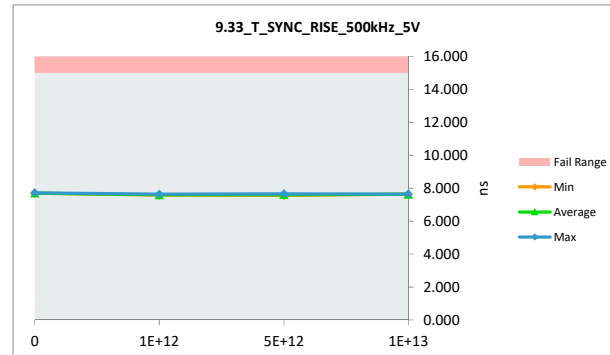


NDD Characterization Report TPS7H5006-SEP

9.33_T_SYNC_RISE_500kHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.279	7.715	0.436
0	49	7.374	7.691	0.317
1E+12	11	7.201	7.631	0.430
1E+12	12	7.180	7.580	0.400
1E+12	13	7.196	7.578	0.382
5E+12	14	7.200	7.649	0.449
5E+12	15	7.146	7.554	0.408
5E+12	16	7.204	7.629	0.425
1E+13	17	7.197	7.644	0.447
1E+13	18	7.245	7.633	0.388
1E+13	19	7.226	7.634	0.408
Max		7.374	7.715	0.449
Average		7.223	7.631	0.408
Min		7.146	7.554	0.317
Std Dev		0.061	0.047	0.038

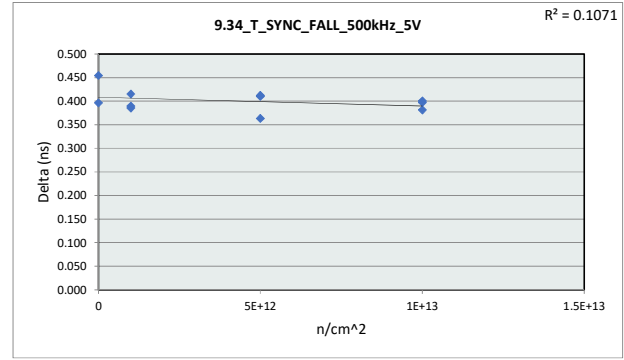


9.33_T_SYNC_RISE_500kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.691	7.578	7.554	7.633
Average	7.703	7.596	7.611	7.637
Max	7.715	7.631	7.649	7.644
UL	15.000	15.000	15.000	15.000

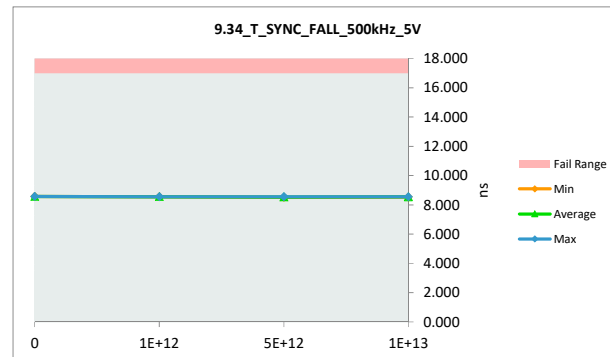


NDD Characterization Report TPS7H5006-SEP

9.34_T_SYNC_FALL_500kHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.122	8.576	0.454
0	49	8.174	8.570	0.396
1E+12	11	8.161	8.550	0.389
1E+12	12	8.165	8.550	0.385
1E+12	13	8.148	8.563	0.415
5E+12	14	8.150	8.562	0.412
5E+12	15	8.149	8.512	0.363
5E+12	16	8.131	8.541	0.410
1E+13	17	8.131	8.528	0.397
1E+13	18	8.160	8.541	0.381
1E+13	19	8.150	8.550	0.400
Max		8.174	8.576	0.454
Average		8.149	8.549	0.400
Min		8.122	8.512	0.363
Std Dev		0.016	0.019	0.023

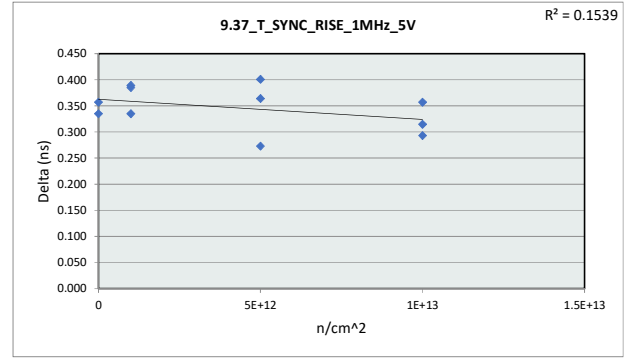


9.34_T_SYNC_FALL_500kHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.570	8.550	8.512	8.528
Average	8.573	8.554	8.538	8.540
Max	8.576	8.563	8.562	8.550
UL	17.000	17.000	17.000	17.000

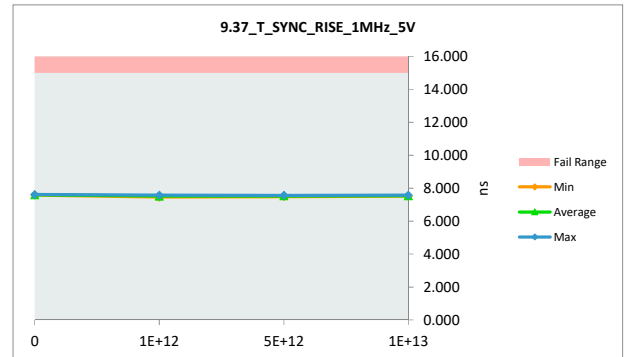


NDD Characterization Report TPS7H5006-SEP

9.37_T_SYNC_RISE_1MHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.229	7.586	0.357
0	49	7.278	7.613	0.335
1E+12	11	7.181	7.516	0.335
1E+12	12	7.076	7.461	0.385
1E+12	13	7.189	7.578	0.389
5E+12	14	7.260	7.533	0.273
5E+12	15	7.096	7.497	0.401
5E+12	16	7.195	7.559	0.364
1E+13	17	7.284	7.577	0.293
1E+13	18	7.163	7.520	0.357
1E+13	19	7.215	7.530	0.315
Max		7.284	7.613	0.401
Average		7.197	7.543	0.346
Min		7.076	7.461	0.273
Std Dev		0.068	0.044	0.040

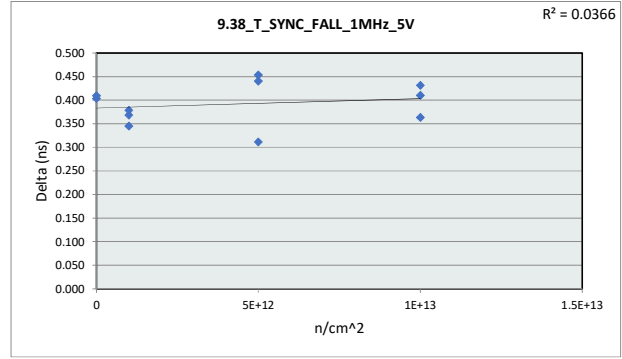


9.37_T_SYNC_RISE_1MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.586	7.461	7.497	7.520
Average	7.600	7.518	7.530	7.542
Max	7.613	7.578	7.559	7.577
UL	15.000	15.000	15.000	15.000

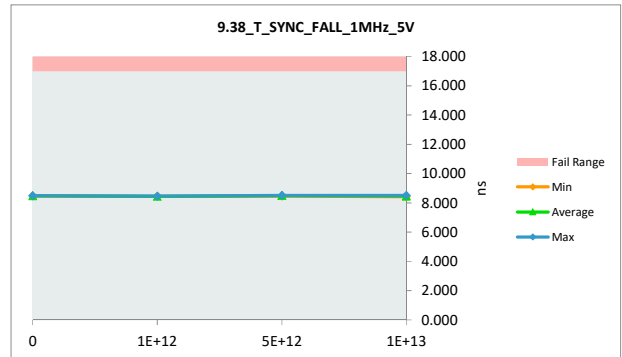


NDD Characterization Report TPS7H5006-SEP

9.38_T_SYNC_FALL_1MHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.077	8.480	0.403
0	49	8.061	8.470	0.409
1E+12	11	8.088	8.456	0.368
1E+12	12	8.105	8.450	0.345
1E+12	13	8.057	8.435	0.378
5E+12	14	8.148	8.459	0.311
5E+12	15	8.068	8.508	0.440
5E+12	16	8.058	8.511	0.453
1E+13	17	8.030	8.440	0.410
1E+13	18	8.056	8.419	0.363
1E+13	19	8.075	8.506	0.431
Max		8.148	8.511	0.453
Average		8.075	8.467	0.392
Min		8.030	8.419	0.311
Std Dev		0.031	0.031	0.043

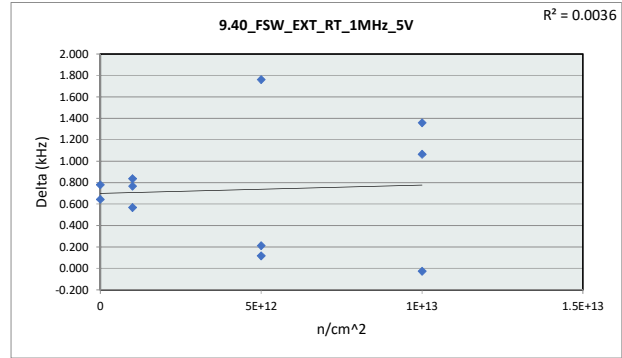


9.38_T_SYNC_FALL_1MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.470	8.435	8.459	8.419
Average	8.475	8.447	8.493	8.455
Max	8.480	8.456	8.511	8.506
UL	17.000	17.000	17.000	17.000

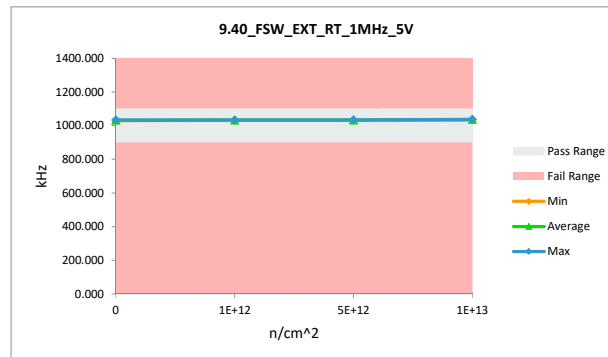


NDD Characterization Report TPS7H5006-SEP

9.40_FSW_EXT_RT_1MHz_5V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1028.667	1029.309	0.642
0	49	1033.862	1034.640	0.778
1E+12	11	1029.855	1030.691	0.836
1E+12	12	1032.644	1033.410	0.766
1E+12	13	1033.702	1034.269	0.567
5E+12	14	1031.362	1031.573	0.211
5E+12	15	1032.665	1034.424	1.759
5E+12	16	1034.408	1034.523	0.115
1E+13	17	1032.994	1034.056	1.062
1E+13	18	1032.793	1034.149	1.356
1E+13	19	1037.559	1037.532	-0.027
	Max	1037.559	1037.532	1.759
	Average	1032.774	1033.507	0.733
	Min	1028.667	1029.309	-0.027
	Std Dev	2.347	2.235	0.532

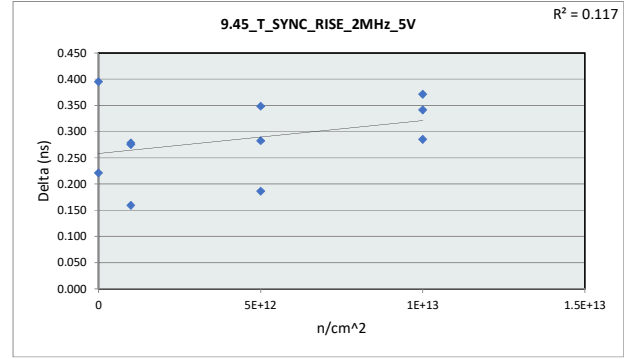


9.40_FSW_EXT_RT_1MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1029.309	1030.691	1031.573	1034.056
Average	1031.975	1032.790	1033.507	1035.246
Max	1034.640	1034.269	1034.523	1037.532
UL	1100.000	1100.000	1100.000	1100.000

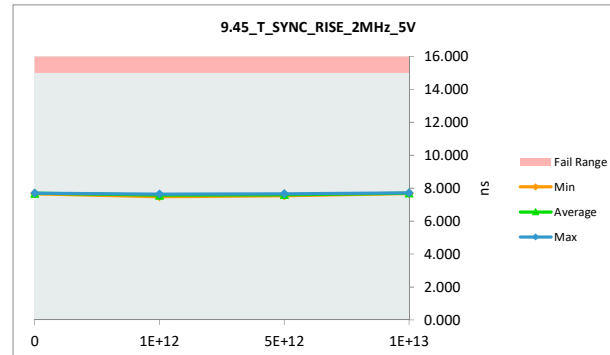


NDD Characterization Report TPS7H5006-SEP

9.45_T_SYNC_RISE_2MHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.311	7.706	0.395
0	49	7.446	7.667	0.221
1E+12	11	7.324	7.602	0.278
1E+12	12	7.320	7.479	0.159
1E+12	13	7.367	7.642	0.275
5E+12	14	7.331	7.613	0.282
5E+12	15	7.349	7.535	0.186
5E+12	16	7.313	7.661	0.348
1E+13	17	7.416	7.701	0.285
1E+13	18	7.341	7.682	0.341
1E+13	19	7.338	7.709	0.371
Max		7.446	7.709	0.395
Average		7.351	7.636	0.286
Min		7.311	7.479	0.159
Std Dev		0.043	0.074	0.075

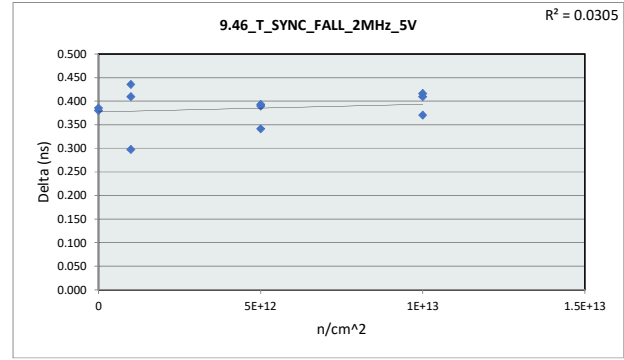


9.45_T_SYNC_RISE_2MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.667	7.479	7.535	7.682
Average	7.687	7.574	7.603	7.697
Max	7.706	7.642	7.661	7.709
UL	15.000	15.000	15.000	15.000

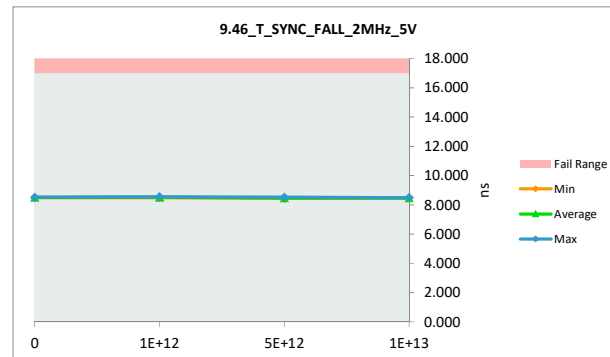


NDD Characterization Report TPS7H5006-SEP

9.46_T_SYNC_FALL_2MHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.094	8.479	0.385
0	49	8.144	8.524	0.380
1E+12	11	8.138	8.547	0.409
1E+12	12	8.187	8.484	0.297
1E+12	13	8.095	8.530	0.435
5E+12	14	8.071	8.464	0.393
5E+12	15	8.127	8.516	0.389
5E+12	16	8.092	8.433	0.341
1E+13	17	8.053	8.469	0.416
1E+13	18	8.093	8.463	0.370
1E+13	19	8.080	8.489	0.409
Max		8.187	8.547	0.435
Average		8.107	8.491	0.384
Min		8.053	8.433	0.297
Std Dev		0.038	0.035	0.038

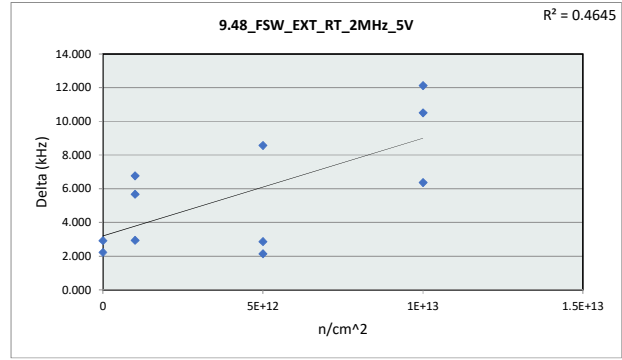


9.46_T_SYNC_FALL_2MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.479	8.484	8.433	8.463
Average	8.502	8.520	8.471	8.474
Max	8.524	8.547	8.516	8.489
UL	17.000	17.000	17.000	17.000

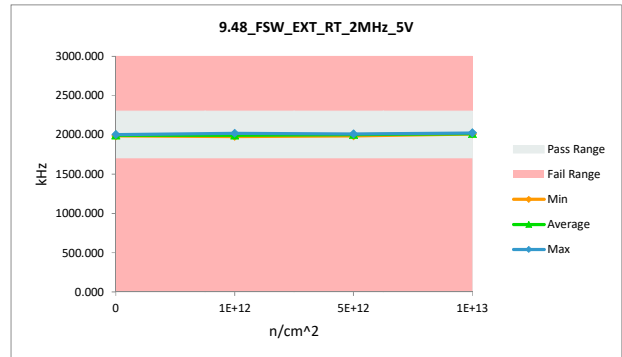


NDD Characterization Report TPS7H5006-SEP

9.48_FSW_EXT_RT_2MHz_5V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2002.150	2004.367	2.217
0	49	1983.602	1986.514	2.912
1E+12	11	1977.461	1980.395	2.934
1E+12	12	1984.282	1991.047	6.765
1E+12	13	2012.981	2018.650	5.669
5E+12	14	2006.776	2008.911	2.135
5E+12	15	1984.607	1987.462	2.855
5E+12	16	2003.388	2011.945	8.557
1E+13	17	1999.997	2012.114	12.117
1E+13	18	2018.828	2025.186	6.358
1E+13	19	1999.725	2010.220	10.495
Max		2018.828	2025.186	12.117
Average		1997.618	2003.346	5.729
Min		1977.461	1980.395	2.135
Std Dev		13.355	14.680	3.496

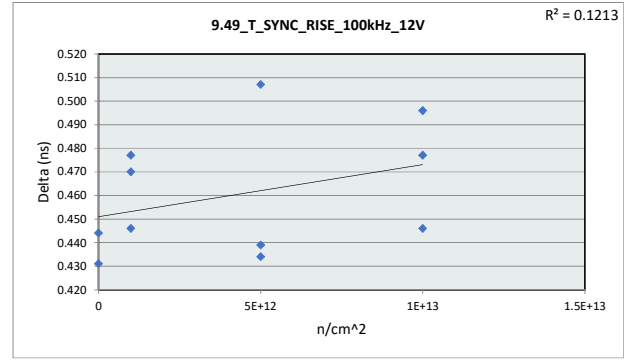


9.48_FSW_EXT_RT_2MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit		2300	kHz	
Min Limit		1700	kHz	
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1986.514	1980.395	1987.462	2010.220
Average	1995.441	1996.697	2002.773	2015.840
Max	2004.367	2018.650	2011.945	2025.186
UL	2300.000	2300.000	2300.000	2300.000

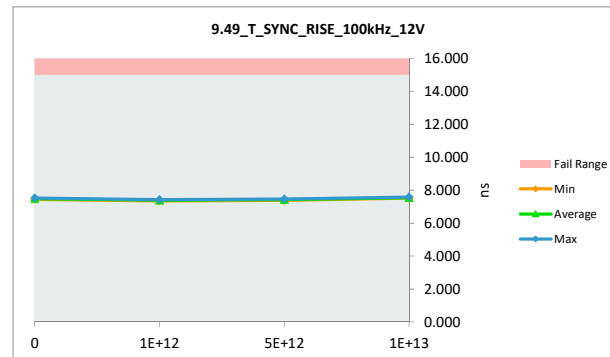


NDD Characterization Report TPS7H5006-SEP

9.49_T_SYNC_RISE_100kHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.015	7.446	0.431
0	49	7.086	7.530	0.444
1E+12	11	6.888	7.365	0.477
1E+12	12	6.906	7.352	0.446
1E+12	13	6.956	7.426	0.470
5E+12	14	7.039	7.473	0.434
5E+12	15	6.942	7.381	0.439
5E+12	16	6.954	7.461	0.507
1E+13	17	7.111	7.588	0.477
1E+13	18	7.075	7.521	0.446
1E+13	19	7.050	7.546	0.496
Max		7.111	7.588	0.507
Average		7.002	7.463	0.461
Min		6.888	7.352	0.431
Std Dev		0.076	0.078	0.026

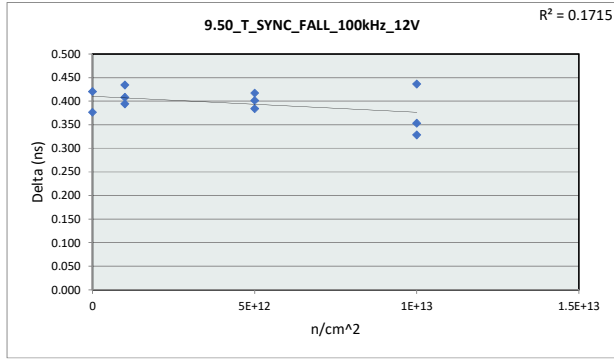


9.49_T_SYNC_RISE_100kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	7.446	7.352	7.381	7.521
Average	7.488	7.381	7.438	7.552
Max	7.530	7.426	7.473	7.588
UL	15.000	15.000	15.000	15.000

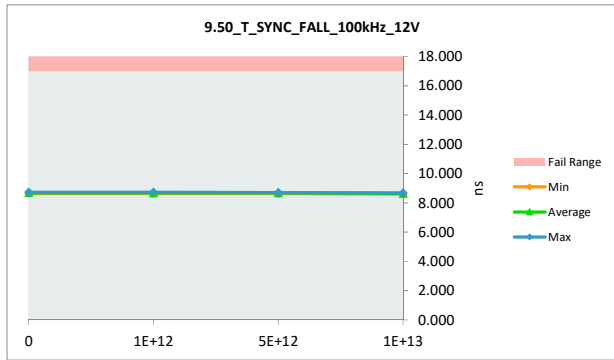


NDD Characterization Report TPS7H5006-SEP

9.50_T_SYNC_FALL_100kHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.309	8.729	0.420
0	49	8.263	8.639	0.376
1E+12	11	8.296	8.730	0.434
1E+12	12	8.267	8.675	0.408
1E+12	13	8.248	8.642	0.394
5E+12	14	8.252	8.636	0.384
5E+12	15	8.283	8.684	0.401
5E+12	16	8.285	8.702	0.417
1E+13	17	8.234	8.587	0.353
1E+13	18	8.242	8.678	0.436
1E+13	19	8.294	8.622	0.328
Max		8.309	8.730	0.436
Average		8.270	8.666	0.396
Min		8.234	8.587	0.328
Std Dev		0.025	0.045	0.034

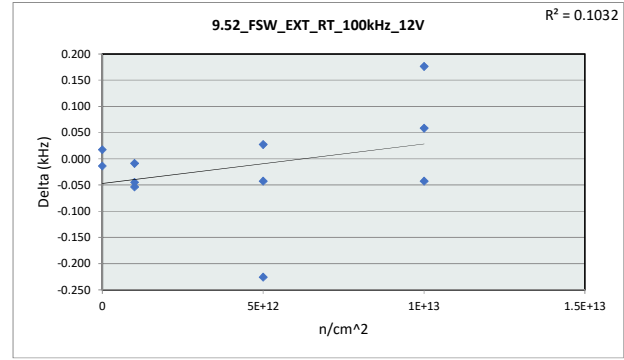


9.50_T_SYNC_FALL_100kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.639	8.642	8.636	8.587
Average	8.684	8.682	8.674	8.629
Max	8.729	8.730	8.702	8.678
UL	17.000	17.000	17.000	17.000

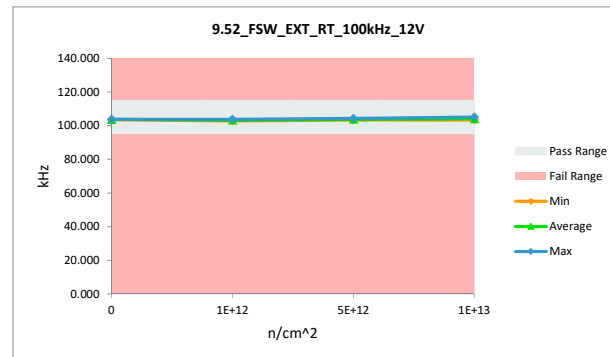


NDD Characterization Report TPS7H5006-SEP

9.52_FSW_EXT_RT_100kHz_12V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.832	103.818	-0.014
0	49	103.533	103.550	0.017
1E+12	11	103.113	103.104	-0.009
1E+12	12	102.888	102.843	-0.045
1E+12	13	103.835	103.781	-0.054
5E+12	14	103.706	103.480	-0.226
5E+12	15	103.558	103.585	0.027
5E+12	16	104.397	104.354	-0.043
1E+13	17	103.323	103.499	0.176
1E+13	18	103.540	103.598	0.058
1E+13	19	105.127	105.084	-0.043
Max		105.127	105.084	0.176
Average		103.714	103.700	-0.014
Min		102.888	102.843	-0.226
Std Dev		0.614	0.599	0.097

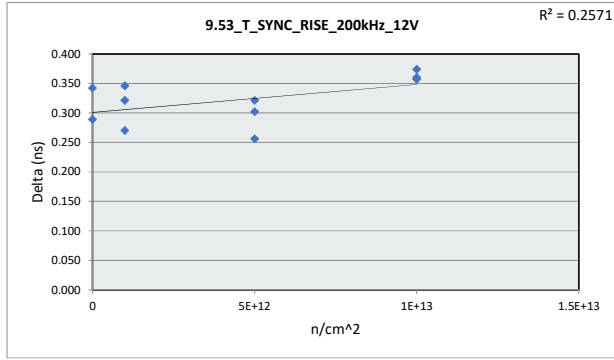


9.52_FSW_EXT_RT_100kHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.550	102.843	103.480	103.499
Average	103.684	103.243	103.806	104.060
Max	103.818	103.781	104.354	105.084
UL	115.000	115.000	115.000	115.000

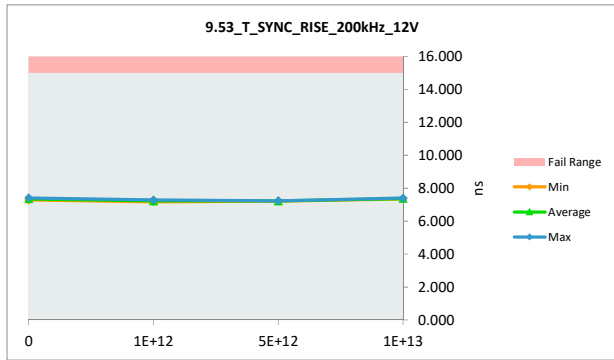


NDD Characterization Report TPS7H5006-SEP

9.53_T_SYNC_RISE_200kHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.992	7.281	0.289
0	49	7.069	7.411	0.342
1E+12	11	6.906	7.176	0.270
1E+12	12	6.870	7.216	0.346
1E+12	13	6.964	7.285	0.321
5E+12	14	6.982	7.238	0.256
5E+12	15	6.889	7.210	0.321
5E+12	16	6.926	7.228	0.302
1E+13	17	7.019	7.393	0.374
1E+13	18	7.017	7.377	0.360
1E+13	19	6.992	7.349	0.357
Max		7.069	7.411	0.374
Average		6.966	7.288	0.322
Min		6.870	7.176	0.256
Std Dev		0.062	0.082	0.039

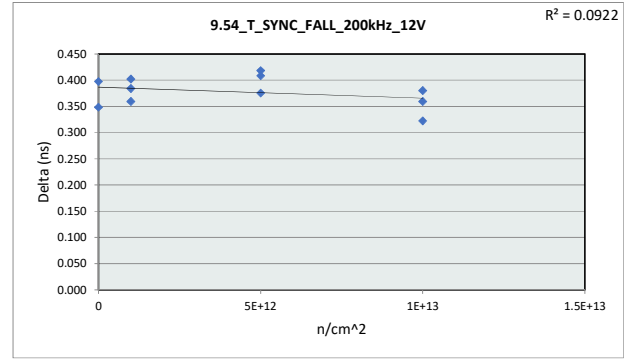


9.53_T_SYNC_RISE_200kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.281	7.176	7.210	7.349
Average	7.346	7.226	7.225	7.373
Max	7.411	7.285	7.238	7.393
UL	15.000	15.000	15.000	15.000

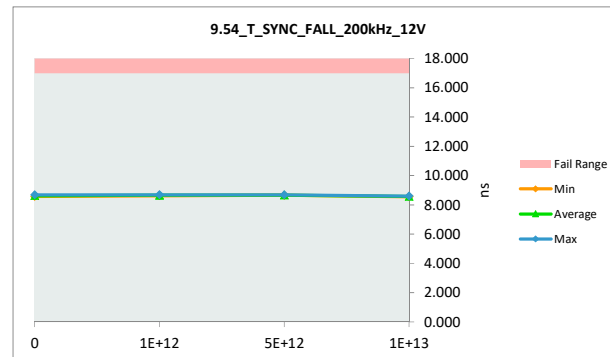


NDD Characterization Report TPS7H5006-SEP

9.54_T_SYNC_FALL_200kHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.285	8.682	0.397
0	49	8.229	8.577	0.348
1E+12	11	8.306	8.690	0.384
1E+12	12	8.272	8.631	0.359
1E+12	13	8.237	8.639	0.402
5E+12	14	8.258	8.676	0.418
5E+12	15	8.244	8.652	0.408
5E+12	16	8.284	8.659	0.375
1E+13	17	8.225	8.605	0.380
1E+13	18	8.204	8.563	0.359
1E+13	19	8.235	8.557	0.322
Max		8.306	8.690	0.418
Average		8.253	8.630	0.377
Min		8.204	8.557	0.322
Std Dev		0.031	0.048	0.029

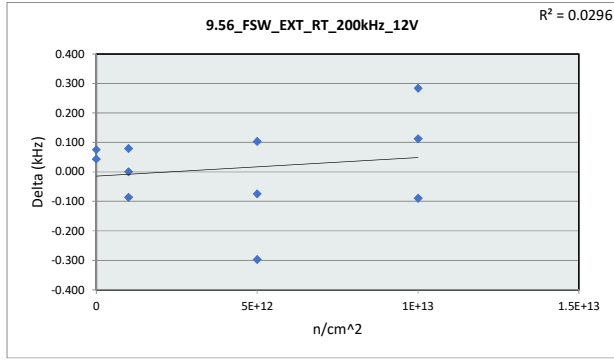


9.54_T_SYNC_FALL_200kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	17			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.577	8.631	8.652	8.557
Average	8.630	8.653	8.662	8.575
Max	8.682	8.690	8.676	8.605
UL	17.000	17.000	17.000	17.000

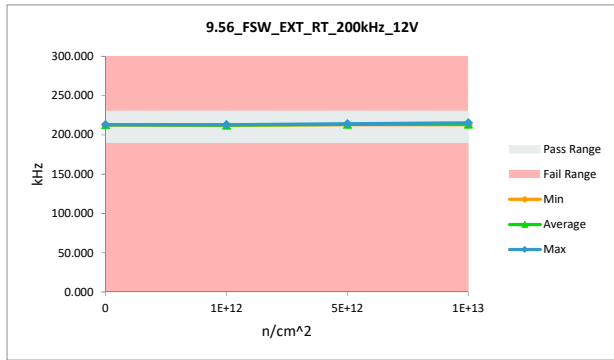


NDD Characterization Report TPS7H5006-SEP

9.56_FSW_EXT_RT_200kHz_12V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	212.955	212.998	0.043
0	49	212.662	212.737	0.075
1E+12	11	211.950	212.029	0.079
1E+12	12	212.027	212.027	0.000
1E+12	13	213.221	213.134	-0.087
5E+12	14	213.081	212.783	-0.298
5E+12	15	212.738	212.841	0.103
5E+12	16	214.158	214.083	-0.075
1E+13	17	212.663	212.946	0.283
1E+13	18	212.770	212.882	0.112
1E+13	19	215.310	215.220	-0.090
Max		215.310	215.220	0.283
Average		213.049	213.062	0.013
Min		211.950	212.027	-0.298
Std Dev		0.954	0.901	0.150

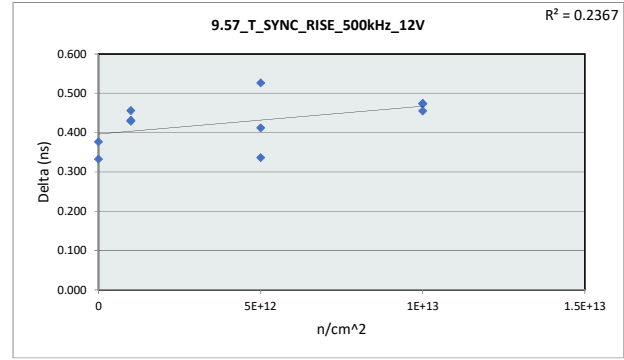


9.56_FSW_EXT_RT_200kHz_12V				
Test Site				
Tester				
Test Number				
Max Limit		230	kHz	
Min Limit		190	kHz	
n/cm ²	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	212.737	212.027	212.783	212.882
Average	212.868	212.397	213.236	213.683
Max	212.998	213.134	214.083	215.220
UL	230.000	230.000	230.000	230.000

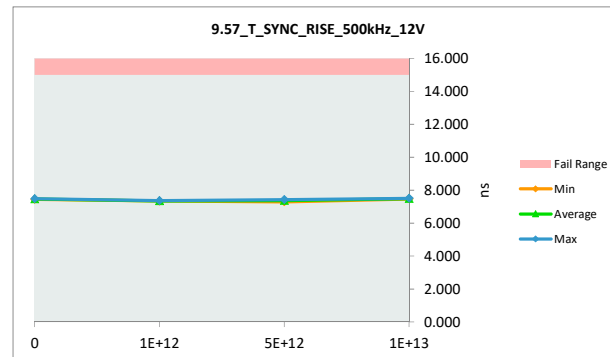


NDD Characterization Report TPS7H5006-SEP

9.57_T_SYNC_RISE_500kHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.072	7.448	0.376
0	49	7.153	7.485	0.332
1E+12	11	6.885	7.341	0.456
1E+12	12	6.935	7.364	0.429
1E+12	13	6.937	7.368	0.431
5E+12	14	7.023	7.435	0.412
5E+12	15	6.957	7.293	0.336
5E+12	16	6.887	7.413	0.526
1E+13	17	7.002	7.475	0.473
1E+13	18	7.059	7.514	0.455
1E+13	19	7.001	7.475	0.474
Max		7.153	7.514	0.526
Average		6.992	7.419	0.427
Min		6.885	7.293	0.332
Std Dev		0.082	0.070	0.060

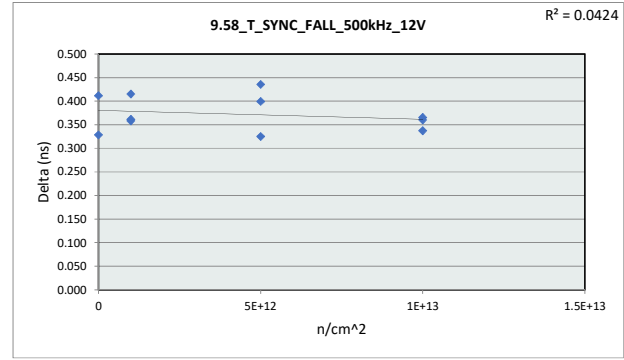


9.57_T_SYNC_RISE_500kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.448	7.341	7.293	7.475
Average	7.467	7.358	7.380	7.488
Max	7.485	7.368	7.435	7.514
UL	15.000	15.000	15.000	15.000

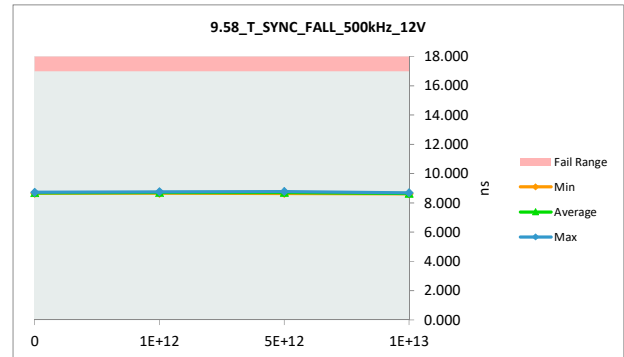


NDD Characterization Report TPS7H5006-SEP

9.58_T_SYNC_FALL_500kHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.391	8.719	0.328
0	49	8.238	8.649	0.411
1E+12	11	8.343	8.758	0.415
1E+12	12	8.319	8.680	0.361
1E+12	13	8.298	8.656	0.358
5E+12	14	8.308	8.633	0.325
5E+12	15	8.337	8.736	0.399
5E+12	16	8.333	8.768	0.435
1E+13	17	8.276	8.613	0.337
1E+13	18	8.285	8.650	0.365
1E+13	19	8.313	8.673	0.360
Max		8.391	8.768	0.435
Average		8.313	8.685	0.372
Min		8.238	8.613	0.325
Std Dev		0.040	0.052	0.037

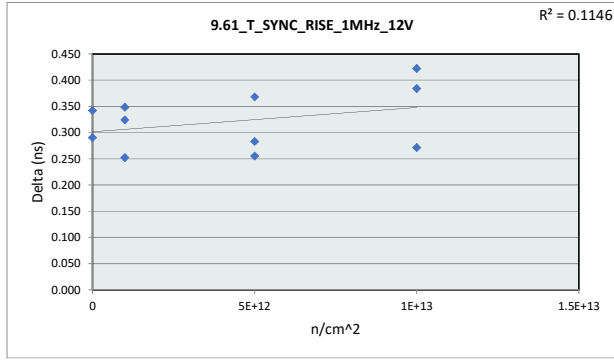


9.58_T_SYNC_FALL_500kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	17			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.649	8.656	8.633	8.613
Average	8.684	8.698	8.712	8.645
Max	8.719	8.758	8.768	8.673
UL	17.000	17.000	17.000	17.000

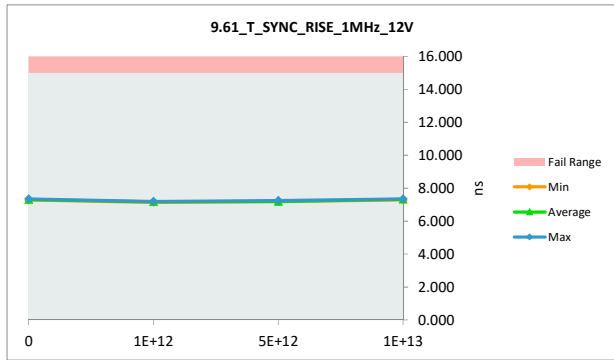


NDD Characterization Report TPS7H5006-SEP

9.61_T_SYNC_RISE_1MHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.942	7.284	0.342
0	49	7.067	7.357	0.290
1E+12	11	6.791	7.139	0.348
1E+12	12	6.859	7.183	0.324
1E+12	13	6.950	7.202	0.252
5E+12	14	6.986	7.241	0.255
5E+12	15	6.821	7.189	0.368
5E+12	16	6.903	7.186	0.283
1E+13	17	7.010	7.281	0.271
1E+13	18	6.963	7.347	0.384
1E+13	19	6.919	7.341	0.422
Max		7.067	7.357	0.422
Average		6.928	7.250	0.322
Min		6.791	7.139	0.252
Std Dev		0.082	0.076	0.056

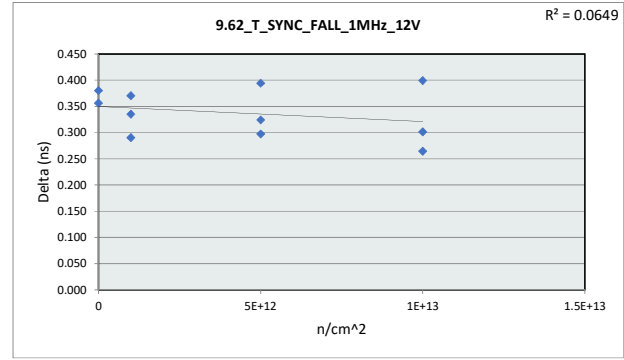


9.61_T_SYNC_RISE_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.284	7.139	7.186	7.281
Average	7.321	7.175	7.205	7.323
Max	7.357	7.202	7.241	7.347
UL	15.000	15.000	15.000	15.000

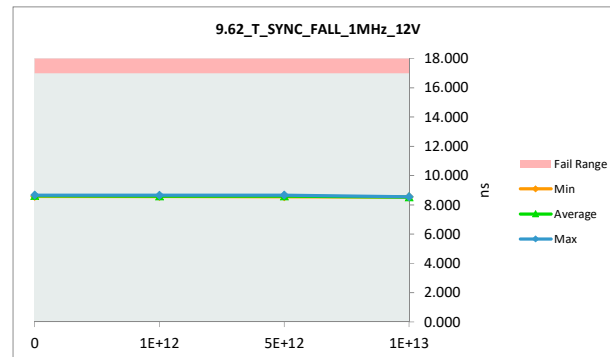


NDD Characterization Report TPS7H5006-SEP

9.62_T_SYNC_FALL_1MHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.279	8.659	0.380
0	49	8.233	8.589	0.356
1E+12	11	8.286	8.656	0.370
1E+12	12	8.250	8.585	0.335
1E+12	13	8.280	8.570	0.290
5E+12	14	8.278	8.575	0.297
5E+12	15	8.265	8.659	0.394
5E+12	16	8.222	8.546	0.324
1E+13	17	8.138	8.537	0.399
1E+13	18	8.265	8.529	0.264
1E+13	19	8.246	8.547	0.301
Max		8.286	8.659	0.399
Average		8.249	8.587	0.337
Min		8.138	8.529	0.264
Std Dev		0.042	0.050	0.046

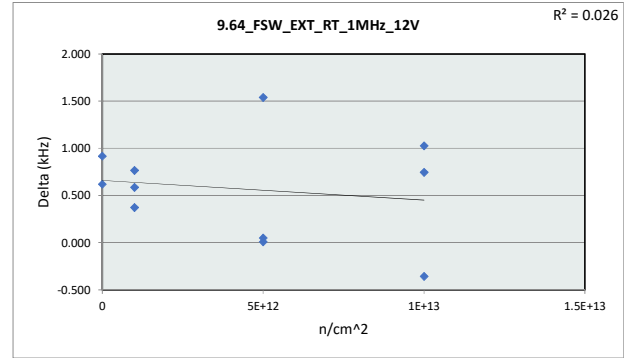


9.62_T_SYNC_FALL_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	8.589	8.570	8.546	8.529
Average	8.624	8.604	8.593	8.538
Max	8.659	8.656	8.659	8.547
UL	17.000	17.000	17.000	17.000

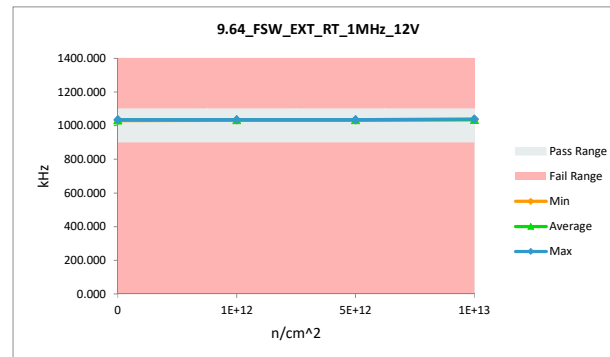


NDD Characterization Report TPS7H5006-SEP

9.64_FSW_EXT_RT_1MHz_12V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1030.177	1030.794	0.617
0	49	1035.219	1036.134	0.915
1E+12	11	1031.892	1032.655	0.763
1E+12	12	1034.282	1034.867	0.585
1E+12	13	1035.204	1035.576	0.372
5E+12	14	1032.655	1032.702	0.047
5E+12	15	1034.247	1035.784	1.537
5E+12	16	1036.072	1036.079	0.007
1E+13	17	1034.408	1035.152	0.744
1E+13	18	1034.094	1035.119	1.025
1E+13	19	1039.002	1038.642	-0.360
Max		1039.002	1038.642	1.537
Average		1034.296	1034.864	0.568
Min		1030.177	1030.794	-0.360
Std Dev		2.291	2.121	0.532

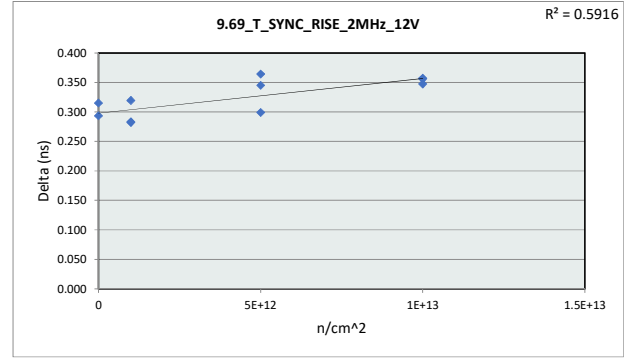


9.64_FSW_EXT_RT_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1030.794	1032.655	1032.702	1035.119
Average	1033.464	1034.366	1034.855	1036.304
Max	1036.134	1035.576	1036.079	1038.642
UL	1100.000	1100.000	1100.000	1100.000

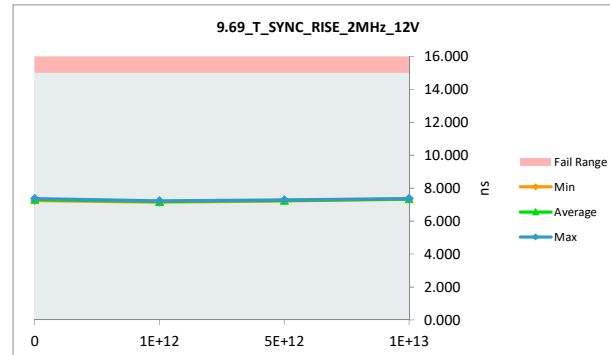


NDD Characterization Report TPS7H5006-SEP

9.69_T_SYNC_RISE_2MHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.946	7.261	0.315
0	49	7.083	7.376	0.293
1E+12	11	6.866	7.148	0.282
1E+12	12	6.860	7.179	0.319
1E+12	13	6.956	7.239	0.283
5E+12	14	6.934	7.298	0.364
5E+12	15	6.883	7.228	0.345
5E+12	16	6.955	7.254	0.299
1E+13	17	7.013	7.369	0.356
1E+13	18	7.000	7.347	0.347
1E+13	19	6.980	7.337	0.357
Max		7.083	7.376	0.364
Average		6.952	7.276	0.324
Min		6.860	7.148	0.282
Std Dev		0.067	0.076	0.031

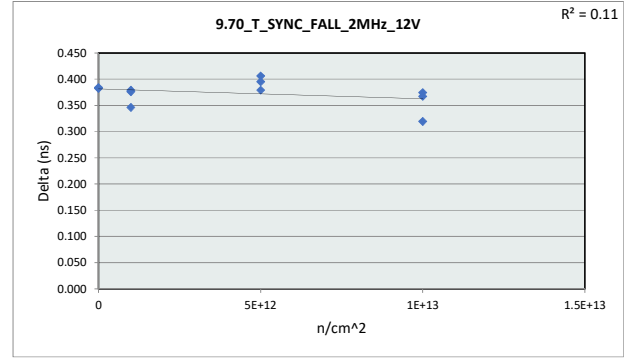


9.69_T_SYNC_RISE_2MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.261	7.148	7.228	7.337
Average	7.319	7.189	7.260	7.351
Max	7.376	7.239	7.298	7.369
UL	15.000	15.000	15.000	15.000

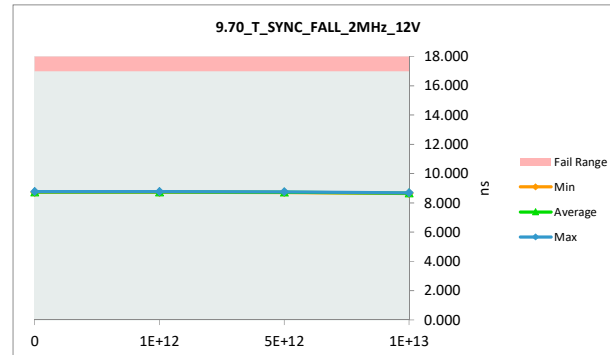


NDD Characterization Report TPS7H5006-SEP

9.70_T_SYNC_FALL_2MHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.382	8.766	0.384
0	49	8.337	8.719	0.382
1E+12	11	8.422	8.768	0.346
1E+12	12	8.342	8.718	0.376
1E+12	13	8.355	8.734	0.379
5E+12	14	8.323	8.702	0.379
5E+12	15	8.345	8.751	0.406
5E+12	16	8.349	8.744	0.395
1E+13	17	8.328	8.647	0.319
1E+13	18	8.320	8.687	0.367
1E+13	19	8.308	8.682	0.374
Max		8.422	8.768	0.406
Average		8.346	8.720	0.373
Min		8.308	8.647	0.319
Std Dev		0.032	0.038	0.024

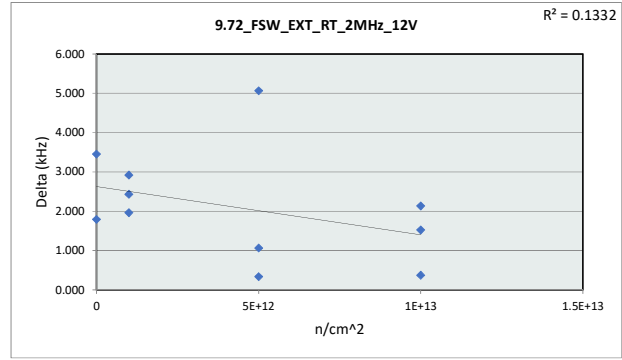


9.70_T_SYNC_FALL_2MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.719	8.718	8.702	8.647
Average	8.743	8.740	8.732	8.672
Max	8.766	8.768	8.751	8.687
UL	17.000	17.000	17.000	17.000

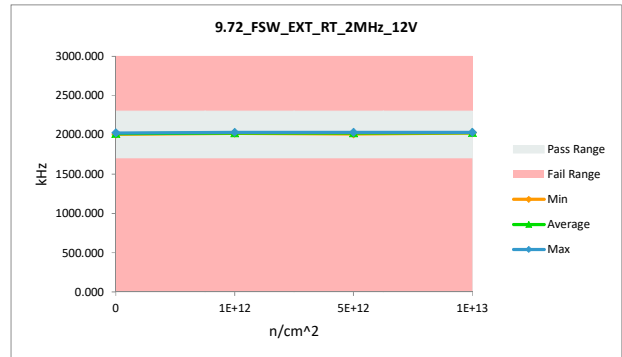


NDD Characterization Report TPS7H5006-SEP

9.72_FSW_EXT_RT_2MHz_12V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2006.342	2008.131	1.789
0	49	2021.882	2025.330	3.448
1E+12	11	2014.990	2017.418	2.428
1E+12	12	2019.835	2022.752	2.917
1E+12	13	2028.171	2030.128	1.957
5E+12	14	2012.140	2012.471	0.331
5E+12	15	2023.236	2028.296	5.060
5E+12	16	2029.798	2030.859	1.061
1E+13	17	2026.866	2028.387	1.521
1E+13	18	2022.649	2024.778	2.129
1E+13	19	2029.341	2029.709	0.368
Max		2029.798	2030.859	5.060
Average		2021.386	2023.478	2.092
Min		2006.342	2008.131	0.331
Std Dev		7.553	7.641	1.379

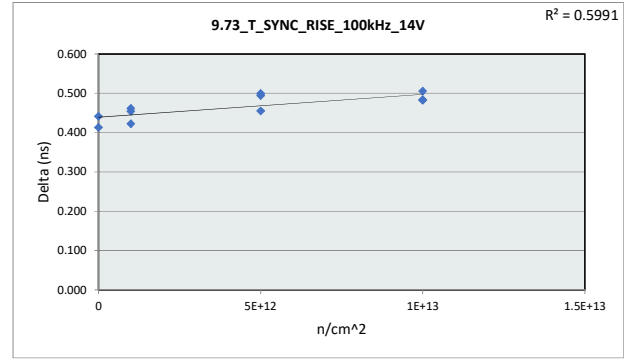


9.72_FSW_EXT_RT_2MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	2008.131	2017.418	2012.471	2024.778
Average	2016.731	2023.433	2023.875	2027.625
Max	2025.330	2030.128	2030.859	2029.709
UL	2300.000	2300.000	2300.000	2300.000

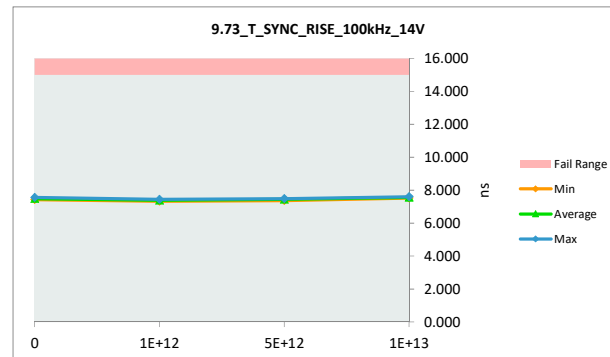


NDD Characterization Report TPS7H5006-SEP

9.73_T_SYNC_RISE_100kHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.019	7.432	0.413
0	49	7.117	7.558	0.441
1E+12	11	6.916	7.377	0.461
1E+12	12	6.911	7.333	0.422
1E+12	13	6.995	7.449	0.454
5E+12	14	7.003	7.497	0.494
5E+12	15	6.920	7.375	0.455
5E+12	16	6.963	7.462	0.499
1E+13	17	7.124	7.606	0.482
1E+13	18	7.044	7.527	0.483
1E+13	19	7.067	7.572	0.505
Max		7.124	7.606	0.505
Average		7.007	7.472	0.464
Min		6.911	7.333	0.413
Std Dev		0.076	0.089	0.031

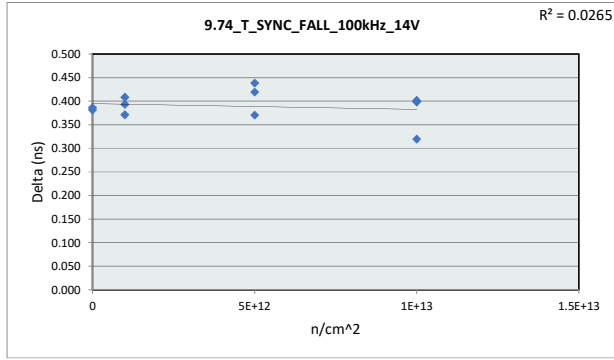


9.73_T_SYNC_RISE_100kHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.432	7.333	7.375	7.527
Average	7.495	7.386	7.445	7.568
Max	7.558	7.449	7.497	7.606
UL	15.000	15.000	15.000	15.000

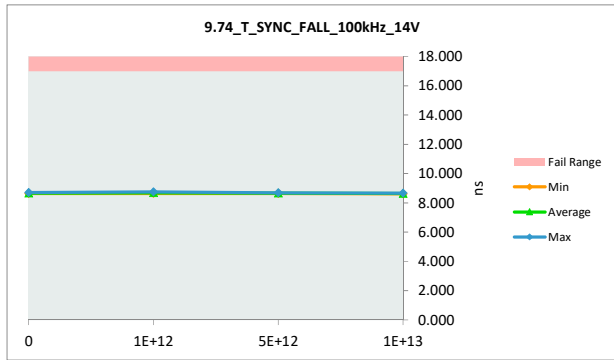


NDD Characterization Report TPS7H5006-SEP

9.74_T_SYNC_FALL_100kHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.316	8.697	0.381
0	49	8.246	8.632	0.386
1E+12	11	8.339	8.747	0.408
1E+12	12	8.288	8.659	0.371
1E+12	13	8.256	8.649	0.393
5E+12	14	8.267	8.637	0.370
5E+12	15	8.257	8.695	0.438
5E+12	16	8.241	8.660	0.419
1E+13	17	8.296	8.615	0.319
1E+13	18	8.225	8.626	0.401
1E+13	19	8.262	8.660	0.398
Max		8.339	8.747	0.438
Average		8.272	8.662	0.389
Min		8.225	8.615	0.319
Std Dev		0.034	0.038	0.031

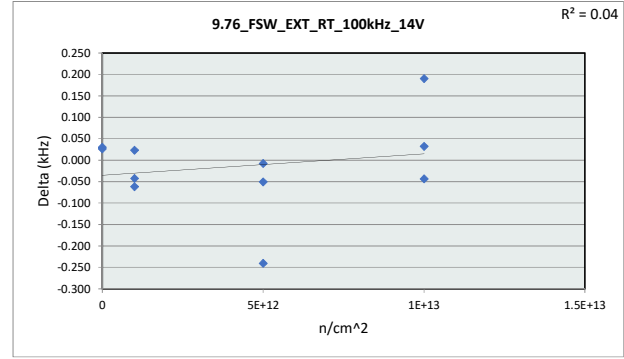


9.74_T_SYNC_FALL_100kHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.632	8.649	8.637	8.615
Average	8.665	8.685	8.664	8.634
Max	8.697	8.747	8.695	8.660
UL	17.000	17.000	17.000	17.000

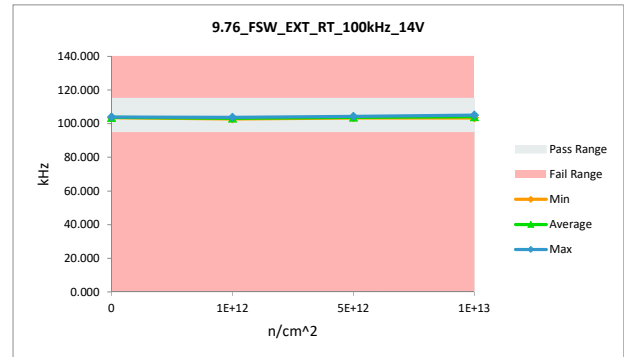


NDD Characterization Report TPS7H5006-SEP

9.76_FSW_EXT_RT_100kHz_14V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.821	103.847	0.026
0	49	103.521	103.551	0.030
1E+12	11	103.112	103.135	0.023
1E+12	12	102.860	102.817	-0.043
1E+12	13	103.841	103.779	-0.062
5E+12	14	103.702	103.461	-0.241
5E+12	15	103.564	103.556	-0.008
5E+12	16	104.393	104.342	-0.051
1E+13	17	103.301	103.491	0.190
1E+13	18	103.557	103.589	0.032
1E+13	19	105.114	105.070	-0.044
Max		105.114	105.070	0.190
Average		103.708	103.694	-0.013
Min		102.860	102.817	-0.241
Std Dev		0.616	0.598	0.103

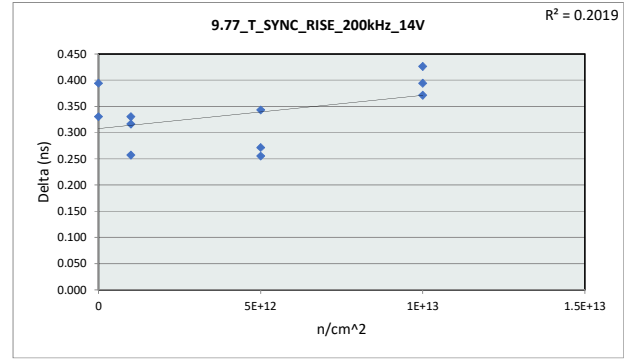


9.76_FSW_EXT_RT_100kHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.551	102.817	103.461	103.491
Average	103.699	103.244	103.786	104.050
Max	103.847	103.779	104.342	105.070
UL	115.000	115.000	115.000	115.000

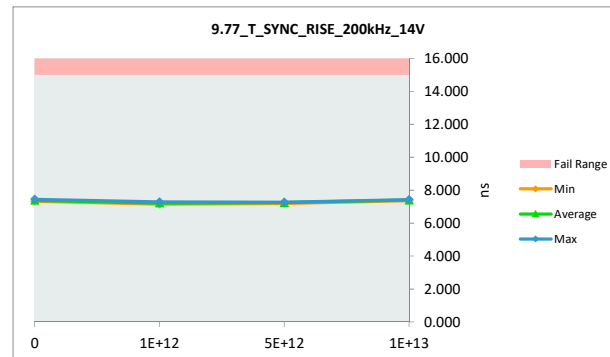


NDD Characterization Report TPS7H5006-SEP

9.77_T_SYNC_RISE_200kHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.001	7.331	0.330
0	49	7.059	7.453	0.394
1E+12	11	6.899	7.156	0.257
1E+12	12	6.876	7.206	0.330
1E+12	13	6.974	7.290	0.316
5E+12	14	7.002	7.273	0.271
5E+12	15	6.939	7.194	0.255
5E+12	16	6.933	7.276	0.343
1E+13	17	6.994	7.388	0.394
1E+13	18	7.003	7.429	0.426
1E+13	19	7.007	7.378	0.371
Max		7.059	7.453	0.426
Average		6.972	7.307	0.335
Min		6.876	7.156	0.255
Std Dev		0.054	0.098	0.058

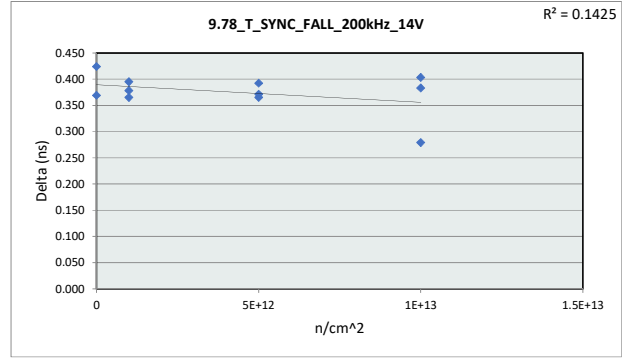


9.77_T_SYNC_RISE_200kHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.331	7.156	7.194	7.378
Average	7.392	7.217	7.248	7.398
Max	7.453	7.290	7.276	7.429
UL	15.000	15.000	15.000	15.000

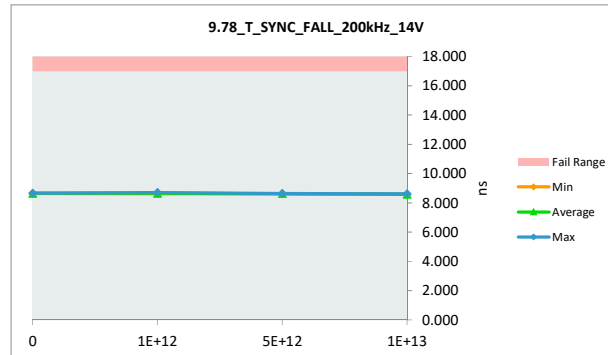


NDD Characterization Report TPS7H5006-SEP

9.78_T_SYNC_FALL_200kHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.281	8.650	0.369
0	49	8.230	8.654	0.424
1E+12	11	8.302	8.697	0.395
1E+12	12	8.271	8.636	0.365
1E+12	13	8.234	8.612	0.378
5E+12	14	8.243	8.635	0.392
5E+12	15	8.246	8.617	0.371
5E+12	16	8.249	8.614	0.365
1E+13	17	8.191	8.574	0.383
1E+13	18	8.303	8.582	0.279
1E+13	19	8.204	8.607	0.403
Max		8.303	8.697	0.424
Average		8.250	8.625	0.375
Min		8.191	8.574	0.279
Std Dev		0.036	0.035	0.037

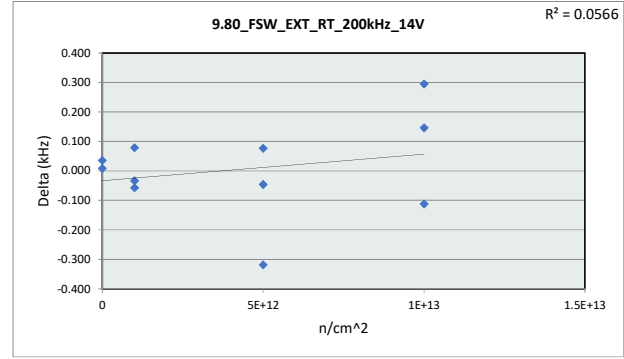


9.78_T_SYNC_FALL_200kHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.650	8.612	8.614	8.574
Average	8.652	8.648	8.622	8.588
Max	8.654	8.697	8.635	8.607
UL	17.000	17.000	17.000	17.000

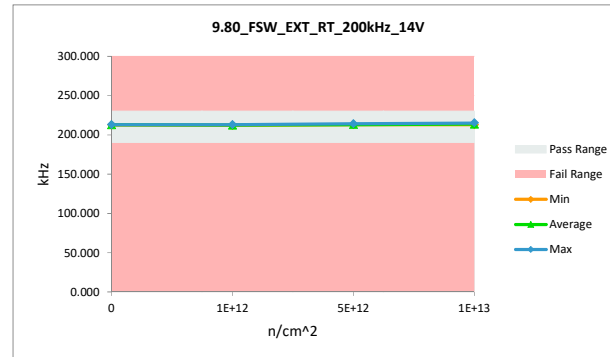


NDD Characterization Report TPS7H5006-SEP

9.80_FSW_EXT_RT_200kHz_14V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	212.997	213.005	0.008
0	49	212.661	212.696	0.035
1E+12	11	211.958	212.036	0.078
1E+12	12	212.011	211.977	-0.034
1E+12	13	213.187	213.129	-0.058
5E+12	14	213.069	212.750	-0.319
5E+12	15	212.733	212.809	0.076
5E+12	16	214.125	214.079	-0.046
1E+13	17	212.638	212.932	0.294
1E+13	18	212.730	212.876	0.146
1E+13	19	215.317	215.204	-0.113
Max		215.317	215.204	0.294
Average		213.039	213.045	0.006
Min		211.958	211.977	-0.319
Std Dev		0.955	0.906	0.155

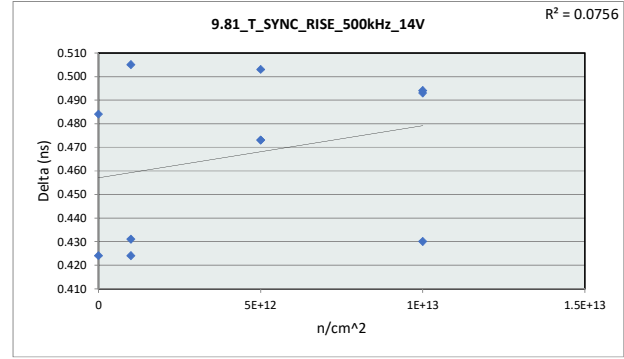


9.80_FSW_EXT_RT_200kHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm ²	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	212.696	211.977	212.750	212.876
Average	212.851	212.381	213.213	213.671
Max	213.005	213.129	214.079	215.204
UL	230.000	230.000	230.000	230.000

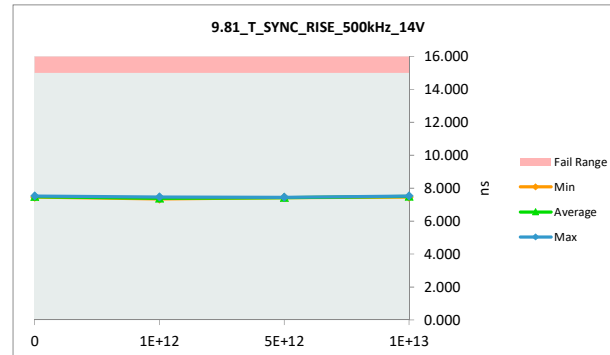


NDD Characterization Report TPS7H5006-SEP

9.81_T_SYNC_RISE_500kHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		15
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.971	7.455	0.484
0	49	7.100	7.524	0.424
1E+12	11	6.911	7.342	0.431
1E+12	12	6.920	7.344	0.424
1E+12	13	6.958	7.463	0.505
5E+12	14	6.982	7.455	0.473
5E+12	15	6.958	7.431	0.473
5E+12	16	6.920	7.423	0.503
1E+13	17	7.030	7.523	0.493
1E+13	18	7.032	7.462	0.430
1E+13	19	7.029	7.523	0.494
Max		7.100	7.524	0.505
Average		6.983	7.450	0.467
Min		6.911	7.342	0.424
Std Dev		0.059	0.064	0.033

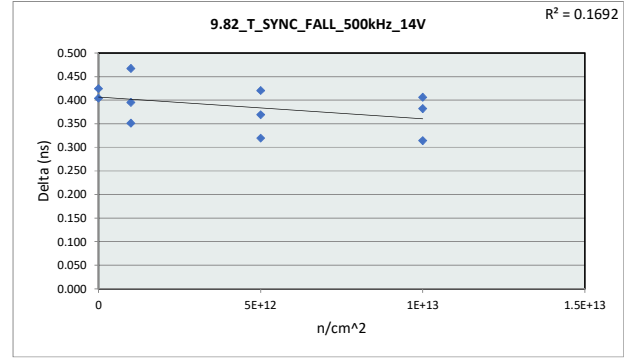


9.81_T_SYNC_RISE_500kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	15			ns
Min Limit				ns
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.455	7.342	7.423	7.462
Average	7.490	7.383	7.436	7.503
Max	7.524	7.463	7.455	7.523
UL	15.000	15.000	15.000	15.000

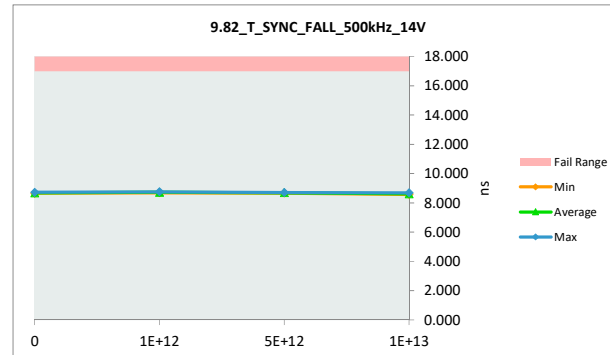


NDD Characterization Report TPS7H5006-SEP

9.82_T_SYNC_FALL_500kHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.289	8.713	0.424
0	49	8.244	8.648	0.404
1E+12	11	8.356	8.751	0.395
1E+12	12	8.334	8.685	0.351
1E+12	13	8.250	8.717	0.467
5E+12	14	8.298	8.667	0.369
5E+12	15	8.289	8.709	0.420
5E+12	16	8.385	8.704	0.319
1E+13	17	8.218	8.600	0.382
1E+13	18	8.265	8.579	0.314
1E+13	19	8.267	8.673	0.406
Max		8.385	8.751	0.467
Average		8.290	8.677	0.386
Min		8.218	8.579	0.314
Std Dev		0.050	0.052	0.046

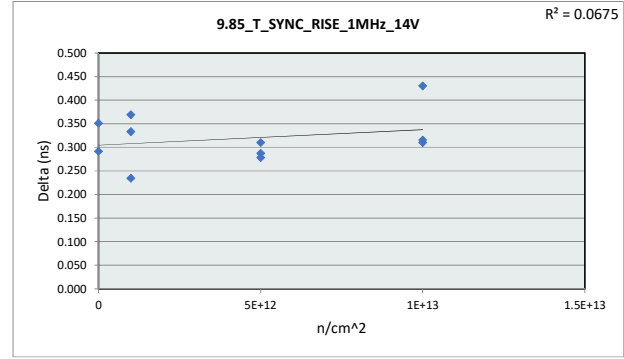


9.82_T_SYNC_FALL_500kHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.648	8.685	8.667	8.579
Average	8.681	8.718	8.693	8.617
Max	8.713	8.751	8.709	8.673
UL	17.000	17.000	17.000	17.000

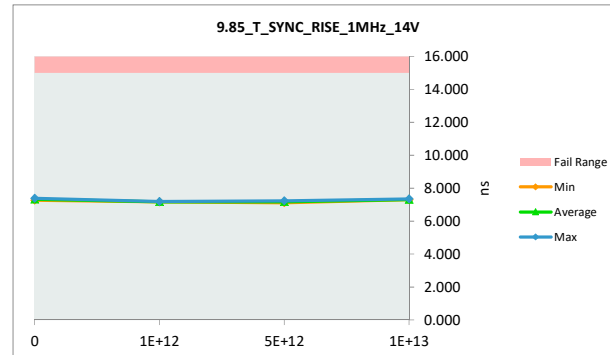


NDD Characterization Report TPS7H5006-SEP

9.85_T_SYNC_RISE_1MHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.976	7.267	0.291
0	49	7.040	7.391	0.351
1E+12	11	6.827	7.160	0.333
1E+12	12	6.823	7.192	0.369
1E+12	13	6.955	7.189	0.234
5E+12	14	6.929	7.239	0.310
5E+12	15	6.844	7.122	0.278
5E+12	16	6.888	7.175	0.287
1E+13	17	6.925	7.355	0.430
1E+13	18	6.995	7.305	0.310
1E+13	19	6.988	7.303	0.315
Max		7.040	7.391	0.430
Average		6.926	7.245	0.319
Min		6.823	7.122	0.234
Std Dev		0.073	0.086	0.052

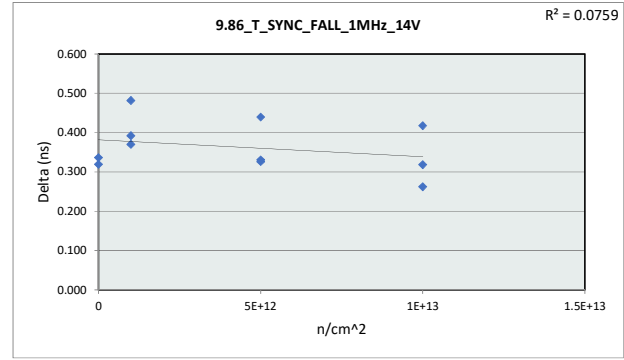


9.85_T_SYNC_RISE_1MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.267	7.160	7.122	7.303
Average	7.329	7.180	7.179	7.321
Max	7.391	7.192	7.239	7.355
UL	15.000	15.000	15.000	15.000

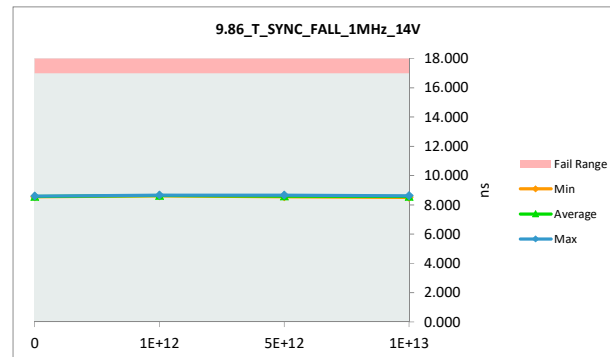


NDD Characterization Report TPS7H5006-SEP

9.86_T_SYNC_FALL_1MHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.281	8.600	0.319
0	49	8.214	8.550	0.336
1E+12	11	8.266	8.658	0.392
1E+12	12	8.238	8.608	0.370
1E+12	13	8.176	8.657	0.481
5E+12	14	8.264	8.594	0.330
5E+12	15	8.223	8.662	0.439
5E+12	16	8.220	8.546	0.326
1E+13	17	8.257	8.519	0.262
1E+13	18	8.213	8.630	0.417
1E+13	19	8.236	8.554	0.318
Max		8.281	8.662	0.481
Average		8.235	8.598	0.363
Min		8.176	8.519	0.262
Std Dev		0.030	0.051	0.064

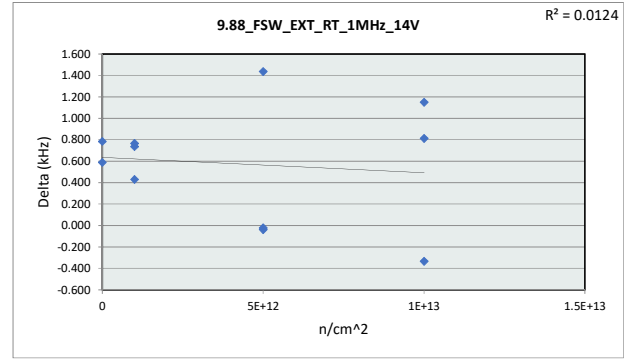


9.86_T_SYNC_FALL_1MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.550	8.608	8.546	8.519
Average	8.575	8.641	8.601	8.568
Max	8.600	8.658	8.662	8.630
UL	17.000	17.000	17.000	17.000

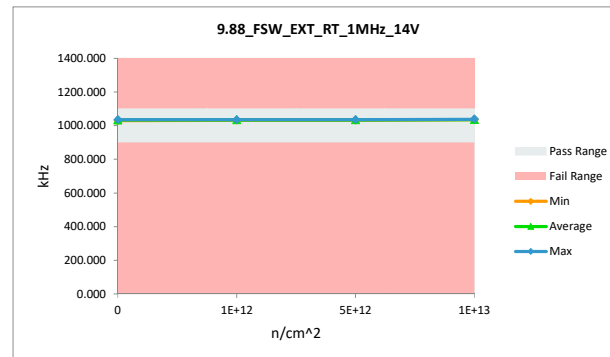


NDD Characterization Report TPS7H5006-SEP

9.88_FSW_EXT_RT_1MHz_14V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1030.166	1030.754	0.588
0	49	1035.121	1035.903	0.782
1E+12	11	1031.878	1032.612	0.734
1E+12	12	1034.107	1034.872	0.765
1E+12	13	1035.096	1035.525	0.429
5E+12	14	1032.672	1032.632	-0.040
5E+12	15	1034.310	1035.745	1.435
5E+12	16	1036.098	1036.075	-0.023
1E+13	17	1034.287	1035.099	0.812
1E+13	18	1033.989	1035.138	1.149
1E+13	19	1038.878	1038.543	-0.335
Max		1038.878	1038.543	1.435
Average		1034.237	1034.809	0.572
Min		1030.166	1030.754	-0.335
Std Dev		2.263	2.106	0.531

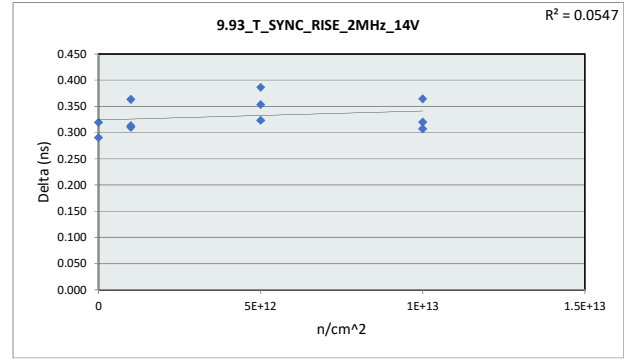


9.88_FSW_EXT_RT_1MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1030.754	1032.612	1032.632	1035.099
Average	1033.329	1034.336	1034.817	1036.260
Max	1035.903	1035.525	1036.075	1038.543
UL	1100.000	1100.000	1100.000	1100.000

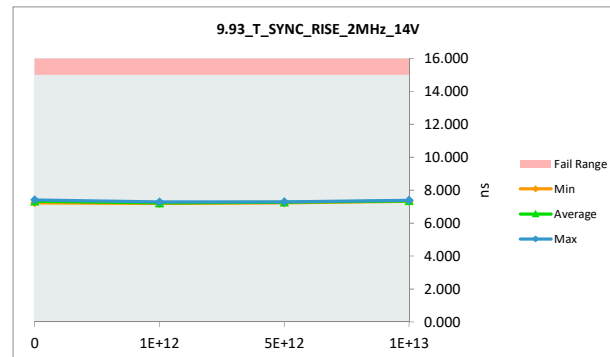


NDD Characterization Report TPS7H5006-SEP

9.93_T_SYNC_RISE_2MHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.950	7.240	0.290
0	49	7.088	7.407	0.319
1E+12	11	6.829	7.192	0.363
1E+12	12	6.887	7.200	0.313
1E+12	13	6.971	7.281	0.310
5E+12	14	6.921	7.274	0.353
5E+12	15	6.905	7.228	0.323
5E+12	16	6.906	7.292	0.386
1E+13	17	7.022	7.386	0.364
1E+13	18	7.017	7.324	0.307
1E+13	19	7.029	7.349	0.320
Max		7.088	7.407	0.386
Average		6.957	7.288	0.332
Min		6.829	7.192	0.290
Std Dev		0.076	0.072	0.030

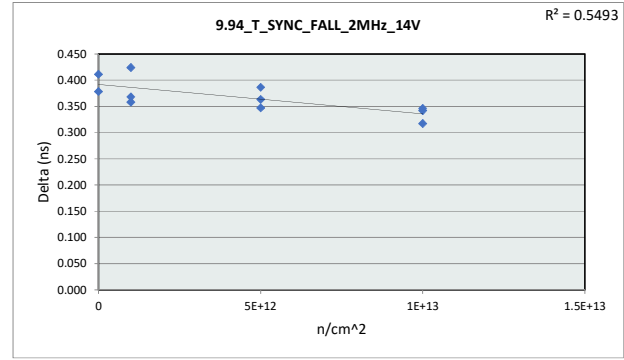


9.93_T_SYNC_RISE_2MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.240	7.192	7.228	7.324
Average	7.324	7.224	7.265	7.353
Max	7.407	7.281	7.292	7.386
UL	15.000	15.000	15.000	15.000

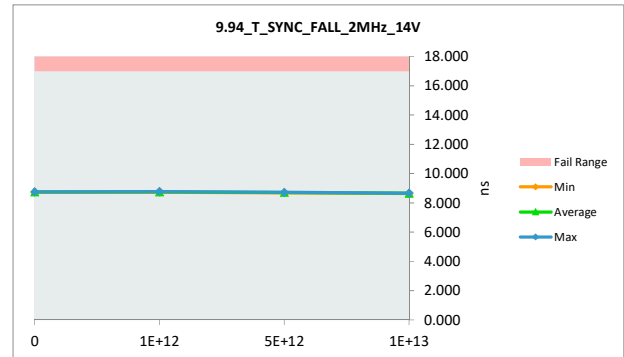


NDD Characterization Report TPS7H5006-SEP

9.94_T_SYNC_FALL_2MHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		14		17
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.338	8.749	0.411
0	49	8.351	8.729	0.378
1E+12	11	8.418	8.776	0.358
1E+12	12	8.360	8.728	0.368
1E+12	13	8.309	8.733	0.424
5E+12	14	8.309	8.695	0.386
5E+12	15	8.360	8.723	0.363
5E+12	16	8.333	8.680	0.347
1E+13	17	8.307	8.649	0.342
1E+13	18	8.317	8.663	0.346
1E+13	19	8.335	8.652	0.317
Max		8.418	8.776	0.424
Average		8.340	8.707	0.367
Min		8.307	8.649	0.317
Std Dev		0.033	0.042	0.031

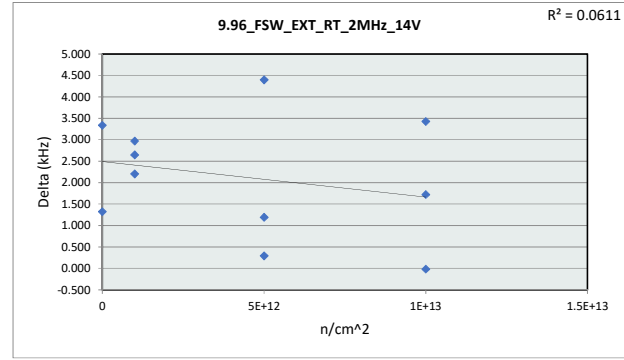


9.94_T_SYNC_FALL_2MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit			ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.729	8.728	8.680	8.649
Average	8.739	8.746	8.699	8.655
Max	8.749	8.776	8.723	8.663
UL	17.000	17.000	17.000	17.000

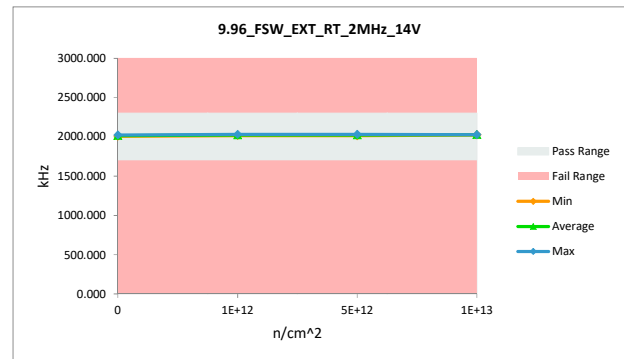


NDD Characterization Report TPS7H5006-SEP

9.96_FSW_EXT_RT_2MHz_14V				
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2006.417	2007.735	1.318
0	49	2021.265	2024.596	3.331
1E+12	11	2014.374	2017.016	2.642
1E+12	12	2019.467	2022.435	2.968
1E+12	13	2027.733	2029.934	2.201
5E+12	14	2012.367	2012.654	0.287
5E+12	15	2023.434	2027.827	4.393
5E+12	16	2029.403	2030.592	1.189
1E+13	17	2026.541	2028.260	1.719
1E+13	18	2021.809	2025.231	3.422
1E+13	19	2029.347	2029.325	-0.022
	Max	2029.403	2030.592	4.393
	Average	2021.105	2023.237	2.132
	Min	2006.417	2007.735	-0.022
	Std Dev	7.459	7.614	1.376

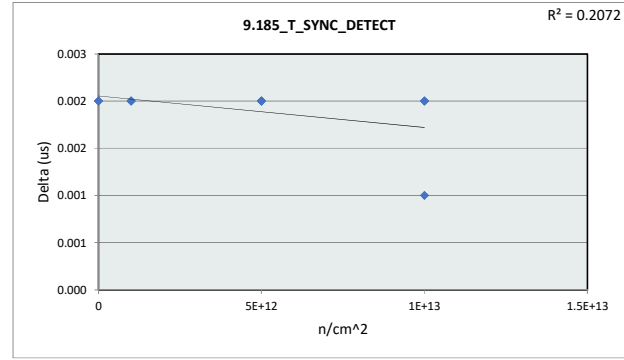


9.96_FSW_EXT_RT_2MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	2007.735	2017.016	2012.654	2025.231
Average	2016.166	2023.128	2023.691	2027.605
Max	2024.596	2029.934	2030.592	2029.325
UL	2300.000	2300.000	2300.000	2300.000

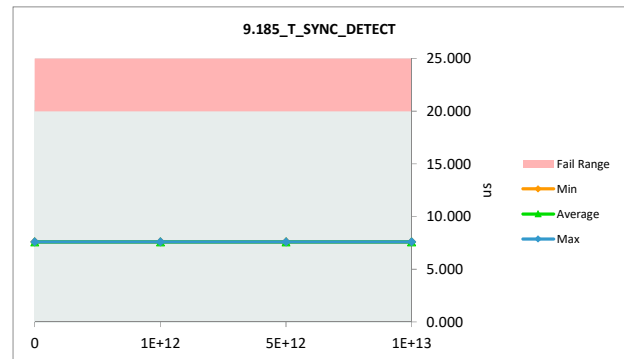


NDD Characterization Report TPS7H5006-SEP

9.185_T_SYNC_DETECT				
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		12	20	
Min Limit		4		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.587	7.589	0.002
0	49	7.587	7.589	0.002
1E+12	11	7.586	7.588	0.002
1E+12	12	7.586	7.588	0.002
1E+12	13	7.587	7.589	0.002
5E+12	14	7.587	7.589	0.002
5E+12	15	7.586	7.588	0.002
5E+12	16	7.587	7.589	0.002
1E+13	17	7.587	7.589	0.002
1E+13	18	7.587	7.589	0.002
1E+13	19	7.587	7.588	0.001
Max		7.587	7.589	0.002
Average		7.587	7.589	0.002
Min		7.586	7.588	0.001
Std Dev		0.000	0.001	0.000

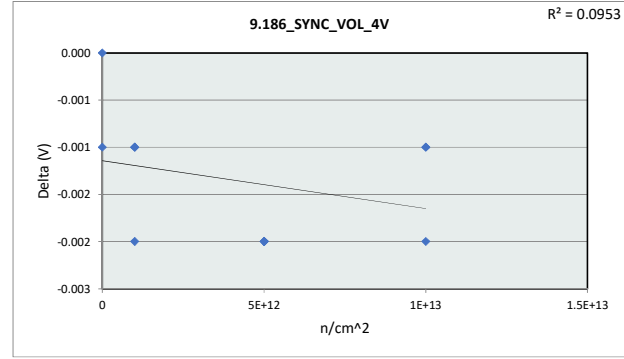


9.185_T_SYNC_DETECT				
Test Site				
Tester				
Test Number				
Max Limit	20	us		
Min Limit		us		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.589	7.588	7.588	7.588
Average	7.589	7.588	7.589	7.589
Max	7.589	7.589	7.589	7.589
UL	20.000	20.000	20.000	20.000

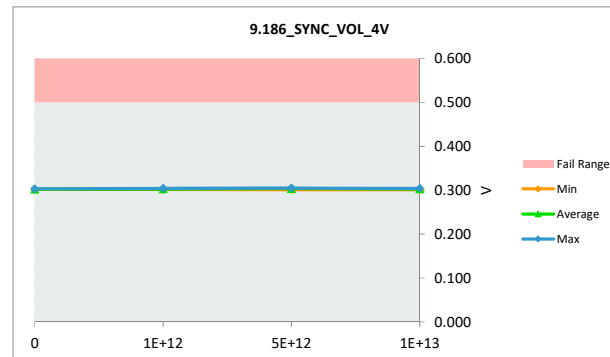


NDD Characterization Report TPS7H5006-SEP

9.186_SYNC_VOL_4V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.5	0.5	
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.303	0.303	0.000
0	49	0.303	0.302	-0.001
1E+12	11	0.304	0.302	-0.002
1E+12	12	0.305	0.304	-0.001
1E+12	13	0.303	0.302	-0.001
5E+12	14	0.307	0.305	-0.002
5E+12	15	0.307	0.305	-0.002
5E+12	16	0.303	0.301	-0.002
1E+13	17	0.302	0.301	-0.001
1E+13	18	0.305	0.304	-0.001
1E+13	19	0.306	0.304	-0.002
Max		0.307	0.305	0.000
Average		0.304	0.303	-0.001
Min		0.302	0.301	-0.002
Std Dev		0.002	0.001	0.001

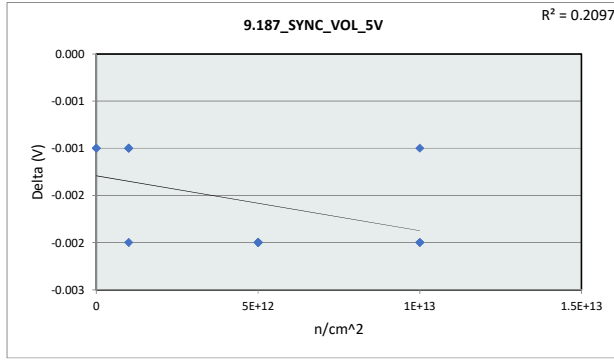


9.186_SYNC_VOL_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	0.302	0.302	0.301	0.301
Average	0.303	0.303	0.304	0.303
Max	0.303	0.304	0.305	0.304
UL	0.500	0.500	0.500	0.500

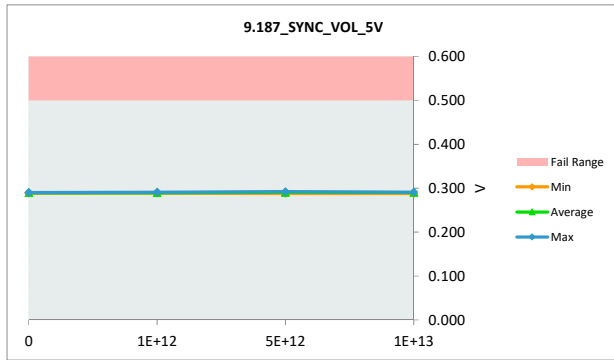


NDD Characterization Report TPS7H5006-SEP

9.187_SYNC_VOL_5V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	0.5	0.5	0.5	0.5
Min Limit	0	0	0	0
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.291	0.290	-0.001
0	49	0.290	0.289	-0.001
1E+12	11	0.291	0.289	-0.002
1E+12	12	0.292	0.291	-0.001
1E+12	13	0.290	0.289	-0.001
5E+12	14	0.294	0.292	-0.002
5E+12	15	0.294	0.292	-0.002
5E+12	16	0.290	0.288	-0.002
1E+13	17	0.290	0.288	-0.002
1E+13	18	0.292	0.291	-0.001
1E+13	19	0.293	0.291	-0.002
Max		0.294	0.292	-0.001
Average		0.292	0.290	-0.002
Min		0.290	0.288	-0.002
Std Dev		0.002	0.001	0.001

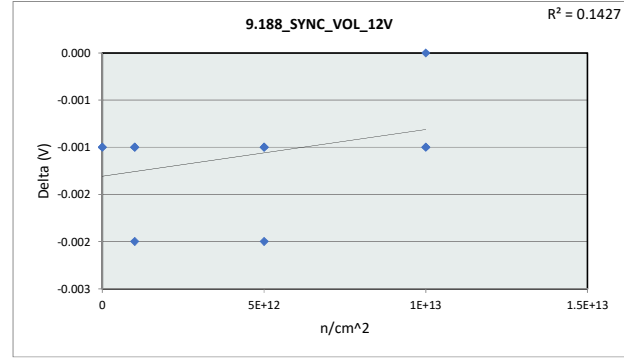


9.187_SYNC_VOL_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.5	V	V	V
Min Limit		V	V	V
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.289	0.289	0.288	0.288
Average	0.290	0.290	0.291	0.290
Max	0.290	0.291	0.292	0.291
UL	0.500	0.500	0.500	0.500

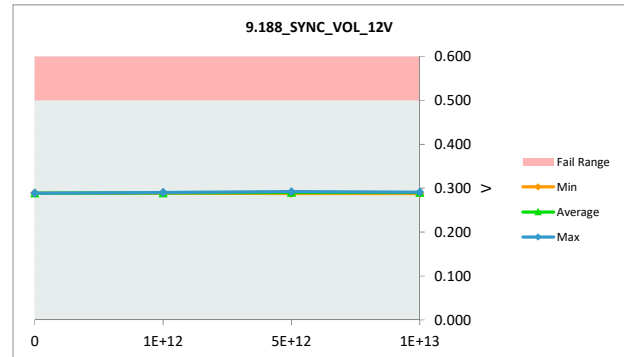


NDD Characterization Report TPS7H5006-SEP

9.188_SYNC_VOL_12V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.5	0.5	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.290	0.289	-0.001
0	49	0.290	0.289	-0.001
1E+12	11	0.290	0.289	-0.001
1E+12	12	0.292	0.290	-0.002
1E+12	13	0.290	0.289	-0.001
5E+12	14	0.293	0.291	-0.002
5E+12	15	0.293	0.292	-0.001
5E+12	16	0.289	0.288	-0.001
1E+13	17	0.289	0.288	-0.001
1E+13	18	0.291	0.291	0.000
1E+13	19	0.292	0.291	-0.001
Max		0.293	0.292	0.000
Average		0.291	0.290	-0.001
Min		0.289	0.288	-0.002
Std Dev		0.001	0.001	0.001

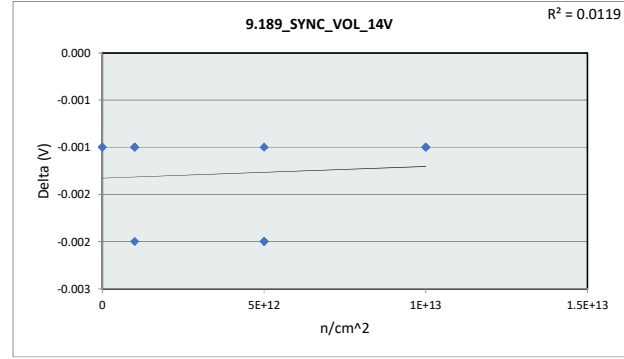


9.188_SYNC_VOL_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.289	0.289	0.288	0.288
Average	0.289	0.289	0.290	0.290
Max	0.289	0.290	0.292	0.291
UL	0.500	0.500	0.500	0.500

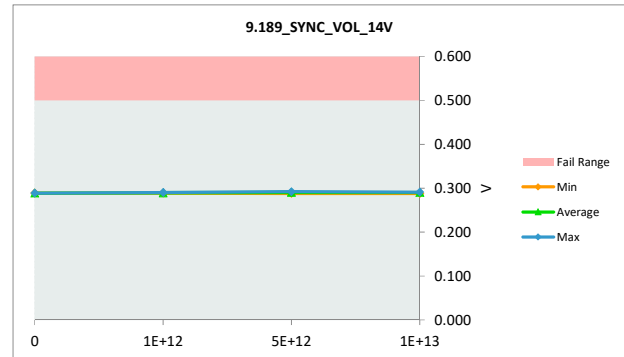


NDD Characterization Report TPS7H5006-SEP

9.189_SYNC_VOL_14V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.5	0.5	
Min Limit		0		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.290	0.289	-0.001
0	49	0.290	0.289	-0.001
1E+12	11	0.290	0.289	-0.001
1E+12	12	0.292	0.290	-0.002
1E+12	13	0.290	0.289	-0.001
5E+12	14	0.293	0.291	-0.002
5E+12	15	0.293	0.292	-0.001
5E+12	16	0.290	0.288	-0.002
1E+13	17	0.289	0.288	-0.001
1E+13	18	0.292	0.291	-0.001
1E+13	19	0.292	0.291	-0.001
Max		0.293	0.292	-0.001
Average		0.291	0.290	-0.001
Min		0.289	0.288	-0.002
Std Dev		0.001	0.001	0.000

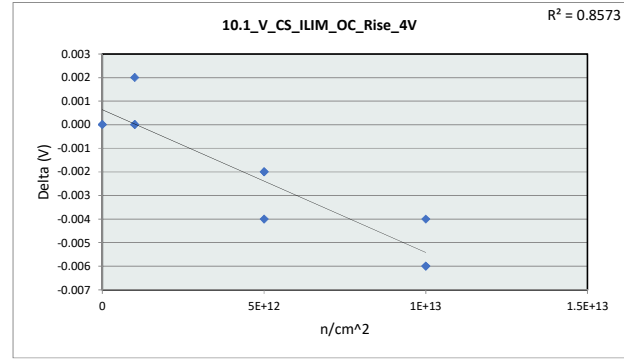


9.189_SYNC_VOL_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	0.289	0.289	0.288	0.288
Average	0.289	0.289	0.290	0.290
Max	0.289	0.290	0.292	0.291
UL	0.500	0.500	0.500	0.500

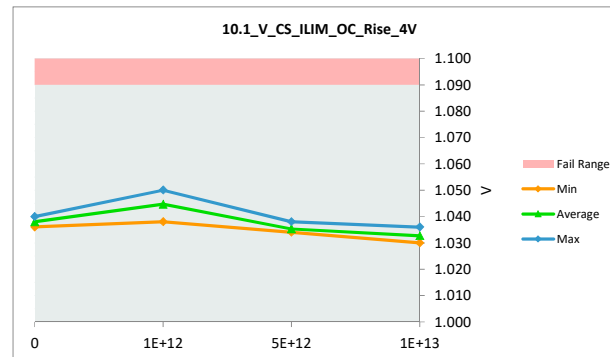


NDD Characterization Report TPS7H5006-SEP

10.1_V_CS_ILIM_OC_Rise_4V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	1.08		1.09	
Min Limit	0.95			
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.036	1.036	0.000
0	49	1.040	1.040	0.000
1E+12	11	1.038	1.038	0.000
1E+12	12	1.044	1.046	0.002
1E+12	13	1.050	1.050	0.000
5E+12	14	1.036	1.034	-0.002
5E+12	15	1.040	1.038	-0.002
5E+12	16	1.038	1.034	-0.004
1E+13	17	1.038	1.032	-0.006
1E+13	18	1.042	1.036	-0.006
1E+13	19	1.034	1.030	-0.004
Max		1.050	1.050	0.002
Average		1.040	1.038	-0.002
Min		1.034	1.030	-0.006
Std Dev		0.004	0.006	0.003

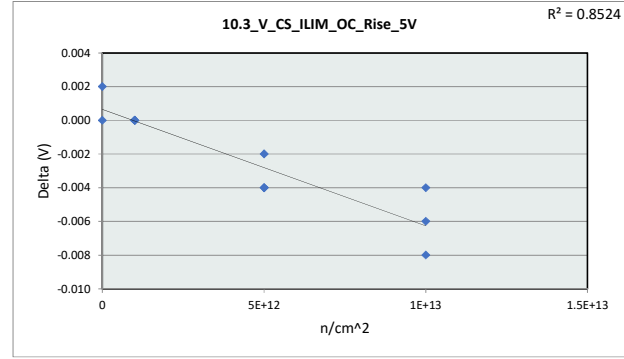


10.1_V_CS_ILIM_OC_Rise_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.09		V	
Min Limit			V	
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	1.036	1.038	1.034	1.030
Average	1.038	1.045	1.035	1.033
Max	1.040	1.050	1.038	1.036
UL	1.090	1.090	1.090	1.090

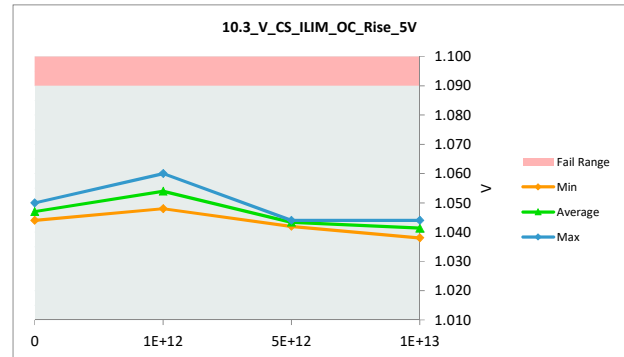


NDD Characterization Report TPS7H5006-SEP

10.3_V_CS_ILIM_OC_Rise_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.08	1.09	
Min Limit		0.95		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.042	1.044	0.002
0	49	1.050	1.050	0.000
1E+12	11	1.048	1.048	0.000
1E+12	12	1.054	1.054	0.000
1E+12	13	1.060	1.060	0.000
5E+12	14	1.044	1.042	-0.002
5E+12	15	1.048	1.044	-0.004
5E+12	16	1.048	1.044	-0.004
1E+13	17	1.046	1.042	-0.004
1E+13	18	1.052	1.044	-0.008
1E+13	19	1.044	1.038	-0.006
Max		1.060	1.060	0.002
Average		1.049	1.046	-0.002
Min		1.042	1.038	-0.008
Std Dev		0.005	0.006	0.003

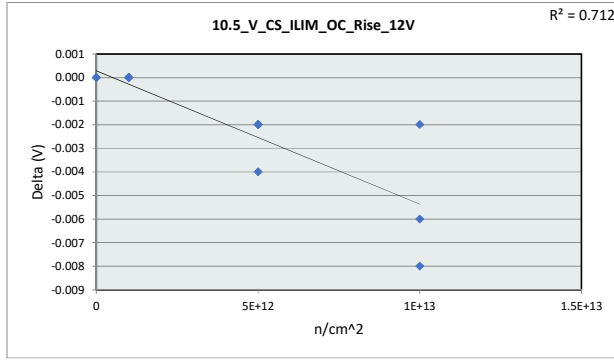


10.3_V_CS_ILIM_OC_Rise_5V				
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm ²	0	1E+12	5E+12	1E+13
LL				
Min	1.044	1.048	1.042	1.038
Average	1.047	1.054	1.043	1.041
Max	1.050	1.060	1.044	1.044
UL	1.090	1.090	1.090	1.090

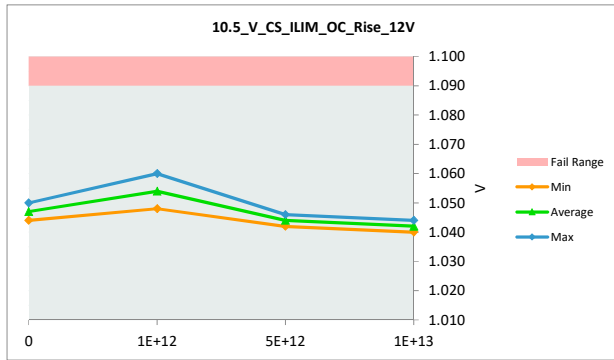


NDD Characterization Report TPS7H5006-SEP

10.5_V_CS_ILIM_OC_Rise_12V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.08	1.09	
Min Limit		0.95		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.044	1.044	0.000
0	49	1.050	1.050	0.000
1E+12	11	1.048	1.048	0.000
1E+12	12	1.054	1.054	0.000
1E+12	13	1.060	1.060	0.000
5E+12	14	1.044	1.042	-0.002
5E+12	15	1.048	1.046	-0.002
5E+12	16	1.048	1.044	-0.004
1E+13	17	1.048	1.042	-0.006
1E+13	18	1.052	1.044	-0.008
1E+13	19	1.042	1.040	-0.002
Max		1.060	1.060	0.000
Average		1.049	1.047	-0.002
Min		1.042	1.040	-0.008
Std Dev		0.005	0.006	0.003

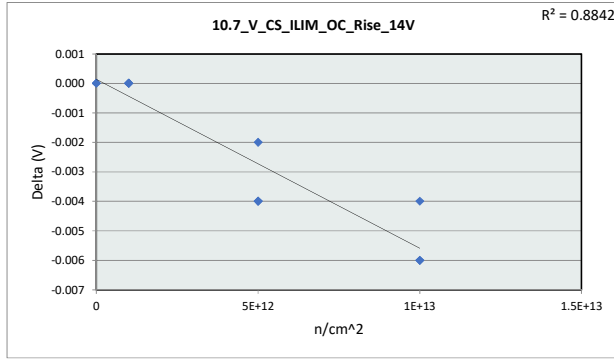


10.5_V_CS_ILIM_OC_Rise_12V				
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.044	1.048	1.042	1.040
Average	1.047	1.054	1.044	1.042
Max	1.050	1.060	1.046	1.044
UL	1.090	1.090	1.090	1.090

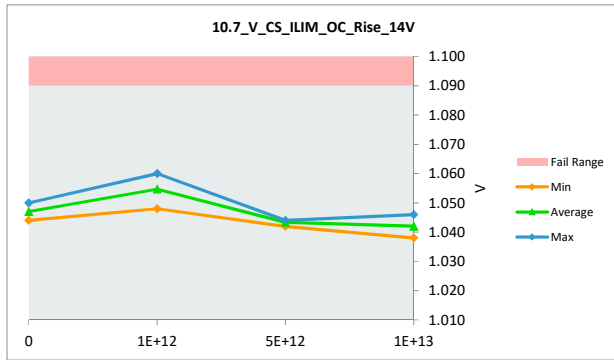


NDD Characterization Report TPS7H5006-SEP

10.7_V_CS_ILIM_OC_Rise_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	1.08		1.09	
Min Limit	0.95			
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.044	1.044	0.000
0	49	1.050	1.050	0.000
1E+12	11	1.048	1.048	0.000
1E+12	12	1.056	1.056	0.000
1E+12	13	1.060	1.060	0.000
5E+12	14	1.044	1.042	-0.002
5E+12	15	1.048	1.044	-0.004
5E+12	16	1.048	1.044	-0.004
1E+13	17	1.048	1.042	-0.006
1E+13	18	1.052	1.046	-0.006
1E+13	19	1.042	1.038	-0.004
Max		1.060	1.060	0.000
Average		1.049	1.047	-0.002
Min		1.042	1.038	-0.006
Std Dev		0.005	0.006	0.003

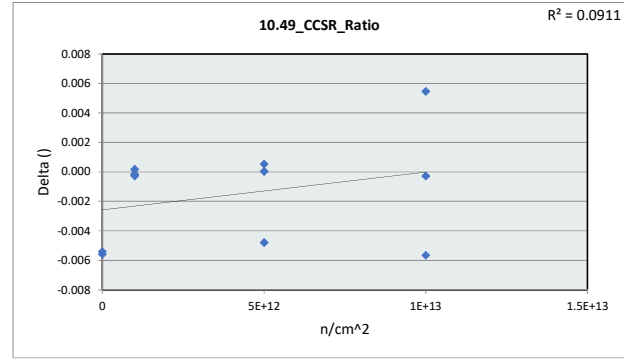


10.7_V_CS_ILIM_OC_Rise_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.09		V	
Min Limit			V	
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.044	1.048	1.042	1.038
Average	1.047	1.055	1.043	1.042
Max	1.050	1.060	1.044	1.046
UL	1.090	1.090	1.090	1.090

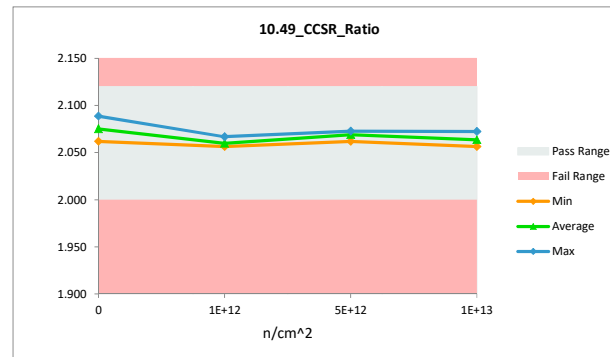


NDD Characterization Report TPS7H5006-SEP

10.49_CCSR_Ratio				
Test Site				
Tester				
Test Number				
Unit				
Max Limit		2.12	2.12	
Min Limit		2	2	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.094	2.089	-0.006
0	49	2.067	2.062	-0.005
1E+12	11	2.067	2.067	0.000
1E+12	12	2.057	2.057	0.000
1E+12	13	2.057	2.056	0.000
5E+12	14	2.067	2.062	-0.005
5E+12	15	2.072	2.073	0.001
5E+12	16	2.073	2.073	0.000
1E+13	17	2.062	2.056	-0.006
1E+13	18	2.073	2.072	0.000
1E+13	19	2.056	2.062	0.005
Max		2.094	2.089	0.005
Average		2.068	2.066	-0.001
Min		2.056	2.056	-0.006
Std Dev		0.011	0.010	0.004

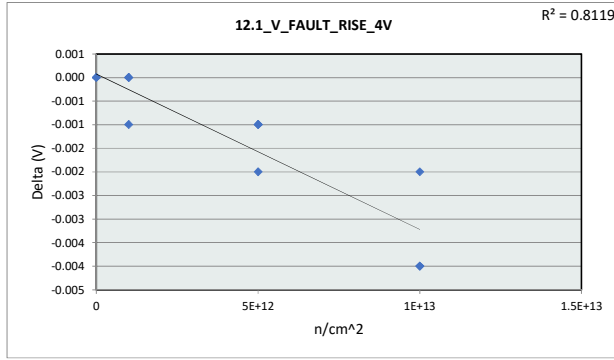


10.49_CCSR_Ratio				
Test Site				
Tester				
Test Number				
Max Limit		2.12		
Min Limit		2		
n/cm ²	0	1E+12	5E+12	1E+13
LL	2.000	2.000	2.000	2.000
Min	2.062	2.056	2.062	2.056
Average	2.075	2.060	2.069	2.063
Max	2.089	2.067	2.073	2.072
UL	2.120	2.120	2.120	2.120

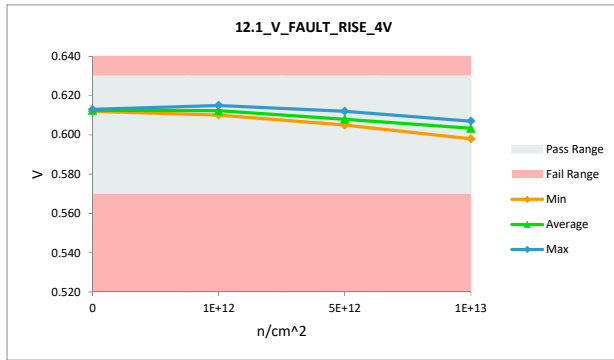


NDD Characterization Report TPS7H5006-SEP

12.1_V_FAULT_RISE_4V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.63		0.63	
Min Limit	0.58		0.57	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.612	0.612	0.000
1E+12	11	0.612	0.612	0.000
1E+12	12	0.615	0.615	0.000
1E+12	13	0.611	0.610	-0.001
5E+12	14	0.608	0.607	-0.001
5E+12	15	0.606	0.605	-0.001
5E+12	16	0.614	0.612	-0.002
1E+13	17	0.607	0.605	-0.002
1E+13	18	0.611	0.607	-0.004
1E+13	19	0.602	0.598	-0.004
Max		0.615	0.615	0.000
Average		0.610	0.609	-0.001
Min		0.602	0.598	-0.004
Std Dev		0.004	0.005	0.002

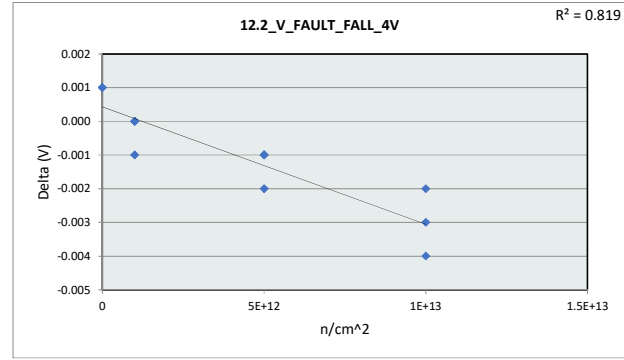


12.1_V_FAULT_RISE_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.63		V	
Min Limit	0.57		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.612	0.610	0.605	0.598
Average	0.613	0.612	0.608	0.603
Max	0.613	0.615	0.612	0.607
UL	0.630	0.630	0.630	0.630

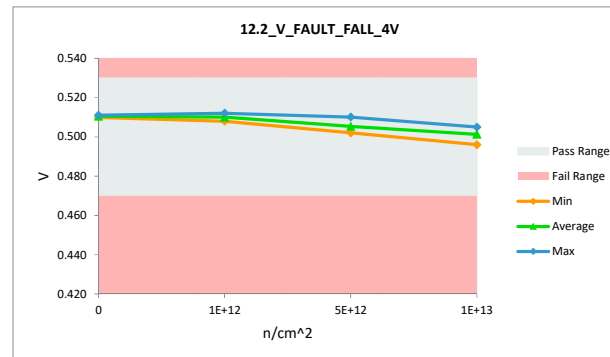


NDD Characterization Report TPS7H5006-SEP

12.2_V_FAULT_FALL_4V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.510	0.511	0.001
0	49	0.509	0.510	0.001
1E+12	11	0.510	0.510	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.509	0.508	-0.001
5E+12	14	0.506	0.504	-0.002
5E+12	15	0.503	0.502	-0.001
5E+12	16	0.511	0.510	-0.001
1E+13	17	0.505	0.503	-0.002
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.500	0.496	-0.004
Max		0.512	0.512	0.001
Average		0.508	0.506	-0.001
Min		0.500	0.496	-0.004
Std Dev		0.004	0.005	0.002

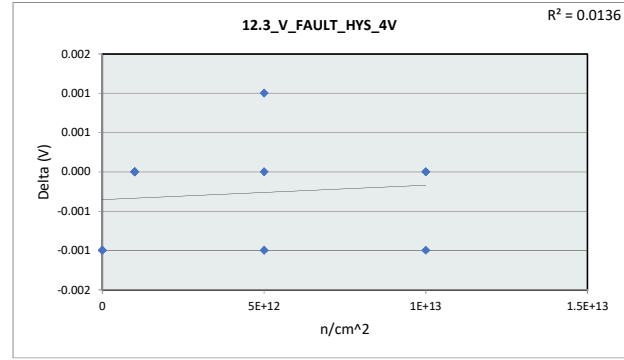


12.2_V_FAULT_FALL_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.510	0.508	0.502	0.496
Average	0.511	0.510	0.505	0.501
Max	0.511	0.512	0.510	0.505
UL	0.530	0.530	0.530	0.530

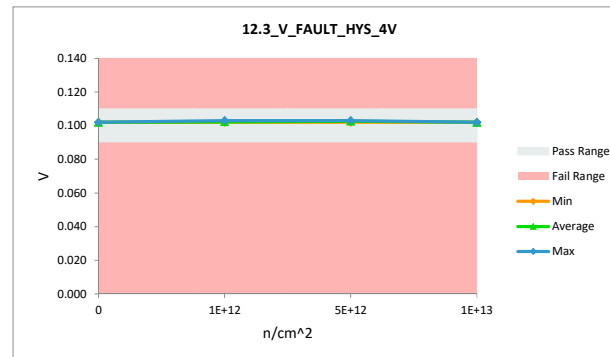


NDD Characterization Report TPS7H5006-SEP

12.3_V_FAULT_HYS_4V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	0.108	0.11	0.11	0.11
Min Limit	0.092	0.09	0.09	0.09
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.103	0.102	-0.001
0	49	0.103	0.102	-0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.103	0.000
1E+12	13	0.102	0.102	0.000
5E+12	14	0.102	0.103	0.001
5E+12	15	0.103	0.103	0.000
5E+12	16	0.103	0.102	-0.001
1E+13	17	0.102	0.102	0.000
1E+13	18	0.103	0.102	-0.001
1E+13	19	0.102	0.102	0.000
Max		0.103	0.103	0.001
Average		0.103	0.102	0.000
Min		0.102	0.102	-0.001
Std Dev		0.001	0.000	0.001

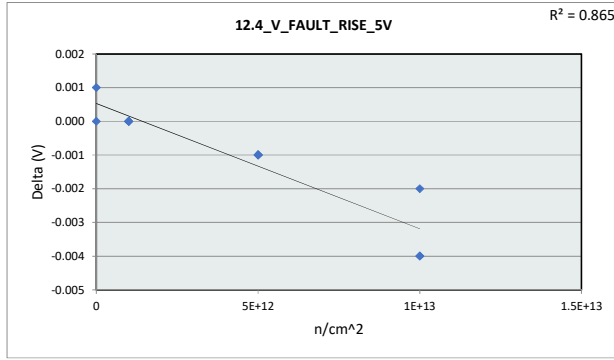


12.3_V_FAULT_HYS_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.102
Average	0.102	0.102	0.103	0.102
Max	0.102	0.103	0.103	0.102
UL	0.110	0.110	0.110	0.110

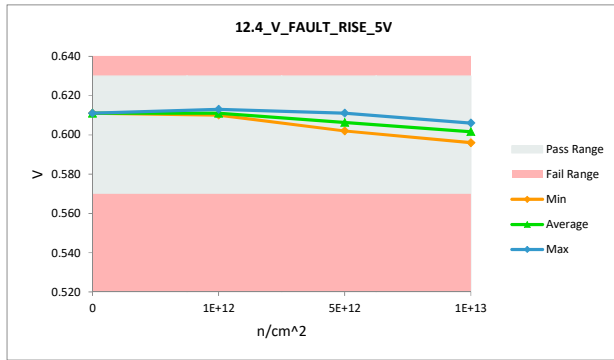


NDD Characterization Report TPS7H5006-SEP

12.4_V_FAULT_RISE_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.58	0.57	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.610	0.611	0.001
0	49	0.611	0.611	0.000
1E+12	11	0.610	0.610	0.000
1E+12	12	0.613	0.613	0.000
1E+12	13	0.610	0.610	0.000
5E+12	14	0.607	0.606	-0.001
5E+12	15	0.603	0.602	-0.001
5E+12	16	0.612	0.611	-0.001
1E+13	17	0.605	0.603	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.600	0.596	-0.004
Max		0.613	0.613	0.001
Average		0.608	0.607	-0.001
Min		0.600	0.596	-0.004
Std Dev		0.004	0.005	0.002

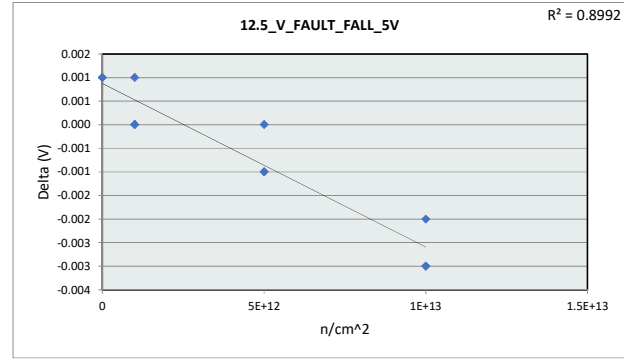


12.4_V_FAULT_RISE_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.611	0.610	0.602	0.596
Average	0.611	0.611	0.606	0.602
Max	0.611	0.613	0.611	0.606
UL	0.630	0.630	0.630	0.630

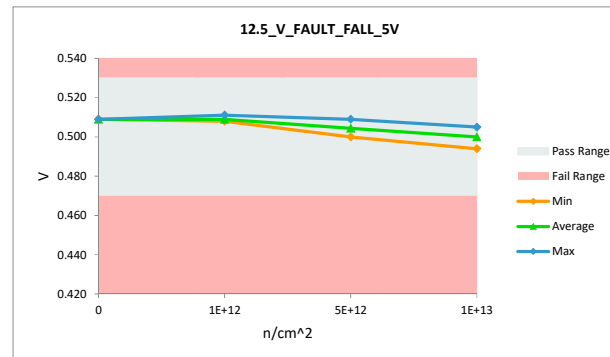


NDD Characterization Report TPS7H5006-SEP

12.5_V_FAULT_FALL_5V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.508	0.509	0.001
0	49	0.508	0.509	0.001
1E+12	11	0.508	0.508	0.000
1E+12	12	0.510	0.511	0.001
1E+12	13	0.508	0.508	0.000
5E+12	14	0.505	0.504	-0.001
5E+12	15	0.500	0.500	0.000
5E+12	16	0.510	0.509	-0.001
1E+13	17	0.503	0.501	-0.002
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.497	0.494	-0.003
Max		0.510	0.511	0.001
Average		0.506	0.505	-0.001
Min		0.497	0.494	-0.003
Std Dev		0.004	0.005	0.002

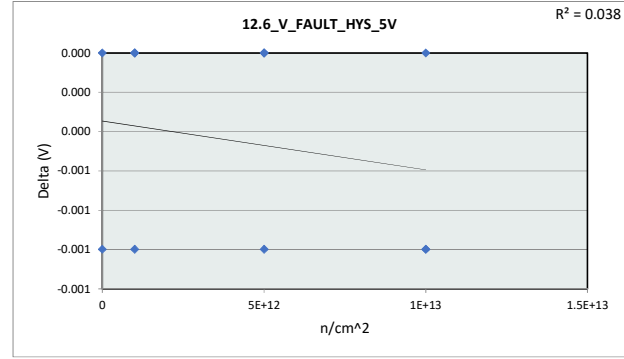


12.5_V_FAULT_FALL_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.509	0.508	0.500	0.494
Average	0.509	0.509	0.504	0.500
Max	0.509	0.511	0.509	0.505
UL	0.530	0.530	0.530	0.530

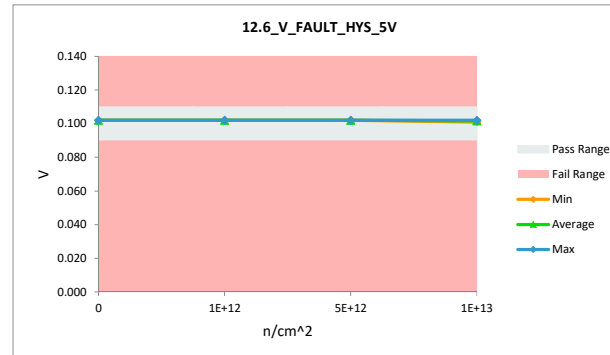


NDD Characterization Report TPS7H5006-SEP

12.6_V_FAULT_HYS_5V				
Test Site				
Tester				
Test Number				
Unit	V	V	V	V
Max Limit	0.108	0.11	0.11	0.11
Min Limit	0.092	0.09	0.09	0.09
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.102	0.102	0.000
0	49	0.103	0.102	-0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.102	-0.001
1E+12	13	0.102	0.102	0.000
5E+12	14	0.102	0.102	0.000
5E+12	15	0.103	0.102	-0.001
5E+12	16	0.102	0.102	0.000
1E+13	17	0.102	0.102	0.000
1E+13	18	0.102	0.101	-0.001
1E+13	19	0.103	0.102	-0.001
Max		0.103	0.102	0.000
Average		0.102	0.102	0.000
Min		0.102	0.101	-0.001
Std Dev		0.001	0.000	0.001

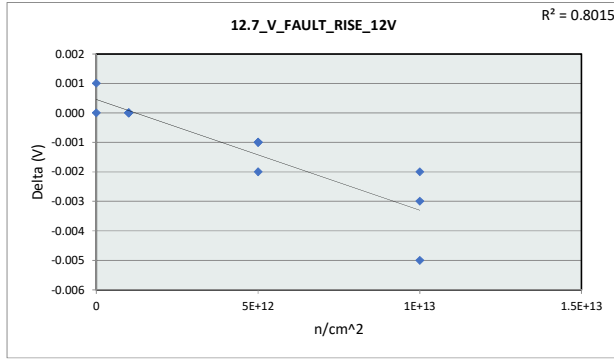


12.6_V_FAULT_HYS_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.101
Average	0.102	0.102	0.102	0.102
Max	0.102	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

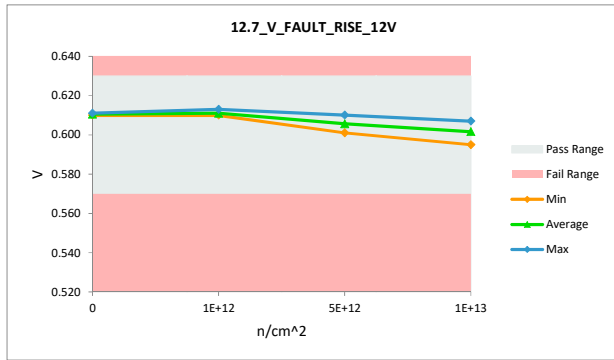


NDD Characterization Report TPS7H5006-SEP

12.7_V_FAULT_RISE_12V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.63		0.63	
Min Limit	0.58		0.57	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.610	0.610	0.000
0	49	0.610	0.611	0.001
1E+12	11	0.610	0.610	0.000
1E+12	12	0.613	0.613	0.000
1E+12	13	0.610	0.610	0.000
5E+12	14	0.607	0.606	-0.001
5E+12	15	0.602	0.601	-0.001
5E+12	16	0.612	0.610	-0.002
1E+13	17	0.605	0.603	-0.002
1E+13	18	0.610	0.607	-0.003
1E+13	19	0.600	0.595	-0.005
Max		0.613	0.613	0.001
Average		0.608	0.607	-0.001
Min		0.600	0.595	-0.005
Std Dev		0.004	0.005	0.002

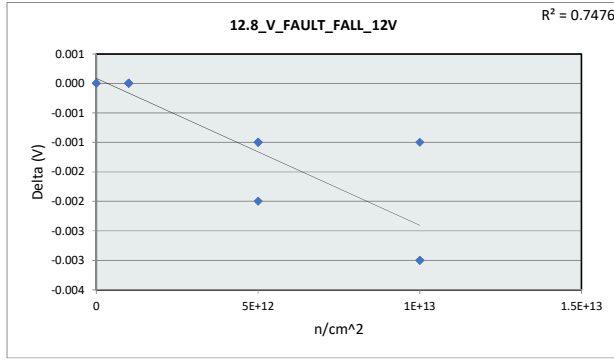


12.7_V_FAULT_RISE_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.63		V	
Min Limit	0.57		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.610	0.610	0.601	0.595
Average	0.611	0.611	0.606	0.602
Max	0.611	0.613	0.610	0.607
UL	0.630	0.630	0.630	0.630

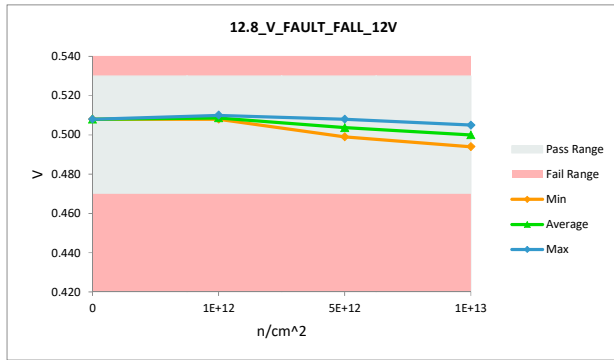


NDD Characterization Report TPS7H5006-SEP

12.8_V_FAULT_FALL_12V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.508	0.508	0.000
0	49	0.508	0.508	0.000
1E+12	11	0.508	0.508	0.000
1E+12	12	0.510	0.510	0.000
1E+12	13	0.508	0.508	0.000
5E+12	14	0.505	0.504	-0.001
5E+12	15	0.500	0.499	-0.001
5E+12	16	0.510	0.508	-0.002
1E+13	17	0.502	0.501	-0.001
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.497	0.494	-0.003
Max		0.510	0.510	0.000
Average		0.506	0.505	-0.001
Min		0.497	0.494	-0.003
Std Dev		0.004	0.005	0.001

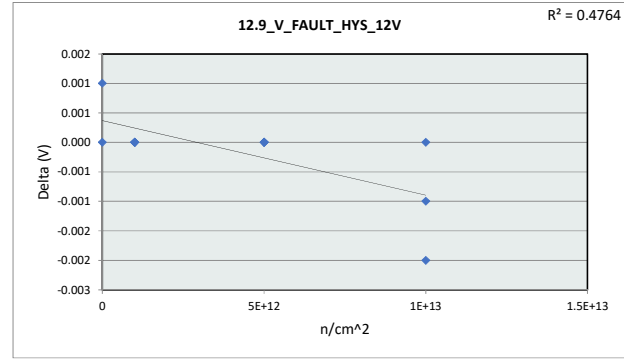


12.8_V_FAULT_FALL_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.499	0.494
Average	0.508	0.509	0.504	0.500
Max	0.508	0.510	0.508	0.505
UL	0.530	0.530	0.530	0.530

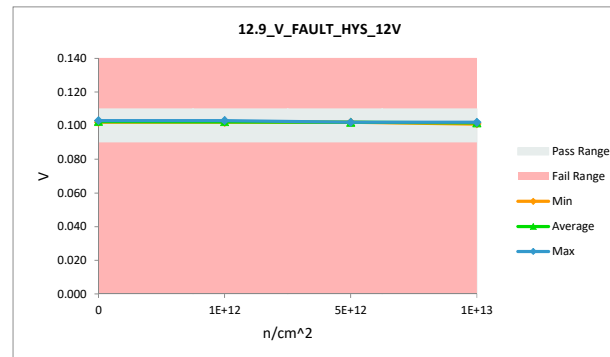


NDD Characterization Report TPS7H5006-SEP

12.9_V_FAULT_HYS_12V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.108		0.11	
Min Limit	0.092		0.09	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.102	0.102	0.000
0	49	0.102	0.103	0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.103	0.000
1E+12	13	0.102	0.102	0.000
5E+12	14	0.102	0.102	0.000
5E+12	15	0.102	0.102	0.000
5E+12	16	0.102	0.102	0.000
1E+13	17	0.103	0.102	-0.001
1E+13	18	0.102	0.102	0.000
1E+13	19	0.103	0.101	-0.002
Max		0.103	0.103	0.001
Average		0.102	0.102	0.000
Min		0.102	0.101	-0.002
Std Dev		0.000	0.001	0.001

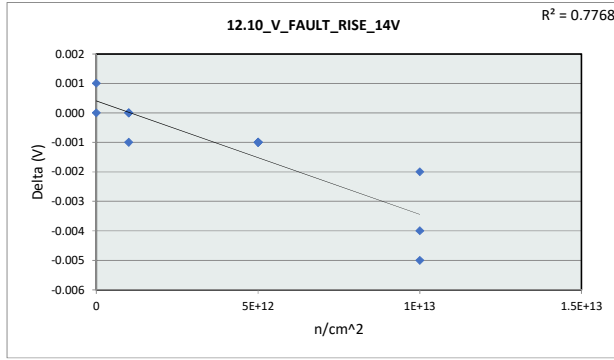


12.9_V_FAULT_HYS_12V				
Test Site				
Tester				
Test Number				
Max Limit	0.11		V	
Min Limit	0.09		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.101
Average	0.103	0.102	0.102	0.102
Max	0.103	0.103	0.102	0.102
UL	0.110	0.110	0.110	0.110

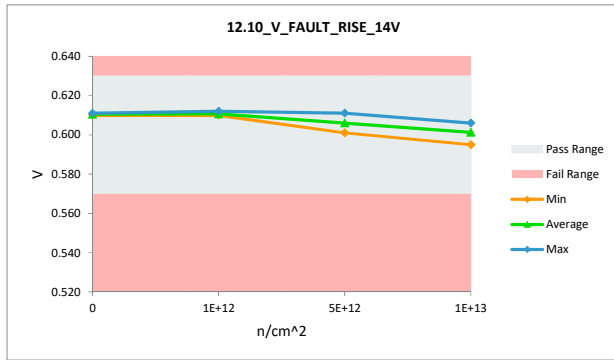


NDD Characterization Report TPS7H5006-SEP

12.10_V_FAULT_RISE_14V				
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.58	0.57	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.610	0.610	0.000
0	49	0.610	0.611	0.001
1E+12	11	0.610	0.610	0.000
1E+12	12	0.613	0.612	-0.001
1E+12	13	0.610	0.610	0.000
5E+12	14	0.607	0.606	-0.001
5E+12	15	0.602	0.601	-0.001
5E+12	16	0.612	0.611	-0.001
1E+13	17	0.605	0.603	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.600	0.595	-0.005
Max		0.613	0.612	0.001
Average		0.608	0.607	-0.001
Min		0.600	0.595	-0.005
Std Dev		0.004	0.005	0.002

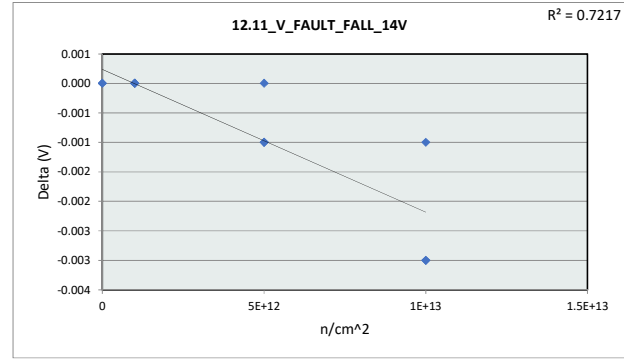


12.10_V_FAULT_RISE_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.610	0.610	0.601	0.595
Average	0.611	0.611	0.606	0.601
Max	0.611	0.612	0.611	0.606
UL	0.630	0.630	0.630	0.630

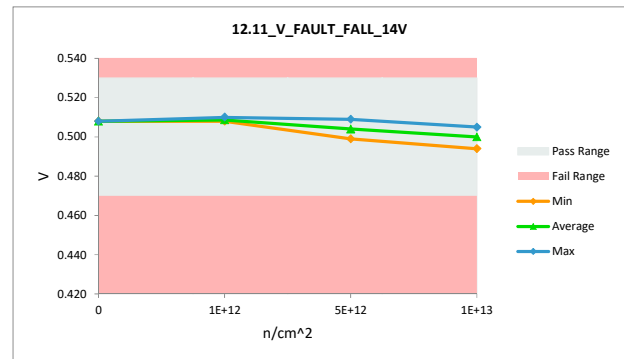


NDD Characterization Report TPS7H5006-SEP

12.11_V_FAULT_FALL_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.53		0.53	
Min Limit	0.48		0.47	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.508	0.508	0.000
0	49	0.508	0.508	0.000
1E+12	11	0.508	0.508	0.000
1E+12	12	0.510	0.510	0.000
1E+12	13	0.508	0.508	0.000
5E+12	14	0.504	0.504	0.000
5E+12	15	0.500	0.499	-0.001
5E+12	16	0.510	0.509	-0.001
1E+13	17	0.502	0.501	-0.001
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.497	0.494	-0.003
Max		0.510	0.510	0.000
Average		0.506	0.505	-0.001
Min		0.497	0.494	-0.003
Std Dev		0.004	0.005	0.001

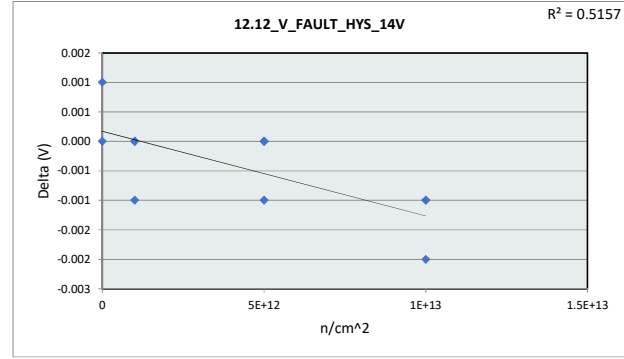


12.11_V_FAULT_FALL_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.53		V	
Min Limit	0.47		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.499	0.494
Average	0.508	0.509	0.504	0.500
Max	0.508	0.510	0.509	0.505
UL	0.530	0.530	0.530	0.530

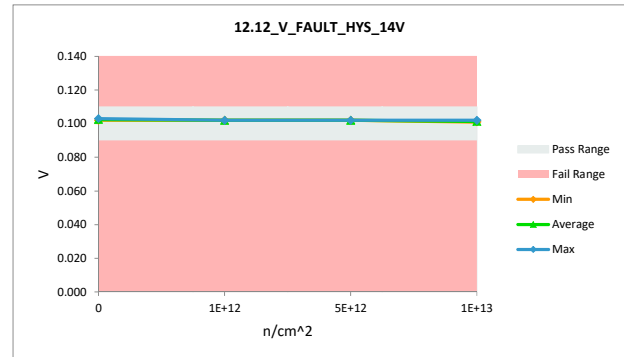


NDD Characterization Report TPS7H5006-SEP

12.12_V_FAULT_HYS_14V				
Test Site				
Tester				
Test Number				
Unit	V		V	
Max Limit	0.108		0.11	
Min Limit	0.092		0.09	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.102	0.102	0.000
0	49	0.102	0.103	0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.102	-0.001
1E+12	13	0.102	0.102	0.000
5E+12	14	0.103	0.102	-0.001
5E+12	15	0.102	0.102	0.000
5E+12	16	0.102	0.102	0.000
1E+13	17	0.103	0.102	-0.001
1E+13	18	0.102	0.101	-0.001
1E+13	19	0.103	0.101	-0.002
Max		0.103	0.103	0.001
Average		0.102	0.102	0.000
Min		0.102	0.101	-0.002
Std Dev		0.001	0.001	0.001

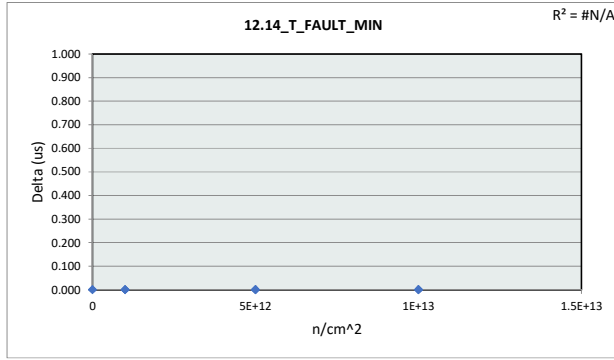


12.12_V_FAULT_HYS_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.11		V	
Min Limit	0.09		V	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.101
Average	0.103	0.102	0.102	0.101
Max	0.103	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

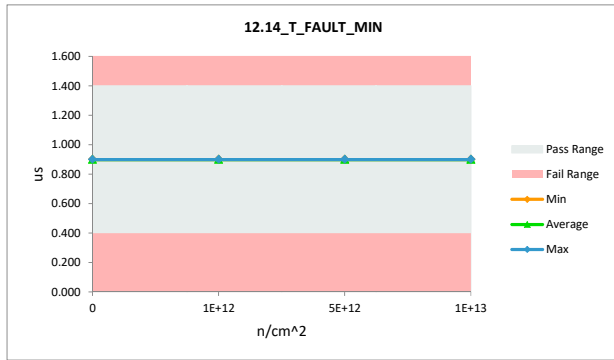


NDD Characterization Report TPS7H5006-SEP

12.14_T_FAULT_MIN				
Test Site				
Tester				
Test Number				
Unit	us		us	
Max Limit	1.2		1.4	
Min Limit	0.6		0.4	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.900	0.900	0.000
0	49	0.900	0.900	0.000
1E+12	11	0.900	0.900	0.000
1E+12	12	0.900	0.900	0.000
1E+12	13	0.900	0.900	0.000
5E+12	14	0.900	0.900	0.000
5E+12	15	0.900	0.900	0.000
5E+12	16	0.900	0.900 </td <td>0.000</td>	0.000
1E+13	17	0.900	0.900	0.000
1E+13	18	0.900	0.900	0.000
1E+13	19	0.900	0.900	0.000
Max		0.900	0.900	0.000
Average		0.900	0.900	0.000
Min		0.900	0.900	0.000
Std Dev		0.000	0.000	0.000

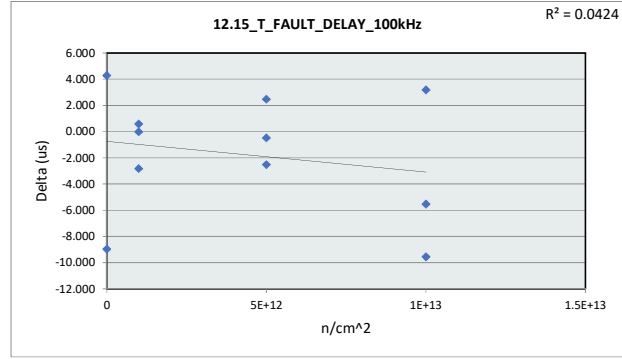


12.14_T_FAULT_MIN				
Test Site				
Tester				
Test Number				
Max Limit	1.4		us	
Min Limit	0.4		us	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.400	0.400	0.400	0.400
Min	0.900	0.900	0.900	0.900
Average	0.900	0.900	0.900	0.900
Max	0.900	0.900	0.900	0.900
UL	1.400	1.400	1.400	1.400

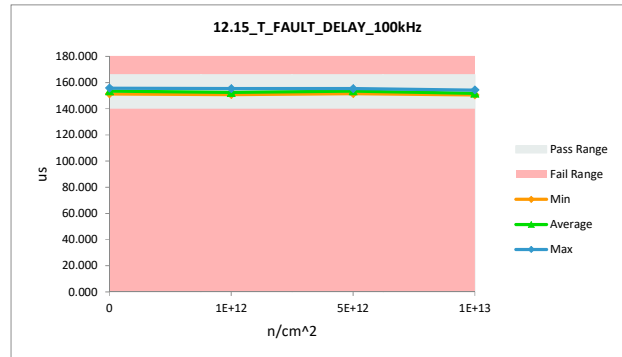


NDD Characterization Report TPS7H5006-SEP

12.15_T_FAULT_DELAY_100kHz				
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		166	166	
Min Limit		140	140	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	160.311	151.330	-8.981
0	49	151.433	155.700	4.267
1E+12	11	153.528	150.692	-2.836
1E+12	12	154.748	155.327	0.579
1E+12	13	150.935	150.911	-0.024
5E+12	14	157.909	155.377	-2.532
5E+12	15	151.252	153.712	2.460
5E+12	16	151.914	151.425	-0.489
1E+13	17	160.029	150.467	-9.562
1E+13	18	151.114	154.282	3.168
1E+13	19	156.232	150.683	-5.549
Max		160.311	155.700	4.267
Average		154.491	152.719	-1.773
Min		150.935	150.467	-9.562
Std Dev		3.616	2.154	4.665

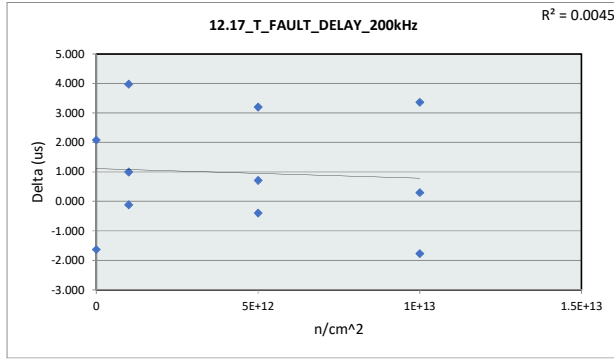


12.15_T_FAULT_DELAY_100kHz				
Test Site				
Tester				
Test Number				
Max Limit	166	us		
Min Limit	140	us		
n/cm ²	0	1E+12	5E+12	1E+13
LL	140.000	140.000	140.000	140.000
Min	151.330	150.692	151.425	150.467
Average	153.515	152.310	153.505	151.811
Max	155.700	155.327	155.377	154.282
UL	166.000	166.000	166.000	166.000

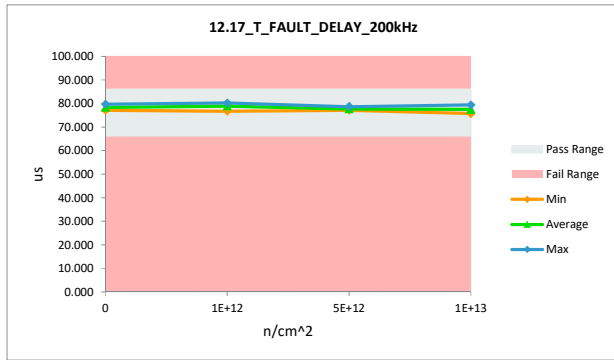


NDD Characterization Report TPS7H5006-SEP

12.17_T_FAULT_DELAY_200kHz				
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		86	86	
Min Limit		70	66	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	78.669	77.034	-1.635
0	49	77.582	79.658	2.076
1E+12	11	76.770	76.646	-0.124
1E+12	12	76.209	80.181	3.972
1E+12	13	78.747	79.738	0.991
5E+12	14	76.345	77.054	0.709
5E+12	15	75.475	78.668	3.193
5E+12	16	77.683	77.281	-0.402
1E+13	17	77.209	77.496	0.287
1E+13	18	75.997	79.354	3.357
1E+13	19	77.474	75.698	-1.776
Max		78.747	80.181	3.972
Average		77.105	78.073	0.968
Min		75.475	75.698	-1.776
Std Dev		1.060	1.499	1.970

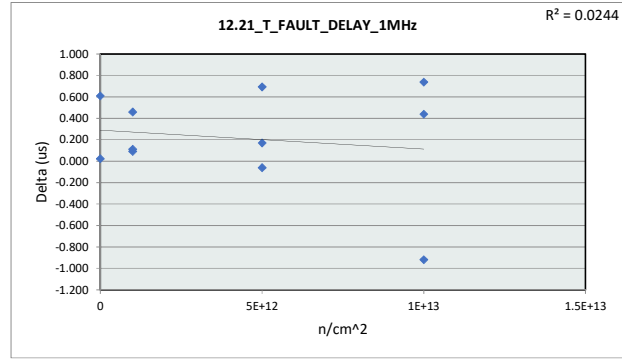


12.17_T_FAULT_DELAY_200kHz				
Test Site				
Tester				
Test Number				
Max Limit	86	us		
Min Limit	66	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	66.000	66.000	66.000	66.000
Min	77.034	76.646	77.054	75.698
Average	78.346	78.855	77.668	77.516
Max	79.658	80.181	78.668	79.354
UL	86.000	86.000	86.000	86.000

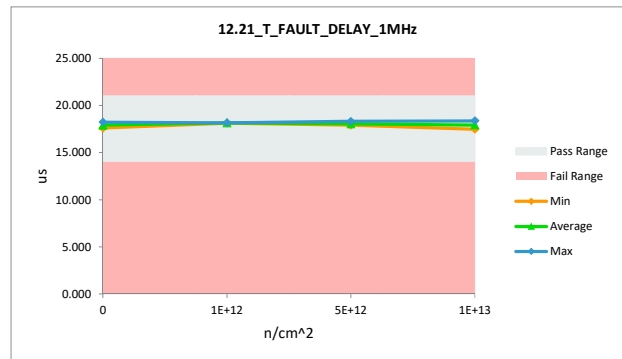


NDD Characterization Report TPS7H5006-SEP

12.21_T_FAULT_DELAY_1MHz				
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		21	21	
Min Limit		14	14	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	17.568	17.590	0.022
0	49	17.617	18.224	0.607
1E+12	11	18.081	18.170	0.089
1E+12	12	17.674	18.130	0.456
1E+12	13	18.044	18.153	0.109
5E+12	14	17.980	17.918	-0.062
5E+12	15	17.733	17.901	0.168
5E+12	16	17.618	18.309	0.691
1E+13	17	18.387	17.467	-0.920
1E+13	18	17.637	18.374	0.737
1E+13	19	17.515	17.953	0.438
Max		18.387	18.374	0.737
Average		17.805	18.017	0.212
Min		17.515	17.467	-0.920
Std Dev		0.276	0.287	0.468

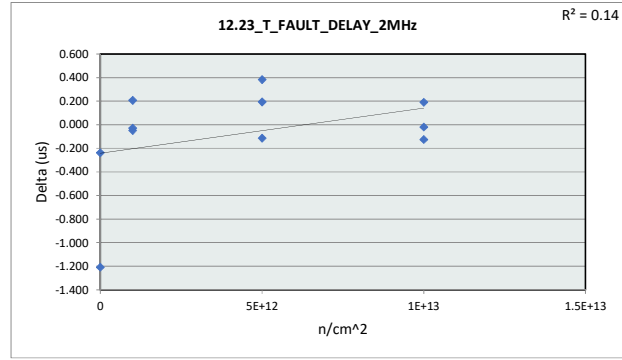


12.21_T_FAULT_DELAY_1MHz				
Test Site				
Tester				
Test Number				
Max Limit	21	us		
Min Limit	14	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	14.000	14.000	14.000	14.000
Min	17.590	18.130	17.901	17.467
Average	17.907	18.151	18.043	17.931
Max	18.224	18.170	18.309	18.374
UL	21.000	21.000	21.000	21.000

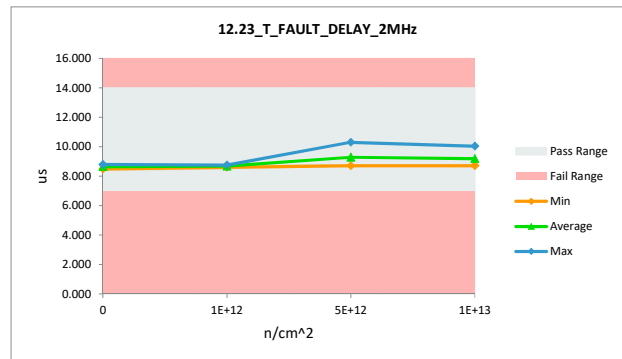


NDD Characterization Report TPS7H5006-SEP

12.23_T_FAULT_DELAY_2MHz				
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		14	14	
Min Limit		7	7	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.728	8.489	-0.239
0	49	9.991	8.782	-1.209
1E+12	11	8.551	8.756	0.205
1E+12	12	8.693	8.663	-0.030
1E+12	13	8.655	8.605	-0.050
5E+12	14	8.508	8.700	0.192
5E+12	15	8.464	8.845	0.381
5E+12	16	10.419	10.303	-0.116
1E+13	17	10.051	10.031	-0.020
1E+13	18	8.946	8.819	-0.127
1E+13	19	8.526	8.715	0.189
	Max	10.419	10.303	0.381
	Average	9.048	8.973	-0.075
	Min	8.464	8.489	-1.209
	Std Dev	0.729	0.602	0.418

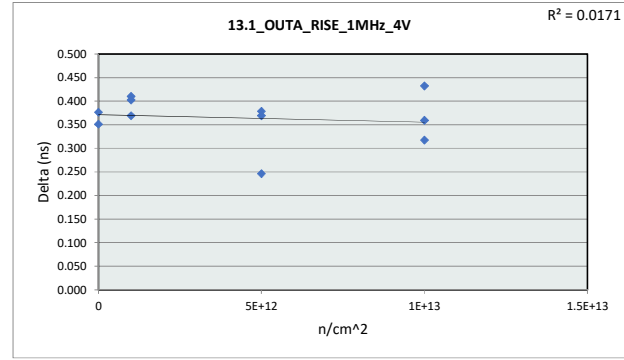


12.23_T_FAULT_DELAY_2MHz				
Test Site				
Tester				
Test Number				
Max Limit	14	us		
Min Limit	7	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	7.000	7.000	7.000	7.000
Min	8.489	8.605	8.700	8.715
Average	8.636	8.675	9.283	9.188
Max	8.782	8.756	10.303	10.031
UL	14.000	14.000	14.000	14.000

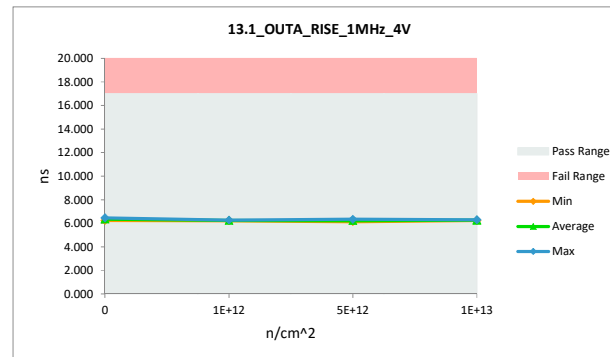


NDD Characterization Report TPS7H5006-SEP

13.1_OUTA_RISE_1MHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.891	6.242	0.351
0	49	6.065	6.441	0.376
1E+12	11	5.892	6.261	0.369
1E+12	12	5.810	6.220	0.410
1E+12	13	5.812	6.214	0.402
5E+12	14	5.941	6.187	0.246
5E+12	15	5.758	6.136	0.378
5E+12	16	5.965	6.334	0.369
1E+13	17	5.883	6.242	0.359
1E+13	18	5.817	6.249	0.432
1E+13	19	5.963	6.280	0.317
Max		6.065	6.441	0.432
Average		5.891	6.255	0.364
Min		5.758	6.136	0.246
Std Dev		0.089	0.080	0.050

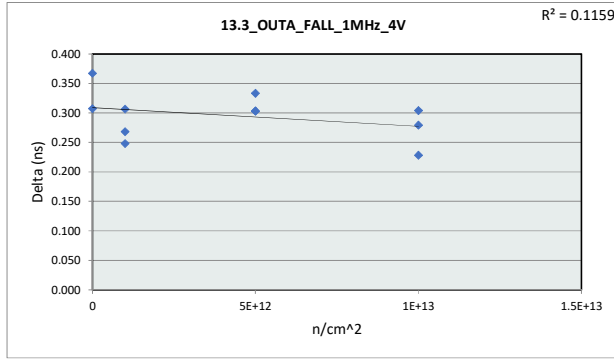


13.1_OUTA_RISE_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.242	6.214	6.136	6.242
Average	6.342	6.232	6.219	6.257
Max	6.441	6.261	6.334	6.280
UL	17.000	17.000	17.000	17.000

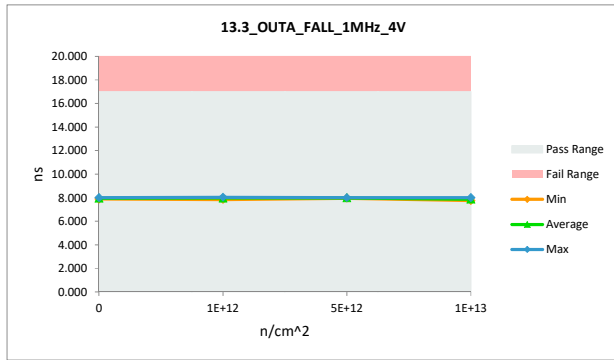


NDD Characterization Report TPS7H5006-SEP

13.3_OUTA_FALL_1MHz_4V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.514	7.881	0.367
0	49	7.693	8.000	0.307
1E+12	11	7.579	7.847	0.268
1E+12	12	7.736	8.042	0.306
1E+12	13	7.751	7.999	0.248
5E+12	14	7.694	7.997	0.303
5E+12	15	7.662	7.995	0.333
5E+12	16	7.659	7.962	0.303
1E+13	17	7.527	7.755	0.228
1E+13	18	7.696	8.000	0.304
1E+13	19	7.579	7.858	0.279
Max		7.751	8.042	0.367
Average		7.645	7.940	0.295
Min		7.514	7.755	0.228
Std Dev		0.082	0.090	0.038

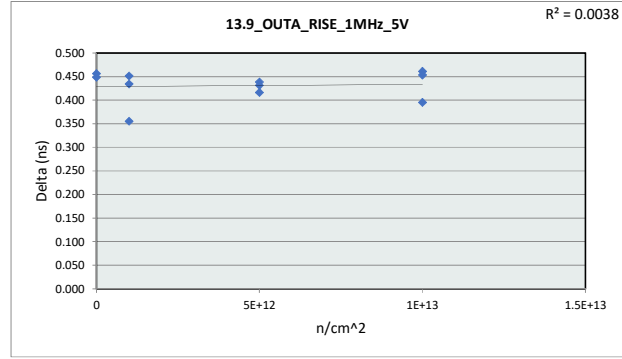


13.3_OUTA_FALL_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.881	7.847	7.962	7.755
Average	7.941	7.963	7.985	7.871
Max	8.000	8.042	7.997	8.000
UL	17.000	17.000	17.000	17.000

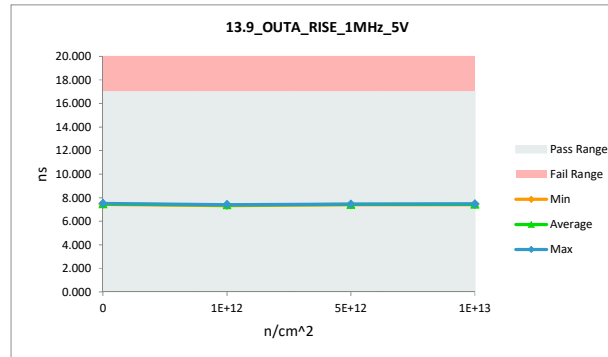


NDD Characterization Report TPS7H5006-SEP

13.9_OUTA_RISE_1MHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.963	7.419	0.456
0	49	7.065	7.513	0.448
1E+12	11	6.959	7.393	0.434
1E+12	12	6.967	7.418	0.451
1E+12	13	6.980	7.335	0.355
5E+12	14	7.034	7.450	0.416
5E+12	15	6.949	7.387	0.438
5E+12	16	7.003	7.434	0.431
1E+13	17	7.021	7.416	0.395
1E+13	18	6.979	7.432	0.453
1E+13	19	7.017	7.478	0.461
Max		7.065	7.513	0.461
Average		6.994	7.425	0.431
Min		6.949	7.335	0.355
Std Dev		0.037	0.047	0.032

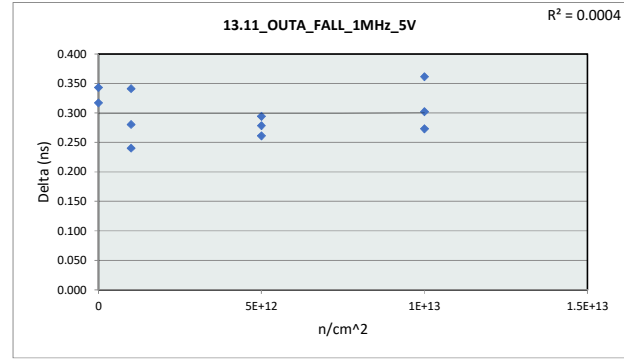


13.9_OUTA_RISE_1MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.419	7.335	7.387	7.416
Average	7.466	7.382	7.424	7.442
Max	7.513	7.418	7.450	7.478
UL	17.000	17.000	17.000	17.000

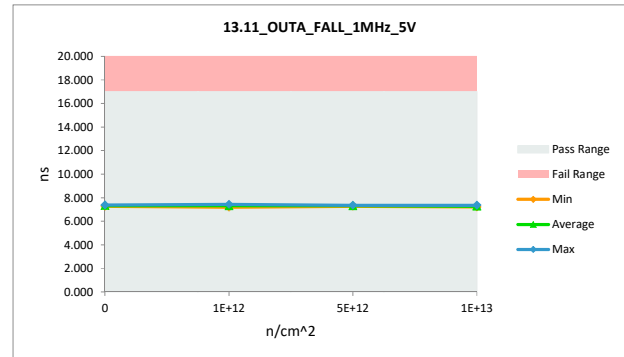


NDD Characterization Report TPS7H5006-SEP

13.11_OUTA_FALL_1MHz_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.964	7.281	0.317
0	49	7.030	7.373	0.343
1E+12	11	6.937	7.177	0.240
1E+12	12	7.081	7.422	0.341
1E+12	13	7.057	7.337	0.280
5E+12	14	7.059	7.353	0.294
5E+12	15	7.030	7.291	0.261
5E+12	16	7.004	7.282	0.278
1E+13	17	6.942	7.215	0.273
1E+13	18	6.994	7.355	0.361
1E+13	19	6.940	7.242	0.302
Max		7.081	7.422	0.361
Average		7.003	7.303	0.299
Min		6.937	7.177	0.240
Std Dev		0.052	0.073	0.038

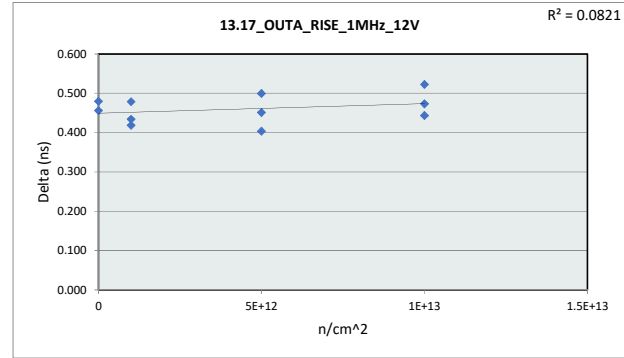


13.11_OUTA_FALL_1MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.281	7.177	7.282	7.215
Average	7.327	7.312	7.309	7.271
Max	7.373	7.422	7.353	7.355
UL	17.000	17.000	17.000	17.000

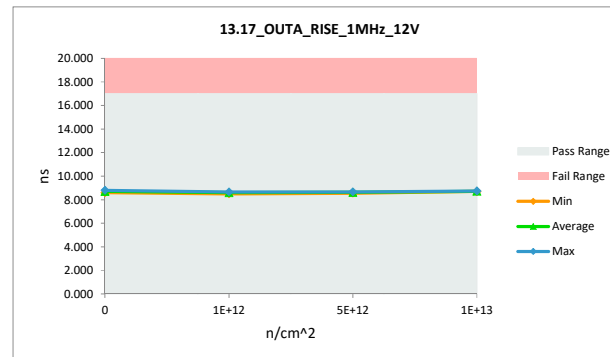


NDD Characterization Report TPS7H5006-SEP

13.17_OUTA_RISE_1MHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.151	8.607	0.456
0	49	8.317	8.796	0.479
1E+12	11	8.086	8.504	0.418
1E+12	12	8.179	8.613	0.434
1E+12	13	8.169	8.647	0.478
5E+12	14	8.199	8.650	0.451
5E+12	15	8.140	8.543	0.403
5E+12	16	8.162	8.661	0.499
1E+13	17	8.212	8.734	0.522
1E+13	18	8.235	8.708	0.473
1E+13	19	8.254	8.697	0.443
	Max	8.317	8.796	0.522
	Average	8.191	8.651	0.460
	Min	8.086	8.504	0.403
	Std Dev	0.062	0.084	0.035

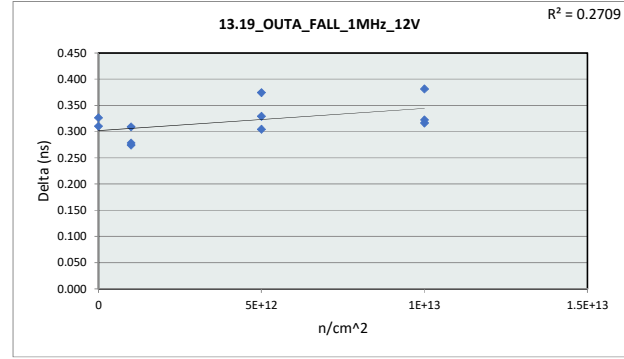


13.17_OUTA_RISE_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.607	8.504	8.543	8.697
Average	8.702	8.588	8.618	8.713
Max	8.796	8.647	8.661	8.734
UL	17.000	17.000	17.000	17.000

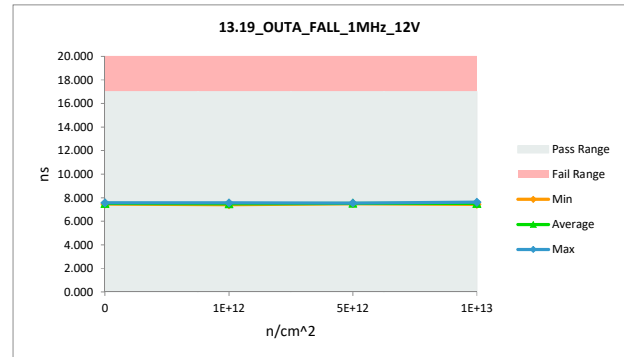


NDD Characterization Report TPS7H5006-SEP

13.19_OUTA_FALL_1MHz_12V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.124	7.450	0.326
0	49	7.249	7.559	0.310
1E+12	11	7.084	7.393	0.309
1E+12	12	7.281	7.555	0.274
1E+12	13	7.217	7.495	0.278
5E+12	14	7.240	7.544	0.304
5E+12	15	7.158	7.532	0.374
5E+12	16	7.162	7.491	0.329
1E+13	17	7.107	7.429	0.322
1E+13	18	7.229	7.610	0.381
1E+13	19	7.172	7.488	0.316
Max		7.281	7.610	0.381
Average		7.184	7.504	0.320
Min		7.084	7.393	0.274
Std Dev		0.064	0.064	0.033

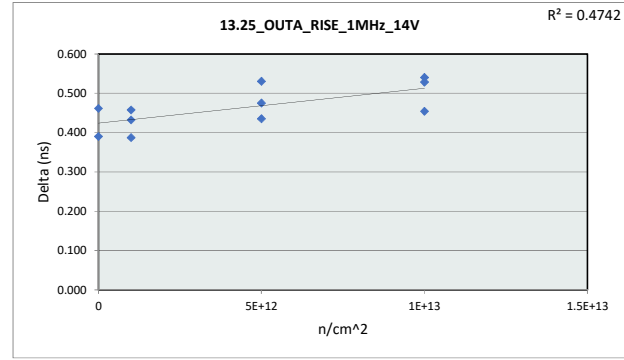


13.19_OUTA_FALL_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.450	7.393	7.491	7.429
Average	7.505	7.481	7.522	7.509
Max	7.559	7.555	7.544	7.610
UL	17.000	17.000	17.000	17.000

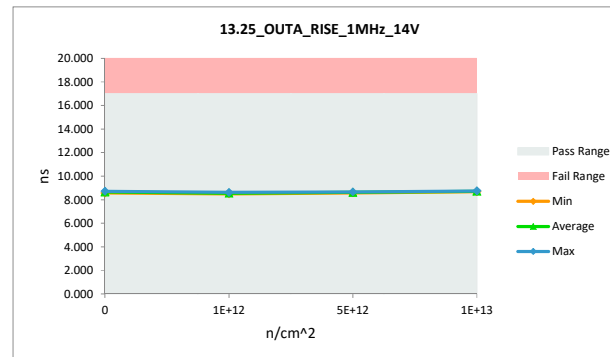


NDD Characterization Report TPS7H5006-SEP

13.25_OUTA_RISE_1MHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.108	8.569	0.461
0	49	8.322	8.712	0.390
1E+12	11	8.032	8.489	0.457
1E+12	12	8.151	8.538	0.387
1E+12	13	8.185	8.617	0.432
5E+12	14	8.184	8.619	0.435
5E+12	15	8.113	8.588	0.475
5E+12	16	8.121	8.651	0.530
1E+13	17	8.210	8.750	0.540
1E+13	18	8.188	8.716	0.528
1E+13	19	8.238	8.692	0.454
Max		8.322	8.750	0.540
Average		8.168	8.631	0.463
Min		8.032	8.489	0.387
Std Dev		0.077	0.082	0.053

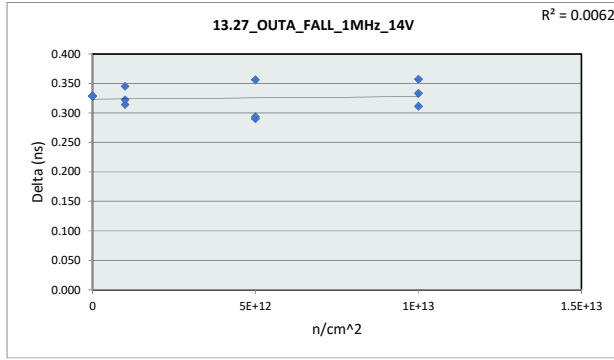


13.25_OUTA_RISE_1MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.569	8.489	8.588	8.692
Average	8.641	8.548	8.619	8.719
Max	8.712	8.617	8.651	8.750
UL	17.000	17.000	17.000	17.000

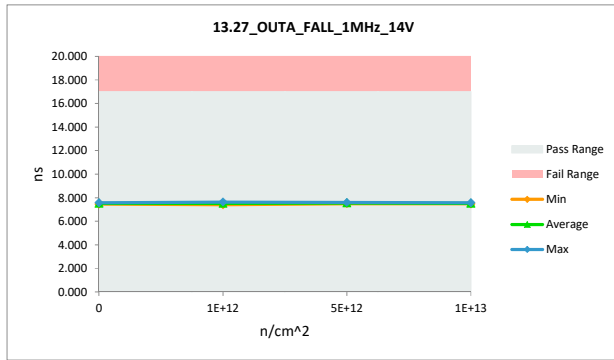


NDD Characterization Report TPS7H5006-SEP

13.27_OUTA_FALL_1MHz_14V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		16.5		17
Min Limit		4		0
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.135	7.463	0.328
0	49	7.248	7.577	0.329
1E+12	11	7.077	7.399	0.322
1E+12	12	7.285	7.630	0.345
1E+12	13	7.228	7.542	0.314
5E+12	14	7.290	7.583	0.293
5E+12	15	7.214	7.570	0.356
5E+12	16	7.206	7.496	0.290
1E+13	17	7.119	7.476	0.357
1E+13	18	7.253	7.564	0.311
1E+13	19	7.173	7.506	0.333
Max		7.290	7.630	0.357
Average		7.203	7.528	0.325
Min		7.077	7.399	0.290
Std Dev		0.069	0.066	0.022

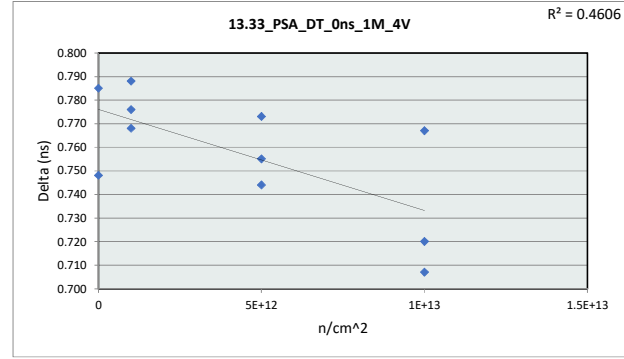


13.27_OUTA_FALL_1MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	17		ns	
Min Limit	0		ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.463	7.399	7.496	7.476
Average	7.520	7.524	7.550	7.515
Max	7.577	7.630	7.583	7.564
UL	17.000	17.000	17.000	17.000

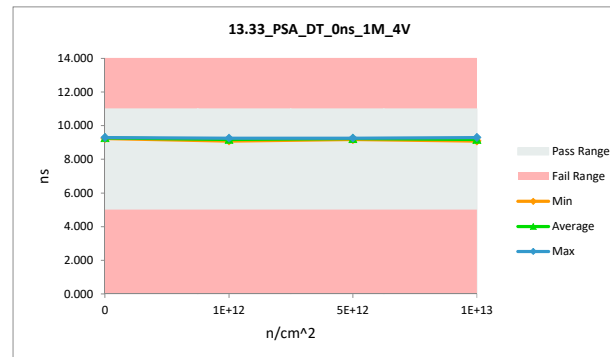


NDD Characterization Report TPS7H5006-SEP

13.33_PSA_DT_0ns_1M_4V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.495	9.243	0.748
0	49	8.509	9.294	0.785
1E+12	11	8.465	9.253	0.788
1E+12	12	8.436	9.204	0.768
1E+12	13	8.311	9.087	0.776
5E+12	14	8.504	9.259	0.755
5E+12	15	8.425	9.169	0.744
5E+12	16	8.485	9.258	0.773
1E+13	17	8.450	9.170	0.720
1E+13	18	8.381	9.088	0.707
1E+13	19	8.527	9.294	0.767
Max		8.527	9.294	0.788
Average		8.453	9.211	0.757
Min		8.311	9.087	0.707
Std Dev		0.064	0.074	0.026

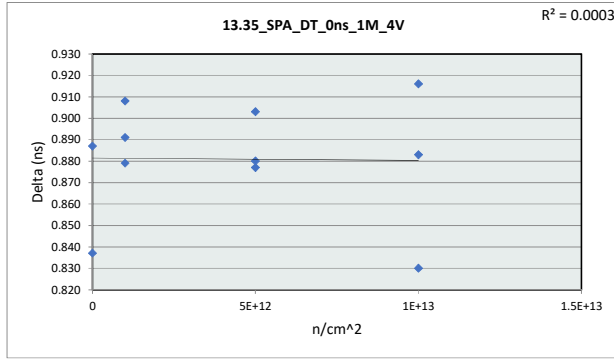


13.33_PSA_DT_0ns_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	9.243	9.087	9.169	9.088
Average	9.269	9.181	9.229	9.184
Max	9.294	9.253	9.259	9.294
UL	11.000	11.000	11.000	11.000

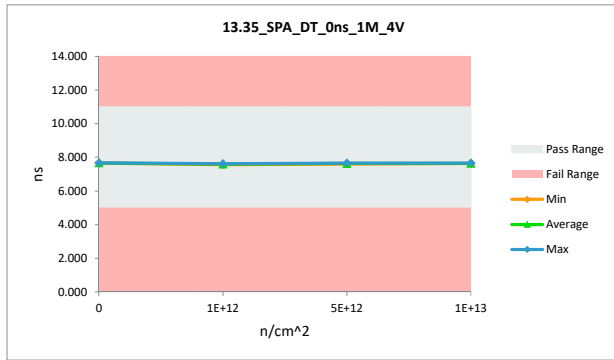


NDD Characterization Report TPS7H5006-SEP

13.35_SPA_DT_0ns_1M_4V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.829	7.666	0.837
0	49	6.775	7.662	0.887
1E+12	11	6.706	7.614	0.908
1E+12	12	6.715	7.606	0.891
1E+12	13	6.681	7.560	0.879
5E+12	14	6.718	7.621	0.903
5E+12	15	6.723	7.600	0.877
5E+12	16	6.769	7.649	0.880
1E+13	17	6.810	7.640	0.830
1E+13	18	6.713	7.629	0.916
1E+13	19	6.763	7.646	0.883
Max		6.829	7.666	0.916
Average		6.746	7.627	0.881
Min		6.681	7.560	0.830
Std Dev		0.047	0.031	0.027

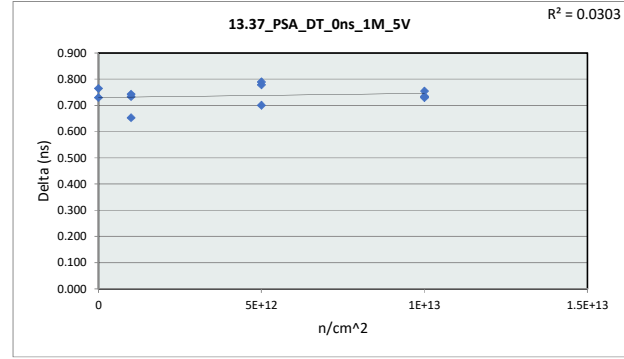


13.35_SPA_DT_0ns_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	7.662	7.560	7.600	7.629
Average	7.664	7.593	7.623	7.638
Max	7.666	7.614	7.649	7.646
UL	11.000	11.000	11.000	11.000

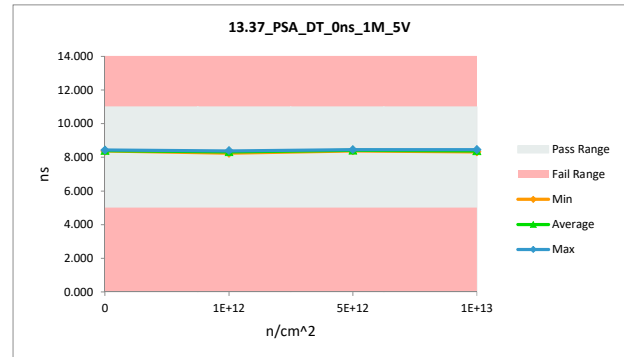


NDD Characterization Report TPS7H5006-SEP

13.37_PSA_DT_0ns_1M_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		11		11
Min Limit		5		5
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.609	8.373	0.764
0	49	7.703	8.432	0.729
1E+12	11	7.646	8.388	0.742
1E+12	12	7.625	8.358	0.733
1E+12	13	7.585	8.237	0.652
5E+12	14	7.702	8.402	0.700
5E+12	15	7.604	8.382	0.778
5E+12	16	7.664	8.453	0.789
1E+13	17	7.650	8.379	0.729
1E+13	18	7.593	8.327	0.734
1E+13	19	7.701	8.455	0.754
Max		7.703	8.455	0.789
Average		7.644	8.381	0.737
Min		7.585	8.237	0.652
Std Dev		0.044	0.062	0.038

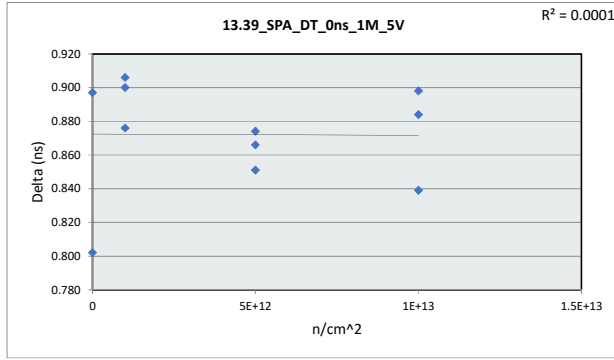


13.37_PSA_DT_0ns_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	11			ns
Min Limit	5			ns
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.373	8.237	8.382	8.327
Average	8.403	8.328	8.412	8.387
Max	8.432	8.388	8.453	8.455
UL	11.000	11.000	11.000	11.000

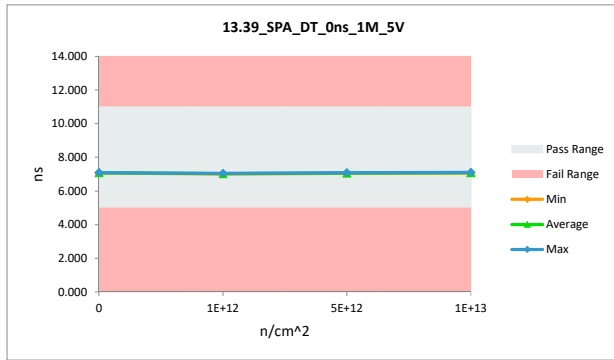


NDD Characterization Report TPS7H5006-SEP

13.39_SPA_DT_0ns_1M_5V				
Test Site				
Tester				
Test Number				
Unit		ns		ns
Max Limit		11		11
Min Limit		5		5
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.254	7.056	0.802
0	49	6.200	7.097	0.897
1E+12	11	6.108	7.008	0.900
1E+12	12	6.153	7.029	0.876
1E+12	13	6.136	7.042	0.906
5E+12	14	6.170	7.044	0.874
5E+12	15	6.182	7.048	0.866
5E+12	16	6.239	7.090	0.851
1E+13	17	6.216	7.100	0.884
1E+13	18	6.192	7.090	0.898
1E+13	19	6.227	7.066	0.839
Max		6.254	7.100	0.906
Average		6.189	7.061	0.872
Min		6.108	7.008	0.802
Std Dev		0.045	0.030	0.031

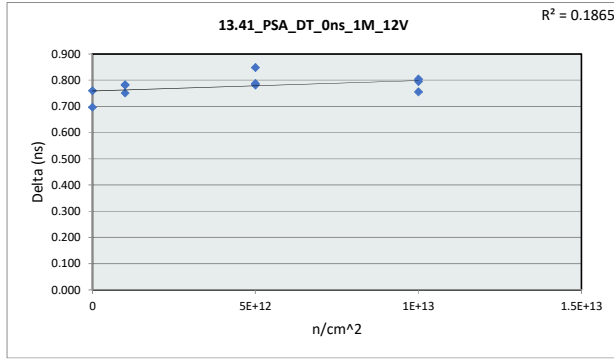


13.39_SPA_DT_0ns_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	11		ns	
Min Limit	5		ns	
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	7.056	7.008	7.044	7.066
Average	7.077	7.026	7.061	7.085
Max	7.097	7.042	7.090	7.100
UL	11.000	11.000	11.000	11.000

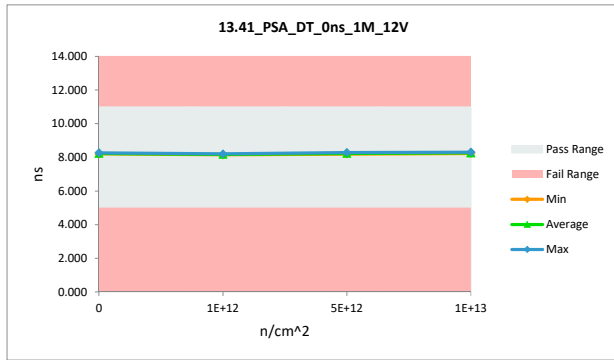


NDD Characterization Report TPS7H5006-SEP

13.41_PSA_DT_Ons_1M_12V				
Test Site				
Tester				
Test Number				
Unit	ns	ns		
Max Limit	11	11		
Min Limit	5	5		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.502	8.198	0.696
0	49	7.510	8.269	0.759
1E+12	11	7.393	8.143	0.750
1E+12	12	7.423	8.204	0.781
1E+12	13	7.390	8.172	0.782
5E+12	14	7.427	8.275	0.848
5E+12	15	7.406	8.187	0.781
5E+12	16	7.457	8.244	0.787
1E+13	17	7.477	8.232	0.755
1E+13	18	7.431	8.235	0.804
1E+13	19	7.507	8.301	0.794
Max		7.510	8.301	0.848
Average		7.448	8.224	0.776
Min		7.390	8.143	0.696
Std Dev		0.045	0.048	0.038

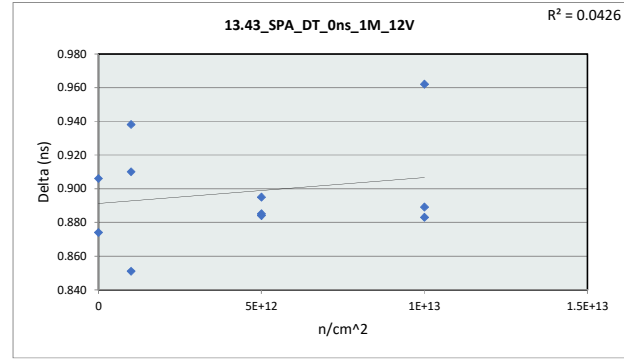


13.41_PSA_DT_Ons_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.198	8.143	8.187	8.232
Average	8.234	8.173	8.235	8.256
Max	8.269	8.204	8.275	8.301
UL	11.000	11.000	11.000	11.000

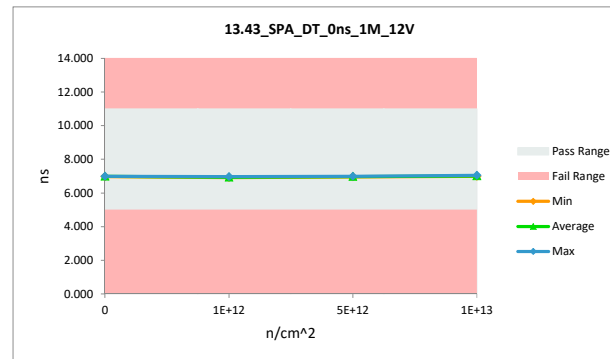


NDD Characterization Report TPS7H5006-SEP

13.43_SPA_DT_Ons_1M_12V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.085	6.991	0.906
0	49	6.105	6.979	0.874
1E+12	11	5.984	6.922	0.938
1E+12	12	6.067	6.918	0.851
1E+12	13	6.057	6.967	0.910
5E+12	14	6.073	6.958	0.885
5E+12	15	6.097	6.992	0.895
5E+12	16	6.087	6.971	0.884
1E+13	17	6.120	7.003	0.883
1E+13	18	6.085	7.047	0.962
1E+13	19	6.095	6.984	0.889
Max		6.120	7.047	0.962
Average		6.078	6.976	0.898
Min		5.984	6.918	0.851
Std Dev		0.036	0.036	0.031

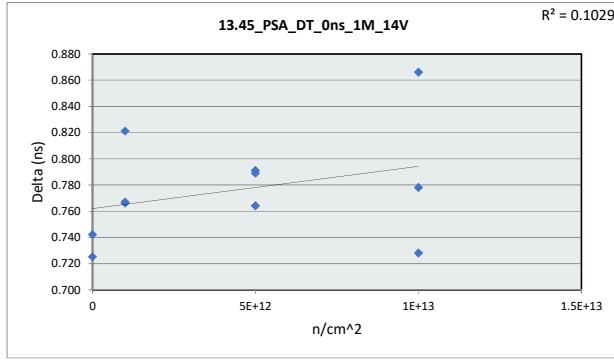


13.43_SPA_DT_Ons_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	6.979	6.918	6.958	6.984
Average	6.985	6.936	6.974	7.011
Max	6.991	6.967	6.992	7.047
UL	11.000	11.000	11.000	11.000

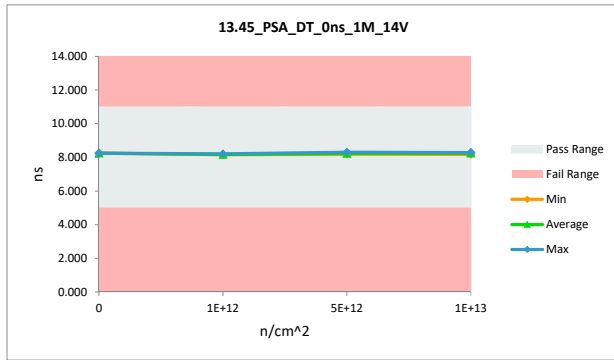


NDD Characterization Report TPS7H5006-SEP

13.45_PSA_DT_Ons_1M_14V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.500	8.242	0.742
0	49	7.515	8.240	0.725
1E+12	11	7.392	8.159	0.767
1E+12	12	7.380	8.201	0.821
1E+12	13	7.392	8.158	0.766
5E+12	14	7.507	8.298	0.791
5E+12	15	7.404	8.193	0.789
5E+12	16	7.460	8.224	0.764
1E+13	17	7.446	8.174	0.728
1E+13	18	7.401	8.267	0.866
1E+13	19	7.503	8.281	0.778
Max		7.515	8.298	0.866
Average		7.445	8.222	0.776
Min		7.380	8.158	0.725
Std Dev		0.054	0.049	0.041

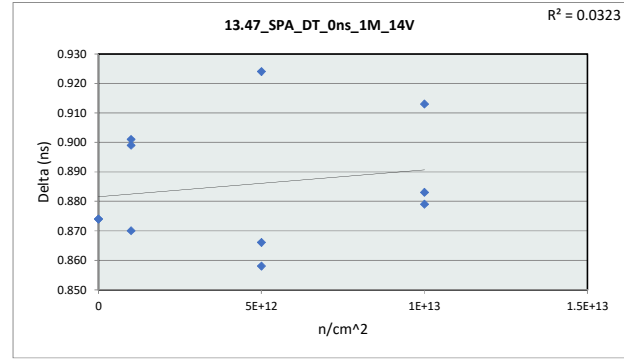


13.45_PSA_DT_Ons_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.240	8.158	8.193	8.174
Average	8.241	8.173	8.238	8.241
Max	8.242	8.201	8.298	8.281
UL	11.000	11.000	11.000	11.000

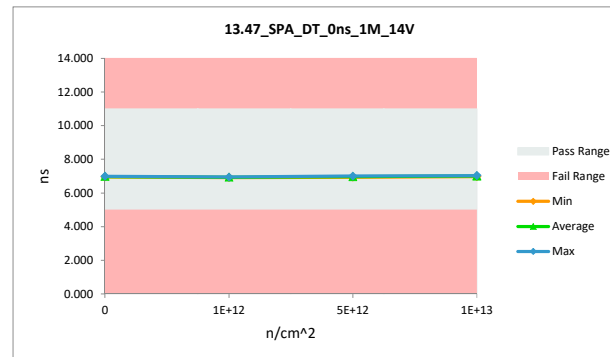


NDD Characterization Report TPS7H5006-SEP

13.47_SPA_DT_Ons_1M_14V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.085	6.959	0.874
0	49	6.115	6.989	0.874
1E+12	11	6.022	6.923	0.901
1E+12	12	6.060	6.930	0.870
1E+12	13	6.048	6.947	0.899
5E+12	14	6.097	6.963	0.866
5E+12	15	6.075	6.933	0.858
5E+12	16	6.074	6.998	0.924
1E+13	17	6.147	7.030	0.883
1E+13	18	6.125	7.004	0.879
1E+13	19	6.067	6.980	0.913
Max		6.147	7.030	0.924
Average		6.083	6.969	0.886
Min		6.022	6.923	0.858
Std Dev		0.036	0.034	0.021

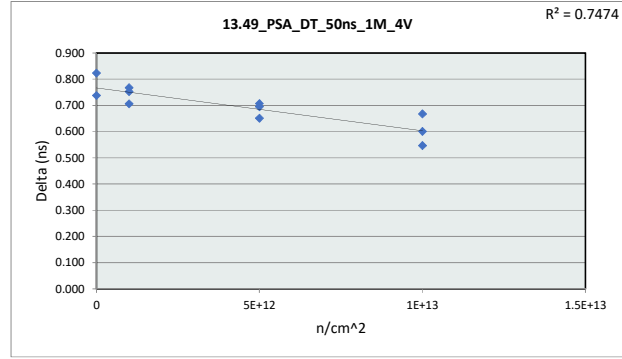


13.47_SPA_DT_Ons_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	6.959	6.923	6.933	6.980
Average	6.974	6.933	6.965	7.005
Max	6.989	6.947	6.998	7.030
UL	11.000	11.000	11.000	11.000

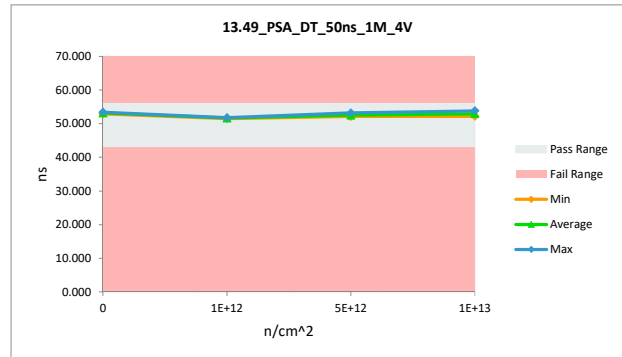


NDD Characterization Report TPS7H5006-SEP

13.49_PSA_DT_50ns_1M_4V				
Test Site				
Tester				
Test Number				
Unit	ns	ns		
Max Limit	56	56		
Min Limit	44	43		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	52.665	53.402	0.737
0	49	52.120	52.943	0.823
1E+12	11	51.013	51.765	0.752
1E+12	12	50.737	51.504	0.767
1E+12	13	51.094	51.800	0.706
5E+12	14	51.579	52.285	0.706
5E+12	15	51.465	52.116	0.651
5E+12	16	52.518	53.213	0.695
1E+13	17	53.270	53.816	0.546
1E+13	18	52.117	52.784	0.667
1E+13	19	51.575	52.175	0.600
Max		53.270	53.816	0.823
Average		51.832	52.528	0.695
Min		50.737	51.504	0.546
Std Dev		0.779	0.751	0.078

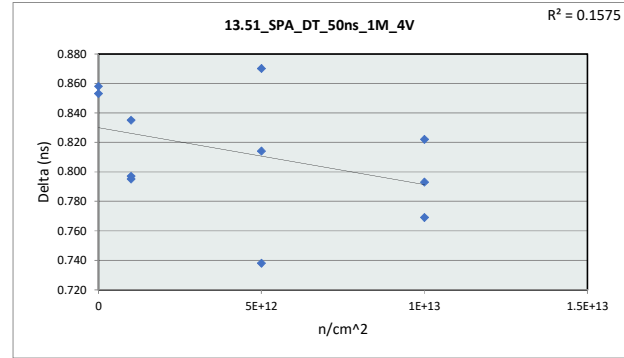


13.49_PSA_DT_50ns_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	56	ns		
Min Limit	43	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	52.943	51.504	52.116	52.175
Average	53.173	51.690	52.538	52.925
Max	53.402	51.800	53.213	53.816
UL	56.000	56.000	56.000	56.000

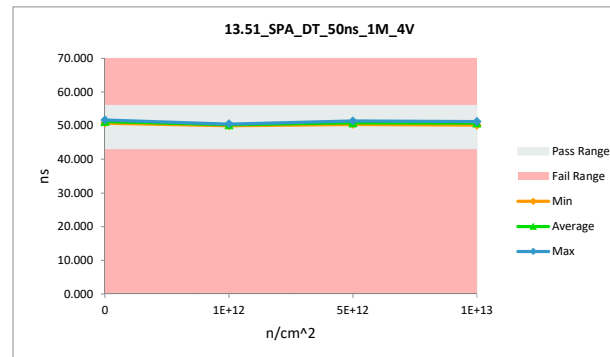


NDD Characterization Report TPS7H5006-SEP

13.51_SPA_DT_50ns_1M_4V				
Test Site				
Tester				
Test Number				
Unit	ns		ns	
Max Limit	56		56	
Min Limit	44		43	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.810	51.668	0.858
0	49	49.931	50.784	0.853
1E+12	11	49.227	50.024	0.797
1E+12	12	49.318	50.153	0.835
1E+12	13	49.705	50.500	0.795
5E+12	14	49.826	50.640	0.814
5E+12	15	49.613	50.351	0.738
5E+12	16	50.538	51.408	0.870
1E+13	17	50.199	51.021	0.822
1E+13	18	50.433	51.202	0.769
1E+13	19	49.328	50.121	0.793
Max		50.810	51.668	0.870
Average		49.903	50.716	0.813
Min		49.227	50.024	0.738
Std Dev		0.534	0.553	0.040

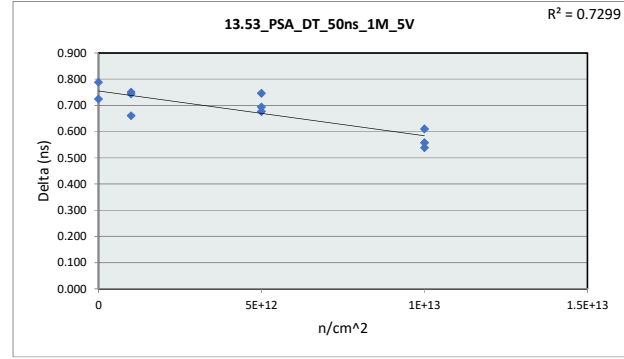


13.51_SPA_DT_50ns_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	56		ns	
Min Limit	43		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.784	50.024	50.351	50.121
Average	51.226	50.226	50.800	50.781
Max	51.668	50.500	51.408	51.202
UL	56.000	56.000	56.000	56.000

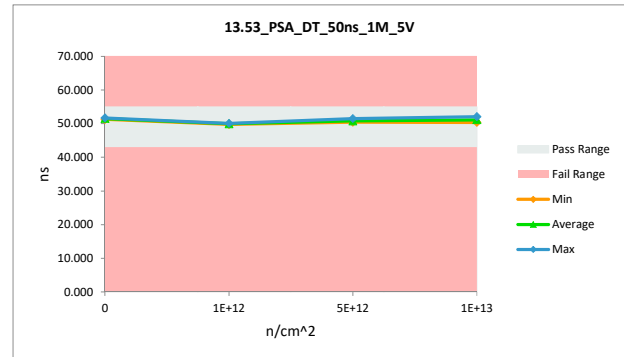


NDD Characterization Report TPS7H5006-SEP

13.53_PSA_DT_50ns_1M_5V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.902	51.690	0.788
0	49	50.550	51.274	0.724
1E+12	11	49.314	50.064	0.750
1E+12	12	49.005	49.748	0.743
1E+12	13	49.388	50.048	0.660
5E+12	14	49.785	50.531	0.746
5E+12	15	49.711	50.387	0.676
5E+12	16	50.783	51.476	0.693
1E+13	17	51.437	52.047	0.610
1E+13	18	50.580	51.137	0.557
1E+13	19	49.819	50.357	0.538
Max		51.437	52.047	0.788
Average		50.116	50.796	0.680
Min		49.005	49.748	0.538
Std Dev		0.773	0.761	0.082

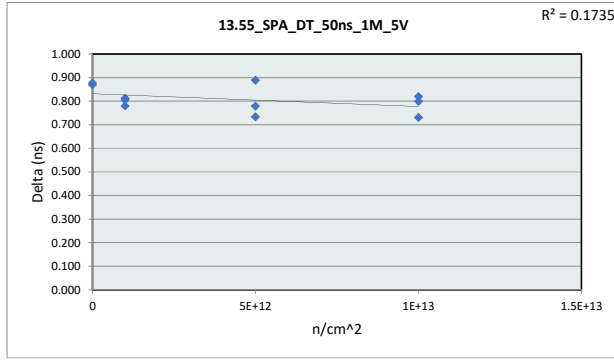


13.53_PSA_DT_50ns_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	51.274	49.748	50.387	50.357
Average	51.482	49.953	50.798	51.180
Max	51.690	50.064	51.476	52.047
UL	55.000	55.000	55.000	55.000

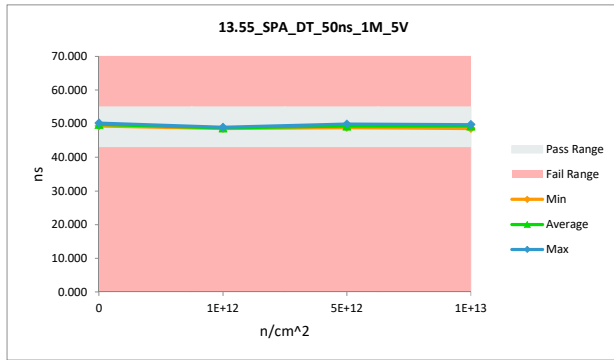


NDD Characterization Report TPS7H5006-SEP

13.55_SPA_DT_50ns_1M_5V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	49.289	50.158	0.869
0	49	48.464	49.341	0.877
1E+12	11	47.731	48.543	0.812
1E+12	12	47.803	48.607	0.804
1E+12	13	48.162	48.941	0.779
5E+12	14	48.339	49.117	0.778
5E+12	15	48.130	48.863	0.733
5E+12	16	49.027	49.915	0.888
1E+13	17	48.726	49.545	0.819
1E+13	18	48.916	49.715	0.799
1E+13	19	47.848	48.578	0.730
Max		49.289	50.158	0.888
Average		48.403	49.211	0.808
Min		47.731	48.543	0.730
Std Dev		0.529	0.565	0.053

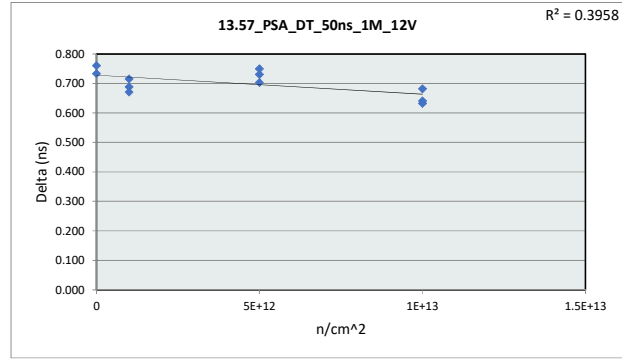


13.55_SPA_DT_50ns_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.341	48.543	48.863	48.578
Average	49.750	48.697	49.298	49.279
Max	50.158	48.941	49.915	49.715
UL	55.000	55.000	55.000	55.000

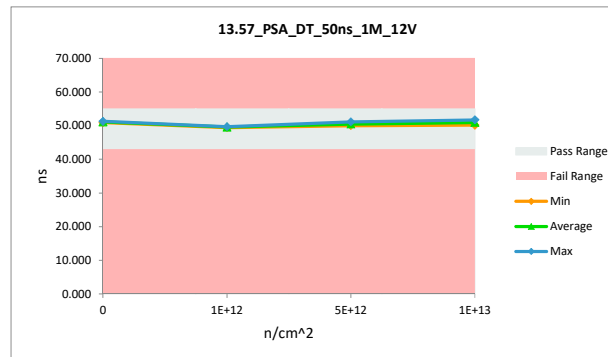


NDD Characterization Report TPS7H5006-SEP

13.57_PSA_DT_50ns_1M_12V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.485	51.245	0.760
0	49	50.189	50.922	0.733
1E+12	11	48.928	49.643	0.715
1E+12	12	48.685	49.373	0.688
1E+12	13	49.007	49.677	0.670
5E+12	14	49.468	50.198	0.730
5E+12	15	49.327	50.030	0.703
5E+12	16	50.367	51.116	0.749
1E+13	17	51.100	51.732	0.632
1E+13	18	50.234	50.874	0.640
1E+13	19	49.448	50.129	0.681
Max		51.100	51.732	0.760
Average		49.749	50.449	0.700
Min		48.685	49.373	0.632
Std Dev		0.767	0.766	0.042

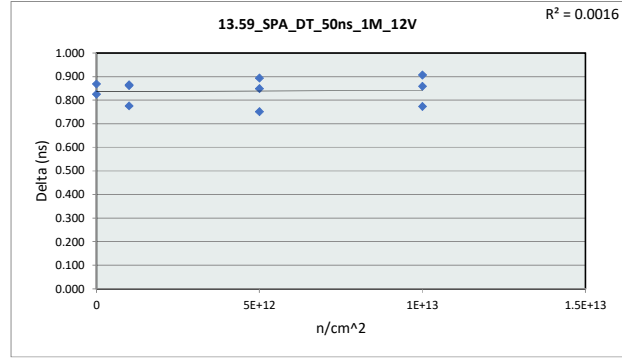


13.57_PSA_DT_50ns_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.922	49.373	50.030	50.129
Average	51.084	49.564	50.448	50.912
Max	51.245	49.677	51.116	51.732
UL	55.000	55.000	55.000	55.000

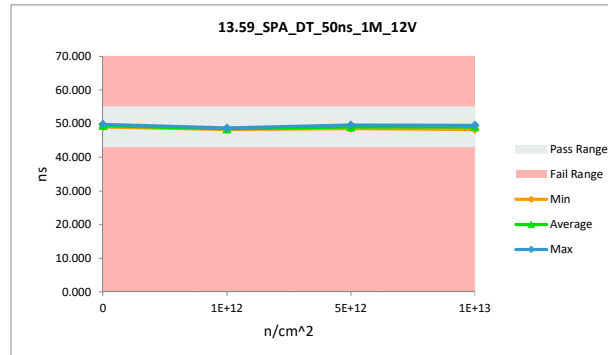


NDD Characterization Report TPS7H5006-SEP

13.59_SPA_DT_50ns_1M_12V				
Test Site				
Tester				
Test Number				
Unit	ns		ns	
Max Limit	55		55	
Min Limit	45		43	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	48.983	49.808	0.825
0	49	48.201	49.069	0.868
1E+12	11	47.376	48.237	0.861
1E+12	12	47.540	48.315	0.775
1E+12	13	47.833	48.698	0.865
5E+12	14	48.005	48.853	0.848
5E+12	15	47.815	48.566	0.751
5E+12	16	48.704	49.597	0.893
1E+13	17	48.421	49.327	0.906
1E+13	18	48.640	49.498	0.858
1E+13	19	47.527	48.300	0.773
Max		48.983	49.808	0.906
Average		48.095	48.933	0.838
Min		47.376	48.237	0.751
Std Dev		0.536	0.562	0.051

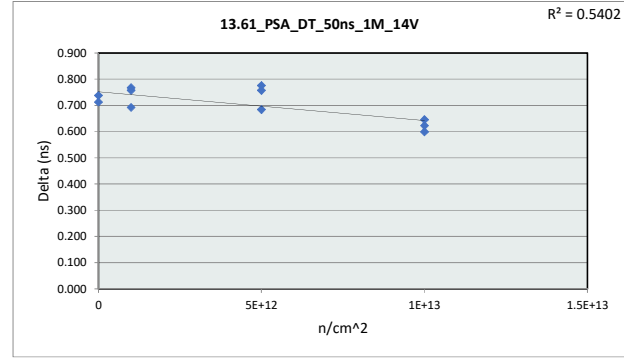


13.59_SPA_DT_50ns_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.069	48.237	48.566	48.300
Average	49.439	48.417	49.005	49.042
Max	49.808	48.698	49.597	49.498
UL	55.000	55.000	55.000	55.000

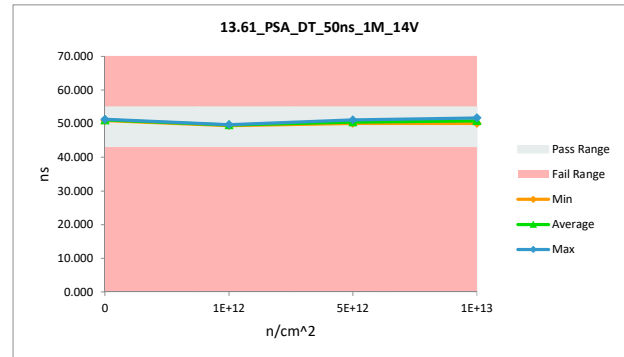


NDD Characterization Report TPS7H5006-SEP

13.61_PSA_DT_50ns_1M_14V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.555	51.267	0.712
0	49	50.192	50.929	0.737
1E+12	11	48.874	49.641	0.767
1E+12	12	48.665	49.422	0.757
1E+12	13	49.021	49.713	0.692
5E+12	14	49.433	50.190	0.757
5E+12	15	49.370	50.054	0.684
5E+12	16	50.320	51.095	0.775
1E+13	17	51.054	51.699	0.645
1E+13	18	50.226	50.825	0.599
1E+13	19	49.464	50.086	0.622
Max		51.054	51.699	0.775
Average		49.743	50.447	0.704
Min		48.665	49.422	0.599
Std Dev		0.768	0.750	0.061

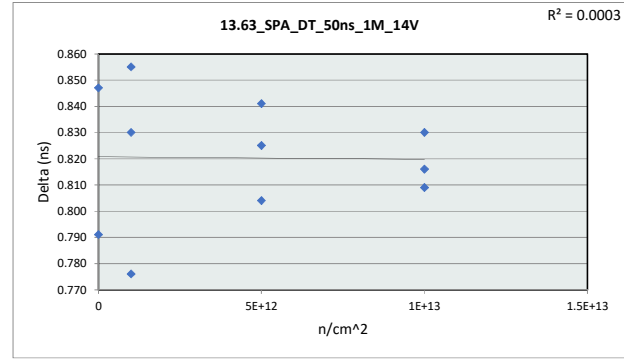


13.61_PSA_DT_50ns_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.929	49.422	50.054	50.086
Average	51.098	49.592	50.446	50.870
Max	51.267	49.713	51.095	51.699
UL	55.000	55.000	55.000	55.000

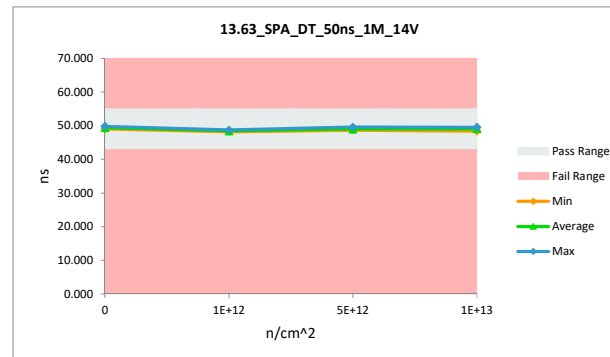


NDD Characterization Report TPS7H5006-SEP

13.63_SPA_DT_50ns_1M_14V				
Test Site				
Tester				
Test Number				
Unit	ns	ns		
Max Limit	55	55		
Min Limit	45	43		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	48.941	49.788	0.847
0	49	48.241	49.032	0.791
1E+12	11	47.360	48.215	0.855
1E+12	12	47.579	48.355	0.776
1E+12	13	47.879	48.709	0.830
5E+12	14	48.029	48.833	0.804
5E+12	15	47.804	48.629	0.825
5E+12	16	48.710	49.551	0.841
1E+13	17	48.505	49.321	0.816
1E+13	18	48.672	49.481	0.809
1E+13	19	47.523	48.353	0.830
Max		48.941	49.788	0.855
Average		48.113	48.933	0.820
Min		47.360	48.215	0.776
Std Dev		0.537	0.540	0.024

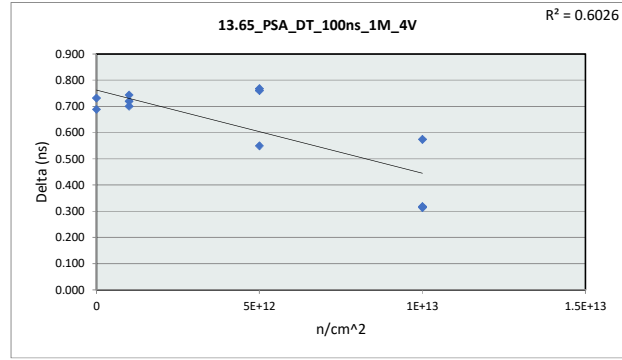


13.63_SPA_DT_50ns_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.032	48.215	48.629	48.353
Average	49.410	48.426	49.004	49.052
Max	49.788	48.709	49.551	49.481
UL	55.000	55.000	55.000	55.000

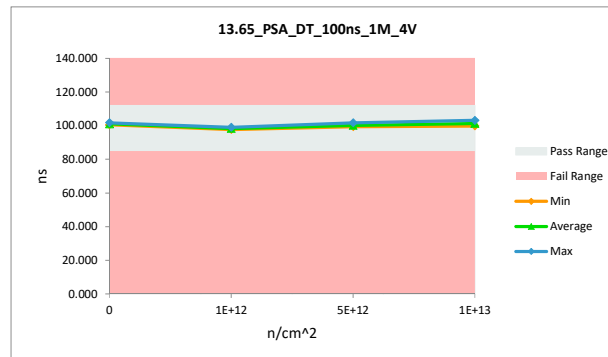


NDD Characterization Report TPS7H5006-SEP

13.65_PSA_DT_100ns_1M_4V				
Test Site				
Tester				
Test Number				
Unit	ns	ns		
Max Limit	112	112		
Min Limit	87	85		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	101.010	101.741	0.731
0	49	99.750	100.438	0.688
1E+12	11	97.342	98.085	0.743
1E+12	12	97.026	97.745	0.719
1E+12	13	98.269	98.969	0.700
5E+12	14	98.639	99.399	0.760
5E+12	15	98.746	99.295	0.549
5E+12	16	100.805	101.572	0.767
1E+13	17	102.828	103.145	0.317
1E+13	18	100.435	100.749	0.314
1E+13	19	99.223	99.797	0.574
	Max	102.828	103.145	0.767
	Average	99.461	100.085	0.624
	Min	97.026	97.745	0.314
	Std Dev	1.722	1.636	0.168

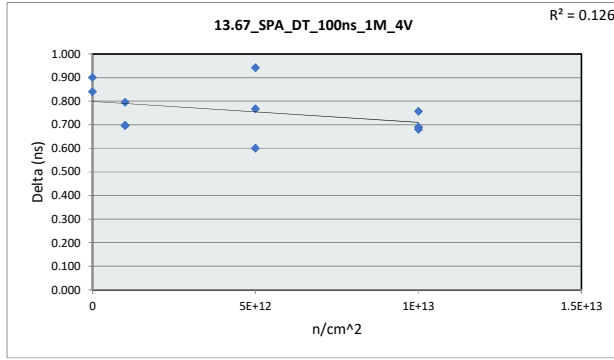


13.65_PSA_DT_100ns_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	112	ns		
Min Limit	85	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	100.438	97.745	99.295	99.797
Average	101.090	98.266	100.089	101.230
Max	101.741	98.969	101.572	103.145
UL	112.000	112.000	112.000	112.000

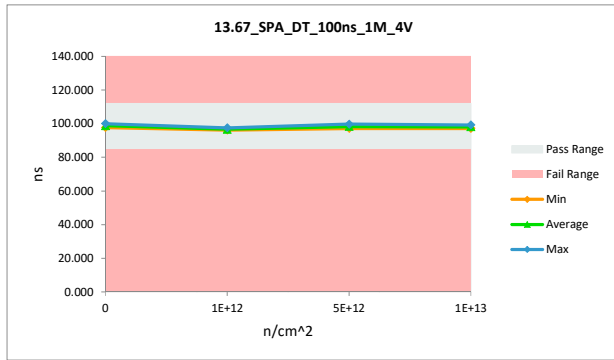


NDD Characterization Report TPS7H5006-SEP

13.67_SPA_DT_100ns_1M_4V				
Test Site				
Tester				
Test Number				
Unit	ns	ns		
Max Limit	112	112		
Min Limit	87	85		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	99.097	99.997	0.900
0	49	96.812	97.651	0.839
1E+12	11	95.423	96.218	0.795
1E+12	12	95.476	96.172	0.696
1E+12	13	96.810	97.506	0.696
5E+12	14	97.216	97.983	0.767
5E+12	15	96.533	97.133	0.600
5E+12	16	98.772	99.713	0.941
1E+13	17	97.162	97.918	0.756
1E+13	18	98.562	99.252	0.690
1E+13	19	96.473	97.153	0.680
Max		99.097	99.997	0.941
Average		97.121	97.881	0.760
Min		95.423	96.172	0.600
Std Dev		1.236	1.292	0.102

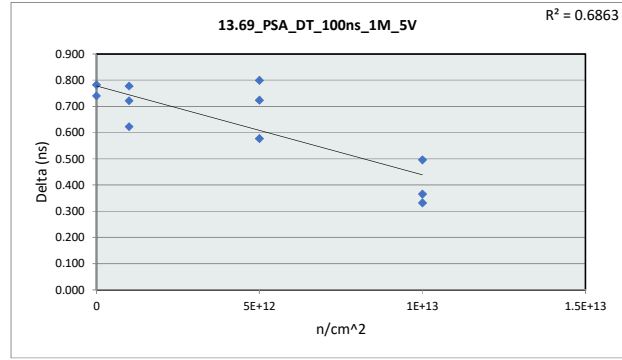


13.67_SPA_DT_100ns_1M_4V				
Test Site				
Tester				
Test Number				
Max Limit	112	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	97.651	96.172	97.133	97.153
Average	98.824	96.632	98.276	98.108
Max	99.997	97.506	99.713	99.252
UL	112.000	112.000	112.000	112.000

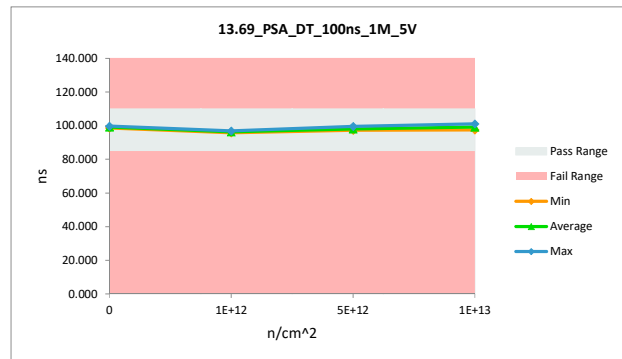


NDD Characterization Report TPS7H5006-SEP

13.69_PSA_DT_100ns_1M_5V				
Test Site				
Tester				
Test Number				
Unit	ns		ns	
Max Limit	110		110	
Min Limit	89		85	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	98.980	99.719	0.739
0	49	97.869	98.651	0.782
1E+12	11	95.409	96.186	0.777
1E+12	12	95.076	95.797	0.721
1E+12	13	96.241	96.863	0.622
5E+12	14	96.652	97.375	0.723
5E+12	15	96.761	97.338	0.577
5E+12	16	98.819	99.618	0.799
1E+13	17	100.662	101.027	0.365
1E+13	18	98.547	98.878	0.331
1E+13	19	96.993	97.488	0.495
Max		100.662	101.027	0.799
Average		97.455	98.085	0.630
Min		95.076	95.797	0.331
Std Dev		1.688	1.624	0.168

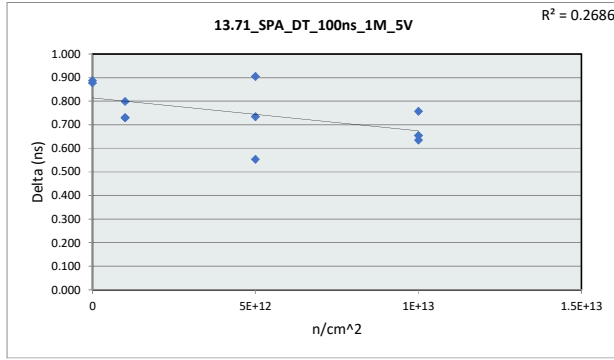


13.69_PSA_DT_100ns_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	110		ns	
Min Limit	85		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	98.651	95.797	97.338	97.488
Average	99.185	96.282	98.110	99.131
Max	99.719	96.863	99.618	101.027
UL	110.000	110.000	110.000	110.000

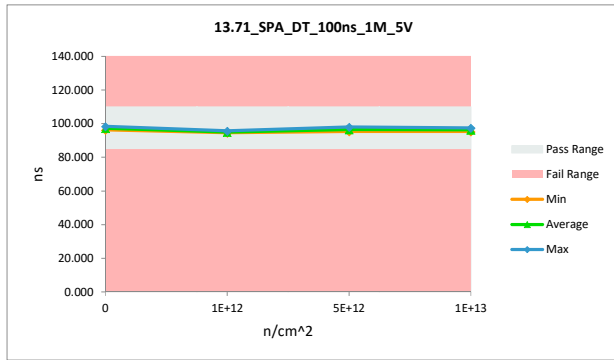


NDD Characterization Report TPS7H5006-SEP

13.71_SPA_DT_100ns_1M_5V				
Test Site				
Tester				
Test Number				
Unit	ns	ns		
Max Limit	110	110		
Min Limit	89	85		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	97.515	98.394	0.879
0	49	95.366	96.255	0.889
1E+12	11	93.795	94.595	0.800
1E+12	12	93.889	94.620	0.731
1E+12	13	95.003	95.735	0.732
5E+12	14	95.480	96.216	0.736
5E+12	15	94.945	95.500	0.555
5E+12	16	97.158	98.064	0.906
1E+13	17	95.668	96.427	0.759
1E+13	18	96.917	97.554	0.637
1E+13	19	94.634	95.290	0.656
Max		97.515	98.394	0.906
Average		95.488	96.241	0.753
Min		93.795	94.595	0.555
Std Dev		1.252	1.295	0.111

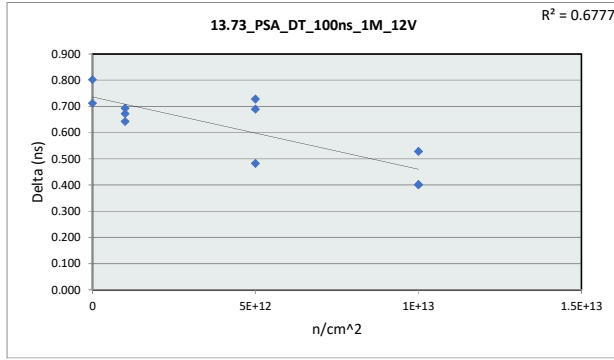


13.71_SPA_DT_100ns_1M_5V				
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	96.255	94.595	95.500	95.290
Average	97.325	94.983	96.593	96.424
Max	98.394	95.735	98.064	97.554
UL	110.000	110.000	110.000	110.000

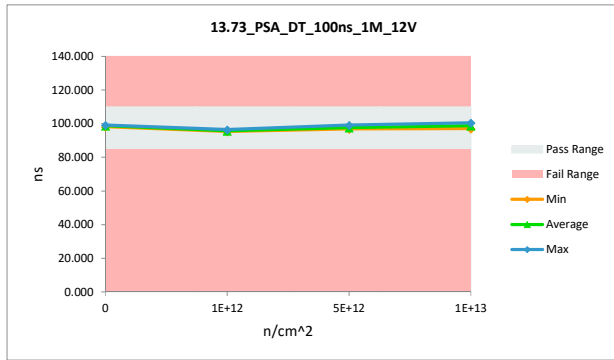


NDD Characterization Report TPS7H5006-SEP

13.73_PSA_DT_100ns_1M_12V				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		110	110	
Min Limit		89	85	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	98.454	99.258	0.804
0	49	97.489	98.203	0.714
1E+12	11	94.998	95.642	0.644
1E+12	12	94.661	95.356	0.695
1E+12	13	95.790	96.464	0.674
5E+12	14	96.180	96.910	0.730
5E+12	15	96.335	96.819	0.484
5E+12	16	98.409	99.100	0.691
1E+13	17	100.191	100.594	0.403
1E+13	18	98.140	98.543	0.403
1E+13	19	96.554	97.084	0.530
Max		100.191	100.594	0.804
Average		97.018	97.634	0.616
Min		94.661	95.356	0.403
Std Dev		1.676	1.634	0.138

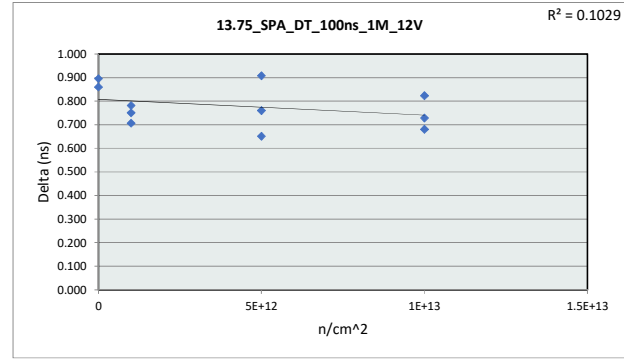


13.73_PSA_DT_100ns_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	98.203	95.356	96.819	97.084
Average	98.731	95.821	97.610	98.740
Max	99.258	96.464	99.100	100.594
UL	110.000	110.000	110.000	110.000

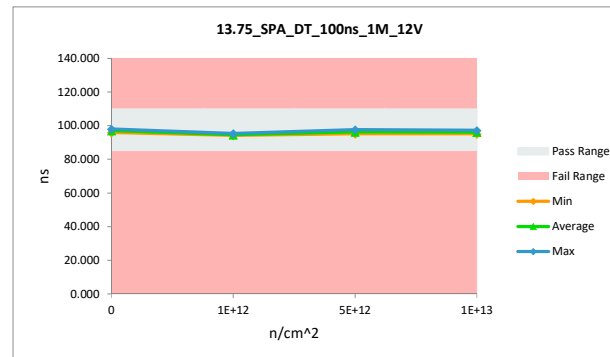


NDD Characterization Report TPS7H5006-SEP

13.75_SPA_DT_100ns_1M_12V				
Test Site				
Tester				
Test Number				
Unit	ns	ns		
Max Limit	110	110		
Min Limit	89	85		
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	97.174	98.035	0.861
0	49	95.110	96.007	0.897
1E+12	11	93.467	94.250	0.783
1E+12	12	93.634	94.342	0.708
1E+12	13	94.694	95.446	0.752
5E+12	14	95.200	95.962	0.762
5E+12	15	94.608	95.261	0.653
5E+12	16	96.834	97.743	0.909
1E+13	17	95.367	96.192	0.825
1E+13	18	96.589	97.319	0.730
1E+13	19	94.393	95.075	0.682
Max		97.174	98.035	0.909
Average		95.188	95.967	0.778
Min		93.467	94.250	0.653
Std Dev		1.235	1.283	0.086

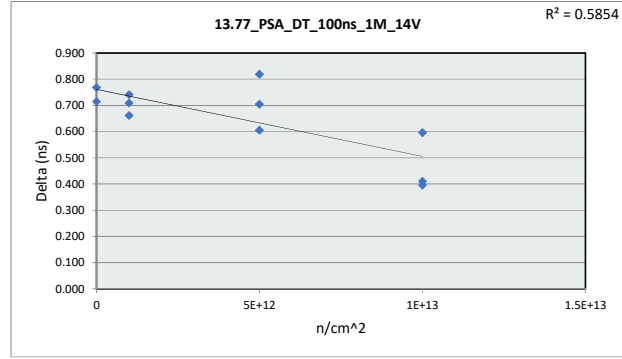


13.75_SPA_DT_100ns_1M_12V				
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm ²	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	96.007	94.250	95.261	95.075
Average	97.021	94.679	96.322	96.195
Max	98.035	95.446	97.743	97.319
UL	110.000	110.000	110.000	110.000

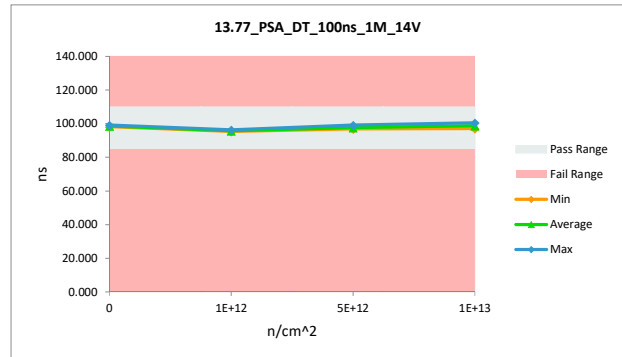


NDD Characterization Report TPS7H5006-SEP

13.77_PSA_DT_100ns_1M_14V				
Test Site				
Tester				
Test Number				
Unit	ns		ns	
Max Limit	110		110	
Min Limit	85		85	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	98.441	99.211	0.770
0	49	97.460	98.176	0.716
1E+12	11	94.962	95.673	0.711
1E+12	12	94.604	95.347	0.743
1E+12	13	95.758	96.421	0.663
5E+12	14	96.197	96.903	0.706
5E+12	15	96.261	96.868	0.607
5E+12	16	98.321	99.142	0.821
1E+13	17	100.198	100.595	0.397
1E+13	18	98.110	98.522	0.412
1E+13	19	96.505	97.103	0.598
Max		100.198	100.595	0.821
Average		96.983	97.633	0.649
Min		94.604	95.347	0.397
Std Dev		1.684	1.630	0.137

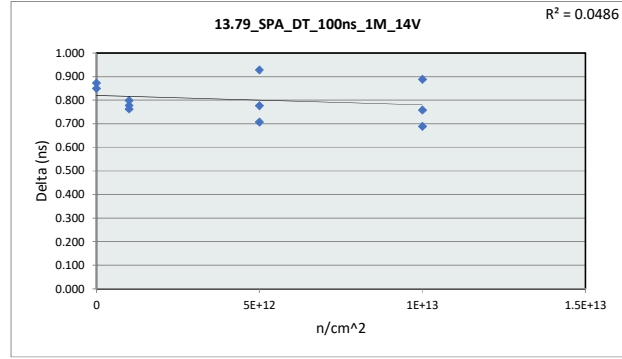


13.77_PSA_DT_100ns_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	110		ns	
Min Limit	85		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	98.176	95.347	96.868	97.103
Average	98.694	95.814	97.638	98.740
Max	99.211	96.421	99.142	100.595
UL	110.000	110.000	110.000	110.000

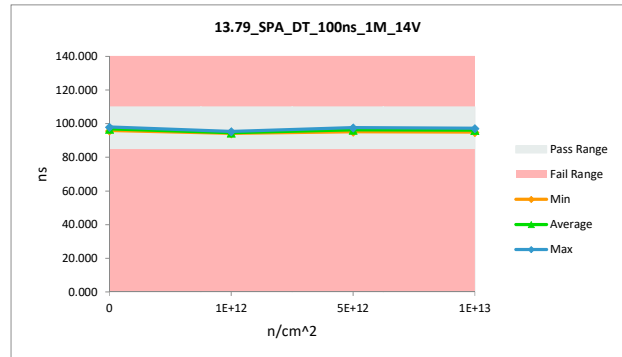


NDD Characterization Report TPS7H5006-SEP

13.79_SPA_DT_100ns_1M_14V				
Test Site				
Tester				
Test Number				
Unit	ns		ns	
Max Limit	110		110	
Min Limit	89		85	
n/cm ²	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	97.173	98.047	0.874
0	49	95.092	95.944	0.852
1E+12	11	93.428	94.207	0.779
1E+12	12	93.593	94.357	0.764
1E+12	13	94.661	95.461	0.800
5E+12	14	95.177	95.955	0.778
5E+12	15	94.563	95.272	0.709
5E+12	16	96.805	97.735	0.930
1E+13	17	95.348	96.238	0.890
1E+13	18	96.558	97.318	0.760
1E+13	19	94.349	95.039	0.690
Max		97.173	98.047	0.930
Average		95.159	95.961	0.802
Min		93.428	94.207	0.690
Std Dev		1.244	1.290	0.076

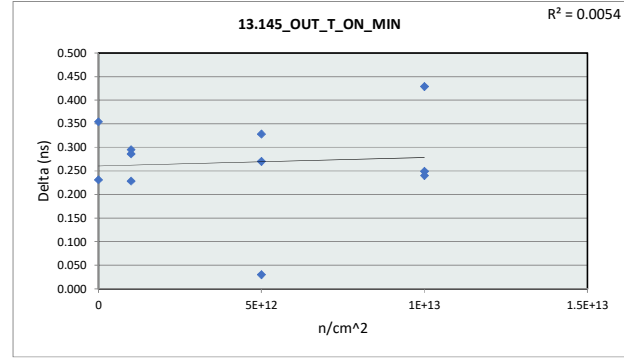


13.79_SPA_DT_100ns_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	110		ns	
Min Limit	85		ns	
n/cm ²	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	95.944	94.207	95.272	95.039
Average	96.996	94.675	96.321	96.198
Max	98.047	95.461	97.735	97.318
UL	110.000	110.000	110.000	110.000

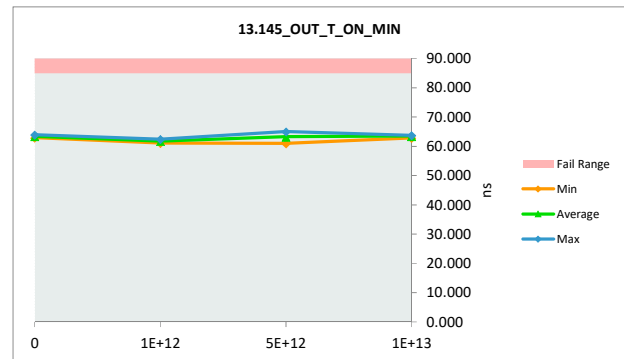


NDD Characterization Report TPS7H5006-SEP

13.145_OUT_T_ON_MIN				
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		85	85	
Min Limit		20		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	63.608	63.963	0.355
0	49	62.727	62.959	0.232
1E+12	11	60.944	61.173	0.229
1E+12	12	61.278	61.574	0.296
1E+12	13	62.178	62.465	0.287
5E+12	14	64.765	65.036	0.271
5E+12	15	60.967	60.998	0.031
5E+12	16	63.399	63.728	0.329
1E+13	17	63.485	63.735	0.250
1E+13	18	62.663	62.904	0.241
1E+13	19	63.393	63.823	0.430
Max		64.765	65.036	0.430
Average		62.673	62.942	0.268
Min		60.944	60.998	0.031
Std Dev		1.227	1.283	0.099

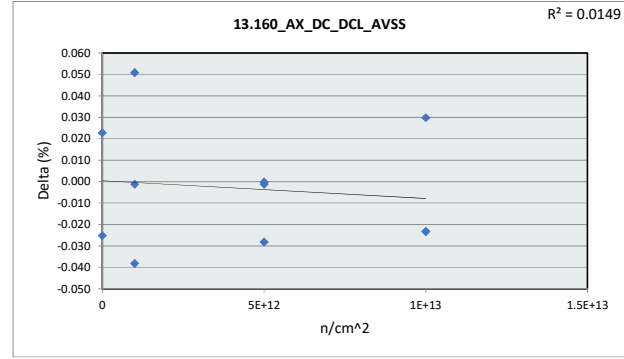


13.145_OUT_T_ON_MIN				
Test Site				
Tester				
Test Number				
Max Limit	85	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	62.959	61.173	60.998	62.904
Average	63.461	61.737	63.254	63.487
Max	63.963	62.465	65.036	63.823
UL	85.000	85.000	85.000	85.000

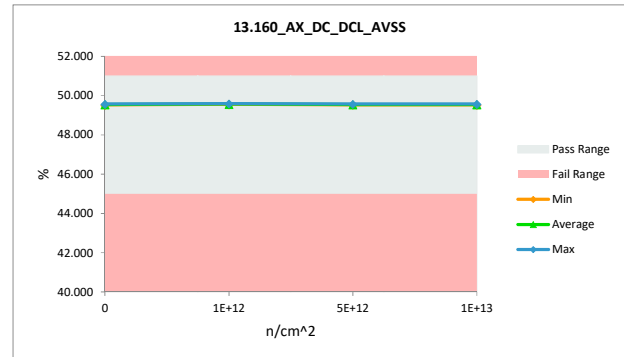


NDD Characterization Report TPS7H5006-SEP

13.160_AX_DC_DCL_AVSS				
Test Site				
Tester				
Test Number				
Unit		%	%	
Max Limit		51	51	
Min Limit		45	45	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	49.550	49.525	-0.025
0	49	49.550	49.573	0.023
1E+12	11	49.547	49.598	0.051
1E+12	12	49.593	49.555	-0.038
1E+12	13	49.563	49.562	-0.001
5E+12	14	49.546	49.546	0.000
5E+12	15	49.574	49.573	-0.001
5E+12	16	49.563	49.535	-0.028
1E+13	17	49.551	49.528	-0.023
1E+13	18	49.561	49.538	-0.023
1E+13	19	49.544	49.574	0.030
Max		49.593	49.598	0.051
Average		49.558	49.555	-0.003
Min		49.544	49.525	-0.038
Std Dev		0.015	0.023	0.028

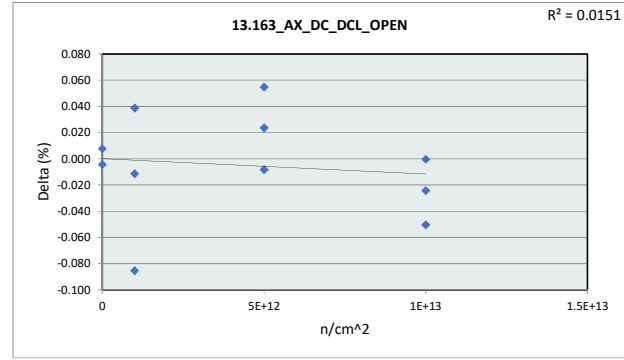


13.160_AX_DC_DCL_AVSS				
Test Site				
Tester				
Test Number				
Max Limit	51	%		
Min Limit	45	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	45.000	45.000	45.000	45.000
Min	49.525	49.555	49.535	49.528
Average	49.549	49.572	49.551	49.547
Max	49.573	49.598	49.573	49.574
UL	51.000	51.000	51.000	51.000

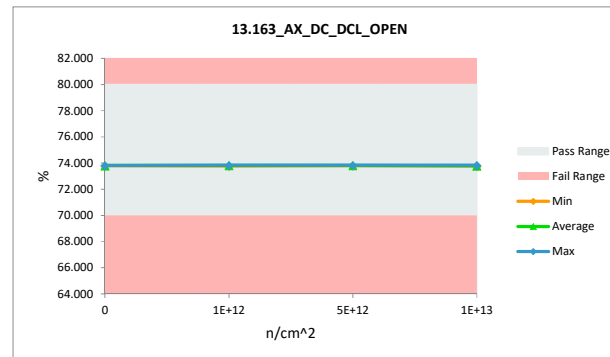


NDD Characterization Report TPS7H5006-SEP

13.163_AX_DC_DCL_OPEN				
Test Site				
Tester				
Test Number				
Unit		%	%	
Max Limit		80	80	
Min Limit		70	70	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	73.810	73.818	0.008
0	49	73.794	73.790	-0.004
1E+12	11	73.867	73.782	-0.085
1E+12	12	73.795	73.834	0.039
1E+12	13	73.854	73.843	-0.011
5E+12	14	73.831	73.823	-0.008
5E+12	15	73.783	73.838	0.055
5E+12	16	73.775	73.799	0.024
1E+13	17	73.837	73.837	0.000
1E+13	18	73.813	73.763	-0.050
1E+13	19	73.815	73.791	-0.024
Max		73.867	73.843	0.055
Average		73.816	73.811	-0.005
Min		73.775	73.763	-0.085
Std Dev		0.029	0.027	0.039

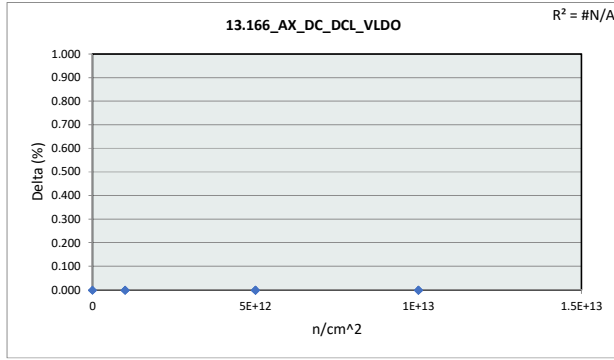


13.163_AX_DC_DCL_OPEN				
Test Site				
Tester				
Test Number				
Max Limit	80	%		
Min Limit	70	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	70.000	70.000	70.000	70.000
Min	73.790	73.782	73.799	73.763
Average	73.804	73.820	73.820	73.797
Max	73.818	73.843	73.838	73.837
UL	80.000	80.000	80.000	80.000

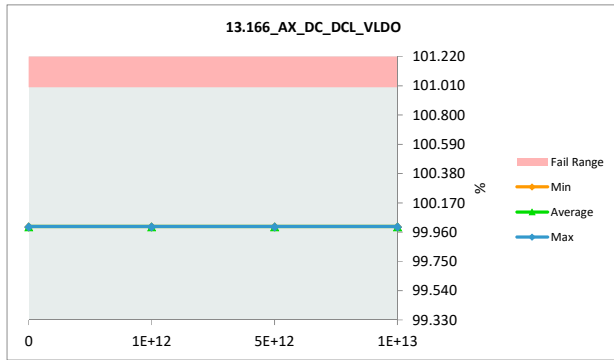


NDD Characterization Report TPS7H5006-SEP

13.166_AX_DC_DCL_VLDO				
Test Site				
Tester				
Test Number				
Unit		%	%	
Max Limit		101	101	
Min Limit		95		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	100.000	100.000	0.000
0	49	100.000	100.000	0.000
1E+12	11	100.000	100.000	0.000
1E+12	12	100.000	100.000	0.000
1E+12	13	100.000	100.000	0.000
5E+12	14	100.000	100.000	0.000
5E+12	15	100.000	100.000	0.000
5E+12	16	100.000	100.000	0.000
1E+13	17	100.000	100.000	0.000
1E+13	18	100.000	100.000	0.000
1E+13	19	100.000	100.000	0.000
Max		100.000	100.000	0.000
Average		100.000	100.000	0.000
Min		100.000	100.000	0.000
Std Dev		0.000	0.000	0.000



13.166_AX_DC_DCL_VLDO				
Test Site				
Tester				
Test Number				
Max Limit	101	%		
Min Limit		%		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	100.000	100.000	100.000	100.000
Average	100.000	100.000	100.000	100.000
Max	100.000	100.000	100.000	100.000
UL	101.000	101.000	101.000	101.000



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to [TI's Terms of Sale](#) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2022, Texas Instruments Incorporated